TECHNICAL MANUAL

DIRECT SUPPORT MAINTENANCE MANUAL

TEST SET GROUP, INDICATOR, RADAR OQ-63A/APS-94D (NSN 6625-01-058-7874)

WARNING

EXTREMELY DANGEROUS VOLTAGES EXIST IN THIS EQUIPMENT

Be careful when working on any connector of Test Set Group, Indicator, Radar OQ-63A/APS-94D. Test Set Subassembly MX-8638A/APS-94D and Test Set Subassembly MX-9639A/APS-94D contain connectors with terminals carrying 640 volts dc, 531 volts dc, 115 volts ac, and +100 volts dc.

DON'T TAKE CHANCES!

EXTREMELY DANGEROUS VOLTAGES EXIST IN THE FOLLOWING UNITS:

Test	Set	Subassembly	MX-8638A/APS-9	94D	+630	vde
Test	Set	Subassembly	MX-8639A/APS-9	94D	+531	vdc

WARNING

The fumes of TRICHLOROETHANE are toxic. Provide thorough ventilation whenever it is used; avoid prolonged or repeated breathing of vapor. Do not use near an open flame or hot surface; trichloroethane is non-flammable but heat converts the fumes to a highly toxic phosgene gas the inhalation of which could result in serious injury or death. Prolonged or repeated skin contact with trichloroethane can cause skin inflammation. When necessary, use gloves, sleeves and aprons which the solvent cannot penetrate.

TECHNICAL MANUAL NO. 11-6625-1833-30

HEADQUARTERS DEPARTMENT OF THE ARMY WASHINGTON, DC 25 April 1979

DIRECT SUPPORT MAINTENANCE MANUAL TEST SET GROUP, INDICATOR, RADAR OQ – 63A/APS – 94D (NSN 6625 – 01 – 058 – 7874)

REPORTING OF ERRORS

You can improve this manual by recommending improvements using DA Form 2928-2 located in the back of the manual. Simply tear out the self-addressed form, fill it out as shown on the sample, fold it where shown, and drop it in the rail.

If there are no blank DA Forms 2028-2 in the back of your manual, use the standard Form 2028 (Recommended Changes to Publications and Blank Forms) and forward to the Commander, Communications and Electronics Materiel Readiness Command, ATTN: DRSEL-ME-MQ, Fort Monmouth, NJ 07703.

In either case a reply will be furnished direct to you.

		Paragraph	Page
CHAPTER 1	INTRODUCTION	1-1	1 - 1
CHAPTER 2	PRINCIPLES OF OPERATION		2.1
Ţ	Test Set Group, Indicator, Radar OQ-63A/APS-94D, block diagram analysis	2-l	2-1 2-3
II		2-15	
	Video simulator and synchronizing circuits, circuit analysis	2-49	2-18
IV		2-61	2-23
V	Video amplifier circuit, circuit analysis	2-73	2-29
VI	Cathode ray tube focus circuit, circuit analysis	2-76	2-30
VIII	BITE and power supply circuits, circuit analysis	2-82	2-33 2-37
	ADAS simulator circuits, circuit analysis	2-93	
CHAPTER 3	Monitor adapter input simulator circuits, circuit analysis DIRECT SUPPORT MAINTENANCE INSTRUCTIONS	2-94	2-38
I	Introduction	3 - 1	3 - 1
II		3 - 4	3 - 1
III	Direct support maintenance of test set group	3-34	3-38
IV	Direct support testing procedures	3-44	3-48
V	Wire list for Test Set Group, Indicator, Radar OQ-63A/APS-94D	3-50	3-51
APPENDIX A	REFERENCES		A - 1
В	EXPENDABLE SUPPLIES AND MATERIALS LIST		B-1
INDEX	• •		Index 1
	List of Illustrations		
Figure No	Title		Page
_	# Annex		-
2-l Crt	Sweep Requirements		2 - 1
2-2 Тез	t Set Group, Indicator, Radar 00–63A/APS–94D, Major Functions, Block Disgram		2 - 2
2-3 Vid	eo Simulator and Synchronizing Circuits, Block Diagram		2-4
2-4 Ind	icating Systems Low Voltage Power Supplies Block Disgram		2 - 1
2-5 Lov	v Voltage Power Supply and Regulator, 1A2A3, Block Diagram		2-12
2-6 Ove	rvoltage Protection Circuit 1A2A5, Block Diagram		2-13
2-7 Dir	ect Current Amplifiers, 2A2/2A3, Block Diagram E Circuit, Block Diagram		2-14
2-8 BIT	E Circuit, Block Diagram		2 - 1 5
2-9 Reg	rulated +28 Volt Power Supply and High Voltage Loads, Block Diagram		2-16 2-17
	-		

	Trike	Page
2-11	Monitor Adapter Input Simulator, Plock Diagram	2-18
2-11	Timing Diagram for 750 Hz Prf Clocked Counter (sheet 1 and 2)	2-19
2-13	Cubing Amplifier, Simplified Schematic Diagram	2-25
2-14	Logarithmic Amplifiers, Simplified Schematic Diagram	2-27
2-15	Antilogarithmic Amplifier Circuit, Simplified Schematic Diagram	2-28
2-16 2-17	Squaring Amplifier Circuit, Simplified Schematic Diagram Stepper Motor Control, Simplified Schematic Diagram	$\frac{2-30}{2-32}$
2-17	Stepper Motor Control, Simplified Schematic Diagram	2-36
2-19	Film Speed Variable Voltage Circuit, Simplified Schematic Diagram Calibrated Film Speed Control Circuit	2-36 2-28
$\frac{2}{2} - \frac{1}{20}$	Deflection Decoder Timing Diagram	2-39
3 - 1	Control Synchro Aquestment Setup (A and B)	3-14
3 - 2	Test Set Group, Indicator, Radar OQ-63A/APS-94D, Waveforms (sheet 1 through 5)	3-18
3 - 3 3 - 4	Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Front Panel, Parts Location	3-40
3 - 4	Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Reat Chassis View, Parts Location	3-41 3-42
3 - 5	Test Set Subassembly MX-8738A/APS-94D, Unit 1A2, Front Panel, Parts Location	3-43
3 - 6 3 - 7	Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, Roar Chassis Top View, Parts Location	3-43
3 - 8	Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, Rear Chassis Bottom View, Parts Location Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, Rear Chassis View, Parts Location	
3 - 9	Test Set Subassembly MA - 5038A/AFS - 94D, Clift 1A2, Rear Chassis View, Farts Lacution Terminal Board 1A2TB3. Parts Location	3-44 3-45
3-10	Test Set Subassembly MX-8639A/APS-94D, Unit 2, Front Panel, Parts Location	3-46
3 - 1 1	Test Set Subassembly MX-8639A/APS-94D, Unit 2, Rear Chassis View, Parts Lecution	3-47
3-12	Test Set Subassembly MX - 8639A/APS - 94D, Unit 2, Bottom View, Parts Location	3-47
3-13	Terminal Board 2TB3, Parts Location	A 11
FO-1	Color Code Markings for Inductors, Resistors, and Capacitors	All fold
FO-2 FO-3	Indicating System Detailed Functions, Block Diagram (sheets 1 through 4)	outs
FO-4	Drift Angle Servo Loop, Block Dugram	are
FO-5	Test Set Group, Basic Test Setup Primary Power Distribution and Control Diagram	located
FO-6	Secondary Power Distribution and Control Curum Diagram (sheets 1 Chrough 8)	at the
FO-7 FO-8	Servo Le a, Simplified Wiring Diagram	back
	Pitteen Volt Power Supplies, Functional Schemuta	of the
FO-9	Test Set Subsecembly MX - 8635A/APS - 96D, Unit 1A1, Interconnection Diagram (wheets 1 and 2)	manual
FO-10 FO-11	ADAS Simulator Module 1A1A1, Schematic Diagram (sheets 1 and 2)	
FO-11 FO-12	Regulated + 28-Volt Power Supply and High Voltage Loads	
FO-13	Low Voltage Power Supply, 1A1AS, and Regulator, 1A3AS, Schematic Diagram Monster Adapter Imput Semulator, Schematic Diagram	
FO-14	Test Set Subsensessly, MX - 8626A/APS- 962, I nd 4A2, interconnection Program (cheets 4 through 4)	
FO-15	Five-MHy Oscillator and Pri Counter, 1A2A1, Schematic Playram	
FO-16	Ambanas Counter, 1A2A2, Schemutte Dissertion	
FO-17 FO-18	Low Voltage Power Supply Regulator, 1 A2A5, Schemate Dagreen	
FO-18 FO-19	BITE Corosia, 1A2A4, Schomatar Dingrum	
FO-19 FO-20	Overvoltage Protection Circuit, 1A2A5, Schomatic Pragram	
FO-21	Video Amplifher, I AZA6, Schemula: Plugrom Tast Set Sebassembly, MX—4786A. AP6—Hells, I on t. 2, Interconnection Pingrom (about 1 through 4)	
FO-22	Year Signalization, 2A.1, Subarmatic Diagram	
FO-23	Dayled Carries Assailant, 2A2/2A2 Indomacu Dagram	
FO-24	Swamp Conservation 234, Settermann Program: Streets I and 2)	
FO-25	Servencessistier, 2A.5, Schemete Diegrem (elnerte 3 and 2)	
FO-26 FO-27	Officet Amplifier, 2A6, Schemistic Diagram	
1.0-27	Offset Constrol, 2A7, Schrematic Tugrum	
	LIST OF TABLES	
	ma	Page
Table No.	學sete	1 450
3 - 1	Madding Calledon Contragueron account the action of the contraction of	V .
3 - 1	Treedlar grand Paret Wigner artister or the contract of the co	ħ s
3 - 1 3 - 2 3 - 3	Tand Period d'insernation Per d'Aranie Matterraries	Ø €*
5 - 5	Primary Feneral Distorduction Trans	第二章: 第二章:
3-4 3-5	Primary Rowal Giaselhusian Tradhodharting	¥ **
3 - 6	Lane Va. age Parene Suggestion Sent Lane Valinage Person Suggestion Sympthism true	b :•
5-0	Frence. in considerate à commentation des la constitution à alconstantes est fils.	

Table No.	Title	Page
3-7	Panel Lights Test	3-9
3-8	Panel Lights Troubleshooting	3-10
3-9	Servo Loop Test	3-10
3-10	Servo Loon Troubleshooting	3-12
3-11	Servo Loop Supplementary Test	3-12
3-12	Clock Waveform Test	3-15
3-13	Clock Waveform Troubleshooting	3-16
3-14	Film SpeedTest	3-22
3-15	Film Speed Troubleshooting	3-23
3-16	Intensity Control Voltage Test	3-24
3-17	Intensity Control Voltage Troubleshooting	3-24
3-18	Vertical Sweep Waveform Test	3-25
3-19	Vertical Sweep Waveform Troubleshooting	3-25
3-20	Horizontal Sweep Waveform Test	3-27
3-21	Horizontal Sweep Waveform Troubleshooting	3-27
3-22	Unblank Circuit Test	3-28
3-23	Unblank Circuit Troubleshooting	3-28
3-24	Offset Circuit Test	3-28
3-25	Offset Circuit Troubleshooting	3-29
3-26	Video Compression Test	3-30
3-27	Video Compression Troubleshooting	3-31
3-28	BITE, Sweep, Indicator and Servo Fault Circuits Test	3-32
3-29	BITE, Sweep, Indicator and Servo Fault Circuits Troubleshooting	3-33
3-30	ADAS Simulator Test	3-35
3-31	ADAS Simulator Troubleshooting	3-35
3-32	Monitor Adapter Input Simulator Test	3-36
3-33	Monitor Adapter Input Simulator Troubleshooting	3-36
3-34	Dynamic Focus Test	3-36
3-35	Dynamic Focus Troubleshooting	3-37
3-36	High Voltage Load Test High Voltage Load Troubleshooting	3-37
3-37	High Voltage Load Troubleshooting	3-38
3-38	Indicator Simulator, Unit IA1. Physical Test and Inspection	3-49
3-39	Indicator Simulator, Unit 1A2, Physical Test and Inspection	3 - 49
3-40	Generator Simulator, Unit 2, Physical Test and Inspection	3-50
3-41	Test Set Subassembly MX-8638A/APS-94D, Unit IA1, Wire List	3-51
3-42	Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, Wire List	
3-43	Test Set Subassembly MX-8639A/APS-94D, Unit2, WireList	3-75

CHAPTER 1

INTRODUCTION

1-1. Scope

- a. This manual contains direct support maintenance instructions for Test Set Group, Indicator, Radar OQ-63A/APS-94D. This manual includes instructions appropriate to direct support maintenance facilities for troubleshooting, testing aligning, and repairing the equipment. It also lists tools and test equipment required for maintenance.
- b. The complete technical manual for this equipment includes TM 11-6625-1833-12.
- 1-2. Indexes of Publications
- a. DA Pam 310-4. Refer to the latest issue of DA Pam 310-4 to determine whether there are new editions, changes or additional publications pertaining to the equipment.
- b. DA Pem 310-7. Refer to the latest issue of DA Pam 310-7 to determine whether there are any modification work orders to the equipment.
- 1-3. Forms and Records
- a. Reports of Maintenance and Unsatisfactory Equipment. Maintenance forms, records, and reports which are to be used by maintenance personnel at all maintenance levels are listed in and prescribed by TM 38-750.

- b. Report of Packaging and Handling Deficiencies. Fill out and forward DD Form 6 (Packaging Improvement Report) as prescribed in AR 700-58/NAVSUPINST 4080.29/AFR 71-18/MCO P4080.29A, and DSAR 4145.6.
- c. Discrepancy in Shipment Report (DISREP) (SF 361). Fill cut and forward Discrepancy in Shipment Report (DISREP) (SF 361) as prescribed in AR 55-38/NAVSUPINST 4610.38B/AFR 75-16/MCO P4610.19C and DLAR 4500.15.
- 1-4. Reporting Equipment Improvement Recommendations (EIR)

EIR's will be prepared using SF 368, Quality Deficiency Report. Instructions for preparing EIR's are provided in TM 38-750, The Army Maintenance Management System. EIR's should be mailed directly to Commander, US Army Communications and Electronics Materiel Readiness Command, ATTN: DRSEL-ME-MQ, Fort Monmouth, NJ 07708. A reply will be furnished directly to you.

1-5. Calibration

Refer to the calibration procedures given in paragraphs 3-41 through 3-43 of this technical manual and the calibration procedures given in TB 11-6625-1638-35-1.

CHAPTER 2

PRINCIPLES OF OPERATION

Section I. TEST SET GROUP, INDICATOR, RADAR OQ-63A/APS-94D, BLOCK DIAGRAM ANALYSIS

2-1. General

Test Set Group, Indicator, Radar OQ-63A/APS-94D (test set group) is a portable test set that permits bench testing, aligning, calibrating, and trouble-shooting of the unite and plug-in modules of Radar Surveillance Set AN/APS-94D cockpit complex (less Recorder-Processor-Viewer, Radar Mapping RO-495/U). The test set group components function together as a single operating unit through interconnecting cables simulating signals and voltages required for Radar Surveillance Set AN/APS-94D operation and testing.

2-2. Overall System Function

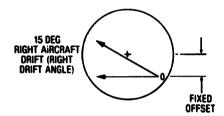
Test set group generates the video information and sweep signals required to operate either the fixed target or moving target cathode-ray tubes, or the monitor crt of Recorder-Processor-Viewer RO-495/U. Through the use of test set group cabling. units of the cockpit complex are tested under dynamic conditions by substituting units electrically for corresponding circuitry in the test set group. Plug-in modules of the units are tested dynamically by physically substituting them for corresponding modules in the test set group. Paragraph 2-3 describes the basic crt sweep requirements of a radar indicating system as information that will help to understand the functional operation of the test set group. Paragraphs 2-4 through 2-14 discuss the major block diagram functions of the test set group. Detailed block diagram functions are discussed in section II of this chapter. Detailed circuit functions are discussed in sections III through IX of this chapter.

2-3. Radar Indicating System Crt Swoop Requirements.

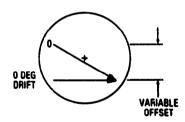
(fig. 2-1)

In order to maintain a linear display of video information on the crt, horizontal and vertical sweep signals must produce constant-velocity traces. Further, the traces must remain in *focus over* their entire length to maintain resolution. Provisions are

required to permit rotation of the trace in correspondence with selectable simulated drift angle inputs (fig. 2-1). A means must be provided to correlate sweep direction and starting and stopping points with selectable simulated antenna switching modes. In the AN/APS-94E right(R) antenna mode,



A LEFT ANTENNA MODE



B RIGHT ANTENNA MODE

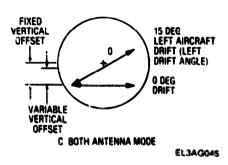


Figure 2-1. Crt sweep requirements.

the trace must start at the left edge of the crt and sweep right. In the left (L) antenna mode, the trace must start at the right edge of the crt and sweep left. In the BOTH antenna mode the trace must start at the center and sweep alternately in each direction in synchronism with antenna switching. Sweep rates must conform to selectable simulated range segments. Finally, vertical offset must be added to the sweep signals to meet crt photomapping requirements.

2-4. Video Simulator and Synchronizing Circuit

$$(fig. 2-2)$$

The video simulator and synchronizing circuit generates video information for display on the crt. In addition, this circuit generates the necessary timing signals for synchronizi, g the functions of other major circuits. The basic time reference for this circuit is a 5-MHz crystal controlled oscillator.

2-5. Sweep Circuit

$$(fig. 2-2)$$

The sweep control circuit contains circuitry for controlling rotation of the crt trace as well as selection of range display.

2-6. Horizontal Sweep Circuit

The horizontal sweep circuit contains circuitry necessary to generate a horizontal sweep ramp signal,

offset this signal during left or right antenna mode, and correct the waveshape of the ramp signal to compensate for pincushion distortion. The ramp signal is also utilized by the vertical sweep circuit, the crt regulator and focus circuit, and the video amplifier.

2-7. Vertical Sweep Circuit

The vertical sweep circuit contains circuitry necessary to generate a vertical sweep ramp voltage in order to rotate the crt trace. The vertical sweep circuit also provides a fixed vertical offset. The ramp signal is also utilized by the crt regulator and focus circuit.

2-8. Video Amplifier

$$(fig. 2-2)$$

The video amplifier amplifies video signals from the video simulator and synchronizing circuit and provides fixed and selectable compression as a function of range display — antenna operation. The video amplifier also contains unblanking circuitry which receives a ramp signal from the horizontal sweep circuit.

2-9. Groundspeed/Drift Angle Servo Loop

The groundspeed/drift angle serve loop provides selectable channel operation. In the drift angle mode, a variable synchro input is supplied to a drift angle amplifier channel and is read out on a stepper-motor-

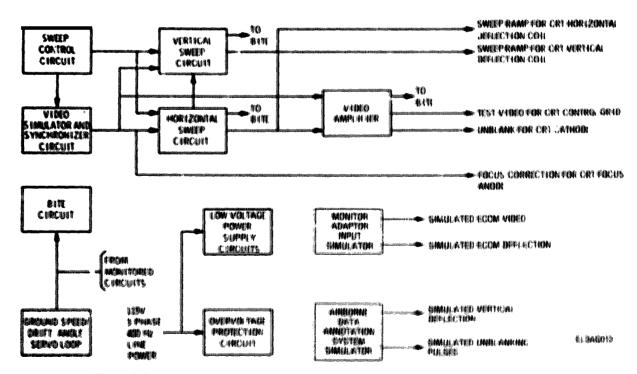


Figure 2-2. Find Sed Group, Indicator Radio (14)-484, APE-441 major functions that diagrams

driven indicator. In the groundspeed mode, the same **variable synchro** input is supplied to a groundspeed **amplifier chan**nel and is read out on the same indicator. With the exception of a fault output to the **BITE circuit** and power source connections, the **groundspeed**/drift angle servo loop is independent of **all other** circuits in the test set group.

2-10. BITE Circuit (fig. 2-2)

The BITE (built-in test equipment) circuit monitors major circuits in the test set group to provide four individual failure lamp indications. The vertical and horizontal sweep circuits and the video amplifier are monitored to provide failure indication on the first of the four lamps. The video amplifier is monitored to provide a sweep fault indication on the second lamp. The anode regulator and crt regulator and focus circuit are monitored to provide a fault indication on the third lamp. Either channel of the groundspeed/drift angle servo loop is monitored to provide a control fault indication on the fourth lamp.

2-11. Overvoltage Protection Circuit (fig. 2-2)

The overvoltage protection circuit monitors each of the three phases of ac line power. At approximately **200 volts peak and above, the** overvoltage **protection** circuit electronically **short circuits each phase of line** power, which is then interrupted by circuit breakers.

2-12. Low Voltage Power Supply Circuits

(fig. 2-2)

The low voltage power supply circuits provide 13 regulated voltages and one unregulated voltage. The voltages range from -20 vdc to +640 vdc.

2-13. Monitor Adapter Input Simulator (fig. 2-2)

The monitor adapter input simulator generates simulated ECCM video and ECCM deflection signals. These signals are used to test the monitor display adapter circuits in Recorder-Processor-Viewer, Radar Mapping RO-495/U.

2-14. ADAS Simulator

(fig. 2-2)

The ADAS simulator provides vertical and unblanking signals to exercise the ADAS printer circuitry of Recorder-Processor-Viewer, Radar Mapping RO-495/U.

Section II. TEST SET GROUP, INDICATOR,

RADAR OQ-63A/APS-94D DETAIL BLOCK DIAGRAM ANALYSIS

2-15. General

This section describes the functioning of the test set group at the detail block diagram level. All of the major circuits discussed in section I of this chapter are discussed on a detail block diagram basis. The sweep control circuit, vertical sweep circuit, horizontal sweep circuit, focus circuit, and the video amplifier, are included on one block diagram illustration due to the functional interrelationship of these circuits.

2-16. Video Simulator and Synchronizing Circuit

(fig. 2-3)

The video simulator and synchronizing circuit generates a basic time reference with a 5-MHz oscillator. The square wave output of the oscillator is supplied to a 750-Hz prf clocked counted and to the video amplifier circuit (para 2-32) through the pulse width logic circuitry. The 750-Hz prf clocked counter counts the 5-MHz square wave down to the 750-pulse repetition frequency (prf) used in the test set group. The output of the 750-Hz prf clocked counter is supplied to each of two groups of pulse width logic cir-

cuitry to establish pulse widths. One of the two groups of pulse width logic circuitry establishes the pulse width for the 750-Hz fixed-target (ft) video signal supplied to the video amplifier circuit. Pulse amplitude is controlled by VIDEO AMPLITUDE control 1A2R19. The other group of logic circuitry **derives** a sweep gate signal and a yoke clamp signal. The pulse width of these two signals is determined by control panel range selection. The third output from this group is supplied to a divide-by384 antenna counter. The output of the counter is supplied to a third group of logic circuitry that provides ft and moving-target (mt) enable pulses and an antenna gate. The antenna gate is selected by control panel selection for left, right, or both antenna operation.

2-17. Sweep Control Circuit-(fig. FO-2 and FO-21)

The sweep control circuit provides control of antenna mode, horizontal and vertical range selection, and cathode ray tube (crt) trace rotation. Paragraphs 2–18 through 2–31 provide a description of the circuits that perform these operations. Figure FO-21 shows module interconnection for Test Set Subassembly MX-8639A/APS-94D (unit 2).

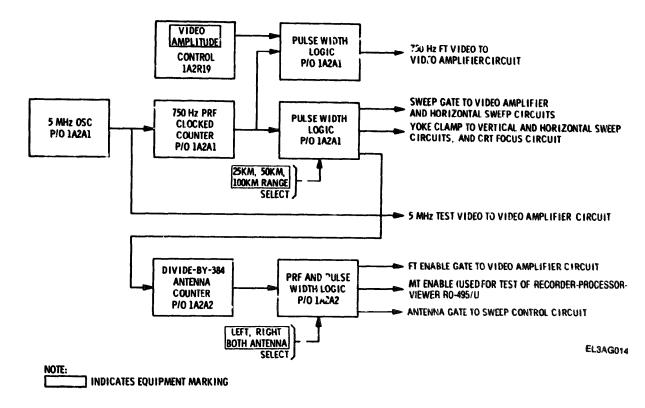


Figure 2-3. Video simulator and synchronizing circuits, block diagram

2-18. A Sine 0/ A Cosine 0 Signal Generation (fig. FO-2)

When ANTENNA switch 2S9 is set to either LEFT or RIGHT, the test set group operates in the single antenna mode. In this mode, the sweep control circuit receives from the video simulator and synchronizer circuit (fig. 2-3) an antenna gate that is either -4 volts (left antenna) or +4 volts (right antenna). When ANTENNA switch 2S9 is set to BOTH, the sweep control circuit receives a square wave antenna gate input from the video simulator and synchronizing circuit (waveform A fig. FO-2). The antenna gate is applied to left/right switch 2A1Q12, Q13 through switch driver 2A1Q10, Q11 via panel connectors and cables. When the antenna gate is +4 volts (right antenna) left/right switch 2A1Q12, 13 applies approximately +10 volts from 25 km right control 2TB3R5 to amplifier 2A6A1AR3, AR4. When the antenna gate is -4 volts (left antenna) left/right switch 2A1Q12, Q13 applies approximately -10 volts from OFFSET GAIN control 2R11 to amplifier 2A6A1AR3, AR4. The square wave outputs of amplifier 2A6A1AR3, AR4 are connected to cosine # voltage divider 2A1R31, R32, R33, and sine voltage divider 2A1R28, R29, R30. The outputs of cosine voltage divider 2A1R31, R32, R33 are connected to DRIFT ANGLE switch 2S11 -3, -2. The outputs of sine voltage divider 2A1R28, R29, F.30

are connected to DRIFT ANGLE switch 2S11, -9, -8. When DRIFT ANGLE switch 2S11 is set to 15, the voltage at wiper 2S11W3 represents the sine of 15 degrees and the voltage at wiper 2S11W1 represents the cosine of 15 degrees. Similarly, setting DRIFT ANGLE switch 2S11 to 1.8 enables the selection of voltages, from the cosine and sine voltage dividers, that represent the cosine and sine of 1'.8 degree. Setting DRIFT ANGLE switch 2S11 to 0 connects wiper 2S11W3 to ground and connects wiper 2S11W1 directly to the output of amplifier 2A6A1AR4. (The signals at wipers W1 and W3 of DRIFT ANGLE switch 2S11 are termed A cosine θ and A sine θ , respectively, to distinguish them from cosine θ and sine θ signals developed through the action of the horizontal range selection circuit (para 2-19) and vertical range selection circuit para 2-20).) The A cosine θ and A sine θ signals at wipers W1 and W3 are coupled through Fource followers 2A6A1AR6 and AR2 to their respec-'ve sections of ANTENNA swtich 289 and to voltage 'n iders 2A7R11 - R14 and 2A7R7 - R10.

2-19. Horizontal Range Selection (fig. FO-2)

The A cosine θ signal is applied to horizontal range voltage divider 2A7R11 - R14 and ANTENNA switch 2S9B through source follower 2A6A1AR6.

Since the divider output is ultimately used as charging voltage for sweep generator 2A4AlAR2 in the horizontal sweep circuit (para 2-21), the slope of the horizontal sweep generator output ramp signal is controlled by selecting one of the horizontal range voltage divider outputs, providing 25, 50, or 100-km ranges. Selection of the proper divider output is accomplished by ANTENNA switch 2S9B in conjunction with RANGE switch 2S8B. The divider output is routed from wiper W4 of RANGE switch 2S8B through source follower 2A6AlAR5 to the horizontal sweep circuit as the cosine 0 signal. The cosine 0 signal developed here is applied to the horizontal sweep circuit (para 2-21 through 2-26) to generate signals necessary to modify the horizontal crt sweep when the trace is rotated 0 degrees.

2-20. Vertical Range Selection (fig. FO-2)

The operation of the A sine 0 channel is similar to that of the A cosine 0 channel with two exceptions. First, there is no A sine 0 signal when DRIFT ANGLE switch 2S11 is set to 0 zero) because in that position wiper W3 is grounded. Second, an offset gain voltage is applied to the A sine 0 signal to provide control of the position of the trace on the crt. The offset gain signal is applied to the antenna gate by adjusting OFFSET GAIN control 2Rll (para 2-18). The A sine 0 output at 2S8B (W1) is routed through source follower 2A6AlARl to the vertical sweep circuit as the sine 0 signal. The sine 0 signal developed here is applied to the vertical sweep circuit (para 2-28 through 2-31) to generate the signals necessary to position and rotate the crt trace to an angle of 0 degrees.

2-21. Horizontal Sweep Circuit (fig. FO-2)

The horizontal sweep circuit contains circuitry necessary to generate a horizontal sweep ramp voltage, offset this ramp signal for single antenna operation, and correct the waveshape of the ramp signal to compensate for pincushion distortion. In addition, the horizontal sweep signal is used by the crt focus circuit and the vertical sweep circuit. Paragraphs 2-22 through 2-26 describe the operation of the circuitry performing these functions.

2-22. Horizontal Offset

(fig. FO-2)

The horizontal sweep circuit receives sweep **gate** (waveform D fig. FO-2) and yoke clamp (waveform E) signals from the video simulator and synchronizing circuit (fig. 2-3). These signals, in conjunction with the cosine 0 output of the sweep control circuit, generate proper drive currents for the ft and mt crt horizontal yoke loads. When the test set group is operated in either the left or right antenna mode, the

crt trace must be offset to start at one edge of the cathode ray tube, rather than at the center. Voltages necessary to provide these offsets are developed by LEFT HORIZONTAL OFFSET control 2R9 and RIGHT HORIZONTAL OFFSET control 2R12 (fig. FO-2). ANTENNA switch 2S9C (W4) selects the appropriate offset control output, routes it through switch 2A4AlQ5 to summing amplifier 2A4AlAR4. Summing amplifier 2A4AlAR4 sums the offset voltage with the output of horizontal sweep generator 2A4AlAR2. Considerable power is required to hold the trace at the edge of the crt. To avoid unnecessary power dissipation, the yoke clamp output of switch driver 2A4AlQ2 inhibits application of the offset voltage, except during the yoke clamp interval, by turning off switch 2A4AlQ5. (Waveforms D and E are shown for zero range delay operation.) When ANTENNA switch 2S9C (W4) is set to BOTH, ground is applied to switch 2A4AlQ5 which, in turn, causes the offset signal input to summing amplifier 2A4AlAR4 to become zero volts, thus allowing the sweep to start at the center of the crt.

2-23. Horizontal Sweep Generator (fig. FO-2)

The cosine 0 output from the sweep control circuit is applied as charging voltage to sweep generator 2A4AlAR2 through switch 2A4AlQ3, Q4. When the sweep gate is present, switch 2A4AlQ3, Q4 is open, allowing the sweep generator to develop a linear ramp output voltage (waveform F). At the end of the sweep gate, switch 2A4AlQ3, Q4 conducts to terminate the sweep. Since the voke clamp terminates at the end of the sweep interval, the blanked trace returns to the center of the crt. When ANTENNA switch 2S9 is set to BOTH, the polarity of the cosine 0 signal revers with the antenna gate signal. This causes the sweep generator to provide a group of positive ramp signal outputs (left antenna), followed by a group of negative ramp signal outputs (right antenna). Before the sweep is supplied for the ft or mt deflection yoke loads, it must be corrected for pincushion distortion.

2-24. Horizontal Pincushion Correction (fig. FO-2)

Pincushion distortion results from the fact that the position of the spot on the face of the crt is not directly proportional to the deflection angle. In addition, spot deflection is not linear with respect to deflection yoke current. To compensate for these conditions, the output waveshape of horizontal sweep generator 2A4A1AR2 is altered to provide the proper yoke current waveshape. The deflection angle is linearly related to the arc sine of the horizontal and vertical yoke currents, and the position of the spot on the face of the crt is linearly related to the tangent of the deflection angle. Horizontal sweep generator 2A4A1AR2 and vertical sweep generator 2A4A1AR6

provide sweep signals that are linear with respect to time. Without correction, therefore, the spot would accelerate as it moved away from the center of the crt. By changing the waveshape of the horizontal and vertical sweep generator outputs, a composite yoke current is obtained so that spot deflection is related to the sine of the uncorrected deflection angle. This results in a constant spot velocity to assure linear display of information on the crt. Cubing amplifier 2A4A2AR9 and summing amplifier 2A4A2AR12 perform the correcting function for the horizontal sweep circuit. The cubing amplifier consists of a nonlinear network and an operational amplifier that generates an output which corresponds to the cube of its input

divided by 100; or $E_{out} - \frac{(E_{in})^3}{100}$. This output is

waveform G. This signal is combined with the offset sweep generator output from summing amplifier 2A4A1AR4 (para 2-22) by summing amplifier 2A4A2AR12. In summing amplifier 2A4A2AR12, the cubed input is divided by 22 and summed with the offset sweep generator output to obtain the corrected output signal (waveform H). This signal is supplied to polarity sensor driver 2A1AR1, dc amplifier 2A2, and HORIZONTAL AMPLIFIER SWEEP LENGTH control 2R3.

2-25. Horizontal Yoke Loads (fig. FO-2 and FO-22)

Dc amplifier 2A2 is a noninverting amplifier that supplies drive current for simulated mt crt horizontal yoke load lA2Ll or simulated ft crt horizontal yoke load 1A2L4. This amplifier receives a feedback sample of yoke load current to assure that the yoke current is following the corrected sweep voltage (waveform H). The output of dc amplifier 2A2 is supplied to either simulated mt crt horizontal voke load IA2L1 or simulated ft crt horizontal yoke load 1A2L4, depending on the position of DISPLAY switch 2S3. HORIZONTAL AMPLIFIER CENTER control 2R2 and HORIZONTAL AMPLIFIER SWEEP LENGTH control 2R3 permit control panel adjustment of horizontal sweep centering and sweep length, depending on the position of HORIZONTAL **AMPLIFIE**'R switch 2S2. The corrected sweep (waveform H) is also supplied to polarity sensor driver 2A1AR1 (fig. FO-22). This driver is an inverting, open loop operational amplifier that saturates or cuts off at microvolt input levels. The output of 2A1AR1 driver power switch 2A1Q3-Q6 via bipolar switch 2A1Q2. Switch 2A1Q2 is opened between sweeps by the yoke clamp gate (waveform E fig FO-2) via switch driver 2A1Q1. This ensures that switch 2A1Q3-Q6 does not conduct in the absence of signal input at 2A1AR1. Current pulses supplied to

simulated mt crt horizontal yoke load 2R8 are of opposite polarity to those supplied to either load 1A2L1 or load 1A2L4. In this manner, the +26-volt and -20-volt power supplies operate into essentially similar load and regulation requirements as are present in the radar system.

2 - 26. **Horizontal Unipolarizer** (fig. FO-2)

In addition to pincushion correction, compensation for incorrect focusing of the edges of the crt (astigmatism) is incorporated in the test set group. Since the required correction is related to the position of the spot on the crt face, samples of horizontal and vertical sweep signals are supplied to the crt regulator and focus circuit, which develops the necessary correction voltages. Before the horizontal sweep sample is routed to the crt regulator and focus circuit, it is modified by a unipolarizer circuit consisting of negative sweep detector 2A4A1AR5 and horizontal unipolarizer 2A4AlAR7. In both antenna operation, the antenna gate causes polarity reversal of the horizontal sweep signal (waveform J). This signal is supplied to negative sweep detector 2A4A1AR5 where positive sweeps are suppressed (waveform K). At unipolarizer 2A4A1AR7 the horizontal sweep signal is summed with the doubled negative sweep detector output and then inverted (waveform L). This signal is supplied to the crt regulator and focus circuit where it is used to develop center-to-edge focus correction. This signal (waveform L) is also supplied to the vertical sweep circuit where it is used in the development of vertical pincushion correction. During single antenna operation, the crt regulator and focus circuit require input signals for edge-to-edge focus correction. The unipolarizer circuit provides the proper horizontal output in the same manner as for both antenna operation. However, since its inputs are different, its outputs are different. Waveforms M, N, and Q illustrate unipolarizer signals for right untenna operation. Waveforms O, P, and Q show the same signals for left antenna operation.

2-27. Regulated Plus and Minus 9-Volt Source (fig. FO-2)

The horizontal and vertical sweep circuits require balanced positive and negative voltage sources. These voltages are developed from the regulated +15 vdc input to the sweep circuits. The +15 volts is supplied to source follower 2A4A2AR1, which provides the +9 vdc output. The -9 volts output is produced by inverter 2A4A2AR3. Consequently, any change in the +9 vdc source causes a corresponding change in the -9 vdc source and balance is maintained.

2-28. Vertical Sweep Circuit (fig. FO-2)

The vertical sweep circuit provides a fixed vertical offset of the crt sweep and generates a vertical sweep ramp signal to permit rotation of the crt sweep. Paragraphs 2-29 through 2-31 describe this function.

2-29. Vertical Offset (fig. FO-2)

The vertical sweep circuit receives an inverted sweep gate signal from driver 2A4AlQl in the horizontal **sweep** circuit. This signal, in conjunction with the **sine** θ and offset gain outputs from the sweep control circuit, generate proper drive currents for the ft and mt vertical yoke loads. In the vertical sweep circuit, two offset signals are required. One is a fixed offset voltage (static offset) from VERTICAL OFFSET contro**l 2R10** that establishes the vertical position for the start or stop of the horizontal sweep. In order to maintain this position during receipt of aircraft drift angle inputs, an offset gain voltage (dynamic offset) is summed with the static offset. The amplitude of the dynamic offset depends upon the setting of ANTENNA switch 2S9, DRIFT ANGLE switch 2S11, and RANGE switch 2S8. In the left antenna mode, with RANGE switch 2S8 set to 25 and DRIFT **ANGLE** switch 2S11 set to 15, the summed static and **dynamic** offsets pass through switch 2A4AlQ6 to appear as one input for summing amplifier 2A4AlAR8. The dynamic offset (offset gain signal) **origin**ates in the sweep control circuit and is supplied to polarity sensor 2A4A1AR1 and switch 2A4A1Q8. **Polarity** sensor 2A4AlARl turns on switch 2A4AlQ3, permitting the dynamic offset voltage to pass through low-pass filter 2A4AlC8, R18, and source follower 2A4AlAR3 in the presence of drift angle input. The output of 2A4AlAR3 is fed to summing network 2A4AlR4, R21 where it is summed with the static offset voltage (2R10), causing the spot position to shift point 0 (A, fig. 2-1). When the sweep gate occurs, the output of vertical sweep generator 2A4A1AR6 is applied to summing amplifier 2A4A1AR8 so that the spot traces the path shown. Setting ANTENNA switch 2S9 to RIGHT reverses polarity of the dynamic offset voltage. Polarity sensor 2A4A1AR1 turns switch 2A4A1Q8 off and turns 2A4A1Q7 on via ANTENNA switch 2S9D (W3). With switch 2A4A1Q7 on, a zero volt level is summed with the static offset signal. Consequently, the output from summing amplifier 2A4A1AR8 causes the trace to sweep down as shown at B, figure 2-1. In the BOTH antenna mode, -20 vdc is supplied to switch 2A4A1Q7 via ANTENNA switch 2S9D (W3) to hold this switch off. Since the polarity of the dynamic offset signal reverses in step with the antenna gate.

switch 2A4A1Q8 is continuously toggled by the polarity sensor. With left aircraft drift (C, fig. 2-1), switch 2A4A1Q8 is on during the right antenna interval, charging capacitor 2A4A1C8 to the value established by voltage divider 2A7R7—R10 in the sweep control circuit. During the left antenna interval, switch 2A4A1Q8 is open; however, capacitor 2A4A1C8 holds its charge, and the dynamic offset is maintained at summing network 2A4A1R4, R21 so that the spot traces the path shown at C, figure 2-1. A vertical offset override signal can be supplied to switch 2A4A1Q6 to inhibit application of the vertical offset signals. This signal is provided by setting VERTICAL OFFSET OVERRIDE switch 1A2S4 to ON which allows approximately -20 vdc turn off potential to be applied to 2A4A1Q6 through load 2A4A1R11.

2-30. Vertical Sweep Generator.

(fig. FO-2)

Sweep generator 2A4AlAR6 and switches 2A4AlQ9, Q10 operate in the same manner as the sweep generator circuitry in the horizontal sweep circuit. However, since the charging voltage is derived from the sine 0 output of the sweep control circuit, the output ramp of the sweep generator reverses with drift angle as well as antenna selection. The offset vertical sweep signal from summing amplifier 2A4AlAR8 is supplied to the pincushion correction circuit before being routed to the ft and mt vertical deflection yoke loads.

2-31. Vertical Pincushion Correction (fig. FO-2)

The conditions relating to pincushion distortion correction in the horizontal sweep circuit are applicable for the vertical sweep circuit. However, the vertical sweep circuit requires incorporation of the horizontal signal since vertical deflection is small with respect to horizontal deflection. Uncorrected vertical and horizontal sweep signals are combined in a multiplier circuit consisting of logarithmic amplifiers 2A4A2AR5, AR7, summing amplifier 2A4A2AR8, and antilogarithmic amplifier 2A4A2AR10. Prior to multiplication, the vertical sweep signal is fed to a unipolarizer circuit (negative sweep detector 2A4A2AR2 and vertical unipolarizer 2A4A2AR4) that performs the same function as the unipolarizer circuitry in the horizontal sweep circuit. Waveform S illustrates the unipolarized uncorrected vertical sweep signal for right antenna mode and either 1.8 or 15 degrees drift angle. The output from unipolarizer 2A4A2AR4 is supplied to summing amplifier 2A4A2AR8 through logarithmic amplifier 2A4A2AR5. The output of 2A4A2AR5 (waveform T) is a function of the logarithm of its input. The second

input to summing amplifier 2A4A2AR8 is the output of logarithmic amplifier 2A4A2AR7 (waveform U). This amplifier has a transfer function equivalent to $E_{out} = log 1.6 (E_{in})^2$. Summing amplifier 2A4A2AR8 adds and inverts its inputs to provide an input for antilogarithmic amplifier 2A4A2AR10. This amplifier provides an output (waveform V) that is proportional to the antilogarithm of its input. Consequently, its output is proportional to the product of the horizontal and vertical sweep signals. A portion of this signal is summed in summing amplifier 2A4A2AR11 with the uncorrected vertical sweep voltage to produce the corrected vertical sweep (waveform W) for the vertical deflection yoke loads. Since the uncorrected sweep signal polarity can be positive or negative, the correction voltage must be inverted as required. This is accomplished by driver 2A4A2AR6, switches 2A4A2Q1 and 2A4A2Q2, and inverter 2A4A2AR13. When the uncorrected vertical sweep (waveform R) is negative, negative sweep detector 2A4A2AR2 provides a positive output that is inverted by driver 2A4A2AR6 to turn on switch 2A4A2Ql. With 2A4A2Ql on, the direct output of the antilogarithmic amplifier passes through the switch. When the uncorrected sweep is positive, negative sweep detector 2A4A2AR2 develops a negative output and switch 2A4A2Q2 is turned on, causing the inverted correction signal from inverter 2A4A2AR13 to pass through switch 2A4A2Q2. The selected output is routed through voltage divider 2A4A2R62, R63, R75, R76 to summing amplifier 2A4A2AR11 where it is summed with the uncorrected sweep signal. The corrected sweep output (waveform W) from summing amplifier 2A4A2AR11 is fed to dc amplifier 2A3 and to VERTICAL AMPLIFIER SWEEP LENGTH control 2R5. (Paragraph 2-41 describes operation of the dc amplifiers). In addition to corrected sweep output, the vertical sweep circuit provides a unipolarized output signal for use by the crt regulator and focus circuit.

2 - 3 2. Video Amplifier Circuit (fig. FO-20)

The video amplifier circuit receives video from the video simulator and synchronizing circuit (fig. 2-3), prepares this information for display, and supplies it to panel connector 2J1. Two video signals are supplied to the video amplifier; an ft video signal that is a 102.4 µs pulse at 750 Hz and a test video signal that is a 5-MHz square wave. Video signal selection is accomplished by setting TEST VIDEO switch IA2S3 to ON for test video or to OFF for ft video. In the ON position, +28 vdc is supplied to the solenoid of relay IA2K4 through TEST VIDEO switch IA2S3. In the OFF position, ft video is applied to video amplitude adjust potentiometer IA2A6A2R2. VIDEO AMPLITUDE control 1A2R19 (fig. 2-3) provides

front-panel control of the ft video input level. The amplified video output of emitter sollower 1A2A6A2Q4 is supplied to fixed compressor 1A2A6A2CR3. This compressor reduces the gain of amplifier 1A2A6A2Q2, Q3 for large signal amplitude. The output of the fixed compressor is amplified by 1A2A6A2Q5, Q6 and supplied to selectable compressor 1A2A6A2CR7, CR8, CR9 through emitter follower 1A2A6A2Q7. This compressor network consists of three compressors that are selected by combinations of ANTENNA switch 2S9 and RANGE switch 2S8 settings. Selectable compression is necessary since increased video amplitude is required as effective range decreases or crt sweep speed increases. Example of a selected compressor: With RANGE switch 2S8A set to 50 and ANTENNA switch 2S9A set to either RIGHT or LEFT the following occurs. A ground is applied to the 50 position (contact 11) of switch 2S8A. This ground is coupled through W4 of 2S8A to ANTENNA switch 2S9A, contact 7 or 9 depending on whether LEFT or RIGHT is selected. The ground is coupled through W3 of switch 2S9A, connectors 2J4, 2J3, 2J1, and 1A2J11 and activates compressor 1 (1A2A6A2CR7) of selectable compressor network 1A2A6A2CR7, CR8, CR9. As shown in table 2-1, only fixed compensation is introduced by the selection of single antenna mode, 25 km range, since this condition provides the highest sweep speed. The compensated video is routed through emitter follower 1A2A6A2Q8 to FT GAIN control 1A2R6. This control permits output gain adjustment of the video amplifier. The output of 1A2R6 is fed to output clamp 1A2A6A1CR11, which operates in conjunction with INTENSITY control 2R6 via DISPLAY switch 2S3 (W5) to establish the proper base level for the video information. A fixed bias voltage is applied through load resistors 2A1R25 and R26, for ft video or mt video display, to output clamp 1A2A6A1CR11 and the contacts of DISPLAY switch 2S3 Varying INTENSITY control 2R6, with the DISPLAY switch in either FT or MT, varies the intensity of the video being displayed on the radar crt under test. The cutput from the clamp circuit is supplied to connector 1A2J1 for intensity modulation at the control grid of the radar crt when the latter is under test.

Table 2-1 Selectable Compressor Networks

ANTENNA switch position	RANGE switch position	Active compressor
RIGHT/LEFT	25 km	Fixed only
RIGHT/LEFT	50 km	CFG
BOTH	25 km	
RIGHT/LEFT	100 km	CR8
вотн	50 km	
вотн	100 km	CR8

2-33. Cathode Ray Tubing and Unblanking (fig. FO-2)

Three operational inputs and one protective input are supplied to diode AND gate 1A2A6A1CR12, CR13, CR14 CR18. When any AND gate input is low, the gate is inhibited to provide crt blanking. The protection signal input (waveform AD) is a sample of the horizontal sweep circuit. This signal is supplied to operational amplifier 1A2A6A1AR1 through bipolar threshold detector 1A2A6A1CR19, CR20. Since one output of the detector is inverted and the other output is not inverted, amplifier !A2A6A1AR1 develops a unipolar output (waveform AE). This output is supplied to switch 1A2A6A1Q9, holding this switch off. If a failure occurs in the horizontal sweep circuit. switch O9 conducts to inhibit the diode AND gate and to provide a return for the SWEEP FAULI indicator lamp in the BITE circuit. The three inputs to the AND gate are the sweep gate (waveform AC) and ft enable gate (waveform Y) from the video simulator and synchronizing circuit (fig. 2-3), and +20 vdc through UNBLANK switch 1A2S6 The enable gate is high during single artenna operation. Consequently, unblanking is controlled by the sweep gate. In the both antenna mode, the enable gate inhibits the AND gate after each antenna gate transition. This permits unblanking to occur only during sweep gate intervals when the enable gate is high. When all inputs to the AND gate are high, switch 1A2A6AlQ10 conducts to provide a ground for clamp 1A2A6AlVR3. This clamp is a +31 vdc breakdown diode supplied by +100 vdc through OR gate 1A2A6AlCR15, 16, When the ground return is removed from the clamp, its output rises toward +100 vdc, providing cutoff potential for crt cathode. In the event of failure in the +100 vdc source, the diode OR gate supplied +28 vdc to maintain a safe cathode bias potential for the crt. Generattion of unblank signals is prevented when UNBLANK switch 1A2S6 is in the OFF position.

2-34. Cathode Ray Tube Regulator **and Focus** Circuit

Static and dynamic focusing is required to maintain the spot on the crt face at a fixed shape and size Paragraphs 2-35 and 2-36 describe these circuits.

2-35. Static Focusing

(fig. FO-2)

Static focus is accomplished by a potentiometer that controls a focus module within the high voltage power supply in the RO-495/U

2-36. Dynamic Focus (fig. FO-2)

Horizontal and vertical unipolarized sweep signals (waveforms S and Q) from the sweep circuits are

supplied to a squaring circuit consisting of a non-linear network and amplifier 244A1AR9 in a closed loop. The transfer function of this circuit is equal to the sum of the squares of its inputs or $(E_1 \text{ in})^2 + (E_2 \text{ in})^2$

 $E out = \frac{11.47}{}$

2-37. Groundspeed/Drift Angle Servo Loop. (fig. FO-3)

The groundspeed/drift angle servo loop consists of a servoamplifier stepper motor 2Bl, two gear trains, synchro control transformer 1A2B1, synchro control transmitter 2B2, NAVIGATION switch 2S6, a NAV SIM control, and a GS/DFT control. The stator of control transmitter 2B2 develops 3-wire information that represents the angular displacement of its rotor with respect to a zero reference point (zero degrees drift angle). Excitation for 2B2 is 26 vac 400 Hz. The S-wire information is supplied to the stator of synchro control transformer 1A2B1 through contacts of relay 1A2K6. The rotor of 1A2B1 is either in a position of minimum inductive coupling (null) with the magnetic vector produced in its stator or displaced from null. When an error signal is induced in the rotor, it rotates away from the null position. The amplitude of the error signal is proportional to cosine 0, when 0 is the angular displacement of the rotor with respect to the magnetic vector. Any error signal output of 1A2B1 is fed through switch 2A5A3Q7, Q8 to buffer 2A5A3AR5 via contacts of relay 1A2K5 (restored). The error signal is either in-phase or outof-phase with respect to the excitation voltage for 2B2, Consequently the error signal has a polarity as well as a magnitude characteristic. Switch 2A5A3Q5, amplifier 2A5A3Q6, and switch 2A5A3Q7, Q8 form a synchronous phase detector. The output of the detector is supplied to integrator 2A5A3AR6 through buffer 2A5A3AR5 (waveform B). Integrator 2A5A3AR6, positive and negative level detectors 2A5A3AR8, AR7; monostable multivibrator 2A5A2U8A, U12B, U8B; inverter 2A5A2U7C; and switch 2A5A3Q9-Qll form a variable prf generator. The integrator develops a positive or negative ramp output (waveform C) until the threshold of the applicable level detector is exceeded. Exceeding either threshold toggles multivibrator 2A5A2U8A, U12B, U8B which causes a negative transition to pass through inverter 2A5A2U7C to turn on switch 2A5A3Q9, Q10, Qll, which clamps the integrator input at ground This terminates the ramp, allowing the level detector output to return high (waveform D). As the error signal amplitude increases or decreases, the slope of the ramp voltage increases or decreases and, therefore, the time required to exceed the threshold level decreases or increases. Assume the error

produces a series of negative ramp signals (waveform C), a train of negative pulses appears at the output of negative level detector 2A5A3AR8, causing a high level to be present at the output of cross-coupled gate U9A and a low-level at the output of cross-coupled gate U9B. These levels will remain until the error signal passes null and positive ramps are developed. During negative ramps the Q outputs of bistable multivibrators 2A5A2U11A and UllB control their steering inputs through comparators 2A5A2U9 and U10. During positive ramps the bistable multivibrators inputs are controlled by the bistable multivibrator Q outputs. Since the output of one bistable multivibrator controls the steering inputs to the other, the sequencing of their outputs are shown in waveforms G and H for a condition when the ramp signal passes through null from negative to positive ramps. Each comparator develops complementary output signals that are used as steering gates for the multivibrators. Toggling of the bistable multivibrators is accomplished by the signal from delay inverter 2A5A2U12A, U12C, U12D. This output is similar to the switch trigger (waveform F), except for a polarity reversal and a slight delay to prevent false triggering of the multivibrators. Waveforms G and H, and their complements, are supplied to drivers 2A5A2Q15-Q18 through inverters 2A5A2U7A, U7D, U7E, and U7F. Each driver provides a ground return for one winding of stepper motor 2Bl to enable that winding when the driver is on. At the occurrence of pulses from switch 2A5A2Q13, Q14, the enabled drivers conduct and supply drive current for two of the stepper motor windings causing the motor to rotate 45°. Waveform I through L illustrate the sequence in which the windings are activated, with brackets to indicate the change of sequence after passing through an error null. When a servo error exists, the error is coupled through amplifier 2A5AlQ7 and switch 2A5AlQ3, Q4 and Q5, as a servo fault to the BITE circuit (para 2-42).

2-38. Indicating System Low Voltage Power Supplies (Modules 1A1A3, A4) (fig. 2-4)

The indicating system low voltage power supplies provide power for the test set group indicating system circuits. Power transformer lAlT1 accepts the 3-phase input and converts it into six 3-phase outputs. Each of these outputs is rectified by a 3-phase bridge rectifier and supplied to a regulator circuit. One regulator circuit contains two shunt regulators while the remaining circuits contain series regulators. Since the operation of the series regulators is similar, only the -28 vdc regulator is discussed.

a. Minus 28-Volt *DC Regulator*. The unregulated output from 3-phase rectifier IAIA3AlCR19 through CR24 is filtered and supplied to series regulator

1A1A3Q1. A sample of the regulated output is taken from a voltage adjustment potentiometer and compared with Zener diode reference voltage in differential error amplifier 1A1A4A1Q3, Q2. The error signal is returned as control voltage to series regulator 1A1A3Q1. Any change in the -28 vdc regulated output produces an error input for series regulator 1A1A3Q1 which compensates for the change. Although operation of the other series regulators is similar, it differs in that they do not have individual voltage adjustment potentiometers. Also, their regulated outputs are summed with the -28 vdc regulated level and compared with a ground reference. The plus and minus 15 vdc regulators use the regulated plus and minus 20 vdc as an input source.

b. Shunt Regulators. The output of bridge rectifier IAIA3AICR13 through CR18 supplied two shunt regulator circuits. One circuit (IAIA3VR1, VR2) is a simple Zener diode regulator that provides +250 vdc for the dynamic focus circuit. The other shunt regulator provides +640 vdc for Recorder-Processor-Viewer, Radar Mapping RO-495/U. In this circuit an error signal is developed by comparing a sample of the regulated +531 vdc with the output of the -28 vdc regulator. The error signal controls shunt regulator IAIA4A2Q4, 1AIA3Q8 which compensates for output voltage variations.

2-39. Low Voltage Power Supplies (Module 1A2A3)

(fig 2-5)

The power supplies on module 1A2A3 supply power to monitoring and signal generating circuits in the test set group. Power transformer 1A2T2 accepts the 3phase input and converts it into three 3-phase outputs. Each of these outputs is rectified by a 3-phase rectifier and supplied to a regulator circuit. The unregulated output of 3-phase rectifier 1A2A3CR1-CR6 is filtered and supplied to series regulator 1A2A3Q9. A sample of regulated output is applied to error amplifier 1A2A3Q7, Q8, and Q10 where it is compared with a Zener diode reference voltage. Any change in the regulated +28 vdc output produces an error signal which is amplified in the error amplifier. The error amplifier produces an output that causes the regulator to increase or decrease conduction to null the error. The error amplifier also contains short circuit switching (Q11) that turns off the regulator in the event of a short circuit at its output. Operation of the -5 vdc and +20 vdc regulators is similar, except that regulators 1A2A3AR1, AR2 operate both as regulators and error amplifiers. Switch 1A2A3Q12 and Q13 function as short circuit protectors Regulator 1A2A3AR1 is referenced to regulated +28 vdc The -5 vdc regulator performs in a similar manner, except that it uses differential

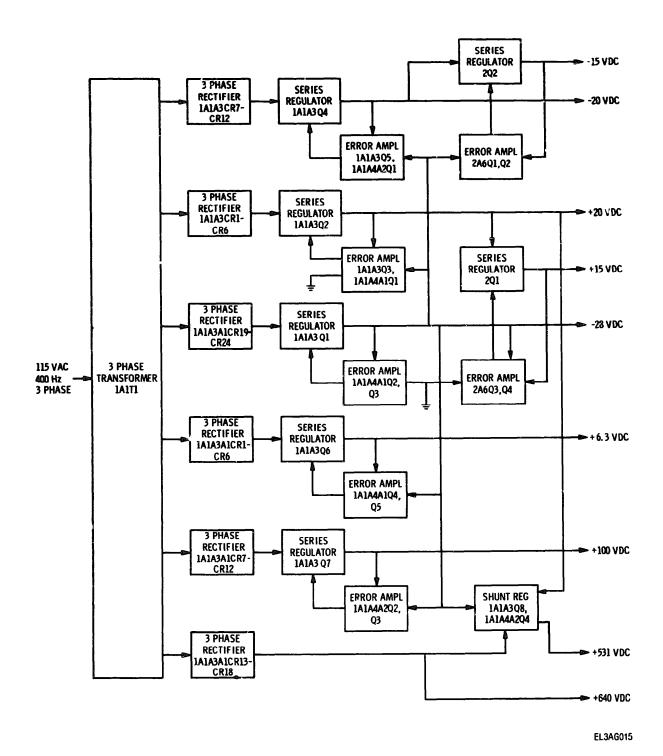


Figure 2-4. Indicating system low voltage power supply block diagram

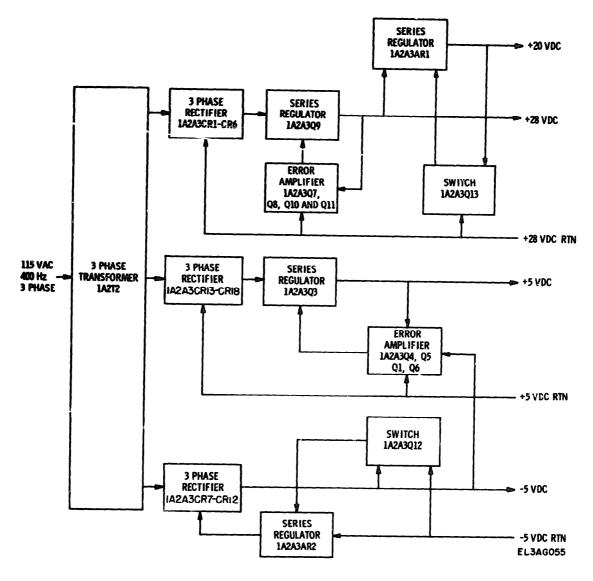


Figure 2-5. Low voltage power supply and regulator IA2A3, block diagram

amplifier 1A2A3Q6 as the input to its error sensing circuit and is referenced to regulated -5 vdc. Switch 1A2A3Q4 provides the short circuit, protection.

2-40. Overvoltage Protection Circuit (fig. 2-6)

The overvoltage protection circuits for the 115-volt, 400 Hz, 3-phase supply consist of identical circuits for each of the three phases A, B and C. The following circuit analysis refers to phase-A circuitry by reference designation. When phase-A peak input voltage remains below approximately 200 vac, all switching componenta remain in their normally off state. When the positive excursions of phase-A peak input voltage rise above 200 vac, Zener diode lA2A5VR1 conducts through CR1 (positive overvoltage sensor). Any overvoltage appears across voltage divider R1 and R2, causing switch driver Q1

to supply the trigger potential at the gate of SCRQ2 (positive excursion grounding switch). With Q2 turned on, the positive excursion of phase-A Es effectively grounded. Near the end of the positive excursion, Q2 turns off and remains off until the occurrence of another overvoltage positive excursion. Capacitor Cl provides transient filtering to reduce the possibility of Q2 being triggered during other than overvoltage conditions. The negative excursion grounding circuit (SCRQ5) functions in the same manner, except for the opposite polarities involved and the addition of inverter 1A2A5Q3 and Zener diode VR3 (threshold clamp). Q3 inverts the negative line excursions to provide a positive voltage for the base of switch driver O4. Zener diode VR3 is used to increase trigg er stability at Q5 (negative excursion grounding switch).

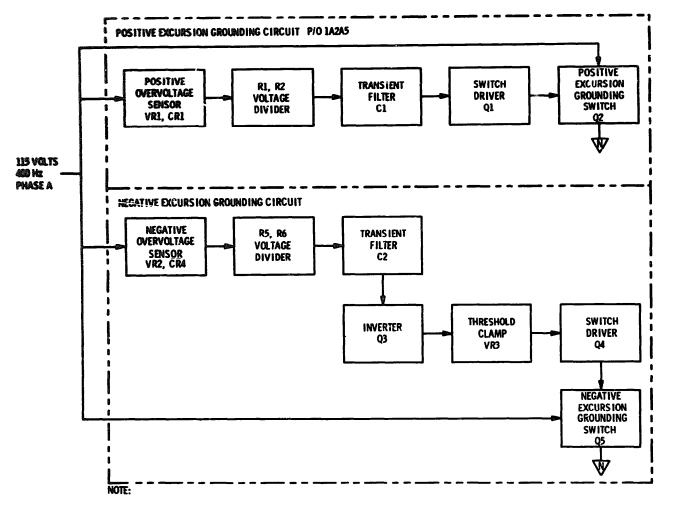
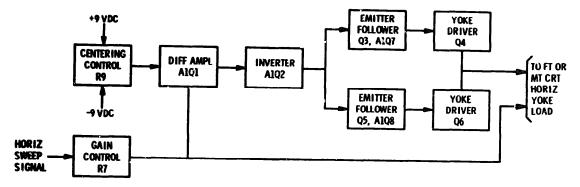


Figure 2-6. Overvoltage protection circuit 1A2A5, block diagram

2-41. Direct Current Amplifiers (fig. 2-7)

Two identical amplifiers are used to provide drive current for the ft and mt deflection yoke loads. External wiring permits the amplifiers to operate as inverting or noninverting amplifiers. An inverted output (2A3) is used to supply ft or mt vertical deflection yoke loads while a noninverting output (2A2) is used to supply ft or mt horizontal deflection yoke loads. The horizontal sweep signal from summing amplifier 2A4A2AR12 (fig. FQ-2) feeds dc amplifier 2A2 and the vertical sweep signal from summing amplifier 2A4A2AR11 (fig. FO-2) feeds dc amplifier 2A3. The amplifiers draw current from the +20 vdc supply and the -20 vdc supply. The dc amplifiers produce deflection yoke currents that retain the waveshape of the sweep signal input voltage. In amplifier 2A2 differential amplifier A1Ql (fig. 2-7) receives an offset

voltage from centering potentiometer R9. Differential amplifier signal input is derived from the sweep signal and a feedback current sample from the deflection yoke load. The output of the differential amplifier is a voltage having a waveshape that will produce a yoke load current with the same shape as the sweep signal input. The output of the differential amplifier is inverted by A1Q2 and applied to complementary compound connected emitter followers Q3/AlQ7 and Q5/A1QS. The outputs of these emitter followers are supplied to complementary yoke drivers Q4 and Q6. The yoke drivers have common emitters with the deflection yoke load in the emitter circuit. Operation of dc amplifier 2A3 is essentially the same as 2A2 except that the sweep signal is supplied to the inverting input of the amplifier and the feedback signal is combined with the offset voltage.



A NON-INVERTING AMPLIFIER 2A2

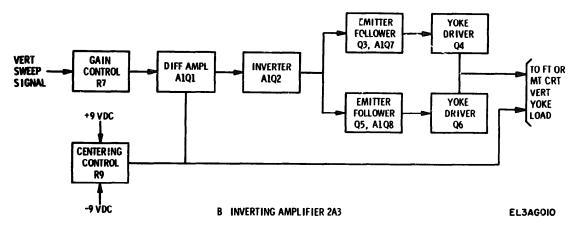


Figure 2-7. Direct current amplifiers 2A2/2A3, block diagram.

2-42. BITE Circuit (fig. 2-8)

The BITE circuit consists of two major circuits; the primary fault detection circuit detects abnormally high or low voltages that may exist in the sweep waveforms (waveforms H and W, fig. FO-2), or in the video and unblank outputs of the video amplifier (fig. 2-3). Detected abnormalities in any of these waveforms cause FAILURE lamp IA2DS2 to turn on. The primary fault detection circuit is intended for use only during single antenna operation. Consequently normal as well as abnormal inputs are sensed as faults during both antenna operations. The fault isolation circuit functions on a go-no-go basis to indicate a malfunction in the sweep circuit, servoamplifier circuit, or the crt focus and regulator cir-

Paragraph 2-43 discusses the primary fault detection circuit, and paragraph 2-44, the fault isolation circuit.

2-43. Primary Fault Detection Circuit (fig. 2-8)

The primary fault detection circuit is enabled when BITE switch 1A2S7 is positioned to ON. Because each of the four input circuits are similar, only the horizontal sweep input circuit is discussed. Horizontal sweep (waveform II, fig. FO-2) is applied to dual differential comparator 1A2A4AR2 through closed loop operational amplifier 1A2A4AR1 (fig. 2-8). The comparator functions as a digital device whose output is normally low. If the peak-to-peak limits of the horizontal sweep waveform exceed the high or low

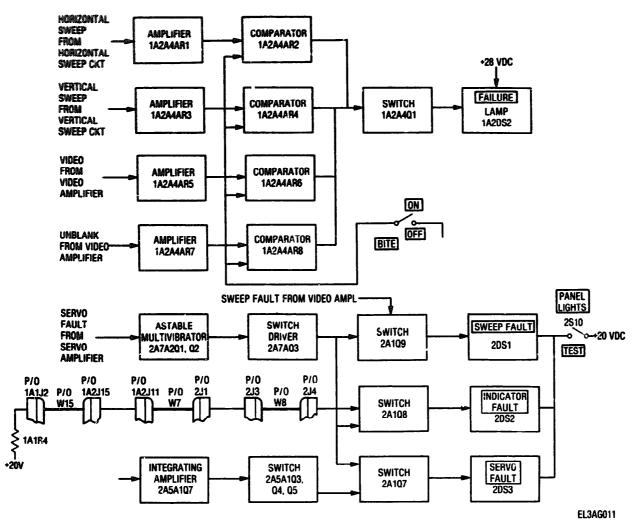


Figure 2-8. BITE circuit, block diagram

limits established by dc reference levels, the comparator output switches state from low to high. During normal input conditions, all comparator outputs are low and switch IA2A4QI is off. However, at any time one or more comparators changes state, switch IA2A4QI is turned on, which causes FAILURE lamp I.A2D52 to turn on. Therefore, all input waveforms must be within their required voltage envelopes to hold the FAILURE lamp off.

2-44. Fault Isolation Circuit (fig. 2-8)

Astable multivibrator 2A7A2Q1, **Q2** generates an asymmetrical rectangular pulse train that continuously toggles switch driver 2A7A2Q3 on and off. In the absence of normal sweep, servo, or high voltage BITE inputs, switch driver 2A7A2Q3 toggles switches 2A1Q7, Q8, Q9 through a control diode located at each switch input. When enabled, the toggled switches cause the SERVO FAULT, INDICATOR FAULT and

SWEEP FAULT lamps to flash on and off in step with the astable multivibrator to indicate malfunction. However, with normal input, a control diode is turned off, isolating the affected switch from the switch driver, thereby turning off the related indicator lamp. The normal sweep input is supplied to the BITE circuit as a positive dc level. The servo fault signal is a variable prf pulse train (same as waveform F, fig. FO-3). The signal is inverted and filtered by amplifier 2A5A1Q7 to become a dc level that varies as a function of the pulse train prf. This dc signal is compared with a threshold level established by switch 2A5AlO3, O4, O5. When the threshold is exceeded, the switch output is supplied to swtich 2AlQ7 as the enabling signal for the SERVO FAULT indicator. The INDICATOR FAULT signal in the OQ-63A is pulled to +20 vdc through lAlR4 which disables switch 2AlO8. When checking the RO-495/U and there is an indicator fault (high voltage power supply failure), the indicator fault signal allows switch 2AlQ8 to be

toggled by the astable multivibrator. PANEL LIGHTS TEST switch 2S10 permits indicator lamps 2DS1 through 2DS3 to be checked for operation.

2-45. +28-Volt **Reg**ulated Power Supply and High Voltage Loads (fig. 2-9)

Anode and focus voltages are divided down for measurement purposes in the networks associated with unity gain isolation amplifier Ul and U2. Rectifiers CR1 through CR4 receive 43 vac and output +28 vdc unregulated. The unregulated voltage is routed through inductor Ll, in the 1Al panel assembly, and routed back to be regulated by Ql, Q2, VRl, and Q3.

2-46 +26-Volt DC Power Supply

The +26-volt power supply is a dc-to-dc supply that is sealed and non-repairable. Its input is +28 volts unregulated from the 1Al panel assembly. Its output is used to test the high voltage power supply in the RO-495/U.

2-47. ADAS Simulator

(fig. 2-10)

The ADAS simulator provides signals to exercise the ADAS printed circuitry of Recorder-Processor< Viewer, Radar Mapping RO-495/U. The simulator contains a programable read only memory which is programmed with BCD data equivalent to a complete ADAS data block. The simulator is started by a data demand pulse that originates in the RO-495/U. This pulse enables the clock generator. The clock pulses through a series of counters and decoders, control the reading of ADAS data from a series of counters and decoders, control the reading of ADAS data from a programable read only memory (PROM). The PROM outputs are routed through a data selector and a level shifter to provide unblanking signals for the RO-495/U. Vertical deflection signals are provided by a clock multivibrator and a deflection clock generator.

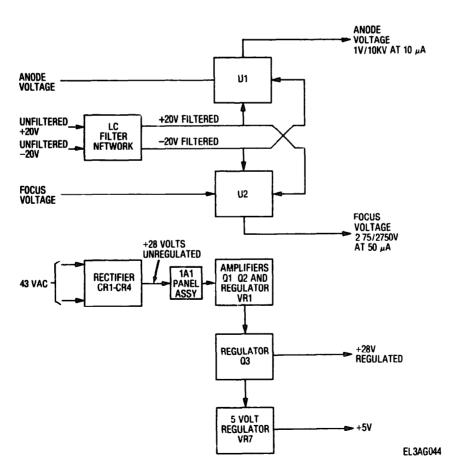


Figure 2-9. Regulated +28-volt power supply and high voltage loads, block diagram

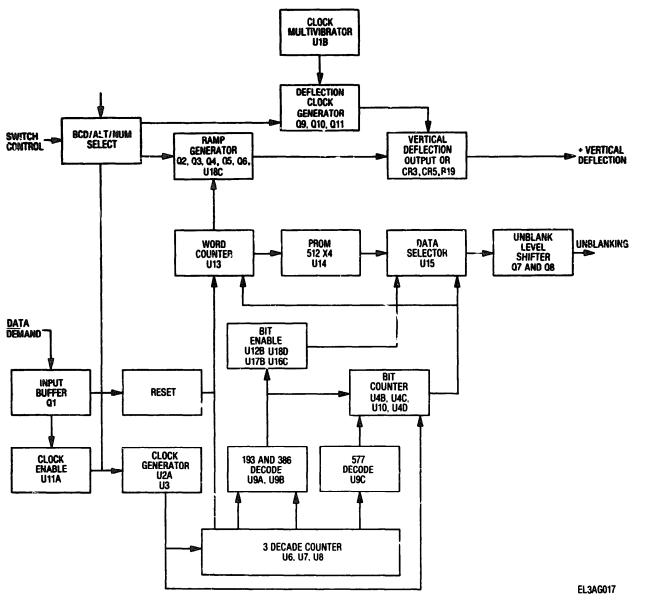


Figure 2-10. ADAS simulator circuit, block diagram

2-48. Monitor Adapter Input Simulator (fig. 2-11)

The monitor adapter input simulator provides signals to simulate system inputs to Recorder-Processor-Viewer, Radar Mapping RO-495/U. Circuit timing is controlled by a 4-flip flop binary counter, which is synchronized by a 13-khz clock. Binary counter count logic is used for gates decoding, in the generation of the ECCM video and the ECCM deflection signals. The count logic is also used to control the duration of a ramp voltage required for the generation of the ECCM deflection signal.

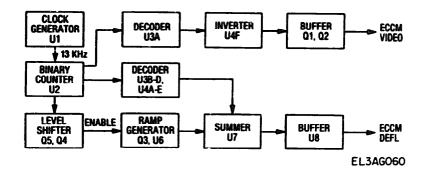


Figure 2-11. Monitor adapter input simulator, block diagram.

Section III. VIDEO SIMULATOR AND SYNCHRONIZING CIRCUITS, CIRCUIT ANALYSIS

2 - 49. **General**

Paragraphs 2-16 through 2-48 describe the functional operation of the test set group on a block dim level. This **section** covers the circuit analysis *of* stages in the video simulator and synchronizing circuits.

2-50. Video Simulator and Synchronizing Circuit

Paragraph 2-16 describes the functional operation, on a block diagram level, of the video simulator and synchronizing circuit. Paragraphs 2-51 through 2-60 provide detailed analysis of stage functioning in this circuit. Circuits covered are as follows: 5-MHz oscillator, 750-Hz prf clocked counter, 750-Hz prf generation, reset pulse generation, test video generation, sweep gate generation, yoke clamp gate generation, antenna counter, ft enable, and mt enable circuits.

2-51. Five-MHz Oscillator

(fig. FO-15 and 2-12)

The basic time reference for the video simulator and synchronizer circuit is the 5-MHz oscillator consisting of amplifiers IA2AIU26A, U26C and 5-MHz crystal YI (fig. FO-15). Amplifiers U26A, U26C are dual input NAND gates that function together as cascaded inverting square wave amplifiers. Regenerative feedback is peaked at 5 MHz by crystal YI. Local negative feedback through resistor R2 stabilizes amplifier U26C. Local negative feedback through resistor R1 stabilizes amplifier U26A. Buffer U25A is a power NAND gate that provides load isolation. The 5-MHz square wave output of buffer U25A is supplied as the clock signal to a 13-stage counter chain. Buffer U25B provides additional load isolation and restoration of logic level for application to a line driver consisting of

transistor driver 1A2A4Q6 (fig. FO-18) and complementary emitter follower output stage 1A2A4Q7, Q8. Capacitor 1A2A4C28 improves 1A2A4Q6 switching time by shunting clock pulse transitions directly to the base of Q6 for rapid charge and discharge of base-emitter capacitance. Diodes 1A2A4CR11, CR12 provide collector-base saturation clamping for improved turn off time of Q6. Additionally, diode CR11 provides required offset for stable turn off of Q6. Complementary emitter followers 1A2A4Q7, Q8 improve output waveshape by providing symmetrical charge and discharge circuits for load capacitance. Resistor 1A2A4R71 provides short circuit protection and resistor 1A2A4R72 provides termination for coaxial transmission. Lowpass filters 1A2A4L1, C33 and L2, C34 decouple high frequencies from the -5 vdc and +5 vdc supplies, respectively.

2-52. 750-Hz Prf Clocked Counter

(fig. FO-15 and 2-12)

The 750-HZ prf utilized in the synchronizing circuit portion of the video simulator and synchronizer circuit is derived from the 5--MHz clock signal by a 13stage clocked counter chain and associated logic circuitry. The binary elements of the clocked counter chain are dc clocked J-K flip-flops 1A2A1U7, Ul through U6, U10 through U12, and U16 through U18. Clocking occurs at the positive transition of the clock pulse. Clock pulses are applied to the toggle (T) inputs. The dual J-K logic inputs Jl, J2 and Kl, K2 are enabled by logical "1" (2.6 vdc minimum). Therefore, unused J-K inputs are connected to +5 vdc. Complementary inputs J, K are enabled by logical "0" (0.40 vdc maximum). Therefore, unused complementary inputs are grounded. Set (S) and reset(R) inputs are activated by logical "0". Because all set inputs are

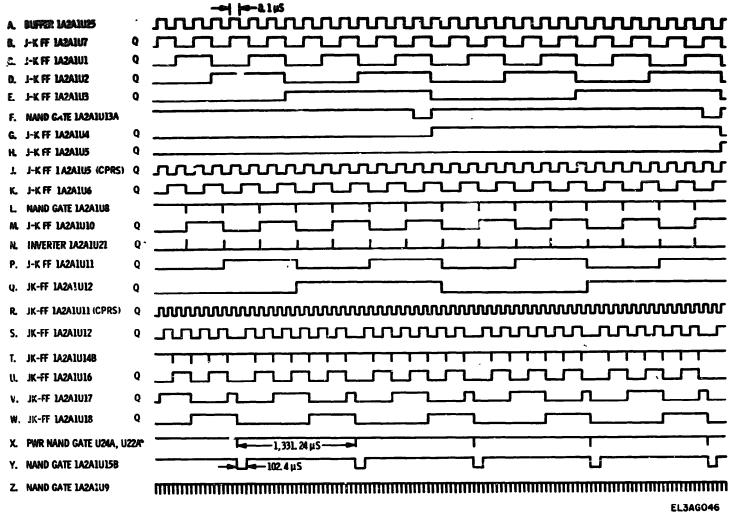
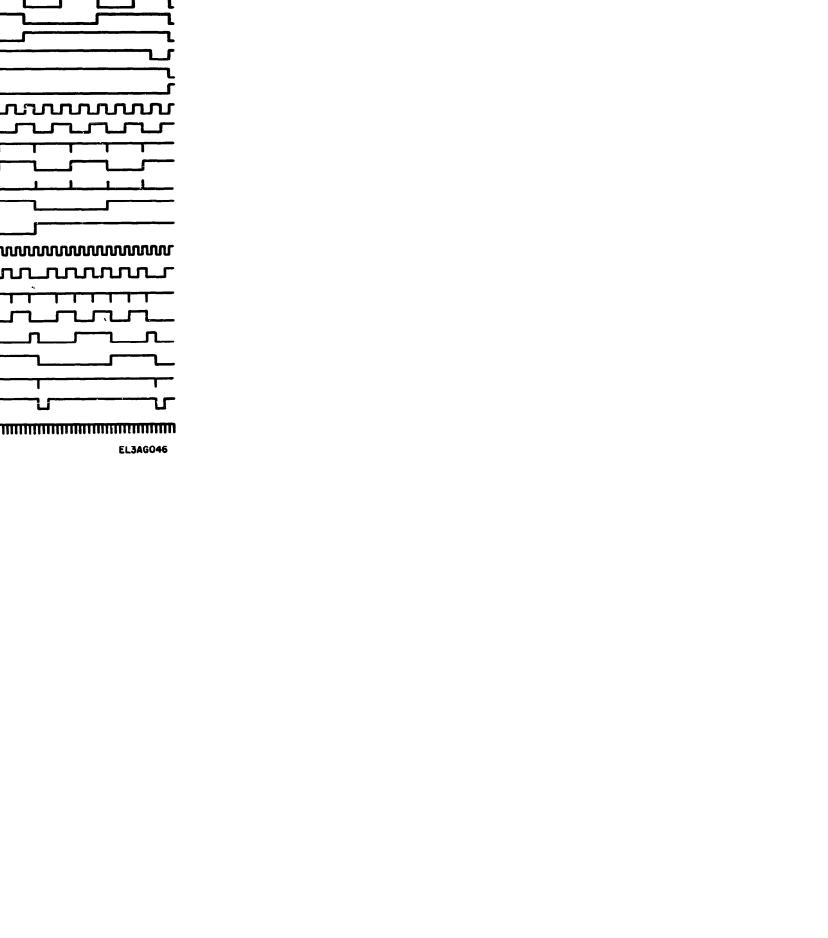


Figure 2-12. Timing diagram for Hz prf clocked counter (sheet 1 of 2)

2 - 1 9



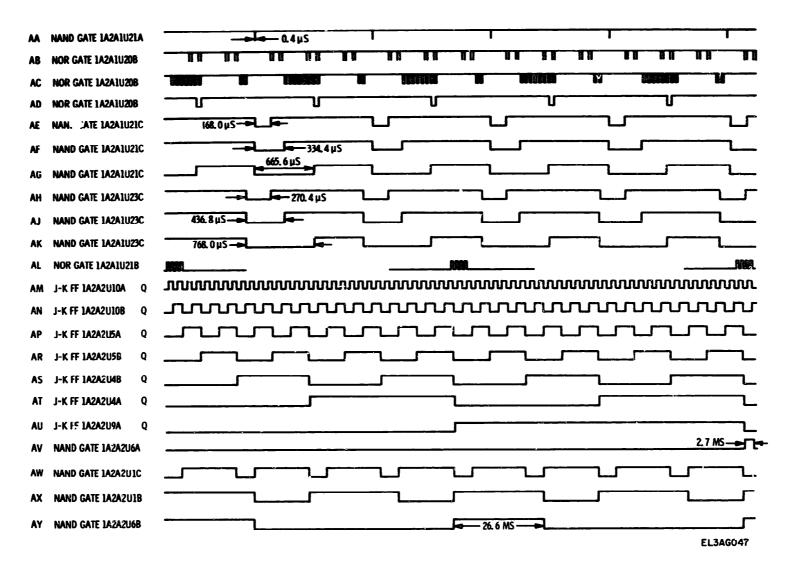


Figure 2-12. Timing diagram for 750 Hz prf clocked counter (sheet 2 of 2)

unused they are connected to +5 vdc. The truth table for the binary elements is given below.

Ja	Kn	Qn+1	Set	Reset	Q
0	0	Qn	0	0	+
1	0	ī	1	0	0
0	L	0	0	1	1
1	1	Qn	1	1	Q
		E 0	1. J2, J K1, K2, K me prior to clock s time following h inputs in "0" state		

The truth table above demonstrates that a toggle occurs only when all logic inputs are enabled and the set and reset inputs are not activated. The timing diagram for the 750-Hz prf clocked counter is shown in figure 2-12, waveforms A through W. Stable switching requires that logic levels are stable for a nanosecond period prior to and following clock pulse threshold voltage. Because the time scale of the timing diagram does not permit the illustration of such a short period, toggling will appear to occur, in many instances, during a logic level transition. Consequently it should be understood that phase separation exists between clock pulse transition (leading) and logic input transition (lagging) owing to propagation and parasitic delays.

Each of the 13 stages of the clocked counter chain performs the divide-by-two function to provide the submultiples required for prf generation. NAND gate 1A2AlU24A adds the Q output of flip-flops U12, U17, and U18 to generate a clock counter reset trigger pulse that occurs at the desired prf rate. The Q output of U12 is supplied to NAND gate U24A through externally connected pins J and W of lA2Al socket. The clock pulse is also supplied to U24A and to R-S flip flop U22 co establish reset pulse width. Assume that all stages of the counter are in the reset state (reset input is logic "0" or low, Q is logic "0" or low). The first positive transition of the clock pulse (waveform A, fig. 2-12) toggles flip-flop 1A2AlU7 (fig. FO-15) whose logic inputs are connected to enable levels (ground or +5 vdc). The Q output of flip-flop U7 (waveform B inverted) enables the J-K inputs of flip flop Ul. With all logic inputs of flip-flop Ul enables, this stage toggles on the positive transition of the clock pulse (waveform C). In a similar manner each of the counter stages toggles on the first positive transition of the clock pulse to occur after enabling of logic inputs. The J-K inputs of flip-flops U4 through U6 are enabled by adding the Q outputs of flip-flops U7, Ul, U2 and U3. This function is performed by NAND gate U13A (waveform F) NAND gate U8 adds the Q

outputs (waveform L) of all stages preceding flip-flop U10 to provide $\overline{J}-\overline{K}$ enable inputs for stages U10 through U12. NAND gate U14B, in conjunction with NAND gates U8, U21 adds the outputs (waveform T) of all stages preceding flip-flop U16 to provide $\overline{J}-\overline{K}$ enable inputs for stages U16 through U18.

2-54. Reset Pulse Generation (fig. FO-15)

NAND gate 1A2A1U24A adds the Q outputs of stages U12, U17, U18 and the inverted clock pulse output of NAND gate inverter U23B to provide the counter reset trigger pulse (waveform X, fig. 2-12). Because the narrowest pulse input to U24A is the clock pulse input, the output pulse width of U24A cannot exceed 0.1µs. The leading edge of this pulse occurs after the counter has counted 6656 clock pulses. This count is determined as follows. If the counter chain were not reset, it would perform the divide-by-8192 (213) function. That is, flip-flop U18 would complete one cycle for each 8192 clock pulses. However, the Q output of flip-flop U18 goes high at the end of (212). Further, the Q outputs of flip-flops U17 and U12 go high at counts 2048 (211) and 512 (29), respectively, following count 4096 of flip-flop U18. Consequently, at count 6656 (212) + 211 + 29). NAND gate U24A is enabled by the inverted clock pulse supplied from NAND gate inverter U23B. This pulse supplied through cross coupled NAND gates (R-S flip-flop) U22A, U22B to provide the $0.1\mu s$ reset pulse (waveform X). This pulse resets all stages of the counter chain. Waveform W shows that the output of flip-flop U18 is not symmetrical. This is because of the occurrence of reset at a count that is not a binary power. Similarly, the waveforms of all stages whose count is not an even submultiple of count 6656 (waveforms S, U, V) are affected by reset. The prf of the reset pulse is the clock prf divided by the clock count at reset, or:

Reset prf = $5(10^6)/6656 = 751.17$

Therefore, the clock counter chain provides the desired nominal prf of 750. R-S flip-flop U22 ensures stable reset of all counter stages by providing a reset pulse whose width (approximately 50 to 100 nanoseconds) is independent of the width of the trigger pulse supplied by U24A. Assume that the output level of U24A is high, which is the condition existing between reset periods. The first clock pulse to appear at the input of U22A is ineffective if the output level of U22A is high (set state). If the output level of U22A is low (reset state), the trailing edge (negative transition) of the first clock pulse sets the R-S flip-flop. Subsequent clock pulses are therefore ineffective. When the reset pulse trigger occurs at the output of U24A, a clock pulse is present at the input of U22A and the R-S flip-flop is reset. The output level at U22A remains low for the duration of the clock pulse at its input, irrespective of the output

level at U24A. The R-S flip-flop is set at the negative transition of the clock pulse.

2-55. Test Video Generation (fig. FO-15 and 2-12)

NAND gate 1A2A1U15B adds the Q outputs of flip-flops U16 through U18 (waveforms U, V, W inverted) and the Q output of flip-flop U12 to obtain a 102.4 μ s pulse (waveform Y, fig. 2-12). Pulse width is established by the Q output of flip-flop U12 (0.2 (2¹⁰⁻³) μ s = 102.4 μ s). Pulse timing with respect to reset (waveform X) is established by the \bar{Q} outputs of U18 and U16. The pulse output of U15B is supplied to the line driver consisting of Q14, Q15. Diode CR5 provides offset for turn off of driver Q14. The base of emitter follower Q15 is connected to ground through external VIDEO AMPLITUDE variable resistor 1A2R19 (fig. FO-14).

2-56. Sweep Gate Generation (fig. FO-15 and 2-12)

NAND gate 1A2A1U9 adds the Q outputs of flip-flops Ui through U6, U10, U11 (waveforms C, D, E, G, H, J, K. M. P inverted, fig. 2-12) to provide the negativegoing 0.448 wide pulse output shown by waveform Z. The leading edge of these pulses is time coincident with the Q output of flip-flop U11 (waveform R). The output of U9 is supplied to NAND gate U21A through NOR gate inverter U19A as positive pulses. The output of NAND gate U15B is supplied to NAND gate U21A as positive pulses through NOR gate inverter U20A. NAND gate U21A adds the inverted outputs of U9 and U15B to provide the negative 0.4µs wide pulses shown at waveform AA. The output of U21A is supplied to R-S flip-flop U21B, U21C. NOR gate U20B also supplies an input to U21B, U21C. The output of U20B is a function of the setting of RANGE switch 2S8C (fig. FO-21). Plus 20 vdc is supplied, through RANGE switch 2S8C, to pin 1A2A1-3 (25 kilometers), pin 1A2A1-D (50 kilometers) or pin 1A2A1-E (100 kilometers). With RANGE switch 2S8 set to 25, switch 1A2A1Q1 (fig. FO-15) turns on to provide an enable level for NCR gate 1A2A1U19D. Similarly, NOR gates U19C or U19B are enabled when RANGE switch 2S8 is set to 50 or 100, respectively. Capacitors C2, C3, or C4 reduce input switch transients. With NOR gate U19D enabled, NAND gate U13B adds the Q output of flip-flops U3, U6, U11, and U16 (waveforms E, K, P, U) to provide the output waveform shown by waveform AB. Each pulse of each pulse pair shown in waveform AB is actually a pulse cluster containing 1.6µs wide pulses established by the Q output of flip-flop U3. The time scale of the timing diagram does not permit the practical illustration of these 1.6µs wide pulses with respect to the times relating to the remaining inputs to NAND gate U13B. The significance of these pulses

is their time relationship to the input to R-S flip-flop U21C, U21B supplied by NAND gate U21A (waveform AA). At the leading edge of the first 1.6µs wide pulse in waveform AB, R-S flip-flop U21C. U21B is set (U21C output is high). Further pulses in waveform AB are ineffective with the R-S flip-flop set. At the occurrence of the first negative pulse in waveform AA, the R-S flip-flop is reset as shown in waveform AF. The R-S flip-flop remains reset until the occurrence of the next 1.6 us wide pulse of waveform AB at which time it is set. Further pulses in waveform AB are ineffective with the R-S flipflop set. With RANGE switch 2S8 (fig. FO-21) set to 50, NOR gate 1A2A1U19C (fig. FO-15) is enables (NOR gates U19D, U19B are inhibited). NAND gate U14A adds the Q output of flip-flops U3, U10, U17 (waveforms E, M, V) to provide the resulting waveforms AC (simplified) and AF. When RANGE switch 2S8 (fig. FO-21) is set to 100, NOR gate 1A2A1U19B (fig. FO-15) is enabled (NOR gates U19D, U19C are inhibited). NAND gate U15A adds the Q outputs of flip-flops U11, U12, U16, U17 (waveforms P. S. U. V) to provide the resulting waveforms AD, AG. The output of U21C is supplied to line driver Q7, Q8, Q9. Diode CR2 provides required offset. Complementary emitter followers Q8, Q9 reduce pulse stretching induced by load capacitance. Resistor R19 inhibits oscillation of Q3, Q9. Resistor R21 provides short circuit protection. The output of U21B (waveform AE, AF, AG, inverted) is supplied to the antenna counter circuit (para 2-58).

2-57. Yoke Clamp Gate Generation (fig. FO- 15 and 2-12)

R-S flip-flop lA2AlU23D, U23C is set (U23D output is **high**) **by** the first negative transition to appear at the output of NAND gate inverter U23A (same as waveform X). The set transition **of** the R-S flip-flop is shown in waveforms AH, AJ, AK. The next negative transition to appear at the output of NOR gate U20B (waveform AB, AC, or AD) causes the R-S flip-flop reset (waveforms AH, AJ, AK). The pulse output of the R-S flip-flop is supplied to line driver Q4, Q5, Q6 whose operation is identical to that for line driver Q7, Q8, Q9 (para 2-56). The yoke clamp gate is connected externally through pine U and 20.

2-58. Antenna Counter (fig. FO-16 and 2-12)

The antenna counter divides the prf of the sweep **gate** to obtain the synchronized 5.9-Hz **square wave** antenna gate. Counting is performed by J-K flipflops IA2A2U4, U5, U9A, and U10, which provide the divide-by-128 function. Consequently, the 751.17 prf of the sweep gate is counted down to the 5.9 Hz

(751.17/2°) antenna gate frequency. The flip-flops in the antenna counter toggle at the negative transition of the toggle input. The reset input (R) is inhibited and the J-K inputs are enabled by connection to +5 vde. The Q outputs of the counter stages are shown in waveforms AM through AU. Counter stages USB and U8 are not used. NAND gate U1A is inhibited by the grounding of pin 1A2A2-V. The Q output of flip-flop U9A is supplied to NAND gate U7D. An inhibit or enable level is supplied to U7D by switch Q1 depending upon the position of ANTENNA switch 2S9C (fig. FO-21). With the ANTENNA switch set to LEFT, switch Q1 (fig. FO-16) turns on to supply an inhibit level to NAND gate U7D. With the ANTENNA switch set to BOTH or RIGHT, Q1 turns off to supply an enable level to U7D. Similarly, NAND gate U7A is inhibited or enabled by switch Q2 as a function of ANTENNA switch position. Consequently the Q output of flip-flop U9A is gated through U7D, U7A only when the ANTENNA switch is in BOTH position. In ANTENNA switch LEFT position, U7A provides a low output. In ANTENNA switch RIGHT position, U7A is inhibited to supply a high output. The output of U7A is supplied to line driver Q10, Q11, Q12 which functions in the same manner as line driver 1A2A1Q7, Q8, Q9 (para 2-56).

2-59. Ft. Enable

(fig. FO-16 and 2-12)

NAND gate 1A2A2U2 adds the Q outputs of flip-flops of U10B, U5A, U5B, U4B, U4A, enable outputs of Q1, Q2 (ANTENNA switch in BOTH position), and an enable output supplied by NAND gate U1D to provide the ft enable signal (waveform AV inverted). The output of U2 is inverted by NAND gate U6A, which is enabled by the inhibit output of NAND gate U1A. The output of U6A is supplied to line driver Q13, Q14, Q15 which functions in the same manner as line driver 1A2A1Q7, Q8, Q9 (para 2-56).

2-60. Mt Enable (fig. FO-16 and 2-12)

NAND gate IA2A2UIC adds the Q output at flip-flops U5A and U5B to provide waveform AW. NAND gate U1B adds the output of U1C and the Q output of flip-flop U4B to provide waveform AX. NAND gate U6B adds the enable outputs of Q1 and Q2 (ANTENNA switch in BOTH position), the Q output of flip-flop U4A, and the output of UIB to provide the mt enable signal (waveform AY). This signal is inverted by NAND gate U7C and supplied to line driver Q3, Q4, Q5. This line driver functions in the same manner as line driver IA2AIQ7, Q8, Q9 (para 2-56).



Section IV. HORIZONTAL AND VERTICAL SWEEP CIRCUITS,

CIRCUIT ANALYSIS

2-61. General

The horizontal sweep circuits are shown on figure FO-2 and discussed functionally, on a block diagram level, in paragraphs 2-21 through 2-26. Paragraphs 2-62 through 2-65 describe the detail functions of the stages in this circuitry. Circuits discussed are as follows: sweep generation, cubing amplifier, negative sweep detector 2A4A1AR5 and unipolarizer A1AR7. and direct current amplifier 2A2. Vertical sweep circuits are shown on figure FO-2 and discussed functionally, on a block diagram level, in paragraphs 2-28 through 2-31. Paragraphs 2-67 through 2-72 describe the detail functions of the stages in this circuitry. Circuits discussed are as follows: sweep generation, negative sweep detector 2A4A2AR2 and unipolarizer A2AR4, logarithmic amplifier 2A4A2AR5 and A2AR7, threshold summing amplifier 2A4A2AR8 and antilogarithm amplifier A2AR10, vertical output switching, and direct current amplifier 2A3.

2-62. Sweep Generation (fig. FO-24)

Horizontal sweep generator 2A4AlAR2 is gates **on** by **a positive sweep gate** signal from the video simulator and synchronizing circuit (fig. 2-3). When gated, the

sweep generator provides a linear ramp **output signal** that is supplied to stunning amplifier AlAR4.

a. Sweep Gate Switches 2A4AlQ3, Q4. The sweep gate signal is capacitively coupled to switch driver 2A4A1Q1, inverted, and used to control two n-channel field effect transistor (fet) switches. Prior to the application of the sweep gate signal, switches AlQ3 and Q4 conduct to hold charging capacitor A1C7 near ground potential. Two switch networks are used since the conducting resistance of these switches is approximately 150 ohms. The cosine 0 signal, from the horizontal range selection circuit, is divided by 33 in voltage divider network AlR14, Q3 and then applied to voltage divider network R15, Q4 where it is again divided by 33. Thus, the input to sweep generator AR2 is effectively clamped at ground. During the interval of the sweep gate, switches AlQ3 and Q4 are cut off, allowing sweep generator AlAR2 to develop its output.

b. Sweep Generator **2A4AlR2 Sweep** generator 2A4AlAR2 is a hybrid module, operational amplifier connected as a bootstrap ramp generator that develops positive and negative output signals depending upon the polarity of the cosine 0 input signal. When switches AlQ3 and Q4 open, charging capacitor AlC7 charges toward the cosine 0 value through



resistors A1R14, R15. Since sweep generator A1AR2 maintains a voltage null between its inputs, it develops an output with an amplitude that is twice that of the voltage appearing across the charging capacitor. This voltage is divided in half by feedback voltage divider A1R16. R19 and also returned to the charging capacitor through bootstrap resistor A1R17. As the exponential charging current through resistors A1R14, R15 and capacitor A1C7 decreases, the bootstrap current through resistor A1R17 and capacitor A1C7 increases, causing a constant current to flow through the charging capacitor. With a constant current flowing through the capacitor, a linear ramp voltage appears across the capacitor and produces a linear ramp voltage of twice the amplitude at the output of sweep generator A1AR2.

c. Summing Amplifier 2A4A1AR4 Operation. Summing amplifier 2A4A1AR4 is a hybrid module. operational amplifier that combines an offset signal with the output of sweep generator A1AR2. The offset voltage is supplied to summing amplifier A1AR4 through switch A1Q5 upon application of the positive-going yoke clamp signal. This switch is a pchannel fet that is driven into conduction by the inverted voke clamp signal from switch driver A1Q2. Depending upon the position of ANTENNA switch 2S9 and RANGE switch 2S8, a variable horizontal offset voltage is supplied from voltage divider 2A7R7-R14 (fig. FO-27). When the ANTENNA switch is set to BOTH, positive and negative ramp voltages from sweep generator A1AR2 are inverted by the summing amplifier A1AR4 and supplied to negative sweep detector A1AR5 and cubing amplifier A2AR9. Setting the ANTENNA switch to LEFT selects a voltage between +3 and +3.6 volts from LEFT HORIZONTAL OFFSET potentiometer 2R9 (fig. FO-21). This voltage and negative ramp voltages from the sweep generator are summed by the summing amplifier to produce positive-going ramps that start below ground. Alternatively. negative ramp voltages that start above ground are produced when the ANTENNA switch is set to RIGHT.

2-63. Cubing Amplifier. (fig. FO-24 and 2-13)

Cubing amplifier 2A4A2AR9 modifies the offset, bipolar ramp voltage from summing amplifier AlAR4. The cubing amplifier is a hybrid module, operational amplifier having a resistor-diode voltage sensitive input network. Figure 2-13 illustrates the cubing amplifier in simplified form, assuming positive input ramp voltages. Resistor R_a can be substituted for the series-parallel combination of resistors A2R27, R28, R32, R33, R37 and R38 since diodes A2CR6, CR7, and CR8 are reverse biased for positive ramp input signals (fig. FO-24). A cubing amplifier voltage gain

of -0.24 is established, therefore, by resistors A2R48 and R53 causing the output to increase from zero volt to -0.96 volt. With the input ramp between +4 and +6.2 volts, diode A2CR3 conducts and the parallel resistor A2R47 with R48 change the voltage gain of the amplifier to approximately -0.5. Network resistor values are selected to provide minimum effect at the output curve break points. At the second and third break points, (+6.2 and 7.7 volts), the voltage gain is increased to -0.74 and -1.0 respectively. The effect of this shaping is to produce an output voltage curve that approximates the cube of the input divided by 100. When the amplifier receives negative ramp voltages, this process is repeated, except that the positive series-parallel network remains passive and the negative network (fig. FO-24) is active. The cubed output is combined with the input ramp voltage in summing amplifier A2A412, through nonsymmetrical summing network A2R60, R61, to produce a horizontal sweep signal that contains 96 percent of the ramp voltage and 4 percent of the cubed output.

2-64. Negative Sweep Detector 2A4A1AR5 and Unipolarizer A1AR7

(fig. FO-24)

Negative sweep detector 2A4AlAR5 and unipolarizer AlAR7 operate together to develop negative-going **ramp** voltages regardless of the polarity of the offset **ramp signals** from summing amplifier AlAR4. Output signals from the unipolarizer are supplied to logarithmic amplifier A2AR7 and the squared summing amplifier AlAR9.

- a. Negative Sweep Detector AlAR5. The negative sweep detector is a hybrid module, operational amplifier circuit that provides a positive-going ramp output when its input ramp signal is negative-going. Positive input ramp voltages produce a zero-volt output level. Degenerative feedback establishes an amplifier gain of one through one of two feedback resistors, AlR28 or R30. When the input is positive, diode A1CR5 conducts and resistor AlR30 acts as the feedback resistor. Since pin 1 of AlAR5 and AR7 is at a virtual ground, no current flows through resistors AlR28 and R29. Thus, the amplifier circuit output at the junction of these resistors is zero volt. When the input ramp signal is negative, diode AlCR4 conducts to switch resistor AlR28 into the circuit as the feedback resistor. This causes the negative sweep detector circuit to develop a positive-going ramp voltage output.
- b. Unipolarizer A1AR7. The unipolarizer receives two inputs that depend upon the polarity of the negative sweep detector input. When this signal is a positive ramp voltage, output from the sweep detector is zero volt. Thus, resistors AlR27 and R36 establish a voltage gain of one for the Unipolarizer,

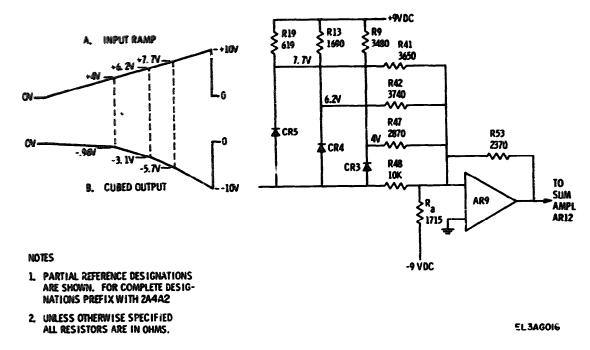


Figure 2-13. Cubing, amplifier, simplified schematic diagram.

causing its output to be a negative ramp signal having the same amplitude as its input. With a negative ramp input to sweep detector AlAR5 positive and negative ramp voltages are combined in a summing network consisting of resistors AlR27 and R29. This results in a negative ramp voltage output from unipolarizer AlAR7 that has the same amplitude as the negative sweep detector input.

Horizontal yoke currents for the ft and mt cathode ray tube deflection yokes are provided by dc amplifier module 2A2. Pincushion corrected horizontal sweep signals from summing amplifier 2A4A2AR12 are supplied to the noninverting input of differential amplifier 2A2A1Q1 through HORIZONTAL AMPLIFIER SWEEP LENGTH control 2R3 through HORIZONTAL AMPLIFIER switch 2S2. The inverting input to the differential amplifier is derived from HORIZONTAL AMPLIFIER CENTER control 2R2. also through 2S2. The centering control is connected In a voltage circuit across ± 9 vdc. The 9-volt sources are developed by two Zener diode regulators, 2AIVR3 and VR4 (fig. FO-22). Amplifier gain is controlled by varying the length control. The feedback to the isverting input is a sample voltage through resistor 2A2A1R11 (fig. FO-23). This sample has the same wave shape as the deflection yoke current; thus, any deviation in yoke current wave shape from the input voltage waveform is corrected by altering the output voltage waveform from differential amplifier

2A2AlQl. The output from the differential amplifier is amplified by inverter 2A2AlQ2 and supplied to complementary, compound-connected emitter followers 2A2AlQ7/Q3 and 2A2AlQ8/Q5. In-phase outputs are taken from these emitter followers and supplied to a complementary push-pull power amplifier consisting of transistors 2A2AlQ4 and 2A2AlQ6. When the input sweep signal is at zero volt, the output amplifier is balanced and no current flows in the ft or mt horizontal deflection yoke.

2-66. Vertical Sweep Circuit

The vertical sweep circuit shown in figure FO-2 is discussed functionally on a block diagram level in paragraphs 2-28 through 2-31. Paragraphs 2-67 through 2-72 describe the detail functions of **the** stages in this circuitry.

2-67. Sweep Generation (fig. FO-24)

Vertical sweep generator 2A4AlAR6 is gated on by a positive sweep gate from the video simulator and synchronizing circuit. When gated, it produces an output ramp signal that is supplied to summing amplifier AlAR8

a. Sweep Generator Switches 2A4A1Q9, Q10. These switches operate in the same manner as the horizontal sweep generator switches AlQ3, Q4 (para 2-62a). However, they control application of the sine 0 signal to vertical sweep generator AlAR6 instead of the cosine 0 signal.

b. Sweep Generator 2A4A1AR6. This sweep generator stage is electrically identical with horizontal sweep generator A1AR2 (para 2-62b). The output from sweep generator A1AR6 is supplied to summing amplifier A1AR8 where it is combined with a vertical offset voltage.

c. Summing Amplifier 2A4A1AR8. Summing amplifier A1AR8 is a hybrid module operational amplifier that combines an offset signal with the output from sweep generator A1AR6. This offset signal is supplied to the summing amplifier through switch A1Q upon application of a yoke clamp signal. The switch is a p-channel fet. ANTENNA switch 2S9 determin's the magnitude of the vertical offset signal. With a negative offset voltage applied to the noninverting input of summing amplifier A1AR6, the summing amplifier provides a negative offset output voltage having a magnitude that is three times greater than the offset input. When sweep generator A1AR6 develops a negative ramp voltage, the summing amplifier inverts and multiplies this signal by two; its output is an offset positive ramp voltage.

d. Summing Amplifier Offset Circuit. When the sine θ output is negative, LEFT antenna operation (ANTENNA switch 2S9) with right aircraft drift (NAV SIM control) or right antenna operation with left aircraft drift, the switch 2A4AlO7 conducts and supplies a zero volt level to source follower AlAR3. The source follower clamps one input to summing network AlR4, R21 at zero volt. Since the other summing network input is a preset voltage between -9.4 and -11.2 vdc, the offset voltage supplied to switch AlQ6 is a dc level between -1.35 and -1.62 volt. When the sine 0 output is positive (right antenna operation with right aircraft drift or left antenna operation with left aircraft drift), polarity sensor driver AlAR1 provides a high negative voltage that turns switch AlQ8 on and switch AlQ7 off. With switch AlQ8 on, the positive sine 0 output is summed with the fixed vertical offset voltage and routed to switch AlQ6. Setting ANTENNA switch 2S9 to BOTH cuts off switch AlO7 and permits the polarity sensor driver to control operation of switch AlQ8. Since the polarity of the sine 0 signal alternates in the both antenna mode, switch A1Q8 conducts when the sine 0 signal is positive, char ging filter capacitor AlC8. During the other half cycle of the antenna gate, capacitor AlC8 holds its charge to maintain the sine 0 level at the input to summing network AlR4, R21.

2-68. Negative Sweep Detector 2A4A2AR2 and Unipolarizer A2AR4 (fig. FO-24)

N'egative sweep detector A2AR2 and unipolarizer A2AR4 operate together to develop negative-going ramp voltages regardless of the polarity of the offset ramp voltage from summing amplifier A1AR8. Out-

put signals from the unipolarizer are supplied to logarithmic amplifier A2AR5 and the dynamic focus circuit. The operation of this circuit is identical with the negative sweep detector and unipolar. In the horizontal sweep circuit (para 2-64). However, an additional output is taken from negative sweep detector A2AR2. For this output the negative sweep detector acts as an inverter having a gain of one.

2-69. Logarithmic Amplifier 2A4A2AR5 and A2AR7

(fig. FO-24 and 2-14)

Two logarithmic amplifiers are used to modify the horizontal and vertical unipolarized ramp voltages as part of an arithmetic process that provides pincushion corrected vertical deflection signals. Both amplifier circuits are shown in figure 2-14 along with their input and output waveforms. In this illustration, resistors Ra and Rb replace series resistors A2R20, R21 and A2R45, R46 respectively. While the vertical input ramp voltage is between zero and -0.57 volt, the output from logarithmic amplifier A2AR5 increases linearly to +3.4 volts. When the threshold voltage of diode A2CR9 is exceeded, resistor A2R23 is connected in parallel with resistor A2R24 which results in reduced amplifier gain. Thus, as the negative input ramp signal continues to increase, the output waveform shown at B, figure 2-14 is produced This signal approximates the logarithm (to the base 1.6) of ten times the vertical input ramp voltage (waveform A, fig. 2-14). Logarithmic amplifier A2AR7 operates in the same manner as logarithmic amplifier A2AR5. However, since its two break points are at different levels, it provides an output voltage wave shape that follows the logarithm (to the base of 1.6) of the horizontal input ramp voltage squared. These two signals are supplied to threshold summing amplifier A2AR8 through summing network A2R29,

2-70. Threshold Summing Amplifier 2A4A2AR8 and Antilogarithm Amplifier A2AR10 (fig. FO-24 and 2-15)

Threshold summing amplifier A2AR8 and antilogarithm amplifier A2AR10 complete the arithmetic process used to develop vertical pincushion corrected deflection signals. These amplifiers and their input and output waveforms are shown in figure 2–15. The summing amplifier is similar in operation to negative sweep detector A1AR5 in that when its summed inputs (waveforms A and B, fig. 2–15) are below the threshold level of the amplifier, its output is zero volt. As the combined input exceeds this threshold level, the amplifier develops a negative-going signal (waveform C, fig. 2–15). This signal is supplied to antilogarithm amplifier A2AR10. Althouth the antilogarithm amplifier appears similar

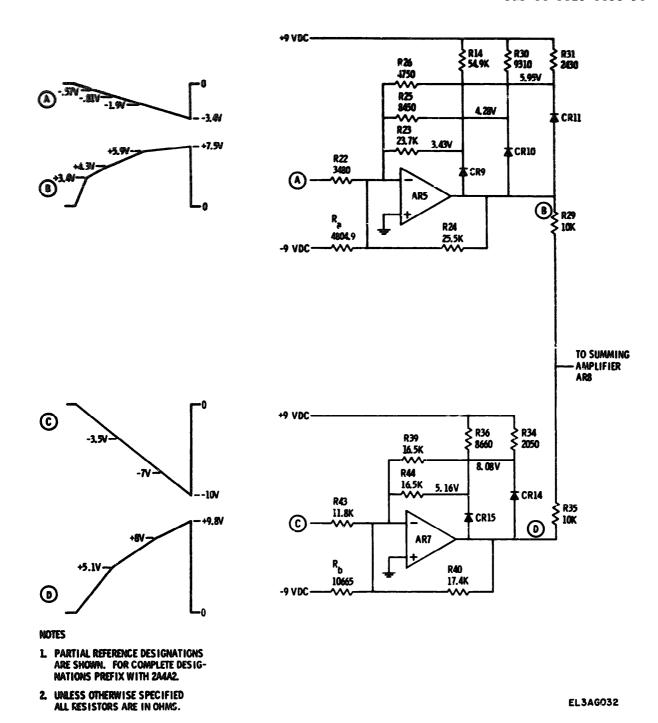
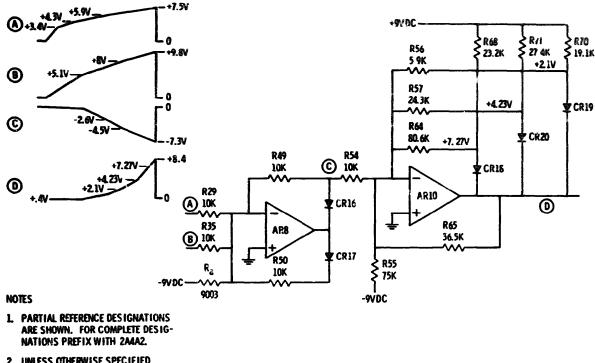


Figure 2-14. Logarithmic amplifiers, simplified schematic diagram.

to logarithm amplifier A2AR5, its operation is somewhat different. With a zero volt level applied to the antilogarithm amplifier input, diodes A2DR18, CR19, and CR20 conduct to parallel resistors A2R64, R57, and R56 with feedback resistor A2R65. As the

negative input signal increases (waveform C, fig. 2-15), the inverted output voltage (waveform D) reverse biases diode A2CR19 to increase the gain of the amplifier. This action continues until all three diodes are reverse biased, resulting in an output



2. UNLESS OTHERWISE SPECIFIED ALL RESISTORS ARE IN OHMS.

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Figure 2-15. Antilogarithmic amplifier circuit, simplified schematic diagram.

voltage wave shape that approximates the antilogarithm (to the base 1.6) of the amplifier input squared +10 volts, divided by 400.

2-71. Vertical Output Switching (fig. FO-24)

Summing amplifier 2A4A2AR11 combines a sample of the output from antilogarithm amplifier A2AR10 with the offset vertical ramp voltages from summing amplifier A2AR8. Since the ramp voltage can be bipolar and the antilogarithm signal is unipolar, the antilogarithm output is inverted by unity gain inverter A2AR13 in order to provide complementary antilogarithm signals. The switches A2Ql and Q2 develop complementary samples of the antilogarithm signals across two voltage dividers A2R62/R63 and A2R75/R76. The antilogarithm sample supplied to summing amplifier A2ARII is determined by the operating switch. Control for these switches is provided by limiting amplifier driver A2AR6, which receives the inverted output from negative sweep detector A2AR2 (para 2-63). The limiting amplifier driver acts as an open loop operational amplifier

when its output is between ±9 volts. Diodes A2VR2 and CR12 or A2VR3 and CR13 clamp the output voltage at one of these values. Thus, bipolar pulses are produced by the bipolar vertical ramp input signal. These **pulses** are **used** to turn on switches A2Ql and Q2. When the uncorrected vertical sweep signal, from summing amplifier AlAR8, is negative, fet A2Ql is turned on by the negative pulse from limiting amplifier driver A2AR6. This results in the summing of negative vertical ramp voltages with positive antilogarithm sample voltages, by summing amplifier A2ARII. Alternately, positive vertical ramp voltages result in the turn on of switch A2Q2 and the summing of inverted antilogarithm samples with the ramp voltage. This vertical sweep signal is routed to dc amplifier 2A3.

2-72. Direct Current Amplifier 2A3 (fig. FO-23)

The dc amplifier used to supply vertical yoke current for the ft and mt cathode ray tube deflection yokes is identical to the horizontal dc amplifier described in paragraph 2-65.

2-73. General

The video amplifier circuits are shown in figure FU-2 and discussed functionally, on a block diagram level, in paragraphs 2-32 through 2-36. Paragraphs 2-74 and 2-75 describe the detail functions of the stages in this circuitry. The circuits discussed are fixed-target video amplifier 1A2A6 and cathode ray tube unblanking.

2-74. Fixed-Target Video Amplifier 1A2A6 (fig. FO-20)

Video amplifier 1A2A6 contains circuitry for controlling blanking and unblanking of the ft cathode ray tube as well as a video amplifier circuit. In the video amplifier, positive fixed target or test video signals, from relay 1A2K4 (fig. FO-2), are ac coupled to complementary input amplifier A2Q2, Q3. Potentiometer A2R2 is adjusted for a 2-volt peak video input signal minimum. Dc voltages for the amplifier are derived from the module plus and minus 20 vdc inputs. Zener diode regulator A2VR1 'evelops -15 vdc from the -20volt source while the +20-volt input is decoupled and supplied direct to the input amplifier. The amplifier increases the signal amplitude to approximately 12volts peak without introducing phase inversion and ac couples its output to temperature stabilized emitter follower A2Q4. Since the de reference is lost due to ac coupling, dc restorer A2CR1, CR2, R9 is used to clamp the signal base line at zero vdc. In the dc restorer, diode A2CRI compensates for the voltage drop across diode A2CR2. The output from emitter follower A2Q4 is applied to a fixed compression network consisting of resistors A2R12/R13, and temperature stabilized diode A2CR3. When the amplitude of the signal is below the diode threshold, the signal is coupled through capacitor A2C8 to complementary amplifier A2Q5/Q6. As the amplitude of the signal increases above the diode threshold, the signal supplied to amplifier Q2Q5/Q6 is divided by voltage divider A2R12/R13. This effectively decreases the overall gain of the video amplifier for large signal inputs. The second complementary amplifier (Q5/Q6) and emitter follower A2Q7 are identical with the input amplifier circuit. Dc restorer A2CR4, CR5 and R20 is used to clamp the base line of the video input signal at zero vdc in the same manner as dc restorer A2CR1, CR2, R9. Output signals from emitter follower A2Q7 are supplied to output emitter follower A2Q8. Three selectable compression networks A2CR7/R26, CR8/R27, and CR9/R28 introduce additional compression depending upon the settings of ANTENNA switch 2S9 and RANGE switch 2S8 (para 2-32). These diodes are either reverse biased by +15 vdc or returned to ground. The output from emitter follower A2Q8 is routed to FT GAIN potentiometer 1A2R6 (fig. FO-2) and returned through pin U to diode clamp A1CR11. This diode clamps the video signal base line at a level determined by INTENSITY potentiometer 2R6 in parallel with resistors 2A1R25 and R26 (fig. FO-22).

2 - 75. Cathode Ray Tube Unblanking (fig. FO-20)

Unblanking of the fixed-target cathode ray tube is controlled by transistor switch 1A2A6A1Q10. When the switch conducts, the cathode of the crt is clamped at a +31 vdc level established by Zener diode A1VR3. With switch A1Q10 cut off, the crt cathode voltage rises to +100 vdc and cuts off the cathode ray tube. Reverse bias for switch A1Q10 is provided by diode A1CR17 and resistor A1R42. Diode A1CR16 protects the cathode ray tube from damage in the event of a +100 vdc source failure. Transistor A1Q10 is switched on and off by the output of diode AND gate A1CR12, CR13, CR14, CR18. This gate receives two direct inputs from the video simulator and synchronizing circuit and one from UNBLANK switch 1A2S6 (fig. FO-2). The fourth input is derived from the yoke feedback signal in the fixed target horizontal sweep circuit. This signal is a bipolar sweep signal that is coupled to unipolarizer A1AR1 through capacitors A1C21, C22. The unipolarizer is a variable gain operational amplifier that provides a negative gate for each sweep signal input. Zener diode A1VR6 reduces the gain of the amplifier when the feedback voltage appearing across resistor A1R38 exceeds 4.3 volts. Positive input signals passing through diode A1CR19 are inverted by A1AR1 while negative inputs that pass through diode A1CR20 develop output gates without inversion. The negative gates are translated through diodes A1CR21, CR22, and CR23 to turn compound-connected switch A1Q9 off. At the end of the gate signal, capacitor A1C20 charges through resistor A1R39 to hold the transistor switch off until the next gate signal occurs. If the horizontal sweep signal is lost, switch A1Q9 conducts, turning off switch A1Q10. Switch A1Q12 suppresses transients when UNBLANK switch 1A2S6 (fig. FO-2) is operated to protect the cathode ray tube.



Section VI. CATHODE RAY TUBE FOCUS CIRCUIT, CIRCUIT ANALYSIS

2-76. General

The cathode ray tube focus circuits are shown on figure FO-2 and discussed functionally, on a block diagram level, in paragraphs 2-34 through 2-36. Paragraphs 2-77 through 2-81 describe the detail functions of the stages in this circuitry. Circuits discussed are as follows: ft and mt dynamic focus circuit, squaring amplifier 2A4AAR9, dynamic focus amplifier, drift angle servo loop, servoamplifier, and servo loop stepper motor.

2-77. Ft. and Mt Dynamic Focus Circuit (fig. FO-24)

Both the ft and mt dynamic focus amplifiers receive their signal input from squaring amplifier 2A4AlAR9. Since the amplifiers are identical, only the ft dynamic focus amplifier is described. Paragraph 2-78 discusses operation of the squaring amplifier.

2-78. Squaring Amplifier 2A4A1 AR9 (fig. 2-16)

The squaring amplifier modifies unipolarized horizontal and vertical ramp voltages to provide the proper wave shape for dynamic focusing of the cathode ray tube electron beams. The amplifier and

its input and output waveforms are shown in figure 2-16. In this illustration, resistor Ra replaces series resistors A1R47 and R48 (fig. FO-24). When the unipolarized horizontal ramp signal (waveform A) is between 0 and -0.7 volt, diodes A1CR7, CR8 and CR9 are reverse baised. Diode A1CR6 is cut off also, since the unipolarized vertical ramp signal (waveform B) is less than -0.7 volt during this interval. Under these conditions the squaring amplifier input is balanced to ground causing its output to be zero volt. The input network is unbalanced when the threshold level for diode A1CR7 is exceeded. This causes the junction of resistors AlR40, R44 to track the input signal down to its maximum value, producing a positive going amplifier output. Exceeding the threshold levels of diodes AlCR8 and CR9 causes the junctions of resistors AlR41, R45, and AlR42, R46 to track the input signal also. Thus, the gain of amplifier AlAR9 is increased at each break point. For the horizontal and vertical ramp signal amplitudes shown in figure 2-16, the threshold for diode AlCR is exceeded when the horizontal ramp input is approximately -2 volts. Beyond this point the horizontal and vertical signals are added at the input of the squaring amplifier. The output from the squaring amplifier (waveform C) approximates the sum of the squares of the input ramp signals divided by 11.47.

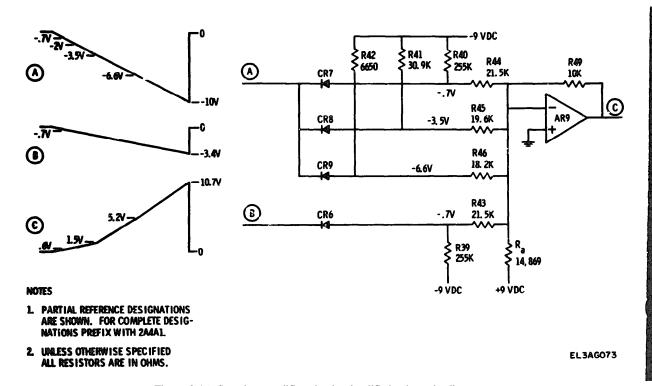


Figure 2-16. Squaring amplifier circuit, simplified schematic diagram

2-79. Drift Angle Servo Loop (fig. FO-3)

The drift angle servo loop consists essentially of the NAV SIM control mechanical linkage, synchro transmitter 2B2, synchro receiver 1A2B1, servoamplifier 2A5, and stepper motor 2B1 (fig. FO-3). GS/DFT DRIVE switch 2S12 (fig. FO-3) supplies +20 vdc to the servo amplifier drivers in the ON position. If NAVIGATION Switch 2S6 (fig. FO-3) is set to AUTO, and relay 2A5A2K1 (fig. FO-3) operates, ±20 vdc is supplied to the drift angle and groundspeed servoamplifiers. With SERVO LOOP switch 2S7 set to DFT, the rotor and stator windings of receiver 1A2B1 are connected to the servoamplifier and transmitter 2B2 through relays 1A2K5 and K6.

2-80. Servoamplifer (fig. FO-25 and FO-3)

Servo amplifier 2A5 contains two indentical amplifiers. One is used in the drift angle servo loop and the other is used in the groundspeed servo loop. Since the amplifiers are identical, only stages of the drift angle servoamplifier are discussed.

a. Buffer A3AR. On alternate half cycles of a 26vac, 400-Hz reference signal from transformer 1A2Tl (fig. FO-14), switch A3Q5 (fig. FO-25) conducts through amplifier A3Q6 and switches A3Q7, Q8 to drive buffer A3AR5. During the other half cycle when the switch is cut off, a sample of the 49-Hz drift angle information is supplied to the inverting input of buffer A3AR5. The buffer is a micromodule operational amplifier having a voltage gain of approximately 45, which is established by feedback voltage divider A3AR9, R37. Waveform B (fig. FO-3), represents the buffered output signal when the error **signal** between synchros 1A3B1 and 2B2 is less than 5 degrees. For an error of greater than 5 degrees, the buffer is overdriven which produces a square wave output signal.

b. Integrator A3AR6. Integrator A3AR6 is a bootstrap generator that develops positive or negative ramp output signals depending upon the polarity of the output from buffer A3AR5. Since the ramp generator input is a pulsating dc signal, charging **ca**bacitor A3C17 holds its output charge during the intervals when the rectifier output is clamped to ground, causing integration of the output from buffer A3AR5. Adjustable degenerative feedback is provided by voltage divider A3R48/R49, and R50 to permit adjustment of the ramp generator voltage gain for a value of 2. Charging resistor A3R40 and bootstrap resistor R47 operate together to establish a constant charging current through capacitor A3C17. With a tonstant current flowing through the capacitor, a linear ramp voltage is developed at the output of integrator A3AR6 (waveform C, fig. FO-3).

c. Level Detectors ASAR7, AR8. Level detectors A3AR7. AR8 are micromodule operational amplifiers incorporating external positive feedback. Positive and negative 1.14 vdc bias voltage is developed from two voltage dividers, A3R51/R52 and A3R53/R54. The positive bias is supplied to the noninverting input of level detector A3AR7, while the negative bias is applied to the inverting input of level detector AR8. Ramp voltages from integrator A3AR6 are fed to the remaining input of both level detectors. When the peak of the ramp voltage is less than the 1.5 volt threshold of the level detectors, the output from both detectors is approximately +7 vdc. If a positive ramp exceeds the threshold of level detector A3AR7, its output switches, producing a negative transient that turns on transistor switches A3Q11, Q10 and Q9 through monostable multivibrator A2U8A, U12B and inverter A2U7C. With transistor switches Q9, Q10 on, charging capacitor A3C17 discharges, causing the output of level detector A3AR7 to return to +7 vdc (waveform D, fig. FO-3). The monostable stretches the output pulse of detector A3AR7 to provide sufficient time for discharge of the capacitor. If a negative ramp voltage from integrator A3R6 exceeds the threshold of level detector A3AR8, its output also goes low, turning on switches A3Q11, Q9, and Q10 in a similar manner.

d. Stepper Motor Control Circuit. The stepper motor control circuit consists of two digital comparators consisting of micromodules A2U110A, A2U9D, A2U10B, A2U9C and two bistable multivibrators A2U11A and UllB. The negative-going pulse from a level detector is transformed by level changer U9A, U9B into complementary inputs at comparators A2U10A, U10B. Each comparator performs an AND-OR-INVERT logic function for the complementary inputs and the crosscoupled outputs from bistable multivibrators A2U11A, U11B to provide the clock steering gates for the J-K inputs. The clock pulse is coupled through monostable multivibrator A2U8A, U12B and delay inverter A2U12A. U12C, U12D to the bistable trigger inputs. The time constant of A2C14, RN, plus the inherent time delays of A2U8A, U12B, U12A, U12C and U12D provide time for the J-K inputs to stabilize before the clock pulse arrives. When triggered, the bistables provide an enable gate for inverters A2U7A, U7E or U7D, U7F, depending on which level detector is providing an output. Simultaneously with the application of the bistable steering gates, the level detector pulse is inverted by A2U8B and applied to inverter A2U7B. Switch A2Q13 and emitter follower A2Q14 provide a delayed output pulse for each input pulse. Before the switch can turn on, capacitor A2C8 must discharge through resistor A2R25. When the input pulse is removed, A2C8 must charge to the A2Q14 cutoff level through resistors A2R26 and R22. The collector out of



A2Q13 is commonly connected to the driver inputs through load resistors A2R29, R31, R33, and R35. The output pulse, therefore, will forward bias the two driver inputs that are enabled by the logic circuitry. The forward-biased driver pair then conducts current through the logically selected motor windings (fig. FO-3).

2-81. Servo Loop Stepper Motor (fig. 2-17)

Internal construction of the stepper motor is represented in view B, figure 2-17. As shown in view B, two coils are wound on each stator pole. These windings are connected to produce polarization of the

stator poles as indicated at view A. Assuming that switches 2A5A2Q18 and Q16 are forward biased, all A and B coils are energized causing stators 1, 2, 5, and 6 to become south poles and stators 3, 4, 7, and 8 to become north poles. Since the permanent magnet rotor tends to position itself to balance all magnetic fields, the rotor assumes the position shown in view B. If transistors 2A5A2Q17 and Q15 are forward biased, the A and B windings are energized providing the polarization indicated in view A. Sequencing of the switches is determined by the stepper motor control circuit. Waveforms J through L of (fig. FO-3) illustrate switch sequencing as the error signal passes through a null.

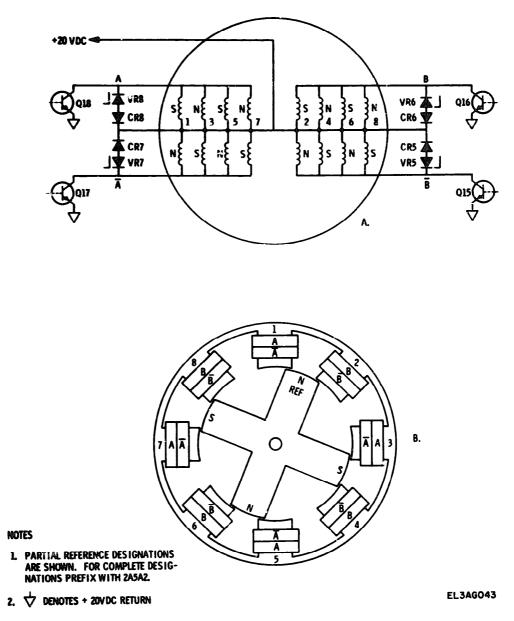


Figure 2-17. Stepper motor contol, simplified schematic diagram

2-82. General

The BITE circuits are shown in figure 2-8 and discussed functionally, on a block diagram level, in paragraph 2-42. Paragraph 2-83 describes the detail functions of the stages in this circuitry. The power supply circuits are shown on figures 2-4 through 2-6 and discussed functionally, on a block diagram level, in paragraphs 2-38 through 2-40. Paragraphs 2-84 through 2-92 describe the detail functions of the stages in this circuitry. Circuits discussed are as follows: indicating system series regulated supplies, indicating system overcurrent protection, secondary power sources, low voltage power supplies, anode and focus loads, and film speed variable voltage source.

2-83. BITE Circuitry

(fig. FO-18)

The BITE circuitry is divided into two major circuits which are functionally described on a block diagram level in paragraph 2-42. Detailed stage analysis of both major circuits are discussed in a and b below.

a. Primary Fault Detection Circuit. The primary fault detection circuit causes FAILURE lamp 1A2DS2 (fig. FO-14) to light if an overvoltage or undervoltage condition exists for the horizontal sweep, vertical sweep, video, or unblank signal. Outputs of the four sensing circuits are commonly connected to the base of switch 1A2A4Q1 so that a positive output from any channel will turn on the switch to provide a circuit path through the FAILURE lamp. Also, voltage clamps in comparators 1A2A4AR2, AR4, AR6, and AR8 are commonly connected through BITE switch 1A2S7 (fig. FO-14) to ground in the OFF position. When BITE switch 1A2S7 is placed in the ON position, the four sensing circuits are enabled. Since circuitry is essentially the same for all four channels, only the video fault detection channel is discussed. A sample of the ft video signal is applied to operational amplifier 1A2A4AR5 which has a gain of approximately 0.5 Diodes CR5, CR6, and CR14 provide voltage limiting. The amplifier positive output is peak detected by CR7 and C35. This dc level appears at pins 4 and 7 of dual comparator AR6. Pin 6 of one comparator is referenced to +1 vdc, and pin 3 of the other comparator is referenced to +10 vdc. If the video signal rises above the +10 volt reference, a noninverted (positive) output occurs. If the signal drops below +1 volt, a positive output also occurs. In either failure mode, switch Ql is turned on.

b. Fault Isolation Circuit. The fault isolation circuit contains two circuits: a high voltage power supply monitor circuit and a servo fault circuit When connected to Recorder-Processor-Viewer, Radar Mapping

RO-495/U, a BITE signal from the high voltage power supply enables switch 2A1Q8 to allow INDICATOR FAULT lamp DS2 to flash (para 2-44). The servo fault circuit in the fault isolation circuit (fig. 2-8) consists of two integrating amplifiers. 2A5A1Q6 and Q7, two emitter followers Q2 and Q3, threshold switch Q4, switch Q5, and switch 2A1Q7. Transistors Q6 and Q2 perform the same functions for the groundspeed servo as transistors Q7 and Q3 do for the drift angle servo. As the drift angle servo error increases, the pulse train pulse repetition frequency from gate 2A5A2U7C increases, causing capacitor 2A5A1C6 to hold its charge throughout the interpulse period. Thus, the average positive dc level at the output of emitter follower Q3 increases until the 5-volt threshold level at the base of threshold switch Q4 is exceeder. When the threshold is exceeded, switches 2A5A1Q4 and Q5 turn off, and allow a stable multivibrator 2A7A2Q1, Q2 (fig. FO-27) to control the operation of the SERVO FAULT indicator through switch 2A1Q7.

2-84. Indicating System Series Regulated Supplies

(fig. FO-12)

a. General. Transformer Tl in low voltage **power** supply module 1A1A3 develops six three-phase voltages from the 115 vac, 400 Hz primary power. These voltages are rectified by six three-phase bridge rectifiers. The unregulated outputs from these **rec**-tifiers are routed to five series-regulator and a shunt-regulator circuit.

b. Regulated -28-Volt Dc Supply. Series regulator 1A1A3Q1 supplies regulated -28 vdc to the other regulator circuits. If the -28 vdc supply does not provide its normal output, the remaining supplies are disabled. A sample (referenced to ground) of the regulated -28 vdc is taken from potentiometer A4AlR13 (fig. FO-12) and supplied to differential amplifier A4AlQ3 where it is compared with a signal (normally 16.3 volts dc) developed by 11.7-volt Zener diode A4AlVR2. Any change in the regulated output voltage is divided by voltage divider A4AlR12, R13, R14. Thus, an increase in the -28-volt output (more negative) causes the differential amplifier to produce a positive-going error voltage for inverter A4AlQ2. Because the inverter supplies base current for series regulator 1A1A3Q1, its collector current decreases, causing the regulated output voltage to return to its original value. Zener diode A4AlVR1 assures proper starting of the regulator. When primary power is applied, the regulator output is zero volt. Base current for series regulator lAlA3Ql (fig. FO-12) is supplied through diode A4AlCR3 and 27-volt Zener

diode A4A1VR1. As the regulator output rises toward the -37-volt unregulated voltage, differential amplifier A4A1Q3 and inverter A4A1Q2 become active, to reverse bias diode A4A1CR3, and disable the starting circuit.

- c. Regulated -20-Volt Dc Supply. Series regulator 1A1A3Q4 (fig. 10-12) operates in a circuit that is similar to the -28 vdc regulator circuit. However, differential amplifier A4A2Q1 receives its supply voltage reference voltage from the regulated -28 vdc output. A -20 vdc reference voltage, developed by voltage divider A4A2R5 through R8, is compared with the -20-volt supply regulated output in differential amplifier A4A2Ql. Any change in this output is inverted by the differential amplifier and supplied to inverter IAIA3Q5 where it is again inverted. The output from inverter Q5 is used to provide drive for series regulator 1A1A3Q4. Since the series regulator also acts as an inverter, any change in output voltage is canceled. Output filtering is incorporated by parallel capacitors 2C4, C5, C6 (fig. FO-21).
- d. Regulated +100-, +20-, and +6 3-Volt DC Supplies. The +100-volt, +20-volt, and +6.3-volt series regulators IAIA3Q7, Q2, and Q6 are driven by similar regulator circuits. In each case, differential amplifiers A4A2Q2/Q3; A4A1Q1; and A4A1Q5, respectively (fig. FO-12) receive input voltage from the regulated output of the -28 vdc supply. Voltage dividers between the respective regulated output and the regulated -28 volts provide a zero volt signal to the differential amplifiers. These signals are compared with a ground reference in the differential amplifiers to develop error output signals. In the +100-volt regulator, the error signal is routed directly to series regulator 1AlA3Q7 while error signals for the +20- and +6.3-volt supplies are routed through emitter follower IAIA3O3 and inverter A4AIO4 respectively, before being applied to their series regulators. Output filtering, for the +20 vdc power supply, is provided by capacitors 2C1, C2, C3 (fig. FO-21). Back-to-back diodes A4A2CR3, CR4 and A4AlCR1, CR2 limit excursion of the input error signal to ± 0.7 volt, for the +100- and +20-volt regulators, to prevent damage to their differential amplifiers.

2-85. Indicating System Shunt Regulated Supplies

(fig. FO-12)

A shunt regulator is fed by the 665-volt unregulated output of three-phase rectifier 1A1A3A1CR13 through CR18. The regulator (1A1A3Q8) provides 531 **volts** dc. This regulator is controlled by emitter follower A4A2Q4 which receives a sample of the regulated output from voltage divider A4A2R22, R23, R24, CR6, CR7. The emitter follower receives its source voltage from the regulated +2-volt supply and

references the sample signal to the -28 vdc output voltage.

2-86. Indicating System Overcurrent Protection

(fig. FO- 12)

Silicon controlled rectifier switch A3AlQl operates relay A3AlK3 in the event that either the plus or minus 20-volt supply is overloaded. With relay A3AlK3 operated, series regulator lAlA3Ql is cut off which removes the -28 vdc power thereby turning off the other series regulators. Switch A3A1VR1 conducts when it receives a positive pulse at its gate and remains on until its anode voltage is removed. Normally, a negative voltage is supplied to the switch through resistor A3AlR2. If either current relay A3AlKl or K2 operate, un**regul**ated +20 vdc is connected to voltage divider A3A!R1/R2 This generates a positive pulse that exceeds the threshold voltage of 12-volt Zener diode A3A1VRl to trigger the silicon controlled rectifier resulting in the turn off of all six power supplies.

2-87. Secondary Power Sources (fig. FO-26 and FO-8)

- a. Fifteen-Volt Regulators. Plus and minus 15 volts are developed from the regulated ±20-volt sources by two series regulator circuits. Operation of the +15-volt regulator is the same as for the +20-volt supply discussed in paragraph 2-84. Two provide negative voltage, a -15-volt reference voltage is derived from the regulated -28 vdc power supply by voltage divider 2A6AlR16, R17 (fig. FO-26). This dc level is compared with the output -1&volt regulator by noninverting differential amplifier 2A6A1Q2. Output from the differential amplifier is direct coupled through emitter follower 2A6AlQ1 to provide base current for series regulator 2Q2 (fig. FO-8). Since the series regulator acts as an inverter, variations in the nominal -15 vdc output level are canceled.
- b. Secondary Power Source Overcurrent Protection. Switch 2A6Ql and switch 2A6Q2 (fig. FO-26) provide overcurrent protection in the +15-volt dc and -15-volt dc regulator circuits. Both overcurrent protection circuits function in a similar manner; consequently, only the +15-volt dc overcurrent protection circuit is discussed. Any time that the output of the +15-volt dc regulator falls below approximately 13 volts dc, Zener diode 2A6VRl conducts, causing switch 2A6Ql to turn on. With switch 2R6Ql turned on, the base of emitter follower 2A6AlQ3 is clamped to the +20-volt dc regulated output, which turns off this stage, thereby removing the base current from series regulator 2Ql (fig. FO-6).
- c. *Nine-Volt Sources*. Plus and minus 9 vdc is generated by cascade operational amplifiers in module 2A4. One amplifier (2A4A2ARI) (fig. FO-24)

is connected as a source follower and is used to provide a low impedance source having power gain. This amplifier receives +9 volts at its noninverting input. This voltage is derived from the +15-volt do regulator through 11.7-volt Zener diode 2A4A2VR1 and potentiometer 2A4A2R2. The output of 2A4A2AR1 is used by circuitry within the sweep generator. This output is fed also to operational amplifier 2A4A2AR3 which is connected as an inverting amplifier having a gain of one; thus, its output is -9 vdc. This voltage is used by the circuits in the sweep generator also.

d. Groundspeed/Drift Any . Servo Sources. Four secondary voltages are supplied by regulators in module 2A5 (fig. FO-25). Two of the regulators (2A5A3Q12 and 2A5A1Q1) are conventional series regulators using Zener diodes as their references. Regulator 2A5A3Q12 provides a plus 12-volt source for operational amplifiers 2A5A3AR3, AR4, AR7, and AR8; while regulator 2A5A3Q1 supplies a plus 5-volt level for the digital micromodule circuitry. The remaining two secondary voltages (plus and minus 6 volts) are supplied by transistors 2A5A3Q13, Q14, and Q15. Transistor Q13 is a conventional Zener referenced series regulator that provides the plus 6volt output. Series regulator Q15 receives its drive signal from inverter Q14; which, in turn, receives an error signal from the temperature compensated voltage divider across the plus and minus regulated outputs. Thus, the negative voltage tracks the positive voltage to maintain balanced outputs. Zener diode VR3 is normally cutoff, but it is incorporated to prevent the negative output from exceeding 8-volts at turn on or as a result of noise transients.

2-88. Low Voltage Power Supplies (Module

(fig. FO-17)

- a. General. Transformer 1A2T2 (fig. FO-14) **develops** three, three-phase voltages from the 115 vac, **400-Hz pr**imary power. These voltages are rectified **by three**, three-phase bridge rectifiers. **The un**regulated outputs from these rectifiers are filtered and fed to three series regulated power supplies.
- b. Plus 28 Vdc Supply. A sample of the output of series regulator IA2A3Q9 (fig. FO-17) is taken from diode temperature-compensated voltage divider CR20, CR19, R29, R28 and applied to error amplifier input stage Q10. The emitter is clamped at 11.7 volts by Zener diode VR4. Any voltage change in the output of series regulator Q9 is inverted and amplified by Q10 and supplied through driver Q8 to the base of Q9. Consequently, an increase or decrease in emitter voltage of Q9 causes a decrease or increase, respectively, in conduction through Q9. Resistor R27 supplies starting current to Q10. Switch Q11 provides short circuit protection. Q7 is a constant current

source for Q9. If the emitter voltage of Q9 approaches ground potential, normally-on switch Q11 turns off and Zener diode VR3 ceases to conduct. The base of constant current source Q7 is switched to 33 volts causing this stage to turn off, thereby turning off Q8 and Q9.

- c. Plus 20 Vdc Supply. The +20 vdc supply circuit consists primarily of series voltage regulator 1A2A3AR1. This regulator receives input power from the +28 vdc supply at terminal 5 and is case grounded to +28 vdc circuit ground. The regulated output is sampled at the junction of R21, R22 and supplied to terminals 4 and 5. Capacitors C8 and C7 provide filtering. Network R18, R19, R20 establishes the output voltage regulation point. Voltage divider R22/P41 provides startup current. Short circuit shutdown is provided by switch Q13 which turns off in the event of a short circuit to supply a +20 vdc shutdown signal.
- d. Minus 5 Vdc Supply. The -5 vdc supply functions in a manner similar to the +20 vdc supply. Unregulated input voltage is supplied to terminal 3 of series voltage regulator 1A2A3AR2. Resistors R42 and R17 supply start up current. Switch Q12 turns off when the -5 vdc output approaches circuit ground and shuts down the series regulator.
- e. *Plus 5 Vdc Supply*. The +5 vdc supply functions in a manner similar to the +28 vdc supply. However, the regulated output is referenced to the regulated output of the -5 vdc supply through series resistors IA2A3R11, R12. Differential amplifier Q6 senses any relative change in the regulated outputs of the 5 vdc supplies, causing driver Q2 and series regulator Q3 to operate to null the change. If the +5 vdc regulated output approaches circuit ground potential, switch Q4 turns off, causing switch Q5 to turn off. With Q5 off, current source Q1 turns off, which causes series regulator Q3 to turn off. Start up current is provided by resistors R4 R13 and Zener diode VR2 which ceases to conduct as output voltage rises.

2-89. Anode and Focus Loads (fig. FO-9)

Anode load module 1A1A6 and focus load module 1A1A5 provide a means of measuring regulated or unregulated anode and focus voltages and the ripple voltage content of these voltages. For the purpose of clarity, only those test set group cable connections *of* immediate interest are discussed.

a. Anode Load When the anode voltage to be checked is connected to connector lAIJ8, series resistors lAlA6R3-R6 and lAlA2R1 provide a 1000-megohm dc load. The voltage drop across the parallel resistance of lAlA6R6 and lAlA2R1 provides the input to the anode voltage follower lAlA2U1. The output of the voltage follower is monitored at ANODE VOLTAGE 1V/10KV test jack E3. Capacitor C1 decouples the high voltage dc to permit ripple voltage

measurements which are taken across resistor 1A1A5R1 via ANODE RIPPLE test jack E1. Neon gas tubes 1A1A6DS1-DS3 limit transient voltages across resistor 1A1R1 to approximately 270 volts. Resistor 1A1A6R2 limits current through the neon gas tubes during periods of conduction. Test jacks 1A1A6E2, E3, and E5 provide test points for checking operation of the neon gas tubes.

b. Focus Load. Focus load module 1A1A5 functions in a manner similar to that covered in a above with the following exceptions: Series resistors 1A1A5R3 — R6 and 1A1A2R4 provide a 55-megohm dc load. The voltage drop acress the parallel resistance of 1A1A5R6 and 1A1A2R4 provides the input to the focus voltage follower 1A1A2U2. The output of the voltage follower is monitored at FOCUS VOLTAGE 2.75V/2.7kV test jack E4.

2-90. Film Speed Sources

There are two film speed sources. One is used to test the interconnections of unit 5 and the load of unit 9. The other provides calibrated film speed levels along with 115 vac servo for film speed servo.

a. RO-495/U Unit 5, Unit 9 Interconnect Test. The circuit shown in figure 2-18 provides a +4v to +27v dc potential, depending upon the setting of FILM SPEED control 1A2R18. When this control is fully

clockwise, maximum voltage is developed by conduction through emitter follower 1A2A4Q4. As the control is rotated in the counterclockwise direction, amplifier Q5 begins to conduct. The emitter of Q4 follows its decreasing base potential until it reaches a level a few tenths of a volt less than the emitter clamp potential of Q5.

b. Calibrated Film Speed Circuit. The calibrated film speed circuit consists of transformer 1A1T1, FILM SPEED switch 1A1S3 and voltage divider 1A1A2R15 – R18. The divider output is approximately 0 to 13.2 vac. These voltages are used to control the film drive servo in Recorder-Processor-Viewer, Radar Mapping RO-495/U during maintenance. This circuit is shown in figure 2-19.

2-91. Regulated +28 Volt Dc Supply and High Voltage Loads

(fig. 2-9)

Plus **28** Vdc regulated **voltage** is generated from the 196 Vac between phases in the 1A1 panel assembly with transformer 1A1T1, reactor 1A1L1 and the regulator circuit on 1A1A2. The primary power is applied to the primary winding of transformer 1A1T1. A 43-volt ac secondary is applied to bridge rectifier 1A1A2CR1 - CR4, the output of which is

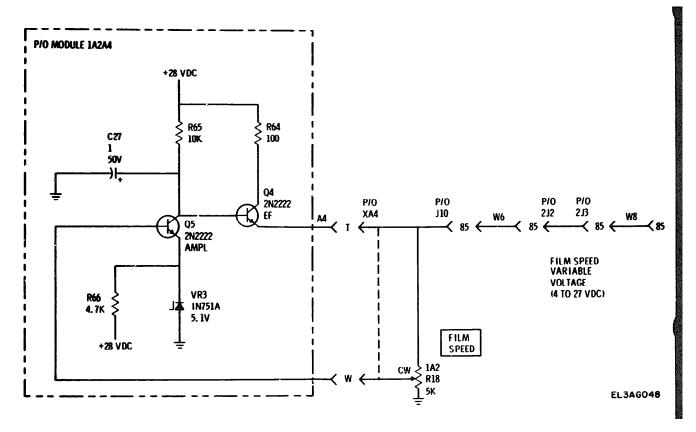


Figure 2-18. film speed variable voltage circuit,, simplified schematic diagram

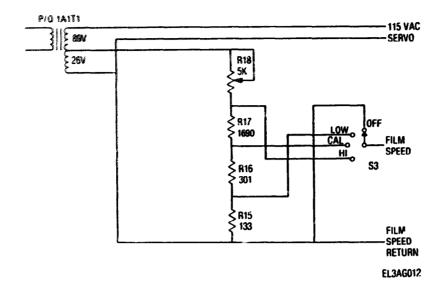


Figure 2-19. Control film speed control circuit

filtered by LC network 1A1L1, 1A1A2C1. Power amplifiers 1A1A2Q1, Q2 amplify the rectified voltage and feed regulator 1A1A2Q3 which develops the output of +28 volts dc. The regulated +28 vdc is used for the film speed servo assembly and the input to VR7 which outputs +5 vdc to the ADAS board.

2-92. Plus 26 Volt DC Power Supply

The +26 Vdc power supply is a dc-to-dc power supply. It is a sealed, non-rep&able module. Its output is used to test the high voltage power supply in the RO-495/U.

Section VIII. ADAS SIMULATOR CIRCUITS, CIRCUIT ANALYSIS

2-93. ADAS Simulator

(fig. FO-10).

ADAS simulator lAlA1 provides unblanking and vertical deflection signals which exercise the ADAS **printer circu**itry of Recorder-Processor-Viewer, **Radar Mappi**ng RO-495/U. The ADAS simulator has three operating modes as set by ADAS MODE switch 1AlSI: BCD, NUM, and ALT. In the BCD mode, BCD ADAS data blocks are generated by the ADAS simulator and output as a series of +80 vdc unblanking pulses. The vertical deflection signal (-20 to +14 vdc ramp) is enabled after each six bits of data in this mode. In the NUM (numeric) data mode, the unblanking pulses are again output, but the ramp signal is disabled. The vertical deflection signal, in this mode, is produced by a deflection clock circuit. In the ALT (alternate) mode, the ADAS simulator switches between BCD and numeric modes for alternate **AD**AS data blocks. The following subparagraphs describe the circuits of the ADAS simulator.

a Input Buffer and Clock Enable.

Input buffer lAlQ1 accepts the 28 volt data demand pulse and converts it to a +5 volt pulse for the clock enable. Clock enable flip-flop U11A is set by the

leading edge of the data demand and is reset when clock pulse 577 from the clock generator is decoded.

- b. *Clock Generator*. The clock generator consists of a **2.048** MHz crystal controlled oscillator (U2A). The output of this oscillator is input to a ripple counter (U3) which divides the frequency by 64 for an output of 32 KHz. The clock enable signal allows the clock to run only during the time for one ADAS data block.
- c. *Reset Circuit*. The reset circuit consists of monostable multivibrator U12A and flip-flop U11B. The flip-flop is used as an inverter to drive the input to the monostable multivibrator. The Q output of the monostable multivibrator is used to reset the word counter. The Q output it used to inhibit the first clock input to the bit enable circuitry.
- d. Three Decade Counter and Decode. The three decade counter, U6, U7, and U8, divides the 32 KHz clock to provide the bit count for the bit counter. The decoder is divided into two sections. The first section, U9A, U9B, U4A, and U5C, decodes the 193rd and 336th counts for the bit inhibit for the BDC data block. The second section, U9C, provides the 577th count to reset the clock enable circuit and to load the count of zero into the bit counter.

- e. Bit Counter. The bit counter consists of monostable multivibrator U1A, four bit binary counter U10, and decoders U4B, U4C, and U4D. Monostable multivibrator U1A provides a 300-nanosecond delay of the bit clock for the counter. The binary counter provides the count for the output data selection, the word clock, and bit counter reset. Bits 3 and 5 are decoded by U4B, U4C, and U4D and used to provide the clock for the word counter. Bit 5 is also used to clear the bit counter which counts from 0 through 5.
- f. Word Counter. The word counter U13 is a 12-bit binary counter. The clock for the word counter is the decoded third and fifth counts of the bit counter. Consequently, the word counter advances twice for each word at the fourth and sixth bit of the word. The counter is reset at the time of data demand. The seventh bit is one of the inputs to the ramp generator (para 2-93e above).
- g. Programable Read Only Memory (PROM) and Data Selection. PROM U14 is a 256-word by 4-bit **PROM** that is programed with the information for a fixed BCD block of data. Each line of data in the data block consists of six bits, of which the first four bits are an even numbered work, i.e., 0,2,4, of the PROM. The remaining two bits are the successive odd word of the PROM i.e., 0, 1, and 2,3. The data selector U15 is a one-of-eight data selector, of which the first six inputs are used. Selection of the six inputs is made by the three control inputs which are driven by the bit counter. The output of the data selector is a single line. The effect is that the word is converted from a parallel six bit word to a serial word. Since the total time for a data bit is approximately 31.25 microseconds, the bit enable circuit controls the inhibit input of the data selector to provide an output pulse of 21 microseconds.

h. Bit Enable *Circuit*. The bit enable circuitry consists of monostable multivibrator U12B, flip-flop U17B, and gates U16 and U18D. Monostable multivibrator U12B is set for 11 microseconds and is NORed with reset flip-flop U17B. The flip-flop is set by reset monostable multivibrator U12A and is reset by the first bit enable pulse. This is to keep the inhibit on the data selector at the beginning of an ADAS cycle. The output of the gate U16C is ANDed with the

decoded bits 193 and 386 bit to inhibit the 193rd and 386th output bits of data selector U15.

i. Unblank Level Shifter. Unblank level shifter Q7 and Q8 receive the output of the data selector U15 and convert it from the 5v CMOS level to the 80v pulse required as the unblanking output.

- j. BDC/ALT/NUM Selection. The BCD/ALT/ NUM selection circuit consists of flip-flop U17A, NOR gates U16B and U16D, and NAND gate U18A. When the ADAS MODE switch is in the BCD mode, the D input of flip-flop U17A is pulled to +5v. The clock to the flip-flop is the data demand. The flip-flop toggles high and enables the ramp generator for every data demand. When the switch is in the ALT mode, the Q output of the flip-flop is connected to the D input and the flip-flop changes state with every data demand. This enables the ramp generator every other data demand. During the data demand that the ramp generator is not enabled, the input to the deflection clock is held low and when the ramp generator is enabled the input to the deflection generator is held high. When the switch is in the NUM mode, the D input of the flip-flop is held at ground. The data demand toggles the flip-flop low. This disables the ramp generator and enables the input to the deflection clock for all data demands.
- k. Deflection Clock. The deflection clock consists of monostable multivibrator UIB and level shifting circuitry Q9, Q10, and Q11, which converts the +5 volt CMOS levels to -26 volt to +20 volt levels. The multivibrator is controlled by the reset input. When the reset is held high, the multivibrator is allowed to run. When the reset is held low, the multivibrator is turned off.
- l. Ramp Generator. Ramp generator consists of U18B, Q2, Q3, Q4, Q5, and Q6. The enable from the BCD/ALT/NUM selection circuit and the 7th bit of the word counter are the inputs to the ramp generator. When both inputs of the gate U18B go high, the output goes low. This turns off Q2, Q3, and Q4 and allows the constant current source Q5 to charge ramp capacitor C12. Output transistor follows the charge of the capacitor and provides the ramp. The output of the ramp generator and the deflection clock are ORed together to provide the vertical deflection signals.

Section IX. MONITOR ADAPTER INPUT SIMULATOR CIRCUITS, CIRCUIT ANALYSIS

2-94. General

(fig. FO-13)

The monitor adapter input simulator provides ECCM video and ECCM deflection signals which are used to test the monitor display adapter circuits in Recorder-

Processor-Viewer, Radar Mapping RO-495/U. The ECCM deflection signal is used for horizontal deflection and is synchronized with the ECCM video signal by a binary counter. The following paragraphs describe the circuits of the monitor adapter input simulator.

2-5. Clock Generator

The clock generator consists of a free-running oscillator (U1). The frequency and duty cycle of the oscillator are controlled by resistors R2 and R3, and capacitor C1. A square wave is produced by selecting a specific ratio of resistors R2 and R3. A 13-kHz square wave clock signal is generated and applied to the binary counter (U2).

2-96. Binary Counter

Counter (U2) is a 4-bit binary synchronous counter which counts from zero through 15 and then recycles. A buffered clock input triggers the 4 internal flipflops on the positive-going edge of the 13-kHz clock generator signal when enabled by internal gating. Binary counter outputs are routed to the video decoder, deflection decoder, and the ramp generator.

2-97. Ramp Generator

The ramp generator consists of a level changer (Q5, Q4), switch circuit (Q3), and operational amplifier (U6). The "D" output of the binary counter is applied to the emitter of transistor Q5. A logic high occurs at the "D" output during the binary counts of 8 through 15. This voltage corresponds to a negative level voltage at the collector of transistor Q4, and is applied to the gate (G) of JEET (Q3). Q3 is cut off and effectively opens the dc feedback path between the output of U6 and the input of U6 (inverting). Capacitor C3 then begins to charge through R17 and causes in increasing negative voltage on the output of U6. During counts of zero through 7, a positive voltage is applied to the gate of JFET Q3. Q3 conducts and capacitor C3

discharges through Q3 at a fast rate causing the negative voltage at the U6 output to increase to its starting voltage level.

2-98. Video Decoder

The video decoder consists of a gate (U3A), inverter (U4F), and level changer (Q1, Q2). The "A" and "D" outputs of the binary counter are applied to the input of U3A. During binary counts 9, 11, 13, and 15, a logic high occurs at the "A" and "D" outputs, producing a logic low at the gate output (U3A). Binary counts other than 9, 11, 13, and 15 produce a logic high at U3A output. The output of U3A is applied to the input of inverter (U4F). The function of the level changer (Q1, Q2) is to change the positive voltage to a negative voltage level. The level changer (Q2) is routed to connector J10 as the ECCM video signal.

2-99. Deflection Decoder (fig. 2-20)

The deflection decoder consists of 5 inverters (U4A through U4E) and 3 gates (U3B, U3C, and U3D). The following timing diagram shows the binary counter output logic applied as input to the decoder and the decoder output which is applied to the summer circuit.

2-100. Summer

The summer consists of an operational amplifier (U7) and current buffer (U8). Operational amplifier (U7) provides for a composite waveform of the output of the ramp generator and the deflection decoder. The

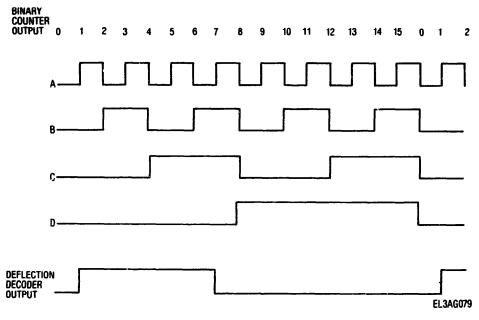


Figure 2-20. Deflection coder, timing diagram.

ramp generator signal is applied to the inverting input of U7. The deflection decoder waveform is applied to the inverting input of U7. The deflection decoder waveform is applied to the non-inverting input of U7. The summed composite signal output of U7 consists of a positive-going ramp voltage (binary counter counts 8 through 15), followed by a low level voltage

(binary counter count zero). This is followed by a positive-going pulse (binary counter counts 1 through 6), followed by a low level voltage (binary counter count 7). The U7 output waveform is applied to the input buffer U8. U8 is used as a current source for external load requirements. The U8 output is routed to connector J11 as the ECCM deflection signal.

CHAPTER 3

DIRECT SUPPORT MAINTENANCE INSTRUCTIONS

Section I. INTRODUCTION

3-1. Scope of Direct Support Maintenance

This chapter contains the following direct support maintenance functions for the test set group; bench testing, troubleshooting, removal and replacement procedures, repair procedures, cleaning, painting, calibration, physical tests and inspection, and electrical testing. The direct support maintenance procedures supplement the maintenance procedures contained in TM 11-6625-1833-12.

3-2. Organization of Direct Support Maintenance

The maintenance duties assigned to direct support maintenance personnel are listed in a through j below together with references to the paragraphs covering the specific maintenance function.

a. Connector continuity checks (pars 3-11 through 3-14).

- b. Bench tests (para 3-16 through 3-33).
- c. Troubleshooting (para 3-16 through 3-33).
- d. Removal and replacement procedures (para 3-36).
 - e. Cable repair (para 3-37).
 - f. Cleaning (para 3-38).
 - g. Painting (para 3-39).
 - h. Calibration (para 3-40 through 3-43).
- i. Physical tests and inspection (para 3-45 **through** 9-48).
- j. Electrical tests (para 3-49).

3-3. Tools and Test Equipment Required for Direct Support Maintenance

The tools and test equipment required to perform direct support maintenance on the test set group are listed in table 3-1 below.

Test Equipment	Technical Manual	Common Name
Multimeter AN/USM-223	TM 11-6625-366-15	Multimeter
Oscilloscope AN/USM-281C	TM 11-6625-2658-14	Oscilloscope
Transformer, Variable Power, General Radio Type M-2G3		Variable transformer
Voltmeter, Digital AN/GSA - 64B	TM 11-6625-444-14-1	Digital voltmeter
Generator, Signal SG-1105/G		Pulse generator
Tool Kit, Electronic Equipment TK-105/G	SC-5180-91-CL-R07	Toolkit
Termination, 100-ohm HP10100B		100-ohm termination

Table 3-1 . Tools and Test Equipment

Section II. TROUBLESHOOTING

WARNING

In normal operation, testing, and troubleshooting of the test set group, voltages up to +640 volts at power levels sufficient to cause DEATH on contact may be present. It is imperative that all warning notices in each particular procedure be observed and instructions complied with step by step.

3-4. General

a. Troubleshooting at direct support maintenance level includes all the techniques outlined for

organizational maintenance and any special or additional techniques required to isolate a malfunction to a defective part. The direct support maintenance

procedures are not complete in themselves but supplement the procedures outlined in TM 11-6625-1833-12.

b. When trouble in the equipment occurs, certain observations, tests, and measurements can be made that will aid maintenance personnel in localizing the malfunction to a particular part. The test procedures in this section are used to verify any malfunction or trouble symptom reported by lower category of maintenance. Additional troubleshooting techniques are described in detail in paragraphs 3-6 through 3-10.

3-5. Organization of Troubleshooting Procedures

- a. Troubleshooting the equipment consists of performing a bench test on the equipment to determine any malfunction within the equipment. The bench tests in this section are arranged in a systematic manner and should be followed sequentially as applicable. If, however, maintenance personnel desire to perform any test within this section, it is necessary to perform the preliminary procedures first.
- **b. Each** bench test in this section is keyed to an associated troubleshooting table. In addition, each trouble symptom listed in the troubleshooting table is also keyed to a particular step in the associated bench test. This technique is used with all the troubleshooting procedures in this section to localize a fault to a defective component, subassembly, or module. After localization of a defective component, subassembly, or module, it is replaced and the defective part is forwarded to a higher category of maintenance.
- c. The schematic and wiring diagrams contained in this technical manual should be used by maintenance personnel as aid when troubleshooting the equipment. The wire lists in section V provide point-to-point (from and to) data of each wire within the test set group. This listing is presented in alpha-numeric sequence format including a designated identifying wire number.
- cl. Continuity checks for each front panel connector is provided in paragraphs 3-11 through 3-14. Checking continuity of test set group cables is given in paragraph 3-37.

3-6. Troubleshooting with BITE

The test set group contains built-in test equipment (BITE) to alert the equipment operator when a malfunction occurs and to provide maintenance personnel with a means for determining the major circuit group in which a malfunction has occurred. The BITE circuit is enabled when the BITE switch is in the ON position. A failure indication detected by BITE circuitry causes the FAILURE indicator lamp

on panel 1A2 to light. Paragraph 3-7 lists the circuits whose failure will light the FAILURE indicator lamp.

3-7. FAILURE Light Indications

The FAILURE indicator lamp will light if an overvoltage or undervoltage condition exists in a horizontal sweep, vertical sweep, sweep video, or unblank circuit. When this indicator lamp is lit, refer to the troubleshooting procedure for the following circuits:

- a. Horizontal sweep troubleshooting, (para 3-25).
- b. Vertical sweep troubleshooting (para 3-24).
- c. Video compression troubleshooting, (para 3-28).
- d. Unblank circuit troubleshooting, (para 3-26).

3-8. SWEEP FAULT Light Indications

This lamp will flash when a fault exists in video amplifier 1A2A6, sweep generator 2A4, or horizontal amplifier 2A2. Refer to paragraphs 3-24,3-25, and 3-28 for troubleshooting these circuits.

3-9. INDICATOR FAULT Light Indications

This lamp will flash when a fault exists in the indicator fault line.

3-10. SERVO FAULT light Indications

- a. This lamp will flash when a fault exists in one or more of the following circuits:
 - (1) Servoamplifier 2A5.
- (2) Servo loop circuits (synchros, drive gears, reduction gears, etc.).
- b. For localizing the fault to a specific circuit or component, refer to paragraph 3-19 or 3-20.

3-11. Connector Continuity Test

a. General. The following tests are to be performed on all multipin electrical connectors of the test set group. Most panel mounted multipin connectors have an array of numbered test points located adjacent to the connector. There is one test point in an array for each associated connector pin. The test points associated with rectangular shaped multipin connectors are numbered to correspond to the number of the connector pin to which they are connected. The test points associated with the round shaped multipin connectors are also numbered but the test point numbers in the array do not correspond to the connector pin designations in their associated connectors since the connector pins are lettered. A crossreference between test point numbering and connector pin lettering is provided in table 3-2.

NOTE

Some connectors do not contain all 41 pins listed in table 3-2.

- b. Test Equipment Required. The only test equipment required for the connector continuity test is Multimeter AN/USM-223.
 - c. Test Connections and Conditions.
- (1) The continuity tests are performed with the test set group disconnected from all other equipment.
- (2) Perform the continuity tests (para 3-12 through 3-14). Connect the multimeter as directed in the test procedures. Refer to the wire list in paragraphs 3-51, 3-52, 3-53 if abnormal measurement indications are encountered.

Table 3-2.	Test	Point-Connector	Pin	Cross-Reference

Test Point No.	Connector Pin Letter	Test Point No.	Connector Pin Letter	Test Point No.	Connector Pin Letter
1	A	15	Ŕ	29	f
2	В	16	S	30	g
3	C	17	T	31	h
4	D	18	U	32	i
5	E	19	v	33	j
6	F	20	W	34	k
7	G	21	X	35	m
8	H	22	Y	36	n
9	J	23	Z	37	D
10	K	24	a	38	q
11	L	25	ь	39	r
12	M	26	c	40	8
13	N	27	d	41	t
14	P	28	е		

3-12. Indicator Simulator (Unit 1A1) Connector Continuity Procedure

a. LOW VOLTAGE POWER SUPPLY Connector Jl. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector Jl with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 4, 5, 7, 9, 16, 17, and 19 through 26. Measurements made at these test points should indicate infinite resistance.

b. HIGH VOLTAGE REGULATOR Connector J2. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J2 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 4, 5, 7, 8, 9, 10, 25, and 27 through 41. Measurements made at these test points should indicate infinite resistance.

c. METERING ROLLER DRIVE Connector J3. Refer to table 3-2 and measure the resistance between the test points and associated pins of J3 with the multimeter. All resistance measurements should be less than 0.5 ohm except those made at test points 16, 17, 18, and 19. Measurements made at these test points should indicate infinite resistance.

d. RACK/RO-495/U Connector J4. Refer to table

- 3 2 and measure the resistance between the test points and associated pins of J4 with the multimeter. All resistance measurements should be less than 0.5 ohm except those made at test points 5, 8, 21, 22, 23, 26, 27, 32 through 38, and 40. Measurements made at tnese test points should indicate infinite resistance.
- e. HIGH VOLTAGE SUPPLY Connector J5. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J5 with the multimeter. All resistance measurements should be less than 0.5 ohm except those made at test points 4, 5, 6, 7, 15, 16, 17, 20, 21, and 26. Measurements made at these test points should indicate infinite resistance.
- f. ADAS SIMULATOR Connector J7. Refer to table 3-2 and measure the resistance between the test points and associated pins of J7 with the multimeter. All resistance measurements should be less than 0.5 ohm except those made at test points 2, 4 through 11, 13, 14, and 16. Measurements made at these test points should indicate infinite resistance.
- g. ADAS DEMAND Connector J9. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J9 with the multimeter. All resistance measurements should be less than 0.5 ohm except those made at test points 3, 5, and 7 through 10. Measurements made at these test points should indicate infinite resistance.

3-13. Indicator Simulator (Unit 1A2) Connector Continuity Procedure

- a. YOKE *DRIVE Connector* Jl. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector **Jl** with the multimeter. All resistance measurements should be less than 0.5 ohm.
- b. RACK/SWEEP Connector J10. Measure the resistance between the test points and associated pins of connector J10 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 52,68,89 through 92,94,95, and 100. Measurements made at these test points should indicate infinite resistance.
- c. INDICATOR/SWEEP Connector- J11. Measure the resistance between the test points and associated pins of connector J11 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points, 6,12,19,20,25,26, 31,34,48,53,56,60,62, and 63. Measurements made at these test points should indicate infinite resistance.
- d. YOKE LOAD Connector J14. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J14 with the multimeter. All resistance measurements should be less than 0.5 ohm.
- e. HIGH VOLTAGE REGULATOR Connector J15.
 Refer to table 3-2 and measure the resistance

between the test points and associated pins of connector J15 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 4, 5, 7 through 10, 25, and 27 through 41. Measurements made at these test points should indicate infinite resistance.

- f. Connector J16. This connector is not used.
- g. NAV SIM/RACK Connector J18. Refer to table 3 2 and measure the resistance between the test points and associated pins of connector J18 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 11 and 12. Measurements made at these test points should indicate infinite resistance.
- h. ADAS/RACK Connector J20. J20. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J20 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 7 through 10. Measurements made at these test points should indicate infinite resistance.
- i. I BOX/RACK Connector *J22*. Refer to table 3-2 and measure **the** resistance between the test points and associated pins of connector J22 with the multimeter. All resistance measurements should be less **than 0.5 ohm, except those made at test** points 1, 10, and 11. Measurements made at these test points should indicate infinite resistance.
- *j. RCDR/RACK Connector J24.* Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J24 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 21,22, 23,27,34, and 40. Measurements made at these test points should indicate infinite resistance.
- k. RGP/RACK Connector J26. Refer to table 3-2 and measure the resistance between the test points and associated pins of connector J26 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 8,17, 18, and 20. Measurements made at these test points should indicate infinite resistance.

3-14. Generator Simulator (Unit 2) Connector Continuity Procedure

- a. SWEEP/INDICATOR Connector Jl. Measure the resistance between the test points and associated pins of connector Jl with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 19,20,25,26,31,34, 48,53,56,60,62, and 63. Measurements made at these test points should indicate infinite resistance.
- b. SWEEP/RACK Connector J2. Measure the resistance between the test points and associated pins of connector J2 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 52,68,84,89,90,91,92,95,

- and 100. Measurements made at these test points should indicate infinite resistance.
- c. SWEEP CONTROL Connector J3. Measure the resistance between the test points and associated pins of connector J3 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 89, 90, 91, 92, 98, 99, and 100. Measurements made at these test points should indicate infinite resistance.
- d. CONTROL/SWEEP Connector J4. Measure the resistance between the test points and associated pins of connector J4 with the multimeter. All resistance measurements should be less than 0.5 ohm, except those made at test points 89 through 92, 94, and 98 through 100. Measurements made at these test points should indicate infinite resistance.
- e. LOW VOLTAGE POWER SUPPLY Connector

 J5. Refer to table 3-2 and measure the resistance
 between the test points and associated pins of connector J5 with the multimeter. All resistance
 measurements should be less than 0.5 ohm, except
 those made at test points 4, 5, 7, 9, 17, and 19 through
 26. Measurements made at these test points should
 indicate infinite resistance.

3-15. Test Set Group Functional Tests (fig. FO-4)

- a. General. The following tests are required to electrically test the test set group. A basic test setup is used for all testing. Modifications to this test setup are described in individual test procedures. Each test is associated with a troubleshooting table which immediately follows the test. Primary power required for test set group operation is 115 vac, 400 Hz and +28 vdc.
- **b.** Tools and Test Equipment Required. The tools and test equipment listed in table 3-1 are required for the test set group functional tests.
- c. *Basic Test Setup*. Remove all cables stored in the upper cover of the generator simulator. Prepare the test set group for the functional tests as follows:
- (1) Arrange the equipment on a suitable workbench in the following left-to-right order: indicator simulator (unit 1A2), generator simulator (unit 2), and indicator simulator (unit 1A1).
- (2) Open (pull out) AC, DC, LOW VOLTAGE circuit breakers on unit 1A2.
- (3) Connect interconnecting cables to the test set group as illustrated in figure FO-4. Additions and/or modifications are given in individual test procedures.
- (4) Set all switches and controls to the off, down, or fully counterclockwise position.

d. Initial Test Equipment Calibration

(1) Apply power to the oscilloscope,, di**gital** voltmeter, variable transformer, and pulse generator and allow a 15 minute warmup period prior to performing tests

- (2) After the test equipment has warmed up, adjust the variable transformer for 115-volt ac output (line to neutral) using the digital voltmeter.
 - e. Initial Waveform Instructions.
- (1) For all waveform displays, connect the A input of the oscilloscope as directed by the test procedure and the low or ground terminal of the oscilloscope to chassis ground.
- (2) The oscilloscope may be triggered internally or the SWEEP GATE output jack 1A2J8 may be connected externally to trigger the oscilloscope to obtain a readable display during testing.
- (3) Waveforms are presented for the conditions specified in the test procedures and waveform illustrations.

WARNING

When power is applied to the test set group, potentials in excess of +640 vdc, +100 vdc, and 115 vac exist in Test Set Subassembly MX-8638A/APS-94D and potentials of +640 and -531 vdc exist

throughout the test set group. Exercise extreme caution when power is applied to avoid contact with any exposed connector terminals. Contact with these voltages may result in injury or DEATH.

NOTE

Each test in this **section** is organized in a systematic manner to assure that a complete test is performed. Connect the test equipment as directed in the test procedure. The tests are arranged to be performed in the sequence given. Should a random test be performed, make sure that all the preliminary steps given in paragraph 3-15 above have been accomplished.

3-16. Primary Power Distribution Trouble-Shooting

a *Bench* Test. Perform the primary power distribution bench test as described in table 3-3 below.

Table 3-3 Primary Power Distribution Test

Step	Conti	rol Settings		Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
1	None	Unit 1A2; DC RESET: Press Down AC RESET · Press Down Unit 2· POWER: ON	Verify that the blower motor in unit 1A1 s not run.	Blower motor does not run in unit 1A1.
2	Digital voltmeter Power: ON RANGE. AUTO FUNCTION: VAC	Unit 1A2 LOW VOLTAGE RESET Press down	After a 2 minute warmup, measure the voltage level between the following test points a 1A2J11-57 and 2J2-56 b 1A2J11-58 and 2J2-56 c 1A2J11-59 and 2J2-56 d 1A1J1-1 and 2J2-56 e 1A1J1-2 and 2J2-56 f 1A1J1-3 and 2J2-56 g Verify that the blower motor in unit 1A1 is operating. h 2J4-1 and 2J4-2	a 115 ± 10 vac b 115 ± 10 vac c 115 ± 10 vac d 115 ± 10 vac e 115 ± 10 vac f 115 ± 10 vac g Blower motor operating h 26 ± 2 vac
3	Digital voltmeter RANGE AUTO FUNCTION: VDC		Measure the voltage level between the following test points a. 1A1J2-18(+) and 1A1J2-19(-) b. 2J4-22(+) and 2J4-23(-) c. 2J4-22(+) and 1A2J20-12(-) d. 2J4-12(+) and 1A2J20-12(-) e. 1A2J22-19(+) and 1A2J15-19(-) f. 1A2J10-υ9(+) and 1A2J11-27(-)	
4	Digital voltmeter RANGE: AUTO FUNCTION: VAC	Unit 1A2 ILLUM ON	Measure voltage level between the following test points 2J4-3 and 2J4-101	48 ± 0 4 vac

b. Troubleshooting Procedure. The following procedure is used when a fault is suspected in the primary power distribution circuits of the test set group. Primary power is defined as the distribution of the 115 vac, 400 Hz, 3-phase and 28 vdc bench power

in the **test set grou**p. Figure FO-5 shows the primary power **distribution** and control system of the **test set** group and will be an aid to the technician when troubleshooting.

Table 3-4. Primary Power Distribution Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	115 vac not present at test points 1A1J1-1, -2, and -3 (all measurements referenced to neutral line test point 2J2-56).	a. AC RESET circuit breaker on panel 1A2 is open b LOW VOLTAGE RESET circuit breaker on panel 1A2 is open c. Defective wiring or connectors	 a. Reset circuit breaker. b Reset circuit breaker. c Measure for 115 vac at test points 1A2J22-3, -4, and -5 referenced to test point 1A2J22-6 If present, defective wiring is indicated Check wiring Refer to wiring lists (section V) If voltage is not present, measure for presence at bench input to the test set group.
		 d. 1A2K1 inoperative e Defective overvoltage protector module 1A2A5. 	d Check for presence of 22 vdc at test point 1A2J22-19 (referenced to ground at 2J3-23) If present, chassis 1A2 must be removed and relay 1A2K1 checked, remove and replace if defective (fig. 3-8) NOTE: Relay 1A2K1 is operative if the POWER ON light on panel 1A2 is illuminated or the blower motor of panel 1A1 is operating e Replace overvoltage protector module 1A2A5 (fig 3-7)
2	Blower motor inoperative.	a. AC RESET circuit breaker on panel 1A2 is open b LOW VOLTAGE RESET circuit breaker on panel 1A2 is open. c Defective wiring or connectors d. Defective blower motor	 a. Reset circuit breaker b Reset circuit breaker c Same as item 1c above d Replace blower motor
3	With the POWER switch of unit 2 in the ON position, +28 ±2 vdc is not present at any of the following test points. Test Point Reference 1A1J2-18 1A1J2-19 2J4-22 2J4-23 2J4-22 1A2J20-12 2J4-12 1A2J20-12 1A2J20-19 1A2J15-19	a. Open DC RESET circuit breaker on 1A2 panel. b Defective wiring W10 or connector 1A2J12	a. Reset the circuit breaker b. Check wiring Refer to wiring lists paras 3-51, 3-52, and 3-53
4	+28 vdc not present at test point 1A2J10-59 (referenced to 28 vdc return at test point 1A2J11-27) or not within ±0.05 vdc tolerance, test points of 3 above are normal	a Defective low voltage power sup- ply and regulator 1A2A3 b Defective wiring or connector	a Replace 1A2A3 (fig 3-7) If still abnormal, proceed to b below b Check wiring Refer to wiring lists paras 3-51, 3-52, and 3-53.
5	28 vdc not present at one or more of the test points given in 3 above At least one test point indicates normal voltage	Defective wiring or connector	Check wiring Refer to wiring lists (paras 3-51, 3-52, and 3-53)
6	4.8 vac not present between test points 2J4-3 and 2J4-101.	a AC RESET circuit breaker on panel 1A2 is open. b LOW VOLTAGE RESET circuit breaker on panel 1A2 is open	a Reset circuit breaker b Reset circuit breaker

Table 3-4. Primary Power Distribution Troubleshooting - Continued

Itans. No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
		c. Defective wiring or connector d. 1A2K1 relay inoperative. e. Defective transformer 1A1T2. f. Defective switch 1A2S1.	c. Check wiring. Refer to wiring lists (paras 3-51, 3-52, and 3-53). d. Replace 1A2K1 relay (fig. 3-8). e. Replace transformer 1A1T2. f. Replace switch 1A2S1.
7	26 vac not present between test points 234-1 and 234-2.	a. AC RESET circuit breaker on panel 1A2 is open. b. Defective transformer 1A1T2.	a. Reset circuit breaker. b. Replace transformer 1A1T2.

3-17. Low Voltage Power Supplies Trouble-shooting

a. Bench Test. Perform the low voltage power supplies test as described in table 3-5 below. Refer to figure FO-6 for location of test points in units 1A1 and 1A2.

WARNING

Dangerous voltages exist in these circuits. Use extreme care when making voltage measurements.

Table 3-5. Low Voltage Power Supplies Test

Step	Contr	ol Settings		Performance
No.	Test Equipment	Equipment Under Test	Test Procedur2	Standard
1	Digital voltmeter: RANGE: AUTO FUNCTION: VDC	Piene	Measure voltage level between the following test points: a. 1A1J1-8(+) and 1A1J1-14(-) b 1A1J1-6(-) and 1A1J1-14(+) c. 1A1J1-10(-) and 1A1J1-14(-) d. 1A1J1-11(+) and 1A1J1-14(-) e. 1A1J1-12(+) and 1A1J1-14(-) f 1A1J1-13(+) and 1A1J1-14(-) g 1A1J1-18(+) and 1A1J1-14(-)	a. +20 0 ±0.2 vdc. b20.0 ±0.2 vdc. c28.0 ±1.0 vdc. d +6 3 ±0.2 vdc. e +101 ±3.0 vdc. f +640 ±40.0 vdc. g +531 ±12.5 vdc.
2	Digital volumeter RANGE. AUTO FUNCTION: VDC	None	a. Remove 18 screws from the front panel of Unit 1A1. b Remove panel 1A1 from the cabinet c Place the +28 volt regulated power supply and high voltage loads card (1A1A2) on extender. d. Measure voltage level between the following test points: (1) 1A13-1(+) and 1A13-2(-) (2) 1A14-6(+) and 1A14-7(-) (3) 1A1A2-T(+) and 1A1A2-1(-) e Remove card 1A1A2 from the extender and replace back in panel 1A1	a None. b None. c None. d Voltages should be as follows: (1) +28.0 ±2.0 vdc. (2) +28.0 ±2.0 vdc. (3) + 5.0 ±0.2 vdc. e None
3	Digital voltmeter RANGE: AUTO FUNCTION VDC	Unit 1A1. HIGH VOLTAGE ON	Measure voltage level between the following test points. 1A1J5-1(+) and 1A1J5-2(-).	26.00 ±0.030 vdc
4	Digital voltmeter. RANGE: AUTO FUNCTION: VDC	Unit 1A2 [.] VERTICAL OFFSET OVERRIDE. ON	a Place the low voltage power supply regulator card (1A2A3) on extender b Measure voltage level between the following test points: (1) 1A2J24-39(+) and 1A2J11-27(-)	 a. None b Voltages should be as follows: (1) +20 ±0.5 vdc

Table 3-5. Low Voltage Power Supplies Test - Continued

Step	Control Settings			D	
No.	Test Equipment	Equipment Under Test	Test Procedure	Performance Standard	
			(2) 1A2A3-J(+) and 1A2A3-1(-) (3) 1A2A3-V(+) and 1A2A3-1(-) (4) 1A2A3-4(-) and 1A2A3-1(+) c. Remove card 1A2A3 from the extender and replace back in panel 1A1. d Replace panel 1A2 back in cabinet. e Replace 18 screws on the front panel of 1A1	(2) +28 ±2 G vdc (3) + 5 ±0.2 vdc (4) - 5 ±0 2 vdc c None d None	
5	Digital voltmeter RANGE: AUTO FUNCTION: VDC	None	Measure voltage level between the following test points α 1A1J2-16(+) and 1A1J2-11(-) b 1A1J2-17(-) and 1A1J2-11(+)		

b. Troubleshooting Procedure. The following procedure is used in troubleshooting the low voltage system of the test set. Secondary power distribution and control circuits are shown in figure FO-6 and will be an aid to the rapairman when troubleshooting.

WARNING

Dangerous voltages exist in the low voltage power supply circuits. Use extreme care when troubleshooting these circuits.

Table 3-6. Low Voltage Power Supply Troubleshooting

Item No	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Abnormal or no voltage measured at one or more of the following test points (referenced to signal ground at test point 1A1J1-14): 1A1J1-8 (+2') vdc) 1A1J1-6 (-20 vdc) 1A1J1-10 (-28 vdc) 1A1J1-11 (+6.3 vde) 1A1J1-12 (+100 vdc) 1A1J1-13 (+640 vdc) 1A1J1-18 (+531 vdc)	a. AC RESET or LOW VOLTAGE RESET circuit breaker on unit 1A2 open. b Defective low voltage power supply 1A1A3 c Defective low voltage regulator 1A1A4	a Reset circuit breaker and retest for corrective voltages b Check for presence of 115 vac at test points 1A1J1-1, -2, and -3 referenced to neutral at test point 2J2-56 If present, replace low voltage power supply 1A1A3 (fig 3-4) If not present, refer to the primary power distribution troubleshooting procedures (para 3-16) c Replace low voltage regulator 1A1A4 (fig 3-3)
2	Abnormal or no voltage measured at one or more of the following test points (referenced to ground at test point 1A2J22-23) 1A2J24-15 (+20 vdc) 1A2J16-10 (+28 vdc) 1A2J24-39 (+20 vdc)	a. AC RESET circuit breaker on unit 1A2 open b Relay 1A2K1 defective or inoperative c Defective low voltage power sup-	a Reset circuit breaker b Check for presence of +28 vdc at test point 1A2J22-19 (referenced to ground at test point 2J3-23) If present, chassis 1A2 must be removed and 1A2K1 checked, remove and replace if defective (fig 3-8) NOTE: Relay 1A2K1 is operative if the POWER ON light on panel 1A2 is illuminated or the blower motor of panel 1A1 is operating c Replace the low voltage power supply and
3	Abnormal or no +28 vdc regulated voltage at the test point 1A1J4-6 (referenced to ground)	ply and regulator 1A2A3 AC RESET or LOW VOLTAGE RESET circuit breaker on unit 1A2 open	regulator 1A2A3 (fig 3-7) Reset circuit breaker

Table 3-6. Low Voltage Power Supplies Troubleshooting - Continued

Item No.	Trouple Symptom	Probable Trouble	Checks and Corrective Actions
4	Abnormal or no voltage measured at one or more of the following connector pins (referenced to signal ground at pin 1 of connector (1A2A3:: 1A2A3-E (+20 vdc) 1A2A3-J (+28 vdc) 1A2A3-V (+5 vdc) 1A2A3-4 (-5 vdc)	Defective low voltage power supply and regulator.	a. Check for presence of 26 vac between pirs 1A2A3-A, 1A2A3-B, and 1A2A3-C. b. Check for presence of 7.4 vac between pins 1A2A3-K, 1A2A3-L, and 1A2A3-M. c Check for presence of 8.1 vac between pins 1A2A3-20, 1A2A3-21, and 1A2A3-22. d If above voltages are present replace the low voltage power supply and regulator (fig 3-4). If not present, refer to the primary power distribution troubleshooting procedures (para 3-16).
5	Abnormal or no voltage measured at one or more of the following connector pins (referenced to signal ground at pin 1 of connector 1A1A2) 1A1A2-Y (+28 vdc) 1A1A2-S (+28 vdc) 1A1A2-C (+28 vdc) 1A1A2-T (+5 vdc)	Defective +28 voit regulated power supply and high voltage loads.	Check for presence of 43 vac between pins 1A1A2-18 and 1A1A2-V. If present, replace the +28 volt regulated power supply and high voltage loads (fig. 3-4) If not present, refer to figure FO-5
6	Abnormal or no voltage measured at one or more of the following test points (referenced to ground at test point 1A1J2-11): a. 1A1J2-16 (+15 vdc). b. 1A1J2-17 (-15 vdc)	a One or more of the following components defective: (1) Offset amplifier (2A6) (2) Regulator transistor 2Q1 (3) Low voltage power supply 1A1A3	 a Replace one or more of the following components: (1) Offset amplifier 2A6 (fig. 3-12). (2) Regulator transistor 2Q1 (fig. 3-12). (3) Check for presence of 115 vac at test points 1A1J1-1, -2, and -3 referenced to neutral at test point 2J2-56. If present, replace low voltage power supply 1A1A3 (fig 3-4). If not present, refer to primary power distribution troubleshooting procedures (para 3-16). b Same as item 6a above.
7	26 vdc not present at test points 1A1J5-1(+) and 1A1J5-2(-).	 a. +28 vdc not present at 1A2J2-18. b Defective power supply 1A1PS1 	 a Refer to primary power troubleshooting (para 3-16). b Replace power supply 1A1PS1 (fig. 3-4).

3-18. Panel Lights Troubleshooting

a. Bench Test. Perform the panel lights bench test as described in table 3-7 below.

Table 3-7. Panel Lights Test

Step	Control Settings		Test Procedure	Performance	
No	Test Equipment	Equipment Under Test		Standard	
1	None	Unit 2 PANEL LIGHTS TEST	Observe all panel lights on this unit	All lights illuminate	
2	None	Unit 1A2 PANEL LIGHTS TEST	Observe all panel lights on this unit	All lights illuminate	

Table 3-7. Panel Lights Test - Continued

Step	Control Settings			Performance	
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard	
3	None	None	Observe POWER on lamps on unit 1A2 and unit 2.	All lights illuminate.	
4	None	Unit 1A1: HIGH VOLT- AGE power supply: ON	Observe HIGH VOLTAGE panel light on this unit.	Light illuminate	
5	None	Unit 1A1: Jumper be- tween test points 1A1J4-6 and 1A1J4- 13	Observe MAP ON panel light on this unit.	Light illuminates	

b. Troubleshooting Procedure. The following procedure is used in troubleshooting the panel lights on the test set group.

Table 3-8. Panel Lights Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	HIGH VOLTAGE ON lamp on panel 1A1 fails to light when HIGH VOLTAGE switch of panel 1A1 is operated to ON position.	Defective HIGH VOLTAGE switch 1A1S2.	Check HIGH VOLTAGE switch (fig 3-3) and replace if necessary.
2	Panel lights fail to light when PANEL LIGHTS switch on panel 1A2 or panel 2 is set to TEST.	a. Unit 2. Defective switch S10. b Unit 1A2. Defective switch S2.	a. Replace switch S10 (fig. 3-11) b. Replace switch S2 (fig. 3-16)
3	POWER ON lamps on panel 1A2 or 2 fail to light.	Defective relay 1A2K1.	Check for presence of +28 vdc at test points 1A2J22-19 (referenced to ground at 2J3-23). If present, and POWER ON lamp fails to light, chassis 1A2 must be removed and relay 1A2K1 checked (fig 3-8)
4	MAP ON lamp on panel 1A1 fails to light.	Defective lamp.	Replace lamp

3-19. Servo Loop Troubleshooting

a. Bench Test. Perform the servo loop bench test as described in table 3-9 below.

Table 3-9. Servo Loop Test

Step No.	Control Settings		Test Procedure	Performance
	Test Equipment	Equipment Under Test	Test Procedure	Standard
1	None	Unit 2 NAVIGATION AUTO SERVO LOOP GS GS/DFT DRIVE ON Unit 1A2 NAV SIM. 15R	Observe GS/DFT indicator dial and SERVO FAULT indicator lamp on unit 2	GS/DFT indicator dial nulls and SERVO FAULT indicator lamp is extinguished
2	None	Unit 2. GS/DFT DRIVE OFF UNIT 1A2 NAV SIM· 10R	Same as 1 above	GS/DFT indicator dial does not null and SERVO FAULT indicator lamp flashes

Table 3-9. Servo Loop Test - Continued

Step	Control Settings			Performance	
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard	
3	None	Unit 2: GS/DFT DRIVE: ON Unit 1A2: NAV SIM: 0	Same as 1 above	GS/DFT indicator dial nulls and SERVO FAULT indicator lamp is extinguished.	
4	None	Unit 2: SERVO LOOP: DFT GS/DFT DRIVE. OFF Unit 1A2: NAV SIM 5R	Same as 1 above	GS/DFT indicator dial does not null and SERVO FAULT indicator lamp flashes.	
5	None	Unit 2. gs/DFT DRIVE: ON Unit 1A2: NAV SIM 15R	Same as 1 above	GS/DFT indicator dial nulls and SERVO FAULT indicator lamp is extinguished.	
6	None	Unit 1A2: NAV SIM. 0	Same as 1 above .	GS/DFT indicator dial nulls and SERVO FAULT indicator lamp is extinguished.	
7	None	Unit 2: GS/DFT DRIVE: OFF	Same as 1 above	GS/DFT indicator dial remains at 0 and SERVO FAULT indicator lamp remains extinguished.	
8	None	Unit 2: NAVIGATION: GS GS/DFT DRIVE: ON Unit 1A2: NAV SIM: 15L	Same as 1 above	GS/DFT indicator dial does not null and SERVO FAULT indicator lamp remains extinguished.	
9	None	Unit 2. NAVIGATION· MANUAL	Same as 1 above .	GS/DFT indicator does not null and servo fault lamp remains extanguished.	
10	None	Unit 2. SERVO LOOP. GS	Same as 1 above	GS/DFT indicator dial does not null and SERVO FAULT indicator lamp remains extinguished.	
11	None	Unit 2. NAVIGATION GS	Same as 1 above .	GS/DFT indicator dial nulls and SERVO FAULT indicator lamp is extinguished.	

b. Troubleshooting Procedure. The following troubleshooting procedure will aid in localizing a servo loop trouble symptom to defective servo amplifier 2A5 or to the remaining components of the servo loop. If the trouble is determined to be in the servo loop but not in the servoamplifier, a more detailed procedure is required to localize a specific synchro, control, or gar train. For this reason a supplementing test

procedure (para 3-20) follows the troubleshooting table. This procedure is used when replacement of servoamplifier 2A5 does not remedy the trouble symptom. It is not intended to be used as a performance test of the servo loop. The simplified wiring diagram shown in figure FO-7 shows cables, wiring, components, and test points pertaining to the servo loop.

Table 3-10. Servo Loop Troublesho

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	GS/DFT indicator fails to null and SERVO FAULT light remains on with the following test set control settings: NAVIGATION. AUTO GS/DFT DRIVE: ON NAV SIM: 15R SERVO LOOP: Operate from GS to DFT position and return to DFT after 20 seconds.	a. Defective servo amplifier 2A5. b. Defective synchro, relay, stepping motor, or reduction gear of the servo loop (fig FO-7)	a Replace servoamplifier 2A5 (fig 3-10) b If GS/DFT indicator fails to null in either position (GS or DFT) of the SERVO LOOP switch, and replacement of servoamplifier 2A5 does not remedy the trouble symptom, perform the detailed servo test of para 3-20. Replace any defective component(s) and realign synchros 1A2B1 and 2B2 (para 3-41 through 3-43).

- 3-20. Servo Loop Supplementary Tests for Troubleshooting (fig. 3-1 and FO-7)
- a. Test Equipment Required. Voltmeter, digital AN/GSM-64B and Oscilloscope AN/USM-281C. b. Test Connections and Conditions.
- (1) Set up the equipment as instructed in paragraph 3-15c.
- (2) Operate the test set group controls to the following positions:

CONTROL	POSITION	LOCATION
NAV SIM	0	Unit 1A2
NAVIGATION	AUTO	Unit 2
SERVO LOOP	DFT	Unit 2
GS/DFT DRIVE	ON	Unit 2
POWER	ON	Unit 2
(All other test set group	un controls may be in	n any position)

- c. Initial Test Equipment Calibration. None Required.
- d. Procedure. The following procedure supplements the servo loop test of paragraph 3-19. This procedure will be used as an aid to troubleshooting the servo loop when replacement of servo amplifier 2A5 does not remedy the trouble symptoms, and is not intended to be used as a performance test of the servo loop. PROBABLE DEFECTIVE COMPONENTS ARE SHOWN IN PARENTHESES BELOW EACH STANDARD IN THE PERFORMANCE STANDARD COLUMN. The servo loop wiring diagram of figure FO-7 shows cables, wiring, components, and test points pertaining to the servo loop.

Table 3-11 . Servo Loop Supplementary Test

Step	Control Settings			Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
1	Digital voltmeter function; ac RANGE AUTO	None	a. Measure the voltage between test points 1A2J18-8 and 1A2J18-9 b Measure the voltage between test points 2J4-1 and 2J4-2	a 26 ± 2 vac (1A2T1, fig 3-7) or (1A2K1, fig 3-8) b 26 ± 2 vac (1A2T1, fig 3-7) or (1A2K1, fig 3-8)
2	Digital voltmeter. FUNCTION: DC	Unit 2· SERVO LOOP: GS	Measure the voltage between test points 1A2J11-61 and 1A2J11-49 (28 vdc return)	+0 7 ± 0 2 vdc (1A2Q1)
3	Oscilloscope VOLTS/DIV: 2 TIME/DIV: 2ms	Unit 2. NAVIGATION: MANUAL SERVO LOOP: DFT	a. Place the scope probes between test points 1A2J18-13 and 1A2J18-14	a $15 \pm 2 \text{ vac} (1\text{A}2\text{B}1, \text{ fig } 3-8)$
	VERT MODE: ADD NOTE Two oscilloscope probes required.	Unit 1A2: NAV SIM: 15R	b Manually vary the NAV SIM con- trol on unit 1A2 throughout its range	b The oscilloscope indication shall be minimum when the NAV SIM control is at zero, and shall peak to 15 ± 2 vac at 15R and 15L (1A2B1, 1A2K5 or 1A2K6, fig 3-6 or 3-8)
4	None	None	Repeat b above with the oscilloscope probes between test points $2J4-17$ and $2J4-18$	Same as 3 above

Table 3-11. Servo Loop Supplementary Test - Continued

Step	Cont	rol Settings		Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
5		Unit 2: NAVIGATION: MANUAL SERVO LOOP: GS	a. Place the oscilloscope probes be- tween test points 1A2J18-5 and 1A2J18-6.	c. Same as 3 above.
		Unit 1A2: NAV SIM: 15R	b. Manually vary the NAV SIM control throughout its range.	b The oscilloscope indication shall be minimum when the NAV SIM control is at zero, and shall peak to 15 ± 2 vac at 15R and 15L.
6	None	None	Repeat 5 above with the oscilloscope probes between test points 2J4-14 and 2J4-15.	Same as 5 above.
7	None	Unit 2: POWER OFF	Disconnect cable W4 from jack 1A2J18. Connect jumper cables and the digital voltmeter as shown in A, figure 3-1.	None
8	Digital voltmeter: FUNCTION. AC RANGE: AUTO	Unit 2 ⁻ POWER ON SERVO LOOP: DFT Unit 1A2: ILLUM: ON	Operate the NAV SIM control on unit 1A2 to obtain maximum reading on the voltmater.	NAV SIM control shall indicate 0 ± 4 divisions when the voltage meter reading is maximum.
9	None	Unit 2: POWER: OFF	Connect the equipment as shown in B, figure 3-1.	none
10	None	Unit 2: POWER: ON SERVO LOOP: DFT Unit 1A2: ILLUM: ON	Operate the NAV SIM control to obtain minimum reading on the voltmeter.	NAV SIM control shall indicate 0 ± 1 divisions
11	None	Unit 2 POWER: OFF	Disconnect jumper leads and the digital voltmeter, and reconnect cable W4 to jack 1A2J18 (fig FO-4).	None
12	Digital voltmeter: FUNCTION: K OHM	Unit 2. power; off	Disconnect cable W8 from jack 2J4 (fig FG-4).	None
13	None	None	Measure the following test points (fig FO-7) 2J4-8 to 2J4-9 (S1 to S2) 2J4-9 to 2J4-10 (S1 to S3) 2J4-8 to 2J4-10 (S2 to S3) 2J4-1 to 2J4-2 (R1 to R2)	Nominal resistance: 12 ohms 12 ohms 12 ohms 39 ohms (2B2, fig. 3-11).
14	None	None	Reconnect cable W8 to jack 2J4 (fig FO-4).	None

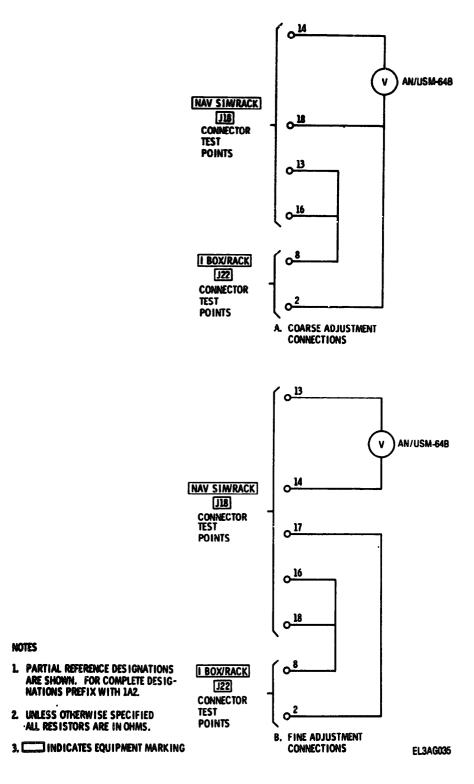


Figure 3-1. Control synchro adjustment test setup (A and B).

3-21. Clock Waveform Troubleshooting.

a. Bench Test. Perform the clock waveform bench test as described in table 3-12 below.

Table 3-12. Clock Waveform Test

Step	Control Settings		Test Procedure	Performance	
No.	Test Equipment	Equipment Under Test	1est Procedure	Standard	
1	None	Unit 2: RANGE: 50 ANTENNA: RIGHT	Connect oscilloscope to test point 1A2J11-37 and observe waveform.	Waveform A, figure 3-2.	
2	None	Unit 2: INTENSITY: Maximum DISPLAY: FT Unit 1A2: TEST VIDEO: ON FT GAIN: Variable	Connect oscilloscope to test point 1A2J1-2 and observe waveform.	Waveform B, figure 3-2.	
3	None	Unit 2: INTENSITY: Minimum Unit 1A2: TEST VIDEO: OFF FT GAIN: Maximum VIDEO AMPLITUDE: Variable	Connect oscilloscope to test point 1A2J1-2 and observe waveform.	Waveform C, figure 3–2.	
4	None	Unit 2: RANGE: 25	Connect oscilloscope to test point 2J1-45 and observe waveform.	Waveform D, figure 3–2.	
5	None	Unit 2: RANGE: 50	Connect oscilloscope to test point 2J1-45 and observe waveform.	Waveform E, figure 3-2.	
6	None	Unit 2: RANGE: 100	Connect oscilloscope to test point 2J1-45 and observe waveform.	Waveform F, figure 3–2.	
7	Oscilloscope: Dc coupled	Unit 2: ANTENNA: RIGHT	Connect oscilloscope to test point 2J4-24 and measure displayed signal voltage.	+4.0 ± 0.5 vdc	
8	None	Unit 2: ANTENNA: BOTH	Connect oscilloscope to test point 2J4-24 and observe waveform.	Waveform G, figure 3–2.	
9	Oscilloscope: Dc coupled	Unit 2: ANTENNA: LEFT	Connect oscilloscope to test point 2J4— 24 and measure displayed signal voltage	-4.0 ± 0.5 vdc	
10	None	Upit 2: ANTENNA: BOTH	Connect oscilloscope to test point 1A2J11-32 and observe waveform.	Waveform H, figure 3-2.	
11	Oscilloscope: Dc coupled	Unit 2: ANTENNA: RIGHT	Connect oscilloscope to test point 1A2Jf1-32 and measure displayed signal voltage.	+4.74 ± 0.25 vdc	
12	None	Unit 2: ANTENNA. BOTH	Connect oscilloscope to test point 1A2J11-33 and observe waveform.	Waveform J, figure 3–2.	
13	Oscilloscope: Dc coupled	Unit 2: ANTENNA: LEFT	Connect oscilloscope to test point 1A2J11-33 and measure displayed signal voltage.	+4.75 ± 0.25 vdc	

b. Troubleshooting Procedure. The following troubleshooting procedure is referenced to the test set group waveforms A, B, C, D, E, F, G, H, and J of figure 3-2. The signals represented by these waveforms originate in either the 5-MHz oscillator

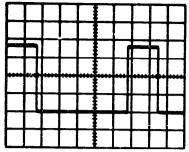
and prf counter 1A2A1, antenna counter 1A2A2 or video amplifier 1A2A6. Use of the troubleshooting procedure will localize a clock waveform trouble to one of these three modules.

Table 3-13. Clock Waveform Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform A (fig. 3-2), measured at test point 1A2J11-37, is abnormal.	Defective 5-MHz oscillator and prf counter 1A2A1	Replace 5-MHz oscillator and prf counte 1A2A1 (fig 3-7)
			NOTE If 1A2A1 is not at fault, refer to figure FO-15 and check all inputs to 1A2A1.
2	Waveform B (fig. 3-2), measured at test point 1A2J1-2, is abnormal with the test set group controls set to the following positions:	Defective video amplifier 1A2A6.	Replace video amplifier 1A2A6 (fig 3-5). NOTE If 1A2A6 is not at fault, refer to figure
	NOTE Waveform B, at this point has an amplitude of approximately 3 volts peak-to-peak.		FO-20 and check all inputs to 1A2A6
	Unit 2: INTENSITY. Minimum Unit 1A2: TEST VIDEO: ON FT GAIN: Maximum VIDEO AMPLITUDE. Variable		
3	Waveform C (fig. 3-2) measured at test point 1A2J1-2, is abnormal with the test set group controls set to the following positions: Unit 2: INTENSITY: Minimum Unit 1A2. TEST VIDEO: OFF FT GAIN: Maximum VIDEO AMPLITUDE: Variable	Same as 2 above.	Same as 2 above.
4	Waveform D (fig. 3-2), measured at test point 2J1-45, is abnormal with the test set group controls set to the following position: Unit 2: RANGE: 25	Same as 1 above.	Same as 1 above
5	Waveform E (fig. 3-2), measured at test point 2J1-45, is abnormal with the RANGE switch on unit 2 set to 50.	Same as 1 above.	Same as 1 above.
6	Waveform F (fig. 3-2) measured at test point 2J1-45, is abnormal with the RANGE switch on unit 2 set to 100.	Same as 5 above.	Same as 5 above.
7	A voltage of +4.0 to +4.5 vdc is not present at test point 2J4-24 with the ANTENNA switch on unit 2 set to P.IGHT.	Defective antenna counter 1A2A2.	Replace antenna counter 1A2A2 (fig 3-7) NOTE If 1A2A2 is not at fault, refer to figure FO-16 and check all inputs to 1A2A2.
8	Waveform G (fig. 3-2), measured at test point 2J4-24, is abnormal with the ANTENNA switch on unit 2 set to BOTH.	Same as 7 above	Same as 7 above

Table 3-13. Clock Waveform, Troubleshooting - Continued

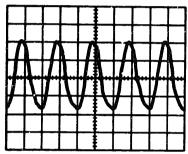
Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
9	A voltage of -4.1 to -4.5 vdc is not present at test point 2J4-24 with the ANTENNA switch on unit 2 set to LEFT.	Same as 7 above.	Same as 7 above.
10	Waveform H (fig. 3-2), measured at test point 1A2J11-32, is ab- normal with ANTENNA switch on unit 2 set to BOTH.	Same as 7 above.	Same as 7 above.
11	A voltage of +4.5 to +5.0 vdc is not present at test point 1A2J11-32 with the ANTENNA switch on unit 2 set to RIGHT.	Same as 7 above.	Same as 7 above.
12	Waveform J (fig. 3-2), measuared at test point 1A2J11-33, is abnormal with ANTENNA switch on unit 2 set to BOTH.	Same as 7 above.	Same as 7 above.
13	A voltage of +4.5 to +5 0 vdc is not present at test point 1A2J11-33 with the ANTENNA switch on unit 2 set to LEFT	Same as 7 above.	Same as 7 above.



TEST POINT: 1A2J11-37

VOLTS/DIV: 1 TIME/DIV: .2 MSEC SYNC: EXT

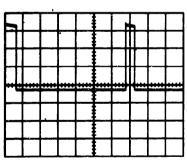
A. SWEEP GATE



TEST POINT: 1A2J1-2

VOLTS/DIV: 2 TIME/DIV: .1 µSEC SYNC: EXT

B. TEST VIDEO

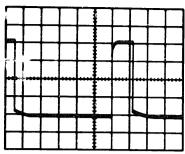


TEST POINT: 1A2J1-2

VOLTS/DIV: 2 TIME/DIV: .2 MSEC SYNC: EXT

C. FT VIDEO

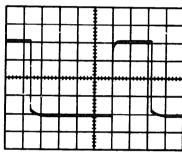
NOTE: ALL WAVEFORMS TAKEN WITHOUT PROBE.



TEST POINT: 2J1-45

VOLTS/DIV: 2 TIME/DIV: .2 MSEC SYNC: EXT

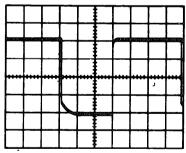
D YOKE CLAMP (25 km)



TEST POINT: 2J1-45

VOLTS/DIV: 2 TIME/DIV: .2 MSEC SYNC: EXT

E. YOKE CLAMP (50 km)



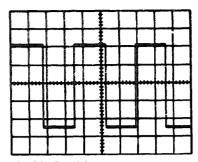
TEST POINT: 2J1-45

VOLTS/DIV: 2 TIME/DIV: .2 MSEC SYNC: EXT

F. YOKE CLAMP (100 km)

EL3AG058

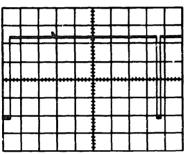
Figure 3-2. Test Set Group, Indicator, Radar OQ-63A/APS-94D, waveforms (sheet 1 of of 5)



TEST POINT: 2J4-24

VOLTS/DIV: 2 TIME/DIV: 50 MSEC SYNC: INT (+)

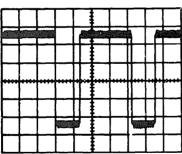
G. ANTENNA GATE



TEST POINT: 1A2J11-32

VOLTS/DIV: 2 TIME/DIV: 10 MSEC SYNC: INT (-)

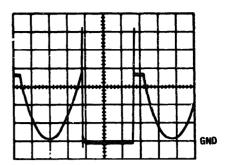
H. FT. ENABLE



TEST POINT: 1A2J11-33

VOLTS/DIV. 2 TIME/DIV: 20 MSEC SYNC: INT(+)

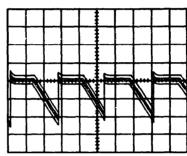
J. MT ENABLE



TEST POINT: 1A2J11-23

VOLTS/DIV: 2 TIME/DIV: 2 MSEC SYNC- EXT

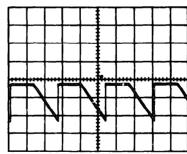
K. ASTIGMATISM



TEST POINT: 1A2J14-10

VOLTS/DIV: .5 TIME/DIV: .5 MSEC SYNC: EXT

L. VERTICAL SWEEP (15 deg)



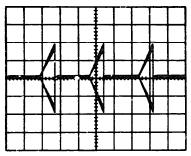
TEST POINT- VERTICAL SWEEP TEST JACK

VOLTS/DIV: .2 TIME/DIV: .5 MSEC SYNC: EXT

M. VERTICAL SWEEP (1.8 dag)

EL3AG033

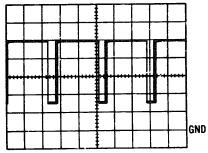
Figure 3-2. Test Set Group Indicator, Radar OQ-63A/APS-94D, waveforms (sheet 2 of 5).



TEST POINT 1A2J14-8

VOLTS/DIV 1 TIME/DIV .5 MSEC SYNC. EXT

N HORIZONTAL SWEEP (50 km)

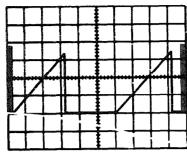


TEST POINT 1A2J1-5

/OLTS/DIV 20 TIME/DIV .5 MSEC SYNC EXT P UNBLANK

EL3AG034 3

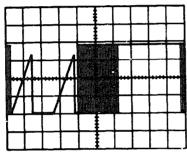
Figure 3-2. Test Set Group, Indicator, Radar OQ-63A/APS-94D, waveforms (sheet 3 of 5)



TEST POINT 1A1J7-1

VOLTS/DIV 10 TIME/DIV 2MS SYNC EXT

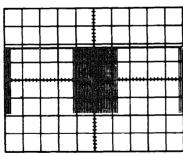
R ADAS RAMPS BCD MODE



TEST POINT 1A1J7-1

VOLTS/DIV 10 TIME/DIV 5 MS SYNC EXT

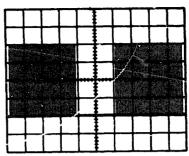
S ADAS RAMP ALT MODE



TEST POINT 1A1J7-1

VOLTS/DIV 10 TIME/DIV 5 MS SYNC EXT

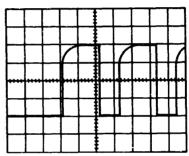
T ADAS RAMPS NUM MODE



TEST POINT 1A1J7-12

VOLTS/DIV 20 TIME/DIV 5MS SYNC EXT

U UNBLANKING



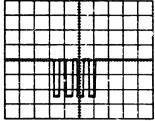
TEST POINT 1A1J7-12

VOLTS/DIV 20 TIME/DIV 10 µS SYNC EXT

V UNBLANKING

EL3AG031

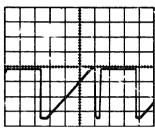
Figure 3-2. Test Set Group, Indicator, Radar OQ-63A/APS-94D, waveforms (sheet 4 of 5)



TEST POINT 1A1J10

VOLTS/DIV 1 TIME/DIV 200 # SEC SYNC EXT

W ECCM VIDEO



TEST POINT 1A1J11

VOLTS/DIV 1 TIME/DIV 200 #SEC SYNC EXT

X ECCM DEFLECTION

EL3AG050

Figure

Radar OQ-63A/APS-94D, waveforms (sheet 5 of 5)

3-22. Film Speed Troubleshooting

a. Bench Test. Perform the film speed bench test as described in table 3-14 below.

Table 3-14 Film Speed Teat

Step	Control Settings			Performance
No.	Test Equipment	Equipment Under lest	Test Procedure	Standard
1	Oscilloscope: VOLTS/DIV: 5 TIME/DIV: 1 Sec	a. Unit 1A2. FILM SPEED CONTROL: Fully clockwise b. Unit 1A2: FILM SPEED CONTROL: Fully counterclockwise	a. Connect oscilloscope to test point \$\times 14-85\$ and measure signal voltage b. Connect oscilloscope to test point \$214-85\$ and measure signal voltage.	a. +25.5 ±1 5 vdc b +5 0 ±1 0 vdc

Table 3-14. Film Speed Test - Continued

Step No.	Control Settings			Performance
	Test Equipment	Equipment Under Test	Test Procedure	Standard
2	Digital voltmeter: RANGE: AUTO FUNCTION: VAC	Unit 1A1: FILM SPEED: OFF	Connect digital voltmeter to test points 1A1J4-16 (+) and 1A1J4-17 (-) and adjust the input variable transformer for 115 vac reading on digital voltmeter.	115 ±0.02 vac
3		Unit 1A1: FILM SPEED: CAL	Connect ligital voltmeter to test points 1A1J3-5 (+) and 1A1J3-6 (-) and measure signal voltage.	2.700 ±0.010 vac
4		Unit 1A1: FILM SPEED: LOW	Connect digital voltmeter to test points 1A1J3-5 (+) and 1A1J3-6 (-) and measure signal voltage.	0.81 to 0.84 vac
5		Unit 1A1 FILM SPEED: HIGH	Same as 4 above.	13.0 to 13.4 vac

b. Troubleshooting Procedure. The following procedure is used in troubleshooting the film speed voltages. Film speed voltage circuits are shown in

figure FO-14 and will be an aid to maintenance personnel when troubleshooting.

Table 3-15. Film Speed Troubleshooting

ltem No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	With the oscilloscope connected to 2J4-85 dc level does not vary from +4 vdc to +27 vdc when the FILM SPEED CONTROL on unit 1A2 is varied from full ccw to full cw position.	a. Defective BITE circuit 1A2A4. b. Defective FILM SPEED control 1A2R18.	a. Replace BITE circuit 1A2A4 (fig. 3-7). If still defective proceed to b below. b. Replace FILM SPEED control 1A2R18 (fig. 3-7).
2	With the digital voltmeter connected to test point 1A1J3-5 with return referenced to test point 1A1J3-6, ac level does not go from zero to 13.4 volts when FILM SPEED switch is operated from OFF to CAL.	a. Defective transformer 1A1T1. b Defective resistor network on 1A1A2. c Defective FILM SPEED switch 1A1S3.	a. Check for presence of 196 vac between test points 1A1J1-1 and 1A1J1-2. If present check transformer 1A1T1 output. If not present, refer to the primary power distribution troubleshooting procedure (para 3-16) b Substitute +28 vdc power supply 1A1A2 (fig. 3-4). If still defective, proceed to c below. c Replace FILM SPEED switch 1A1S3.

3-23. Intensity Control Voltage Troubleshooting

a. Bench Test. Perform the intensity control voltage bench test as described in table 3-16 below.

Table 3-16. Intensity Control Voltage Test

Step No.	.Control Settings			D
	Test Equipment	Equipment Under Test	Test Procedure	Performance Standard
1	Oscilloscope: VOLTS/DIV: 5 TIME/DIV: 1 Sec	Unit 2: DISPLAY: FT INTENSITY: Minimum	a. Connect oscilloscope to test point 1A2J1-2 and observe voltage level as the INTENSITY control on unit 2 is increased to maximum. b. Operate the DISPLAY switch on unit 2 to MT position and observe voltage level displayed on oscilloscope.	 a. Voltage level rises from -28 to 6 vdc as control is increased. b Voltage level drops rapidly to -27 ±1 vdc.
2	None	Unit 2: DISPLAY: MT INTENSITY: Minimum	a. Connect oscilloscope to test point 1A2J11-30 and observe voltage level as the INTENSITY control on unit 2 is increased to maximum. b. Operate the DISPLAY switch on unit 2 to MT position and ob- serve voltage level displayed on oscilloscope.	a. Same as la above b. Same as lb above.

b. Troubleshooting Procedure. The following procedure is used to troubleshoot the intensity control voltage circuits. The intensity control voltage cir-

cuits are shown in FO-6 and will be used as an aid for maintenance personnel when troubleshooting.

Table 3-17. Intensity Control Voltage Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	The dc voltage measured at test point 1A2J1-2 does not change from -28 to 0 vdc when the IN-TENSITY control on unit 2 is varied from minimum to maximum and the DISPLAY control on unit 2 is in the FT position	Defective video smplifier 1A2A6	Replace video amplifier 1A2A6 (fig 3-5).
2	With the DISPLAY control on unit 2 in the MT position, the voltage at test point 1A2J1-2 is not between -26 vdc and -28 vdc.	Same as 1 above.	Same as 1 above.
3	The dc voltage measured at test point 1A2J11-30 does not change from -28 to 0 vdc when the IN-TENSITY control on unit 2 is varied from minimum to maximum and the DISPLAY CONTROL on unit 2 is in the FT position.	Defective yoke simulator 2A1.	Replace yoke sımulator 2A1 (fig 3-12)
4	With the DISPLAY control on unit 2 in the MT position, the voltage at test point 1A2J11-30 is not between -26 vdc and -28 vdc.	Same as 3 above	Same as 3 above

3-24. Vertical Sweep Waveform Troubleshooting

a. Bench Test. Perform the vertical sweep waveform test as described in table 3-18 below.

Table 3-18. Vertical Sweep Waveform Test

Step	Control Settings		!	Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
1	None	Unit 1A2: VERTICAL OFFSET OVERRIDE: ON	a. Connect oscilloscope to test point 1A2J14-10 and observe wave- form displayed, while adjusting VERTICAL AMPLIFIER SWEEP LENGTH and CENTER controls on unit 2.	a. Waveform L, figure 3-2.
		Unit 2: RANGE: 100 ANTENNA: LEFT DISPLAY: FT DRIFT ANGLE: 15 VERTICAL AMPLI- FIER OPERATE TEST: OPERATE	b. Operate DISPLAY switch on unit 2 to MT position and observe voltage level on oscilloscope.	$b.~~0~\pm0.3$ vdc (noise may be present).
2	None	Unit 2: DISPLAY: FT DRIFT ANGLE: 1.8	Connect oscilloscope to vertical sweep test jack (VERTICAL AMPLI- FIER section) on unit 2 and ob- serve waveform while adjusting VERTICAL AMPLIFIER SWEEP LENGTH control on unit 2.	Waveform M, figure 3—2.
3		Unit 2: DISPLAY: MT DRIFT ANGLE: 15	a. Connect oscilloscope to test point 1A2J11-10 and observe wave- form displayed while adjusting the VERTICAL AMPLIFIER SWEEP LENGTH control on unit 2. b Operate DISPLAY switch on unit 2 to FT position and observe the voltage level displayed on the oscilloscope connected to test point 1A2J11-10	a. Waveform L, figure 32. $b = 0 \pm 0.3$ vdc (noise may be present).

b. Troubleshooting Procedure. The following troubleshooting procedure is referenced to the test set group waveforms L and M of figure 3-2. The signals represented by these waveforms originate in either

video amplifier 1A2A6 or vertical amplifier 2A3. Use of the troubleshooting procedure will localize a vertical sweep trouble to one of these two modules.

Table 3-19. Vertical Sweep Waveform Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform L (fig. 3-2), measured at test points is abnormal with test set controls set as instructed in step 1 or 3 of paragraph 3-24a.	Defective video amplifier 1A2A6.	Replace video amplifier 1A2A6 (fi _k ; 3-5).

Table 3-19. Vertical Sweep Waveform Troubleshooting - Continued

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
2	Signal measured at test points is not 0 ±0.3 vdc with test set controls set as instructed in step 1 or 3 of paragraph 3-24a except, that DISPLAY control is changed from FT to MT.	Same as 1 above.	Same as 1 above.
3	Waveform M (fig. 3-2), measured at the vertical sweep test jack (above) left of OPERATE/TEST switch) on panel 2 is abnormal with the test set group controls on unit 2 set to the following positions: DISPLAY: FT DRIFT ANGLE: 1.8 RANGE: 100 OPERATE/TEST: OPERATE VERTICAL AMPLIFIER CENTER: adjust as required. VERTICAL AMPLIFIER SWEEP LENGTH: adjust as required.	Defective sweep generator 2A4.	Replace sweep generator 2A4 (fig. 3—10).
4	Unit 1A1: VERTICAL OFFSET OVER- RIDE: ON Signal measured at test point 1A2J11-10 is not 0 ±0.3 vdc with the test set group controls set as in 3 above except that the DRIFT ANGEL control is changed from 1.8 to 15. NOTE Signal may be noisy.	Defective vertical amplifier 2A3.	Replace vertical amplifier 2A3 (fig. 3—12).
5	Waveform measured at test point 1A2J11-10 cannot be adjusted to the configuration of waveform L (fig. 3-2) by the VERTICAL AMPLIFIER SWEEP LENGTH and VERTICAL AMPLIFIER CENTER controls with the test set group controls positioned as in 3 above except that the DISPLAY control is changed from FT to MT position.	Same as 2 above.	Same as 2 above.

3-25. Horizontal Sweep Waveform Troubleshooting

a. Bench Test. Perform the horizontal sweep waveform bench test as described in table 3-20 below.

Table 3-20. Horizontal Sweep Waveform Test

Step No.	Control Settings			Performance
	Test Equipment	Equipment Under Test	Test Procedure	Standard
1	None	Unit 2: RANGE: 50 ANTENNA: BOTH DISPLAY: PT HORIZONTAL AM- PLIFIER OPERATE— TEST: OPERATE	Connect the oscilloscope to test point 1A2J14-8 and observe waveform. Adjust the HORIZONTAL AMPLIFIER SWEEP LENGTH and CENTER controls and OFFSET GAIN control on unit 2.	Waveform N, figure 3–2.
2	None	Unit 2: DISPLAY: MT	Connect oscilloscope to test point 1A2J11-4 and observe waveform while adjusting HORI-ZONTAL SWEEP LENGTH control on unit 2.	Waveform N, figure 3–2.

b. Troubleshooting procedure. The following troubleshooting procedure is referenced to test set group waveform N of figure 3-2.

Table 3-21. Horizontal Sweep Waveform Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform N, figure 3-2, measured at test point 1A2J14-8, is abnormal with test set group controls set as instructed in step 1 of paragraph 3-25c.	Defective horizontal amplifier 2A2.	Replace horizontal amplifier 2A2 (fig. 3-11).
2	Waveform N, figure 3-2, measured at test point 1A2J11-4, is abnor- mal with test set group controls set as in 1 above except DISPLAY control set to MT.	Same as 1 above.	Same as 1 above.
8	Similar to Waveform N, figure 3-2, but lesser in amplitude measured at horizontal sweep test jack (between CENTER and SWEEP LENGTH controls) on panel 2 is abnormal with the test set controls set as instructed in 1 of paragraph 3-25a.	a. Defective sweep generator 2A4. b Defective resistors 2TB3R16, potentiometer 2R3, switch 2S2 or capacitor 2TB3C1.	 a. Replace sweep generator 2A4 (figure 3-10). b. Check and replace defective part (fig. 3-12 or 3-13).

3-26. Unblank Circuit Troubleshooting

a. Bench Test. Perform the unblank circuits bench test as described in table 3-22 below.

Table 3-22. Unblank Circuit Test

_	Control Settings			
Step No.	Test Equipment	Equipment Under Test	Test Procedure	Performance Standard
1	None	Unit 1A2: UNBLANK ON Unit 2: RANGE: 25 ANTENNA: LEFT display; ft	Connect oscilloscope to test point 1A2J1-5 and observe waveform.	Waveform P, figure 3-2.
2	None	None	Operate the UNBLANK switch on unit 1A2 to OFF and observe the voltage level displayed on the oscilloscope.	+100 ±10 vdc

b. Troubleshooting Procedure. The following troubleshooting procedure is referenced to waveform P of figure 3-2.

Table 3-23. Unblank Circuit Troubleshooting

Item No.	Trouble Symptom	Probable Trouble Checks and Corrective Actions	
1	Waveform P of figure 3-2, measured at test point 1A2J1-5, is abnormal with the test set group controls set as follows: Unit 1A2: UNBLANK: ON Unit 2: RANGE: 25 ANTENNA: LEFT diaplay; FT	Defective video amplifier 1A2A6.	Replace video amplifier 1A2A6 (fig. 3-5).
2	The voltage measured at test point 1A2J1-5 is not 100 ±10 vdc with the two: set group controls positioned as in above except that the UNBLANK switch is positioned to OFF	Same as 1 above.	Same as 1 above.

3-27. Offset Circuit Troubleshooting

a. Bench Test. Perform the offset circuit bench test as described in table 3-24 below.

Table 3-24. Offset Circuit Test

	Cont	rol Settings		
Step No.	Test Equipment	Equipment Under Test	Standard	Performance
1	None	Unit 2: ANTENNA. BOTH RANGE. 100 DRIFT ANGLE: 15 DISPLAY: FT	Connect the oscilloscope to test point 1A2J1-8 and observe waveform.	Waveform N, figure 3-2

Table 3-24. Offset Circuit Test -Continued

Step	Con	trol Settings		Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
2	None	Unit 2: ANTENNA: RIGHT	a. Vary the LEFT HORIZONTAL OFFSET control on unit 2 and observe the waveform displayed on oscilloscope connected to to test point 1A2J1-8.	a. Waveform is not affected as control is varied.
			b. Vary the RIGHT HORIZONTAL OFFSET control on unit 2 and observe that the ramp portion of the waveform offsets positive as control is increased.	b. Waveform offsets positive as control is increased.
3	None	Unit 2: ANTENNA: LEFT	 a. Vary the RIGHT HORIZONTAL OFFSET control on unit 2 and observe the waveform displayed on oscilloscope connected to test point 1A2J1-8. b. Vary the LEFT HORIZONTAL OFFSET control on unit 2 and observe that the ramp portion of the waveform offsets negative as control is increased. 	a. Waveform is not affected as control is varied. Waveform offsets negative as control is increased
4	None	Unit 1A2: VERTICAL OFFSET OVERRIDE: ON Unit 2: ANTENNA: LEFT RANGE: 100 VERTICAL AMPLI- FIER OPERATE TEST: GFERATE	a. Connect oscilloscope to test point 1A2J1-10 and observe wave- form. b. Vary the VERTICAL OFFSET control on unit 2 and observe waveform.	a. Waveform L, figure 3-2. b Waveform is not affected as control is varied.
5	None	Unit 1A2: VERTICAL OFFSET OVERRIDE: OFF	Vary the VERTICAL OFFSET control clockwise on unit 2 and observe the waveform displayed on oscilloscope connected to test point 1A2J1-10.	Waveform moves in the negative direction as control is increased.

 $\it b.\ Troubleshooting$ Procedure. The following troubleshooting procedure is referenced to test set group waveforms N and L of figure 3-2.

Table 3-25. Offset Circuit Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform N of figure 3-2, measured at test point 1A2J1-8, is abnormal with the test set group controls on unit 2 positioned as follows: ANTENNA: BOTH RANGE: 100 DRIFT ANGLE: 15 DISPLAY: FT OFFSET GAIN: Adjust as required.	a. Defective yoke simulator 2A1. b Defective offset control 2A7. c Defective resistors 2TB3R6, R38, R36, or potentiometer 2R11.	a. Replace yoke simulator 2A1 (fig. 3-12). b. Replace offset control 2A7 (fig. 3-12). c Check and replace defective part (fig. 3-12) and 3-13).

Table 3-25. Offset Circuit Troubleshooting - Continued

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
2	a. The sweep ramp of waveform N does offset as the LEFT HORIZONTAL OFFSET control is varied with the ANTENNA switch in the RIGHT position.	a. Defective switch 289.	a. Replace switch 289 (fig. 3-11).
	b. The sweep ramp of waveform N does not offset positive as the RIGHT HORIZONTAL OFFSET control on unit 2 is increased with the ANTENNA switch in the RIGHT position.	b. One or more of the following defective: (1) Offset control 2A7. (2) Resistors 2TB3R14, R13; potentiometer 2R12; switch 2S9; or transistor 2Q2 (right offset). (3) Resistors 2TB3R15, R35, R37, R10, R12, R8; potentiometer 2R5, 2R9; or transistor 2Q1 (left offset).	 b. Replace one or more of the following: (1) Offset control 2A7 (fig. 3-12). (2) Check and replace defective part (fig. 3-11, 3-12, or 3-13). (3) Check and replace defective part (fig. 3-12 or 3-13).
3	a. The sweep ramp of waveform N does offset as the RIGHT HORI-ZONTAL OFFSET control is varied with the ANTENNA switch in the LEFT position.	a. Defective switch 289.	a. Replace switch 289 (fig. 3-11).
	b. The sweep ramp of waveform N does not offset negative as the LEFT HORIZONTAL OFFSET control on unit 2 is increased with the ANTENNA switch in the LEFT position.	b. One or more of the following defective: (1) Yoke simulator 2A1. (2) Offset control 2A7. (3) Offset amplifier 2A6.	 b. Replace one or more of the following: (1) Yoke simulator 2A1 (fig. 3-12). If still abnormal, proceed to (2) below). (2) Offset control 2A7 (fig. 3-12). If still abnormal, proceed to (3) below. (3) Offset amplifier 2A6 (fig. 3-12).
4	Waveform L, measured at test point 1A2J1-10 is not movable in the negative (up) direction by the VERTICAL OFFSET control with the VERTICAL OFFSET OVERBIDE control in the OFF position.	 a. Defective offset amplifier 2A6. b. Defective offset control 2A7 (fig. 3-12). c. Defective resistors 2TB3R11, R7, or potentiometer 2R10. 	 a. Replace offset amplifier 2A6 (fig. 3-12). If still abnormal, proceed to b below. b. Replace offset control 2A7 (fig. 3-12). c. Check and replace defective part (fig. 3-12 or 3-13).

3-28. Video Compression Troubleshooting

a Bench Test. Perform the video compression bench test as described in table 3-26 below.

Table 3-26. Video Compression Test

Step	Control Settings			Performance	
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard	
1	None	Unit 1A2: FT GAIN: Maximum TEST VIDEO: OFF VIDEO AMPLITUDE: Maximum	 a. Connect oscilloscope to test point 1A2J1-2 and observe waveform. 	a. Waveform C, figure 3-2.	
		Unit 2: RANGE: 25 ANTENNA: RIGHT DISPLAY: FT INTENSITY: Maximum	b. Adjust VIDEO AMPLITUDE control on unit 1A2 for a peak voltage indication on the oscilloscope of 10 volts.	b. Peak voltage of waveform is 10 volts.	
2	None	Unit 2: ANTENNA: LEFT RANGE: 25	Observe peak voltage indicated on oscilloscope.	+10 ±0.5 volts peak	

Table 3-26. Video Compression Test - Continued

Step No.	Cont	rol Settings		Perfc. nance
	Test Equipment	Equipment Under Test	Test Procedure	Standard
3	None	Unit 2: ANTENNA: BOTH RANGE: 100	Observe peak voltage level indicated on oscilloscope.	+4.2 ±0.4 volts peak
4	None	Unit 2: ANTENNA: RIGHT RANGE: 50	Observe peak voltage level indicated on oscilloscope.	+7.1 ±0.7 volts peak
5	None	Unit 2: ANTENNA: LEFT RANGE: 50	Observe peak voltage level indicated on oscilloscope.	+7.1 ±0.7 volts peak
6	None	Unit 2: ANTENNA: BOTH RANGE: 25	Observe peak voltage level indicated on oscilloscope.	+7.1 ±0.7 volts peak
7	None	Unit 2: ANTENNA: RIGHT RANGE: 100	Observe peak voltage level indicated on oscilloscope.	+4.2 ±0.4 volts peak
8	None	Unit 2: ANTENNA: LEFT RANGE: 100	Observe peak voltage level indicated on oscilloscope.	+4.2 ±0.4 volts peak
9	None	Unit 2: ANTENNA: BOTH RANGE: 50	Observe peak voltage level indicated on oscilloscope.	+4.2 ±0.4 volts peak

b. Troubleshooting Procedure. The following procedure is referenced to waveform C of figure 3-2.

Table 3-27. Video Compression Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform C of figure 3-2, measured at test point 1A2J1-2, is abnormal or cannot be set to a minimum of 10 volts peak by adjustment of the VIDEO AMPLITUDE control.	Defective video amplifier 1A2A6.	Replace video amplifier 1A2A6 (fig. 3-5)
2	Waveform C of figure 3-2 is not 10 ±0.5 volts peak with the AN-TENNA switch in the LEFT position and the RANGE switch set to 25.	Same as 1 above.	Same as 1 above.
3	Waveform C of figure 3-2 is not +4.2 ±0.4 volts peak with the test set group controls in the following position: ANTENNA: BOTH RANGE. 100	Same as 1 above	Same as 1 above.

Table 3-27. Video Compression Troubleshooting - Continued

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
4	Waveform C of figure 3-2 is not +7.1 ±0.7 volts peak with the test set group controls in the following positions: ANTENNA: RIGHT, LEFT or BOTH RANGE: 50 or 25	Same as 1 above.	Same as 1 above
5	Waveform C of figure 3-2 is not +4.2 ±0.4 volts peak with the test set group controls in any of the following positions: ANTENNA: RIGHT, LEFT or BOTH RANGE: 100 or 50	Same as 1 above	Same as 1 above

^{3-29.} BITE, Sweep, Indicator and Servo Fault Circuits Troubleshooting.

Table 3-28. BITE. Sweep, Indicator and Servo Fault Circuits Test

Step	Cont	rol Settings		Performance	
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard	
1	Digital voltmeter: RANGE: AUTO FUNCTION: VDC	None	a. Measure voltage level between test points 2J4-62 (+) and 2J4-23 (-). b Measure voltage level between test point 2J4-63 (+) and 2J4-23 (-). c Measure voltage level between test points 2J4-60 (+) and 2J4-23 (-) d. Measure voltage level between test points 2J4-29 (+) and chassis ground. e. Measure voltage level between test points 2J4-67 (+) and chassis ground. f. Measure voltage level between test points 2J4-25 (+) and chassis ground. g Measure voltage level between test point 2J4-69 (+) and chassis ground.	a +28 ±2 0 vdc b +28 ±2 0 vdc c +28 ±2 0 vdc d +19 5 ±0.5 vdc e +19.5 ±0 5 vdc f +19 5 ±0 5 vdc g. +19 5 ±0.5 vdc	
			h Measure voltage level between test points 2J4—70 (+) and chas- sis ground.	h +195±05 vdc	
2	None	Unit 2: NAVIGATION: AUTO GS/DFT DRIVE: OFF Unit 1A2: NAV SIM: Same reading as GS/DFT indicated on Unit 2.	 a. Observe SERVO FAULT indicator lamp on unit 2 b Operate NAV SIM control on Unit 1A2 to ±5 percent of GS/DFT reading 	a. SERVO FAULT lamp is 'FF b SERVO FAULT is. p flashes when NAV SIM control is moved greater than ±5 percent of the GS/DFT reading	

a. Bench Test. Perform the BITE, sweep, indicator and servo fault circuit test as described in table 3-28 below.

Table 3-28. BITE, Sweep, Indicator and Servo Fault Circuits Test - Continued

Step	Control Settings			Performance
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard
3		Unit 2: ANTENNA: BOTH	Observe SWEEP FAULT indicator lamp on unit 2.	Indicator lamp is off.
4	None	None	a. Disconnect one end of cable W21 connected between jacks 1A2J8 and 1A2J9 and observe SWEEP FAULT indicator lamp on unit 2 b. Connect cable end of W21 that was removed.	a. Indicator lamp flashes. b None.
5	None	Unit 2: DRIFT ANGLE 15 DISPLAY FT ANTENNA. LEFT Unit 1A2: UNBLANK: ON FT GAIN: Maximum VIDEO AMPL!TUDE Maximum	a Operate the BITE switch on unit 1A2 to ON and observe FAILURE indicator lamp on unit 1A2. b Operate the ANTENNA switch on unit 2 to RIGHT and observe FAILURE indicator lamp on unit 2. c Operate the FT GAIN and VIDEO AMPLITUDE controls on unit 1A2, one at a time, to their minimum positions and observe the FAILURE indicator lamp on unit 1A2.	a FAILURE indicator lamp is off. b Same as a above. c FAILURE indicator lamp lights as each control is set to minimum position

b. Troubleshooting Procedure. The following procedure is to be used when the SWEEP, INDICATOR or SERVO FAULT lamps fail to light

when failures are known to exist in the sweep, indicator, or servo circuits, or when failures are intentionally simulated.

Table 3-29. BITE, Sweep, Indicator and Servo Fault Circuits Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	No +28 vdc (nominal) at any of the following test points: 2J4-62 2J4-63 2J4-60	Defective wiring or improper cable connections	Check wiring. Refer to wiring lists (para 3-51, 3-52, and 3-53) or figure FO-4
2	No +28 vdc (nominal) at test point 2J4-62; other test points in 1 above normal and no FAULT indication	Defective diode 1A2TB3CR2	Replace diode 1A2TB3CR2 (fig 3-9)
3	No +28 vdc (nominal) at test point 2J4-63; other test points in 1 above normal and no FAULT indication	Defective diode 1A2TB3CR3	Replace diode 1A2TB3CR3 (fig 3-9)
4	No +28 vdc (nominal) at test point 2J4-60; other test points in 1 above normal and no FAULT indication.	Defective diode 1A2TB3CR4	Replace diode 1A2TB3CR4 (fig 3-9)

Table BITE, Sweep, Indicator and Servo Fault Circuits Troubleshooting - Continued

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
5	No +20 vdc (nominal) at any of the following test points: 2J4-67 2J425 2J4-70 2J4-69 2J4-29	a. Defective wiring or improper cable connections. b. Defective low voltage power supply and regulator 1A2A3.	a. Refer to wiring lists paras 3-51, 3-52, and 3-53 or figure FO-4 b. Replace low voltage power supply and regulator 1A2A3 (fig. 3-7).
æ	No +20 vdc (nominal) at test point 2J4-67; other test points in 5 above normal and no FAULT indication.	Defective diode 1A2TB3CR5.	Replace diode 1A2TB3CR5 (fig 3—9)
7	No +20 vdc (nominal) at test point 2J4-25 and 2J4-29; other test points in 5 above normal and no FAULT indication	Defective diode 1A2TB3CR6.	Replace diode 1A2TB3CR6 (fig 3-9)
8	No +20 vdc (nominal) at test point 2J4-70; other test points in 5 above normal and no FAULT indication	Defective diode 1A2TB3CR7	Replace diode 1A2TB3CR7 (fig 3-9).
9	No +20 vdc (nominal) at test point 2J4-69; other test points in 5 above normal and no FAULT indication.	Defective diode 1AZTB3CR8.	Replace diode 1A2TB3CR8 (fig. 3-9)
10	SERVO FAULT indicator is not illuminated when the following actions are taken. Unit 2. NAVIGATION switch. AUTO GS/DFT DRIVE switch. OFF Unit 1A2: NAV SIM control manually set to ±5 divisions greater than GS/DFT indicator.	a. Defective wiring or improper cable connections b Defective offset control 2A7 c Defective FAULT circuit 2A1	a Refer to wiring lists paras 3-51, 3-52, and 3-53 or figure FO-4 b Replace offset control 2A7 (fig 3-12) c Replace FAULT circuit 2A1 (fig 3-12)
11	SWEEP FAULT indicator is not illuminated when the following actions are taken: a. Remove W21 between 1A2J8 and 1A2J9. b Place the ANTENNA switch to BOTH c. Place the DISPLAY switch to FT.	a. Defective wiring or improper cable connections b Defective offset control 2A7 c Defective FAULT circuit 2A1	 a. Refer to wiring lists (paras 3-51, 3-52, and 3-53) or figure FO-4. b. Replace offset control 2A7 (fig. 3-12) c. Replace FAULT circuit 2A1 (fig. 3-12)
12	FAILURE indicator lamp is on.	a. Defective or abnormal horizontal sweep circuit. b Defective or abnormal vertical sweep circuit c Defective or abnormal unblank circuit d Defective or abnormal video circuit e Defective BITE circuit 1A2A4	 a. Refer to paragraph 3-25 b Refer to paragraph 3-24 c Refer to paragraph 3-26 d Refer to paragraph 3-28. e Replace BITE circuit 1A2A4 (fig 3-7)

3-30. ADAS Simulator Troubleshooting

a. Bench Test. Perform the ADAS simulator bench test as described in table 3-30 below.

Table 3-30. ADAS Simulator Test

Step	Control Settings			Performance
No.			Standard	
1	Pulse generator Pulse width: 1ms 15v Pulse frequency 33 pps (≈30ms) Oscilloscope TIME/DIV: 2 ms Sync scope on pulse generator	Unit 1A1 ADAS MODE BCD	Connect pulse generator to 1A1J9-1. Connect oscilloscope to test point 1A1J7-1 and observe waveform.	Waveform R, figure 3–2.
2	Oscilloscope TIME/DIV: 5ms	Unit 1A1 ADAS MODE ALT	Same as step 1 above	Waveform S, figure 3-2.
3	•	Unit 1A1 ADAS MODE NUM	Same as step 1 above	Waveform T, figure 3-2.
4	Oscilloscope VOLTS/DIV: 20V		Connect oscilloscope to test point 1A1J7-12 and observe waveform	Waveform U, figure 3–2
5	Oscilloscope TIME/DIV·10us		Same as step 4 above	Waveform V, figure 3-2.

b. Troubleshooting Procedure. The following troubleshooting procedure is referenced to the test set group waveforms R, S, T, U, and V of figure 3-2. The

signals represented by these waveforms originate in ADAS simulator 1A1A1.

Table 3-31. ADAS Simulator Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform R of figure 3-2 measured at test point 1A1J7-1 is abnormal with ADAS MODE switch 1A1S1 set at BCD.	a. Defective ADAS simulator 1A1A1. b Defective ADAS MODE switch 1A1S1	 a. Replace ADAS simulator 1A1A1 (fig. 3-4) If still defective, proceed to b below. b. Check and replace defective switch.
2	Waveform S of figure 3-2, measured at test point 1A1J7-1 is abnormal with ADAS MODE switch 1A1S1 set at ALT.	Same as 1 above.	Same as 1 above.
3	Waveform T of figure 3-2, measured at test point 1A1J7-1 is abnormal with ADAS MODE switch 1A1S1 set at NUM.	Same as 1 above.	Same as 1 above.
4	Waveform U of figure 3-2, measured at test point A1J7-12 is abnormal.	Defective ADAS simulator 1A1A1.	Replace ADAS simulator 1A1A1 (fig. 3-4).
5	Waveform V of figure 3-2, measured at test point 1A1J7-12 is abnormal.	Same as 4 above	Same as 4 above.

3-31. Monitor Adapter Input Simulator Troubleshooting

a. Bench Test. Perform the monitor adapter input simulator test as described in table 3-32 below

Table 3-32 . Monitor Adapter Input Simulator Test

Stan	Control Settings					
Step No.	Test Equipment	Equipment Under Test	Test Pro	cedure		Performance Standard
1	Oscilloscope VOLTS/DIV· 2V TIME/DIV· 200 us. Sync scope on connector J11 negative NOTE Connect 100-ohm termination (HP10100) to oscilloscope probe.	Unit 1A1.	Connect oscilloscope observe waveform.	to 1A1J10	and	Waveform W, figure 3-2.
3	Same as step 1 above.	Unit 1A1	Connect oscilloscope observe waveform	to 1AiJ11	and	Waveform X, figure 3 -2

b. Troubleshooting Procedure. The following troubleshooting procedure is referenced to the test set group waveforms W and X cf figure 3-2. The signals

represented by these waveforms originate in the monitor adapter input simulator 1A1A7.

Table 3-33. Monitor Adapter Input Simulator Troubleshooting

Item No.	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
1	Waveform W of figure 3-2, measured at connector J10 is abnormal	Defective monitor adapter input simulator 1A1A7.	Replace monitor adapter input simulator 1A1A7
2	Waveform X of figure 3-2, measured at connector J11 is abnormal	Same as 1 above	Same as 1 above

3-32. Dynamic Focus Troubleshooting

a. Bench Test. Perform the dynamic focus bench test as described in table 3-34 below.

Table 3-34. Dynamic Focus Test

a .	Control Settings			
Step No	Test Equipment	Equipment Under Test	Test Procedure	Performance Standard
1	Oscilloscope (dc coupled). VOLTS/DIV 2 TIME/DIV· 0 2 MSEC SYNC: EXT	Unit 2: ANTENNA LEFT RANGE. 50 DRIFT ANGLE 15 degrees	Connect oscilloscope to test point 1A2J11-23 and observe wave- form while adjusting LEFT HOR- IZONTAL OFFSET, VERTICAL OFFSET, and GAIN OFFSET, on Unit 2	Waveform K, figure 3-2

b. Proubleshooting Procedure. The following troubleshooting procedure is used in troubleshooting the dynamic focus circuit.

Table 3-35. Dynamic Focus Troubleshooting

Yearn No.	Trouble Symptom	Probable Trouble	Checks and Corrective Action
l.	Waveform K (fig. 3-1) measured at test point 1A2I11-21 is adnormal.	a. Defective wiring or improper cable connections.	a. Check wiring. Refer to wiring lists (gars 3–51, 5–52, and 3–53) or Eguer FG-4.
3		5. Defective away generator 2A4.	b. Regisco overp generator ZA4 (fig. 2—19)

3-33. High Voltage Load Troubleshooting

a. Bench Test. Perform the high voltage load bench test as described in Luble 3-36 below

WARNING

Dangerous voltages exist in the high voltage load circuits. Use extreme care when performing the following beach test.

Table 3-36. High Voltage Load Test

State	Cont	of Senne		Parlamadaa	
No.	Test Equipment	Equipment Under Test	Test Procedure	Standard	
B.	Signal Generator 3G-1105/C (pulse generator): Output amplitude: 1 voit. Pulse width: 300 microseconds. Prequency 750 pps	Unit 1A1 (high voitage loads).	a. Remove 18 screws from the front panel of Unit 1A1 b. Remove panel 1A1 from the calmet. c Place the +28 VDC power supply high voltage loads 1A1A2 on an extender. d. Connect pulse generator and one channel of esculloscope to pin XA2-3 (signal) and E16 (ground) of +28 VDC power supply (fig. 3-4). Connect other oscilloscope channel to ANODE VOLTAGE 1V/10 KV terminal E3 on Unit 1A1.	a None. b. None. c. None. d. Pulue generator diagnaped on beth oscillosenge chamain.	
2	Same as 1 above	Same as 1 above.	Compare the amplitudes of the two oscilloscope channels.	Both channels should be the sume amplitude.	
3	Same as 1 above	Same as t above.	Check for ground de offset of os- cilloscope channel connected to ANODE VOLTAGE 1 V/10 KV terminal E3.	Ground affect should be been them ±0.5 vde	
4	Pulse generator Output ampli- tude 3 volts. Pulse width 305 microsseconds Frequency: 750 pps.	Same as t above	Connect pulse generator and one channel of oscillozoga to pin XA2-C (signal) and £16 (ground) of +28 VDC PS high voltage leads 1A1A2 (fig. 3-4).	Pulse generator waveform displayed on both oscilluscope channels	
85	Same as 4 above	Same as I above	Connect the other oscilloscope channel to FOCUS VOFTAGE 2.75 V/2.75 KV terminal 24 on Unit 1A1 Compare the amplitudes of the two channels of the oscilloscope.	Both channels should be the same amplitude	

Start .	Construi Sections				
X	Tes Leopassi	Equipment Under Ten	Test Procedure	Performance Standart	
6	Sume as 4 above	Same as 1 allows	Check for ground de officet of the qualifatorpe channel connected to POCUS VOLTAGE 2.75 V/2.75 EV terminal E4	Offices channels for loss than with budge	
7	Same as 4 above:	Same as I alanve	a Remove card IAIA2 from the ex- tender and replace back in panel IAI b Replace panel IAI back in cab- ities c Replace 18 acrews on the front panel of IAI	6 None c None	

b. Troubleshooting Procedure The following procedure is used in troubleshooting the high voltage load curvaits.

Table 3-37. High Voltage Load Troubleshooting

Man Ma	Trouble Symptom	Probable Trouble	Checks and Corrective Actions
\$	Wateform abnormal or missing at ANDE VOLTAGE 1V/10EV terminal E2 test point	Defective +28 wdc power supply and high voltage load 1A1A2	Replace +28 vdc power supply and high voltage load 1A1A2
7	Waveform abnormal or missing at POCUS VOLTAGE 2.75V/2.75KV terminal E4 test point	Defective +28 vdc power supply and harh voltage load 1A1A2	Replace +28 vdc power supply and high volt- age load 1A1A2
2	a Roussance from IAIA6-E4 to ground IAIA6-E5 with IAIA2 removed in not 2008.	a. Defective anode load 1A1A6.	c. Replace anode load 1A1A6
	h Besistance from 1A1A6-E1 to 1A1A6-E5 not I magchm	b Defective anode load 1A1A6	b Replace anode load 1A1A6
4	a. Resistance from IAIAS-E4 to ground IAIAS-E5 with IAIA2 removed is not INEK ohm.	a Defective focus load IAIA5	a. Replace focus load 1A1A5 (fig. 3-4).
	8 Resistance from IAIA5-El to IAIA5-E5 aut 1 megohm.	b Defective focus load IAIA5.	6 Replace focus foad 1A1A5 (fig. 8-4).

Section III. DIRECT SUPPORT MAINTENANCE OF TEST SET GROUP

3-34. General

- a. Direct support maintenance of the test set group includes the following:
 - (1) Removal and replacement procedures.
 - (2) Cable Repair.
 - (3) Cleaning.
 - (4) Painting.
 - (c) Calibration.

- (6) Physical tests and inspection.
- (7) Electrical tests.
- b. The above maintenance procedures supplement those maintenance procedures performed at the lower categories of maintenance. Refer to TM 11-3325-12 when servicing the equipment.

performing operational checks, or preparing the equipment for shipment or limited storage.

3-35. Removal and Replacement Techniques

Most parts of the test set group can be reached and replaced without special procedures. The general directions given in a through d below apply.

a. Disassemble the equipment only to the extent needed to clean, adjust, repair or replace a part.

- b. When performing maintenance, inspect the equipment for frayed or broken wiring, burns, arcing, missing or damaged piece parts, or other obvious signs of damage.
- c. When replacing parts, note the position of the part and its leads. Replace parts in essentially the same position to avoid undesired coupling or shorting of wires.
- d. Check the entire equipment for evidence of fungus, rust, and corrosion.
- 3-36. Removal and Replacement Procedures

WARNING

Remove all power from the equipment when performing removal and replacement procedures.

Removal and replacement of components at the direct support maintenance category are obvious upon inspection of the parts location illustrations and require no special instructions.

- a. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1.
- (1) Remove the 18 screws securing unit 1A1 front panel to the case.
 - (2) Carefully lift the panel from the case.
- (3) Refer to figures 3-3 and 3-4 for location of parts.

CAUTION

When removing plug-in modules from the chassis, pull straight out. Do not twist or otherwise put stress on these boards.

- b. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2.
- (1) Remove the 18 screws securing unit 1A2 front panel to the case.
 - (2) Carefully lift the panel from the case.
- (3) Refer to figure 3-5 through 3-9 for location of parts.
- c. Test Set Subassembly MX-8639A/APS-94D, Unit 2.
- (1) Remove the 18 screws securing unit 2 front panel to the case.
 - (2) Carefully lift the panel from the case.
- (3) Refer to figure 3-10 through 3-13 for location of parts.

3-37. Cable Repair

NOTE

The wires within each cable are connected to associated pins as follows: pin A to pin A, pin B to pin B, etc. In certain cables, the wires are connected to associated pins as follows: pin A to 1, pin B to 2, etc.

- a. Using ohmeter, check continuity of the cable from pin-to-pin.
- b. Replace any wire indicating an open condition (no continuity).
- c. Replace wire with wire of identical type, size, and gauge.
- d. Cables which cannot be repaired by any of the above methods, refer to higher category of maintenance.

3-38. Cleaning

WARNING

The fumes of TRICHLOROETHANE are toxic. Provide thorough ventilation whenever it is used; avoid prolonged or repeated breathing of vapor. Do not use near an open flame or hot surface, trichloroethane is nonflammable but heat converts the fumes to a highly toxic phosgene gas the inhalation of which could result in serious injury or death. Prolonged or repeated skin contact with trichloroethane can cause skin inflammation. When necessary, use gloves, sleeves, and aprons which the solvent cannot penetrate.

- a. Clean dirt and grime from switch contacts, cable connectors, and corroded terminal connections using clean cloth dampened (not wet) with trichloroethane.
- b. Remove dirt and dust from interior and exterior surfaces of the equipment. Use clean cloth dampened with mild soap or detergent if necessary.

3-39. Painting

- a. Minor damage to finishes on the equipment, such as small scratches, require touchup painting the affected areas only. Major surface damage requires complete repainting. Major surface damage to the equipment would normally be forwarded to higher category of maintenance.
- b. Inspect the equipment to determine the extent of painting required. Refer to TB 43-0118, Field Instructions for Painting and Preserving Electronics Command Equipment, for information on painting.

3-40. Calibration

Paragraphs 3-41 through 3-43 contain the adjustment procedures necessary to calibrate the test

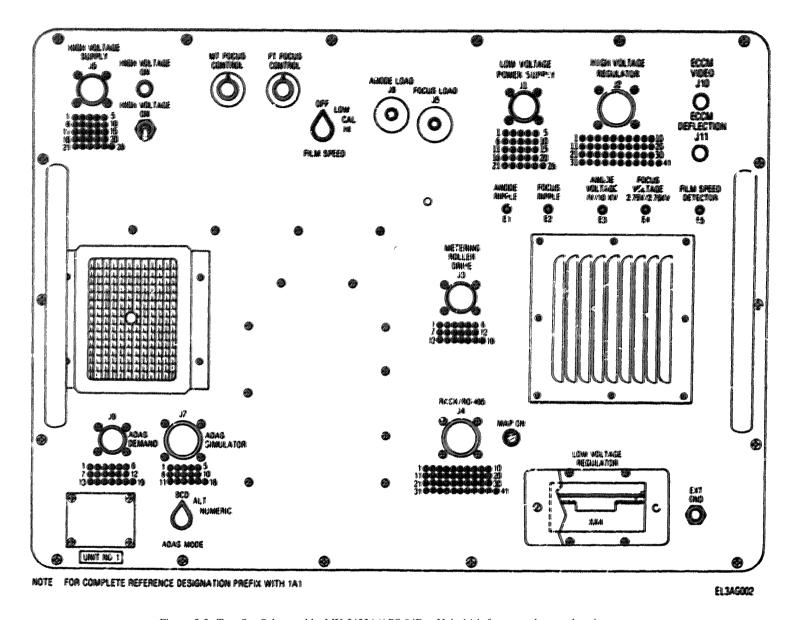


Figure 3-3. Test Set Subassembly MX-3433A/APS-94D, Unit 1A1 front panel, parts location.

3 - 4 0

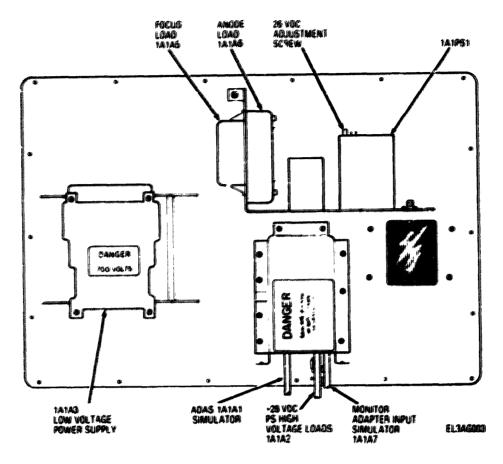


Figure 3-4. Test Set Subassembly MX-8638A/APS-94D, 1A1, rear chassis view, parts location.

set group. The only calibration required at the direct support maintenance level are the servo control synchro coarse and fine calibration, and GS/DFT dial calibration.

- 3-41. ServoControl-Synchro Coarse Calibration
- a. Test Equipment Required. The multimeter is the only test equipment required for the calibration procedure.
 - b. Preliminary Procedures.
- (1) Remove the 18 machine screws that secure canel of unit 1A2 in case.
 - (2) Carefully lift panel from case.
- (3) Position all subassemolies on a clean workbench with a convenient access to both front and rear panel of unit 1A2.
- (4) Deenergize 115 vac, 400 Hz and +28 vdc bench power circuits.
- (5) Open (trip) AC, DC, LOW VOLTAGE, and HIGH VOLTAGE RESET circuit breakers on unit
 - (6) Set POWER switch on unit 2 to OFF.
 - c. Test Setup and Conditions.

- (1) Connect the equipment as illustrated in figure FO-4.
- (2) Set all switches and controls to the off, down, or fully counterclockwise position.
- d. Initial Test Equipment Calibration. Set the multimeter FUNCTION switch to AC VOLTS and connect the probes on the multimeter to measure 10 vac.
 - e. Calibration Procedure.
- (1) Disconnect cable W4 from NAV SIM/RACK connector 1A2J18.
- (2) Perform the equipment connections as illustrated in A, figure 3-1.
- (3) Energize the 115 vac, 400 Hz and +28 vdc bench power circuits.
- (4) Close all circuit breakers, except HIGH VOLTAGE RESET breaker on unit 1A2 and set the POWER switch on unit 2 to ON position.
- (5) Turn the SERVO LOOP switch on unit 2 to DFT and set the ILLUM switch on unit 1A2 to ON.
- (6) Disassemble the locking mechanism of the NAV SIM dial on the panel of unit 1A2.
 - (7) Turn the NAV SIM dial in either direction

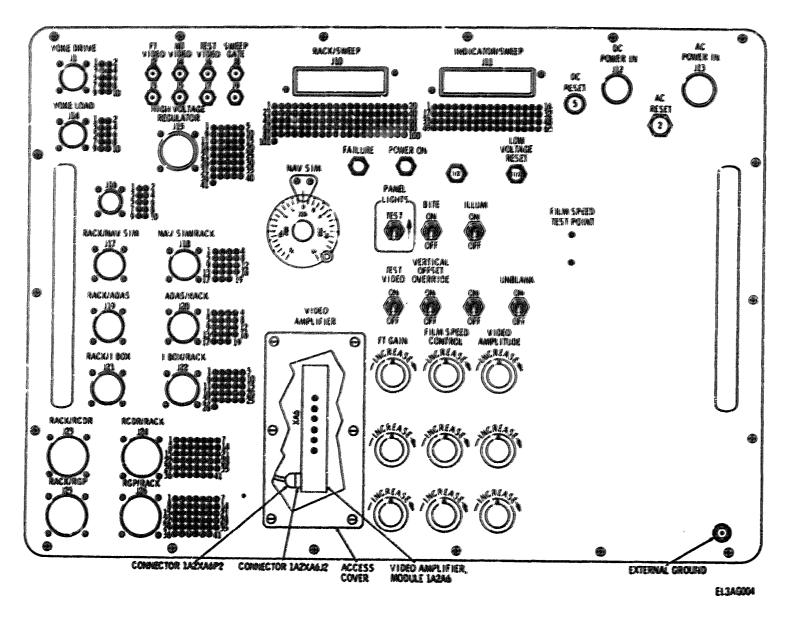


Figure 3-5. Test Set Subassembly MX-8633A/APS-94D, Unit 1A2, front panel parts location.

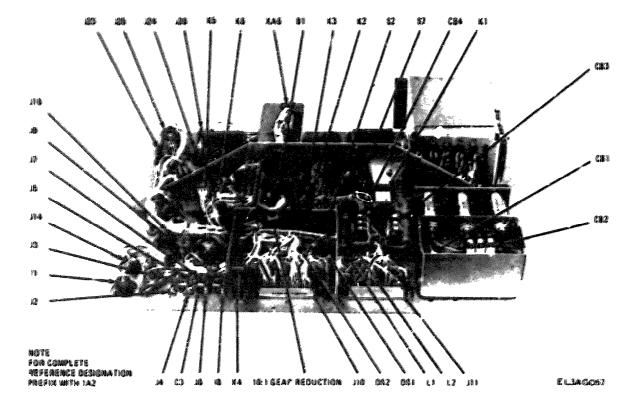


Figure 3-6. Test Set Subassembly Mx-8638A/APS-94D, Unit 1A2, rear chassis top view, parts location.

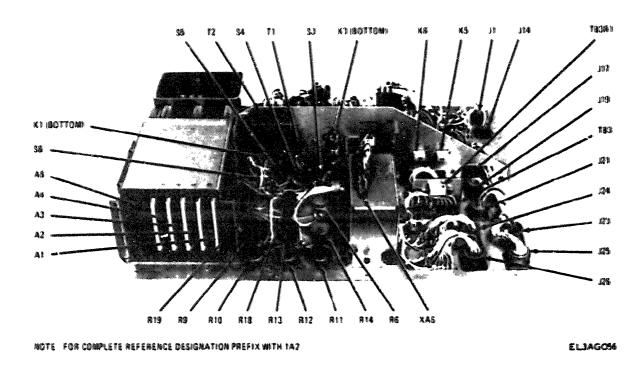


Figure 3-7. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 rear chassis bottom view, parts location

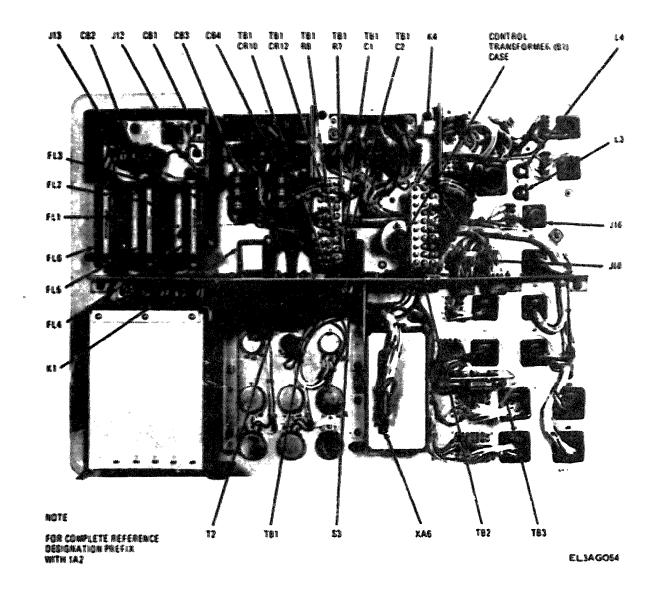
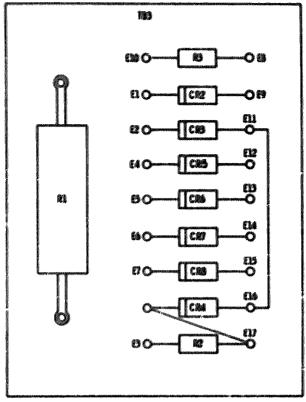


Figure 3-8. Test Set Subassembly MX8638A/APS-94D, Unit 1A2, rear chassis parts location



- MOTES
- PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. FOR COMPLETE BESIGNATIONS PREFIX WITH 1A2.
- 2. UNLESS OTHERWISE SPECIFIED ALL RESISTORS ARE IN CHARS.

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Figure 3-9. Terminal board 1A2TB3, parts location.

(ten revolutions maximum) to obtain maximum deflection of the multimeter.

- (8) Reassemble the locking mechanism of the NAV SIM dial.
- (9) Turn the NAV SIM dial to 0 and lock the dial at this setting with the dial lock.
- (10) Loosen the three clamp screws that secure the case of synchro motor 1A2B1 (fig. 3-8).
- (11) Observe the multimeter and slowly turn the case of motor 1A2B1 to produce a maximum deflection on the mulitmeter.
- (12) Tighten the three clamp screws that secure the case of motor 1A2B1.
- (13) Reconnect cable W4 to NAV SIM/RACK connector 1A2J18.
- 3-42. Servocontrol Synchro Fine Calibration
- a. Test Equipment Required. The multimeter is the only test equipment required for the calibration

procedure.

- b. Primary Procedures. Perform instructions given in paragraph 3-41b.
- c. Test Setup and Conditions. Same as described in paragraph 3-41c.
- d. Initial Test Equipment Cohbration. Same as described in paragraph 3-41d.
 - e. Calibration Procedure.
- Disconnect cable W4 from NAV SIM/RACK connector 1A2J18.
- (2) Perform the equipment connections as illustrated in B, figure 3-1.
- (3) Perform instructions (3) through (5) in paragraph 3-41e.
- (4) Turn the NAV SIM dial on unit 1A2 to 0 and lock the dial at this setting with the dial lock.
- (5) Loosen the three clamp screws (fig. 3-8) that secure the case of synchro motor 1A2B1.
 - (6) Observe the raultimeter and slowly turn the

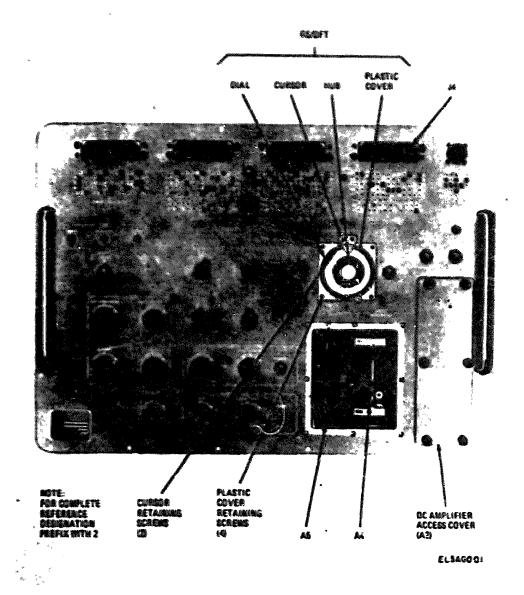


Figure 3-10. Test Set Subassembly MX-8632A/APS-94D, Unit 2, front panel, parts location.

case of synchro motor 1A2B1 to produce minimum deflection on the mulitmeter.

- (7) Tighton the three clamp screws that secure the case of the synchro motor 1A2B1.
- (8) Unlock the NAV SIM dial and carefully rock the dial to identify the precise position of the multimeter null.
- (9) Lock the dial at the position determined in (8) above.
- (10) Loosen the screws that secure the indication reference for the dial and move the indication reference so that the dial indicates 0; then tighten the screws.
- (11) Reconnect cable W4 to NAV SIM/RACK connector 1A2J18.

3-43. GS/DFT Dial Calibration

- a. Test Equipment Required. None required.
- b. Preliminary Procedures. Perform instructions given in (3) through (6) of paragraph 3-41b.
- c. Test Setup and Conditions. Same as described in paragraph 3-41c.
 - d. Calibration Procedures.

CAUTION

Do not attempt to turn the GS/DFT dial manually while the dial is secured to the dial shaft. Equipment damage may result.

(1) Perform instructions (3) and (4) of paragraph 3-41e.

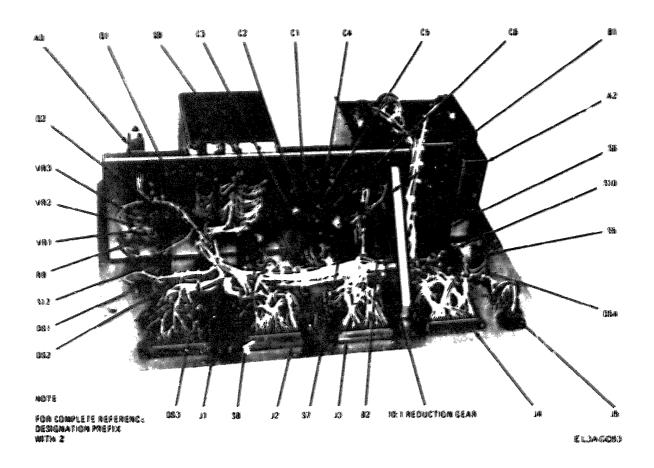


Figure 3-11. Test Set Subassembly MX-8639A/APD-94D, Unit 2 rear chassis new, parts location

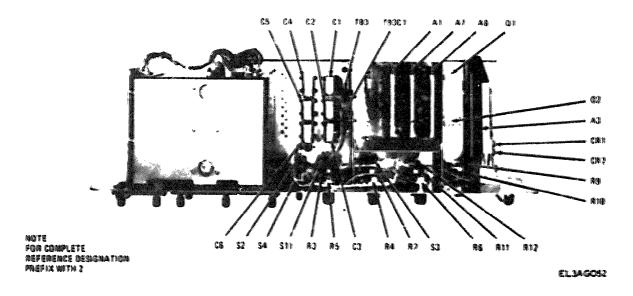


Figure 3-12. Test Set Subassembly MX-8639A/APS-94D, Unit 2, bottom chassis new, parts location

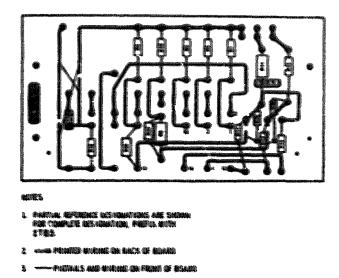


Figure 3-13. Terminal board parts locations

- PART OF MARKE ON BACK OF BOARD

- (2) Wait 5 tainutes for the equipment to warm up and stabilize.
- (3) Make the following control adjustments on unit 2:
 - (a) Turn the SERVO LOOP switch to DFT.
 - (b) Set the GS/DFT DRIVE switch to ON.
 - (c) Set the NAVIGATION switch to AUTO.
- (4) Remove the indication reference for the GS/DFT dial and the dial plastic cover.
 - (5) Install the indication reference for the dial.

(6) Loosen the setscrews in the dial hub and slide the dial off the dial shaft.

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- (7) Asign 0 on the dial and the indexing line on the indicatioz reference for the dial; then slide the dial back onto the dial shaft and tighten the setscrews in the dail hub.
 - (8) Remove the indication reference for the dial.
- (9) Install the dial plastic cover and indication reference for the dial, taking care to align the indication reference index line with the dial 0.

Section IV. DIRECT SUPPORT TESTING PROCEDURES

3-44. General

- a. Testing procedures are prepared for use by organizations responsible for direct support maintenance of electronic equipment to determine the acceptability of repaired electronic equipment. These procedures set forth specific requirements that repaired electronic equipment must meet before it is returned to the using organization. The testing procedures include performing a physical test and inspection on the equipment and an electrical test.
- b. The tests in this section are arranged to be performed in the sequence given. Comply with instructions preceding each test. Perform each step of each test procedure in sequence. For each step, perform all the actions required in the Control settings columns; then perform each specific test procedure and verify it against its performance standard.

3-45. Physical Tests and Inspections

- a. General. The following physical tests over each component of test set group and are divided into three groups covering the test set group as follows: Test Set Subassembly MX-8636A/APS-94D (indicator simulator unit 1A1) (lower); (indicator simulator unit 1A2) (upper); and Test Set Subassembly MX-8639A/APS-94D (generator simulator unit 2). The physical tests and inspection are to be performed on each component being tested before it is connected into its test setup. The procedure is intended to minimize the possibility of damage caused by the application of bench power.
 - b Test Equipment Required. None required.
- c. Test Connections and Conditions. Prepare the equipment for test as directed below.
 - (1) Equalize the inside-to-outside air pressure by

degreesing the red button at the center of breather saive on , seh test set group case.

- (2) Puil up on each of the eight cover latches and free lasches from cover.
- (3) Separate the case covers and arrange the summoment on a suitable of the bench that is capable of

accommodating the test set group.

3-46. Indicator Simulator, **Unit 1A1, Physical**Test and Inspections

Perform the indicator simulator, unit 1A1, physical test and inspection as described in table 3-38 below.

Table 3-38. Indicator Simulator. Unit 1A1, Indicator Physical Test and Inspection

than	Control Settings		Test Procedure	Performance	
Ño.	Yest Equipment	Equipment Under Test	rest r roteuare	Standard	
ž.	None	Controls may be in any position.	a. Inspect all control and nechanical assemblies for loose or micsing screws, bolts, and nuts. b. Inspect jacks J1 through J11 for damage	a. Screws, bolts, and nuts must be tight, none missing. b No looseness or damage evident.	
*	Monte.	Controls may be in any position	a. Remove 4 screws, lockwashers, and washers securing the filter housing to control panel. Inspect remoed parts b Remove the filter element and visually inspect it. After inspection, replace all parts removed	a No mechanical damage evident, rfi gasket not cracked, torn, or pinched b dirt or foreign objects visible	
3	Voste	Controls may be in any position	Remove low voltage regulator cover plate and inspect low voltage regulator subassembly 1A1A4 for secure positioning in mating connector Replace all parts removed.	Subassembly 1A1A4 is secure in connector	
\$	None	Centrols may be in any position	Remove lens cover from HIGH VOLTAGE ON indicator lamp In- spect the lamp for secureness in their connectors. Replace lens cover after inspection	Lamp secure in connector, lens cover intact.	

3-47. Indicator Simulator, Unit 1A2, Physical Test and Inspection

Perform the indicator simulator, unit 1A2, physical test and inspection as described in table 3-39 below.

Table 3-39. Indicator Simulator Unit 1A2, Physical Test and Inspection

Cont	rol Settings	Test Procedure	Performance Standard	
Test Equipment	Equipment Under Test	rest Procedure		
None	Controls may be in any position	a Inspect all controls, mechanical assemblies and panels for loose or missing screws, bolts, and nuts b Inspect jacks J1 through J26 for	a Screws, bolts, and nuts must be tight: none missing b No looseness or damage evident	
None	Controls may be in any position	evidence of damage Remove screws from VIDEO AM- PLIFIER access cover, remove cover and inspect assembly 1A2A6 for security in its mating con- pector Replace all parts removed	Assembly 1A2A6 is secure in its con- nector All removed parts now secured.	

Table 3-39. Indicator Simulator, Unit 1A2, Physical Test and Inspection-Continued

Step No.	Control Settings			Performance	
	Test Equipment	Equipment Under Test	Test Procedure	Standard	
3	None	Controls may be in any position	a. Turn the NAV SIM control from one extreme to the other and back. b. Actuate (in the direction of the arrow) and release the PANEL LIGHTS TEST switch. c Operate the following ON/OFF switches BITE, ILLUM, TEST VIDEO, VERTICAL OFFSET OVERRIDE, HIGH VOLTAGE and UNBLANK. d Operate the following controls throughout their full range of mechanical travel FT GAIN, FILM SPEED CONTROL, and VIDEO AMPLITUDE	a. Control operates freely in both directions throughout its range. b Switch operates freely and returns to its normal operating position c All switches operate freely d All controls operate freely throughout the full range of mechanical travel, no roughness or binding evident	

3-48. Generator Simulator, Unit 2, Physical Test and Inspection

Perform the generator simulator, unit 2, physical test and inspection as described in table 3-40 below.

Table 3-40. Generator Simulator, Unit 2, Physical Test and Inspection

Step No.	Control Settings		The A December 1	Performance	
	Test Equipment	Equipment Under Test	Test Procedure	Standard	
1	None	Controls may be in any position.	a. Inspect all controls and mechanical assemblies for loose or missing screws, bolts, and nuts. b Inspect jacks J1 through J5 for damage	a Screws, bolts, and nuts must be tight, none missing b Jacks show no evidence of looseness or damage	
2	None	Controls may be in any position	Remove screws securing the SERVO AMPLIFIER and SWEEP GEN- ERATOR access covers and in- spect the subassemblies for secure- ness in their mating connectors Replace covers after inspection.	Subassemblies secure in then mating connectors, covers intact	
3	None	Controls may be in any position.	Remove screws from HORIZONTAL AMPLIFIER access cover and remove cover. Inspect subassembly 2A2 for secureness in its mating connector Replace cover after inspection.	Subassembly 2A2 is secure in its mating connector	
4	None	Controls may be in any position.	a. Actuate (in the direction of the arrow) and release the PANEL LIGHTS TEST switch. b Operate the POWER ON/OFF switch to both positions. c Operate the NAVIGATION switch to all three positions.	 a. Switch operates freely and returns to its normal operating position. b Switch operates freely in both directions c Switch operates freely in all three positions. 	

Table 3-40. Generator Simulator, Unit 2, Physical Test and Inspection-Continued

Step	Control Settings Test Equipment Equipment Under Test			Performance
No.			Test Procedure	Standard
			d. Operate the following controls to all their panel-indicated positions: RANGE, ANTENNA, SERVO LOOP, DISPLAY, DRIFT ANGLE, GS/DFT DRIVE, and HORIZONTAL AMPLIFIER and VERTICAL AMPLIFIER controls. e Operate the following controls throughout their full range of mechanical travel. OFFSET and INTENSITY controls	d All controls operate freely to each of their panel-indicated positions e All controls operate freely throughout their range of mechanical travel, no roughness or binding evident

3-49. Electrical Tests

- a. Tools and Test Equipment Required.
 - (1) Multimeter AN/USM-223.
 - (2) Oscilloscope AN/US \mathbf{M} -281 \mathbf{C} .
- (3) Transformer, Variable Power, General Radio **Type M2G3.**
 - (4) Voltmeter, Digital AN/GSM-64B.
 - (5) Generator, Signal SG-1105/G.
 - (6) Tool Kit, Electronic Equipment TK-105/G.
 - ('7) Termination, 100-ohm HP 10100B.
 - b. Test Conditions and Connections.

- (1) Arrange the equipment on a workbench in the following left-to-right order. Indicator simulator (unit 1A2), generator simulator (unit 2), and indicator simulator (unit 1A1).
- (2) Connect interconnecting cables to the test set group as illustrated in figure FO-4.
- (3) Perform the preliminary procedures given in paragraph 3-15.
- c. *Procedure.* The electrical tests for the test set group are identical to the bench tests given in Section II, Troubleshooting. Perform all the bench tests in Section II in the sequence given.

Section V. WIRE LIST FOR TEST SET **GROUP**, INDICATOR, RADAR OQ-63A/APS-94D

3-50. General

This section contains the wire lists for the test set group. The wire lists cover the wiring for the three **units** of the test set group. Each list presents point-to-**point** (from and to) data in alphanumerical sequence and the wire number. The lists are *also* double-ended, that is, any one wire appears twice in the left hand column with the *From* and To locations (wire ends) occurring in alphanumerical sequence. Wired in sub-

assemblies are covered by individual illustrations which are referenced in the appropriate troubleshooting paragraphs.

3-51. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1 Wire List

The wire list for unit 1A1 is presented in table 3-41. The wire list will be an aid to the repairman when testing or troubleshooting unit 1A1.

Table 3-41. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire List

From	То	Wire No	From	То	Wire No.
A5-E1 A5-E4 A5-E5 A6-E1 A6-E4	E-2 XA2-C E-17 E-1 XA2-3	182 181 183 178 179	A6-E5 B1-A B1-B B1-C	E-17 E-6 E-7 E-8	180 · 215 216 217

Table 3-41 Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire Last- Continued

**************************************	T _	T	I _		
From	То	Wire No.	From	То	Wire No.
E-1	A6-E1	178	J1-TP1	E-6	13
E-2	A5-E1	182	J1-TP1	T1-1	228
E-3 E-4	XA2-D XA2-B	200	J1-TP1	J1-A	1
E-5	XA2-B XA2-P	199 194	J1-TP2 J1-TP2	E7	14
E-6	P1-A	215	J1-TP2	J1-B T1-2	2
E-6	XA1-A	16	J1-TP3	E-8	221 15
E-6	J1-TP1	13	J1-TP3	J1-C	3
E-7	XA1-B	17	J1-TP4	NC	1
E-7	B1-B	216	J1-TP5	NC	
E-7	J1-TP2	14'	J1-TP6	XA2-E	15A
E-8	XA1-C	18	J1-TP6	J1-H	5
E-8	B1-C	217	J1-TP7	NC	_
E-8	J1-TP3	15	J1-TP8	XA2-5	15B
E-9 E-9	J3-TP10 J3-TP8	83 81	J1-TP9 J1-TP10	NC	
E-9	J3-TP12	85	J1-TP10	XA1-K J1-K	21 6
E-10	J4-TP19	118	J1-1710 J1-TP11	J1-L	7
E-10	J4-TP41	123	J1-TP11	XA1-L	22
E-10	XDS2-2	220	J1-TP12	XA2-6	15C
E-11	J5-TP13	148	J1-TP12	J1-M	8
E-11	J5-TP14	149	J1-TP13	J1-N	9
E-11	J5 -TP25	154	J1-TP13	XAI-N	24
E-11	λDS1-2	218	J1-TP14	J1-P	10
E-12	J7-TP3	159	J1-TP14	XA1-P	25
E-12 E-12	J7-TP15 S1-3	161 222	J1-TP15 J1-TP16	J1-R NC	26
E-13	J9-TP11	176	J1-TP17	NC	
E-13	J9-TP12	177	J1-TP18	J1-U	12
E-14	R1-2	221	J1-TP18	XA1-U	27
E-15	XA6- A	186	J1-TP19	NC	
E-16	XA2-A	197	J1-7P20	NC	
E-16	XA2-22	198	J1-TP21	NC	
E-16	PS1-2	227	J1-TP22	NC	
E-17	A5-E5	183	J1-TP28	NC NC	
E-17 E-18	A6-E5 J2-TP3	180 49	J1 – TP24 J1 – TP25	NC NC	
E-18	J2-TP19	53	J1-TP26	NC NC	
J1-A	J1-TP1	i	J2-A	J2-TP1	28
J1-B	J1-TP2	2	J2- B	J2-TP2	29
J1-C	J1-TP3	3	J2-C	J2-TP3	30
J1-D	NC		J2-D	NC	
J1-E	NC TO		J2-E	NC	0.0
J1-F J1-G	J1-TP6 NC	4	J2-F J2-G	J2-TP6 NC	31
J1-d J1-ri	J1-TP8	5	J2-H	NC NC	
J1-J	NC	5	J2-J	NC	
J1-K	J1-TP10	6	J2-K	NC	
J1-L	J1-TP11	7	J2-L	J2-TP11	32
J1-M	J1-TPt2	8	J2-M	J2-TP12	33
J1-N	J1-TP13	9	J2-N	J2-TP13	34
J1-P	J1-TP14	10	J2-P	J2- T P14	35
J1-R	J1-TP15	11	J2-R	J2- TP15	36
J1-S J1-T	NC NC		J2-S J2-T	J2-TP16 J2-TP17	37 38
J1-U	J1-TP18	12	J2-U	J2-TP18	39
J1-V	NC NC		J2-V	J2-TP19	40
J1-W	NC NC		J2-W	J2-TP2 0	41
J1-X	NC		J2 – X	J2-TP21	42
J1-Y	NC		J2-Y	J2 – TP22	48
J1-Z	NC		J2-Z	J2~TP28	44
Ji-a	NC		J2-a	J2 - TP24	46
J1-b	NC NC		J2 - b	NC J2 - TP2 6	46
J1-c	NC		J2-c	32-1120	करा

Table 3-41. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire List-Continued

-			[II	I	<u> </u>
1	from	То	Wire No.	From	То	Wire No.
١.	J2-d	NC		J3-TP1	XA2-S	74
	J2-e	NC		J3-TP1	J3-A	55
	J2-f	NC	1	J3-TP2	XA2-Z	75
100	J2-g	NC		J3-TP2	J3-A	55
107	J2-h	NC		J3-TP3	J3-TP6	76
	J2 -i	NC]	J3-TP3	J3-C	57
	J2-j	NC		J3-TP4	T1-5	77 58
ě.	J2-k	NC NO		J3-TP4 J3-TP5	J3-D XA2-9	78
8	J2-1	NC NC		J3-1F5 J3-TP5	J3-E	59
	J2-m J2-n	NC NC		J3-175 J3-TP6	XA2-F	79
	J2-n J2-p	NC NC	<u> </u>	J3-TP6	J3-F	60
	J2-р J2- г	NC NC		J3-TP6	J3-TP3	76
ă.	J2-s	NC	1	J3-TP7	J3-G	61
8	J2-t	NC		J3-TP7	XA2-1	80
a .	J2-TP1	J2-A	28	J3-TP8	J3-H	62
	J2-TP1	XA6-U	47	J3-TP8	E9	81
8	J2-TP2	XA6-W	48	J3-TP9	XA2-S	82
	J2-TP2	J2-B	29	J3-TP9	J3-J	63
8	J2-TP2	J2-TP12	54	J3-TP10	J3-K	64
8	J2-TP3	J2-C	30	J3-TP10	E9	83
	J2-TP 3	E-18	49	J3-TP11	XA2-R	84
	J2-TP6	R1-1	50	J3-TP11	J3-L	65
	J2-TP6	J2-F	31	J3-TP12	E9	85 66
	J2-TP11	E-18	51	J3-TP12	J3-M J3-N	66 67
	J2-TP11 J2-TP12	J2-L J5-TP19	32 52	J3-TP13 J3-TP14	J3-N J3-P	68
	J2-1F12 J2-TP12	J2-M	33	J3-TP15	J3-R	69
	J2-TP12	J2-TP2	54	J3-TP16	NC NC	1 "
	J2-TP13	J2-N	34	J3-TP17	NC	•
	J2-TP14	J2-P	35	J3-TP18	NC	
Γ,	J2-TP15	J2-R	36	J3-TP19	NC	İ
! .	J2-TP16	J2-S	37	, J4-A	J4-TP1	86
	J2-TP17	J2-T	38	J4-B	J4-TP2	87
	J2-TP18	J2-U	39	J4-C	J4-TP3	88
	J2-TP18	J5-TP8	143	J4-D	J4-TP4	89
	J2-TP19	E-18	53	J4-F	J4-TP6	90 91
	J2-TP19 J2-TP19	J2-V J5TP9	40 144	J4-G J4-H	J4-TP7 NC	31
		J2-W	41	J4-11 J4-J	J4-TP9	92
	J2-TP21	J2-X	42	J4-K	J4-TP10	93
	J2-TP22	J2-Y	43	J4-L	J4-TP11	94
	J2-TP23	J2-Z	44	J4-M	J4-TP12	95
	J2TP24	J2-a	45	J4-N	J4-TP13	96
	J2-TP26	J2-c	46] J4-P	J4-TP14	97
	J3-A	J3-TP1	55	J4-R	J4-TP15	98
	J3-B	J3-TP2	56	J4-S	J4-TP16	99
	J3-C	J3-TP3	57	J4-T	J4-TP17	100
	J3-D J3-E	J3-TP4 J3-TP5	58 59	J4-U	J4-TP18	101 102
	J3-E J3-F	J3-TP6	60	J4 – V J4 – W	J4-TP19 J4-TP20	102
	J3-G	J3-TP7	61	J4-X	NC	100
	J3-H	JS-TP8	62	J4-Y	NC	
	J3-J	J3-TP9	63	J4-Z	NC	
	J3-K	J3-TP10	64	J4-a	J4-TP24	104
88	J3-L	J3-TP11	65	J4-b	J4-TP25	105
	J3-M	J3-TP12	66	J4-c	NC	
	J3-N	J3-TP13	67	J4-d	NC	
	[3−P	J3-TP14	68	J4-e	J4-TP28	106
	13-R	J3-TP15	69	J4-f	J4-TP29	107
	13-5 13-T	NC NC		J4-g	J4-TP30	108
	13-1 13-U	NC NC		J4-h	J4-TP31	109
	13-V	NC NC		J4-j J4-k	NC NC	
	·- ·	110	ı]	NO	l

Table 3-41. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire List - Continued

From	То	Wire No.	From	То	Wire No.
J4-1	NC		J5J	J5-TP9	128
J4-m	NC	ļ	J5K	J5-TP10	129
J4-n	NC		j5L	J5-TP11	130
J4-p	NC		J5M	J5-TP12	181
J4-r	J4-TP39	110	u jen	J5-TP13	182
J4-8	NC_	l	J5P	J5-TP14	133
J4-t	J4-TP41	111	J5R	NC	1
J4-TP1	J4-A	86	J 58	NC	
J4-TP2	J4-B	87	J5T	NC	ł
J4-TP3	J4-C	88	J 5U	J5-TP18	184
J4-TP4	J4-D	89	J5V	J5-TP19	135
J4-TP5	NC	1	J5W	NC	
J4-TP6	XA2-16	112	J5X	NC	1
J4-TP6	J4-F	90	J5Y	J5-TP22	136
J4-TP6	J4-TP16	116	J5Z	J5-TP23	157
J4-TP7	XA2-Z	113	J5a	J5-TP24	138
J4-TP7	J4-G	91	J5b	J5-TP25	139
J4-TP8	NC	Ì 00	J5c	NC	
J4-TP9	J4-J	92	J5-TP1	J5-A	19:
J4-TP10 J4-TP11	J4-K J4-L	93 94	J5-TP1	PSI-3	140
		95	J5-TP2	J5-B	125
J4-TP12 J4-TP13	J4-M XDS2-1	114	J5-TP2	J5-TP3	142
J4-1713 J4-TP13	J4-N	96	J5-TP2	PSI-4	141
J4-TP14	XA6-B	115	J5-TP3	J5-Tr2	142 126
J4-TP14	J4-P	97	J5-TP3	J5 C	127
J4-TP15	J4-R	98	J5-TP8 J5-TP9	75-H J5-J	128
J4-TP16	J4-TP6	116	J5-TP10	J5-K	129
J4-TP16	J4-5	99	J5-TP11	J5-L	130
J4-TP17	T1-5	117	J5-TP12	J5-M	131
J4-TP17	J4-T	100	J5-TP13	J5-N	132
J4-TP18	J4-U	101	J5-TP14	J5-P	133
J4-TP19	E10	118	J5-TP16	NC .	1
J4-TP19	J4-V	102	J5-TP17	NC	1
J4-TP20	J4-W	103	J5-TP18	J5-U	134
J4-TP21	NC]	J5-TP19	J5-V	135
J4-TP22	NC	1	J5-TP19	J2-TP12	53
J4-TP23	NC	1	J5-TP20	NC	1
J4-TP24	J4-a	104	J5-TP21	NC	I
J4-TP25	J4-b	105	J5 -TP22	J5-Y	136
J4TP26	NC	1	J5-TP23	J5-Z	.37
J4-TP27	NC	}	J5-TP24	J5-a	138
J4-TP28	J4-e	106	J5-TP25	J5-b	139
J4-TP29	J4-f	107	J5-TP26	NC	1
J4-TP30	J4-g	108	J7-A	J7-TP1	155
J4-TP31	J4-h	109	J7-B	NC	
J4-TP32	NC	1	J7-C	J7-TP3	157
J4-1P33	NC	1	J7-D	NC	
J4-TP34	NC	!	J7-E	NC	
J4-TP35	NC	I	J7-F	NC	
J4-TP36	NC NC	i	J7-G	NC	
J4-TP37	NC NC	!	J7-H	NC NC	1
J4-TP38	NC	110	.7−J	NC	
J4-TP39 J4-TP40	J4-r NC	1 110	J7-K	NC NC	
J4-1P40 J4-TP41	J¢-t	111	J7-L	J7-TP12	156
J5A	J5TP1	124	J7-M	NC NC	100
J5B	J5-TP2	125	J7 – N J7 – P	NC	1
J5C	J5 - TP8	126	J7-P J7-R	SHIELD	
J5D	NC	1 ***	37-K 37-5	NC	
J5E	NC	1	J7-TP1	J7-A	155
J5F	NC	i	J7-TP1	· XA6-P	158
J5G	n.C	!	J7-TP3	E12	159
J5H	J5-TP8	127	J7-TP3	J7-C	157
	1	1 -5.	64 9. Tro	,	·

Table 3-41. Test Set Subassembly MX8638A/APD-94D Unit 1A1, Wire List - Continued

in the second	То	Wire No.	From	To	Wire No.
J7-TP12	XA6V	160	NC	J2-G	
77-TP12	J7-M	156) NC	J2-H	
17-TP15	E-12	161	NC	J2-J	
17-TP15	SHIELD OF M	160A	NC	J2-K	
17-7P17	SHIELD OF M	155B	NC	J2-b	
P)A	J9-TP1	162	NC NC	J2-d	
19-B	J9-TP2	163	NC NC	J2-e	
19-C	NC	į.	NC NC	J2-f	
B− D	J9-TP4	164	NC	J2-g	
19—E	NC	ł	NC	J2-h	
19 - F	J9-TP6	165	NC	J2-i	
B−G	NC	}	NC	J2-j	
19-H	NC		NC	J2-k	
19-J	NC	1	NC	J2-1	
D-K	NC		NC	J2-m	
19-L	J9-TP11	166	NC NC	J2-n	
19-L	J9TP12	167	NC	J2-P	
D-N	J9-TP13	168	NC	J2-r	
19-P	J9-TP14	169	NC	J2-8	
J9-R	J9-TP15	170	NC	J2-t	
19-S	J9-TP16	171	NC NC	J8-S	
19-T	J9-TP17	172	NC	J3-T	
J9-U	J9-TP18	173	NC	J8-U	
J9-V	J9-TP19	174	NC	J3-V	
J9-TP1	J9-A	162	NC	J4-H	
19-TP1	XA6-B	175	NC	J4-X	
J9-TP2	J9-B	175	NC	J4-Y	
J9-TP:	NC		NC	J4-Z	
19-TP4	J9-D	164	NC	J4-c	
J9-TP5	NC TO		NC	J4-d	
J9-TP6	J9-F	165	NC	J4-j	
J9-TP7	NC	1	NC	J4-k	
J9-TP8	NC	1	NC	J4-1	
19-TP9	NC NC]	NC	J4-m	
19-TP10	NC D	1	NC	.14-n	
19-TP11	E-13	176	NC	J4-p	
99-TP11	J9-L	166	NC NC	J4-8	
79-TP12	J9-M	167	NC NC	J5-c	
J9-TP12 J9-TP13	E-13 J9-N	177 168	NC NC	J5-d	
9-1713 19-TP14	J9-P	169	NC NC	J5-E	
19-11-14 19-TP15	J9-R	170	NC NC	J5-F	
I9-TP16	J9-S	171	NC	J5-G	
19-TP17	J9-T	172	NC NC	J5R J5S	
9-TP18	J9-U	173	NC	I I	
9-TP19	J9-V	174	NC	J5-T J5-W	
.ii. .i.−1	XA2-Y	205	NC	J5-X	
1-2	XA2-20	210	NC	J5-TP4	
VC	J1-W	1 210	NC	J5-TP5	
NC .	J1-X	1	NC	J5-TP6	
ic	J1-Y		NC NC	J5-TP7	
iC	J1-Z		NC	J5-TP15	
iC	J1-a		NC	J5-TP16	
1C	J1-b		NC NC	J5-1716 J5-TP17	
ic	J1-c		NC	J5-TP19	
iC	J2-d		NC	J5-TP20	
iC	J1-D		NC	J5-TP21	
ič	J1-E		NC NC	J5-1721 J5-TP26	
iC	J1-G		NC NC	J5-1726 J7-B	
iČ	J1-J		NC NC	J7-B J7-D	
ic	J1-8		NC NC	J7−D J7−E	
iC	J1-T		NC NC	J7-E J7-F	
iC	J1-V		NC NC	J?-F J7-G	
ic	,				

Table 3-41. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire List-Continued

NC J7-J NC J7-K NC J7-L NC J7-N NC J7-P XA1-Z XA1-a XA1-b XA2-A XA2-A	NC NC NC
NC J7-L XA1-b XA2-A	
NG J7-N XA2-A	I NC I
	NC 107
	E-16 197
NC	XA2-1 195 E-16 197
NC J9-E XA2-B	E-4 199
NC J9-G XA2-C	A5-E4 181
NC J9-H XA2-D	E3 200
NC J9-J XA2-E	XA6-U 193
NC J9-K XA2-F	J3-TP6 79
PS1-1 S2-1 223 XA2-F	XA2-L 201
PS1-1 XDS1-2 219 XA2-G	NC See See See See See See See See See Se
PS1-2 E16 227 XA2-H PS1-3 J5-TP1 140 XA2-J	S3-3 202 T1-6 203
PS1-4 J5-TP2 141 XA2-K	NC 205
R2-1 J5-TP10 145 XA2-L	J4-TP29 120
R2-2 J5-TP11 146 XA2-L	XA2-M 206
R2-3 J5-TP12 147 XA2-M	T1-7 211
R3-1 J5-TP22 151 XA2-M	S3-1 212
R3-2 J5-TP23 152 XA2-M	XA2-L 206
R3-3 J5-TP24 1.3 XA2-N	NC
SHIELD OF A SHIELD OF M 155B XA2-P	E-5 194
SHIELD OF e & f J4-TP28 119 XA2-R	J3-TP11 84
SHIELD OF M	XA2-15 213 J3-TP9 82
S1-W XA6-D 189 XA2-S	J3-1F9 82 J3-TP1 74
S1-1 XA6-E 188 XA2-T	XA6-Y 191
S1-2 XA6-E 190 XA2-U	NC
S3-1 XA2-M 212 XA2-V	T1-9 204
S3-2 XA2-6 207	NC]
S3-3 XA2-H 202 XA2-X	NC
S3-4 XA2-7 208 XA2-Y	L1-1 205
T1-5	J3-TP2 75 J4-TP7 113
T1-6 XA2-J 203 XA2-Z	XA2-22 196
T1-7 S3-1 225 XA2-1	J3-TP7 80
T1-7 XA2-M 211 XA2-1	XA2-A 195
T1-8 XA2-18 209 XA2-2	NC
T1-9 XA2-V 204 XA2-3	A6-E4 179
XA1-A E6 16 XA2-4	NC
XA1-B E7 17 XA2-5	J1-TP8 15B
XA1-C E8 18 XA2-5 XA1-D NC XA2-5	J5-TP18 150 XA6-W 192
XA1-D NC XA2-5 XA1-E NC XA2-6	J1-TP12 15C
XA1-F XA6-U 19 XA2-6	S1-2 207
XA1-G NC XA2-7	S1-4 208
XA1-H XA6-W 20 XA2-8	NC
XA1-J NC XA2-9	J3-TP5 78
XA1-K J1-TP10 21 XA2-9	J4-TP30 121
XA1-L J1-TP11 22 XA2-10	S3-W 226
XA1-M XA6-X 23 XA2-11	NC J4-TP39 122
XA1-N J1-TP13 24 XA2-12 XA1-P J1-TP14 25 XA2-13	J4-TP39 122 NC
XA1-P	NC NC
XA1-8 NC XA2-15	XA2-16 214
XA1-T NC XA2-15	Xa2-S 213
XA1-U J1-TP18 27 XA2-15	S2-2 224
XA1-V NC XA2-16	X42-15 214
XA1-W NC XA2-16	J4-TP6 112
XA1-X NC XA2-17	NC T1-8 209
XA1-Y NC XA2-18	T1-8 209

Table 3-41. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, Wire List - Continued

Prom	To	Wire No.	From	То	Wire No.
XA2-19	NC		XA6-Y	XA2-T	191
XA2-20	L1-2	210	XA6-Z	NC	
XA2-21	NC NC		XA6-1	XA6-A	184
XA2-22	E-16	198	XA6-2	NC	
XA2-22	XA2-2	196	XA6-3	NC	1
RAG-A	E-15	196	XA6-4	NC	1
XAS-B	NC		XA6-5	NC	1
XA6-C	31-1	188	XA6-6	NC	
XA6-D	31-W	189	XA6-7	NC	I
XAF-E	81-2	190	XA6-8	NC	
XAS-P	NC	-	XAS-9	NC	1
XA6-G	NC		XA6-10	NC	
XA6-H	NC NC		XA6-11	NC	
Xas-J	NC		XA6-12	l NC	
TAS-K	NC		XA6-13	NC	
48-L	NC		XA6-14	NC	
XA5-M	NC		XA6-15	NC	
XAS-N	NC		XA6-16	NC	
XA6-P	NC		XA6-17	NC	1
KA6-R	NC		XA6-18	NC	
XA6-5	NC		XA6-19	NC	
XA6-T	NC		XA6-20	NC	
XA6-U	XA2-E	198	XA6-21	NC	
XAG-U	J2-TP1	47	XA6-22	XA6-2	185
Kag-V	NC	-	XD\$1-1	PS1-1	219
LAS-W	XA2-5	192	XDS1-2	E-11	218
XA6-X	J2-TP14	54	XD82-2	E-10	220

3-52. Test Set Subassembly MX-8638A/APD-94D, Unit 1A2 Wire List.

The wire list for unit 1A2 is presented in table 3-42. The wire list will be an aid to the repairman when testing or troubleshooting unit 1A2.

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List

From-	To-	Wire No.	From-	To-	Vise No.
B1-R1	K5-B2	709A	E5	J15-TP23	683A
B1-R2	K5-A2	700B	E6	J15-TP21	682B
B1-S1	K6-B2	718A	27	J15-TP20	682A
B1-52	K6-A2	718B	E7	R14-CW	934
B1-63	J18-TP3	277	E 10	XA6-D	726
B1 -6 3	J18-7718	718C	E 11	, XA6-U	726
CB1-A1	J12−B	496	B 15	R6-CCW	930
CB1-A2	FL2-1	527	E 16	R10-CW	932
CB2-A1	J13-A	652	E15	R18-3CW	233
CB2-A2	FL3-1	66?	E 15	R19-CCW	935
CB2-B1	J13-B	653	E 15	TB2-7	233
CB2-B2	FL4-1	668	E17	722 SHLD	829
CB2-C1	J13-C	654	E17	722 SHLD	830
CB2-C2	PL5-1	669	E17	722 SHLD	845
CB3-A1	CB4-A1	675	E17	729 SHLD	831
CB3-A2	J11—TP50	607	E17	730 SHLD	832
CB3-81	CB4-B1	856	E18	K4-X2	467
CB3-B2	J11—TP61	608	E18	682 SHLD	631
CB3-C1	CB4-C1	857	2 18	719 SHLD	828
CB3-C?	J11-TP52	609	E18	731 SHLD	827
CB4-A1	CBS-A1	675	E23	J11—TP61	278
CB4-A1	J11-TP57	610	E2 5	S2-2	276
CB4-A2	K2-A2	624	E25	TB1-8	572
CB4-B1	CB3-B1	856	E25	TB213	378
CB4-B1	J11-TP58	611	ž&	XA4-H	529
C34-32	K2-B2	625	FL1-:	J12-A	548
C34-C1	CB3-C1	857	FL1-2	J22-TP2	558
CB4-C1	J11-TP59	612	FL1-2	K1-X2	455
CB4-C2	K2-C2	626	FL2-1	CB1-A2	527
B 1	J15-TP24	683B	FL2-2	K1-D2	528
B2	J11-TP23	743	FL3-1	CB2-A2	687
E3	J15-TP26	683C	FL3-2	R22-1	235
E4	J15-TP22	682C	FL4-1	CB2-B2	668

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

F10402	**	Wee No.	Fram-	***	Wes Mo.
PLA-8	R21-1	2:16	J10-TP10	J10-14	16
9L5-1	CB2-C2	669	J10-TP10	J17-U	71.8C
PL3-2	B20-1	227	J19—TP11	J10-11	413
PLS-1	J13-E	671	J10—TP11	713 SHLD	757
PLS-3	XA5-10	672	J10-7712	J10-12	17
11-1191	J1-A	361	J10—TP12	J17-K	239
31-TP1	XASP1-A	460	J10-1713	J10-13	18
J1-193	11-8	1	J10-TP13	J25-7	315
J1-1793	T32-30	720	J10-TP14	J10-14	19
J1-173	11-C	382	J10-7914	J17-P	1038
11-120	XAGP1-C	493	J10-7718	J16-16	29 703A
ハーで94	J1-D	411	J10-7715	J17-B	B
J1-1794	XAAP1-D	687	J10-TP16	J10-16	414 753
J1-176	11-8	2	J10-TP16	703 SHLD	21
11-176	TB3-31	239	J10-7917	J10-17	7648
n-179	J1-F XA4P1-P	676	J10-TP17	J17-P J10-18	23
11-179	1	747	J10-TP18 J10-TP18	J17-N	764 A
A-177	Ji-G	141	J10-7710	J10-19	415
J1-179 J1-179	XASP1-H	677	J10-1719	704 SHLD	759
	J1-J	8	J10-TP20	J10-20	420
J1-1799	XASP1-J	673	J10-1720 J10-TP20	J21-V	408
J1-1770	J1-K	7	J10-TP21	J10-21	679
J1-4710	XASP1-K	l ero l	J10-TP21	J21-W	561
N-A	J1-771	381	J10-TP22	J10-22	431
J1-8	J1-TP2	1	J10-TP22	182-6	630
J1-C	J1-TP3	383	J10-TP23	J10-23	541
J1-D	J1-TP4	411	J10-TP23	TB2-3	631
J1-2	J1-TP5	2	J10-7724	J10-24	20
J1-7	J1-T76	3	J10-TP24	J25-G	319
J1-0	J1-797	747	J:0-TP25	J10-25	24
J1-H	J1-T78	5	J10-TP25	J35-B	317
カー・	J1-TP9		.*10-TP26	J10-28	416
J1-K	J1-TF10	7	J10-TP26	705 SHLD	760
J ₂	34	844	J10-TP27	J10-27	25
J 3	K4-83	728	J10-TP27	J25-Z	705 3
J4	J3	844	J10-TP28	J10-28	379
Ja	XA1-4	722	J10-TP28	J25Y	105A
J 5	K4-A3	729	J10-TP29	J10-29	350
33	XA4-3	724	J10-TP29	J25-C	316
<i>37</i>	K4-A1	730	J10-TP30	J10-30	417
13	XA1-R	719	J10-TP30	714 SHLD	761
30	TD1-9	731	J10-TP31	J10-31	23
J10-171	J10-1	8	J10-7731	J25-k	714C
J10-TP1	J17-H	637	J10-TP32	J10-32	27
J19-173 J19-172	J10-2 J17-J	9	J10-TP33	J25-A	714A
J10-173	J10-3	645 627	J10-TP33	J10-33	29
410-173	710-3 1782-1	603	J10-TP33	375 -X	714B
J10-TP4	Ji0-4	11	J10-TP34	J10-34	29
J10-TP4	J17-A	712A	J10-TP34 J10-TP35	J25-q	334
319-TYS	J20-5	12	J10-7735 J10-7735	J10-35 J25-s	30
J10-TP5	J17-B	7128	J10-1735 J10-7736	J10-36	338 31
J10-TF6	J10-6	13	310-1736 310-7736	J25-h	331
J10-T76	J17-C	712C	J10-TF37	J10-37	331
J10-TP7	J10-7	412	J10-7737	J25-i	332
J10-TP7	712 SHLD	756	J10-TP38	J10-38	33
J10~TP8	J10-8	14	J10-TP38	J25j	333
J10-778	J17-8	713A	J10-TP39	J10-39	34
J10-TP9	J10-9	15	J10-1739 J10-TP39	J25-a	324
J10-TP9	J17-T	7138		[TOV 0	i and

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

		Wire No.	Freedra.	7.	West No.
J10-7940	J25-b	325	J10-TP72	J10-72	6.0
J10-TP41	J10-41	36	J10-TP72	125-H	320
J10-TP41	J25-S	326	J10-TP73	J10-78	59
J10-7742	J10-42	37	J10-TP73	J25-L	822
J10-TP42	J25-d	\$27	J10-TP74	J10-74	60
J10-7943	J10-43	38	J10-TP74	J19-F	290
J10-TP43	J25−+	825	J10-TP75	J10-75	61
J10-TP44	J10-44 J25-f	29 229	J10-TP75 J10-TP76	J19-D J10-76	291 62
J10-TP44 J10-TP45	J10-45	40	J10-TP76	J19-B	290
J10-1745 J10-TP45	J25-g	230	J10-TP77	J10-77	
J10-TP46	J10-46	41	J10-TP77	J19-N	294
J10-TP46	J25-R	691	J10-TP78	J10-78	64
J10-TP47	310-47	542	J10-TP78	J19-P	296
J10-TP47	691 SHLD	762	J10-TP79	J10-79	65
J10-TP48	J10-48	418	J10-TP79	J19-R	296
J10-7748	TB2-4	554	J10-TP80	J10-60	66
J10-TP49	J10-49	42	J10—TP80	J19-8	297
J10-TP49	323-m	690	J10-TP61	J10-81	67
J10-TP50	J10-50	4.3	JIG-TPS1	J19-T	298
J10-TP50	690 SHLD	763	J10-TP82	J10-62	68
J10-7751	J10-61	44	J10-TP82	116-A	299
J10-TP51	TB2-5	840	J10-TP83	J10-83	800
J10-7752	NC J10-53	628	J10-TP83 J10-TP84	J19-V NC	auu
J10-TP53	710-03 782-11	604	J10-1784 J10-1785	J10-66	71
J10—TP63 J10—TP54	J10-64	629	J10-1785	XAC-T	341
J10-1754 J10-TP54	732-9	605	J10-TP86	J10-86	72
J10-TP55	J10-65	630	J10-TP86	TP-E2	692
J10-TP55	TB2-10	606	J10-TP87	J10-87	458
J10-TP56	J10-66	548	J10-TP87	192-7	446
J10-TP56	TB2-12	555	J10-TP86	J10-88	419
J10-TP57	J10-57	466	J10-TP88	692 SHLD	764
J10-TP57	J25-F	471	J10-TP89	NC	
J10-TP58	J10-58	467	J10-TP90	NC	
J10-TP58	125-J	472	J10-TF91	NC	
J10-TP59	J10-69	482	J10-TP92	NC	
J10-TP59	TB2-17	499	J10-TP93	J10-93	78
J10—TP60	J10-60	46	J10-TP93	TB2-2	342
J10—TP60	J21-P	304	J10-TP94	NC	ı
J10-TP61	J10-61	47	J10-TP95	NC	81
J10-TP61	321 −c	310	J10-TP96	J10 -96	1
J10-TP62	J10-62	48 302	J10-TP96 J10-TP97	J25-p J10-97	335 82
J10-7763	J21-M J10-63	49	J10-1797 J10-7797	J25-m	334
J10-TP63	M	303	J10-TP98	J10-98	83
J10—T763 J10—T764	J21-N J10-64	50	J10-1798	J23-i	813
J10-1764 J10-TP64	J21-R	305	J10-TP90	J10-99	84
J10-TP85	J10-66	51	J10-TP99	J23-i	814
J10-TP65	J21-T	807	J10-TP100	NC .	
J10-TP66	J10-66	62	J10-TP101	J10-101	86
J10-TP66	J21-8	306	J10-TP101	J23J	311
J10-TP67	J10-67	55	J10-1	J10-TP1	8
J10-TP67	J21-U	308	₫10 −2	J10-TP2	9
J10-TP68	NC		J10-3	J10-TP3	627
J10-TF69	J10 –69	55	J10-4	J10-TP4	11
J10-TP69	J23-R	312	J10-5	J10-TP5	12
J10-TP70	J10-70	56	J10-6	J10-TP6	13 412
J10-TP70	J25-t	337	J10-7	J10-TP? J10-TP8	14
J10-TP71	J10-71	57	J10-8	J10-TP9	15
J10-TP71	J21-J	1 301	1 310 -8	. 474 922	. ***

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

Prom-	***	Wo.	Frank	*	Wite Mas.
J10-10	J10-7710	18	J10-71	210-7771	67
J10-11	J10-7711	413	316-72	J10-7972 I20-7973	5.0
J10-12	J10-7712	17	J10-73 J10-74	10-7774	59 80
J10-13 J10-14	J10-TP13	19	1 210-75	J10-TP75	61
J10-14 J10-15	110-7715	20	J10-78	J10-TP76	62
J10-16	J10-77916	414	J10-77	J10-7777	6.3
J10-17	J10-7717	21	J10-78	J10-TP78	64
J10-18	J10-TF18	23	J10-79	J16-7770	65
J10-19	J10-TP19	415	J10-80	J10-7700	166
J10-20	J10-1720	446 649	J10-81 J10-82	J10-TP31 J10-TP32	61
J16-21 J10-22	J10-TP21 J10-TP22	481	J10-63	J10-TP93	6.0
J10-23	J10-1793	541	110-64	NC	
J10-24	J10-TP24	23	J10-65	J10-1785	72
J: 0-26	J10-7723	24	J10-86	J10-7788	12
J10-26	J10-1728	416	J10-87	J10-1797	453
J10-27	J10-17977	25	J10-88	J10-TP88	419
J10-28	J10-4728	379	J10-89	MC MC	
£0-29 J10-30	J10-1729 J10-1720	330	J10-60 J10-01	NC NC	2
J10-31	J10-1731	23	J:0-92		1
J10-32	J10-7732	27	J10-03	J10-77793	73
J10-33	J10-TP33	23	J10-94	NC	
J10-34	J10-TP34	29	J10-95	NC	
J10-35	J10-7725	30	J10-98	J10-1770	81
J10-36 J10-37	J10-7736 J10-7737	31 32	J10-97 J10-98	J10-1797 J10-7798	53 83
J10-38	J10-TP38	1 33	J10-99	J15-TP90	84
J10-39	J10-1739	34	J16-100	NC	
J10-40	J10-TP40	35	J10-101	J10-TP191	84
J10-41	J10-TP41	36	Ji i - TPi	J11-1	81
J10-42	J10-1742	37	J::-TP1	XA6-1	69:3
J10-43	J10-TP43	38	J11-1792	J11-3	3.3
J10-44 J10-45	J10-T744 J10-T745	39 40	J11-TP2 J11-TP3	793-19 J11-3	194 420
J10-46	J10-T748	41	J11-TP3	694 SHLD	766
J10-47	J10-1747	542	J11-TP4	311-4	
J10-48	J10-TP48	418	J11-TP4	Li-i	1:13
J10-49	J10-7749	42	J11-TP5	J11-6	9:0
J10-60	J10-1750	43	J11—TPS	L1-2	224
J10-51	310-TP51	44	J11-TP6	NC	
J10-62 J10-63	NC J10-1763	629	J11-177	J11-7	91
J10-64	J10-TP54	629	J11-177 J11-778	XA6-8 J11-8	995
J10-65	J10-TP55	630	J11-TP8	TB220	404
J10-58	J10-TP56	543	J11TP9	J119	422
J10-67	J10-1767	466	J11-T79	696 SHILD	76.9
J10-68	JIO-TPS8	467	J11-TP10	J11-10	95
310-69 310-60	J:0-TP59 310-TP60	483	J11-TP10	L2-1	235
J10-61	J10-TP61	46	J11-TP11 J11-TP11	J11-11 L2-2	94 238
J10-62	J10-TP62	48	J11-TP12	NC	4-20
J10-63	J10-TP63	49	Ji i -TP i 3	J11-13	677
J10-64	J10-TP64	50	J11-TP13	TB1-1	581
J10-65	J10-TP65	5.1	J11-TP14	J11-14	483
J10-60	J10-TP06	53	J11-TP14	TB1-2	500
J10-67 J10-68	J10-TP67	53	J11-TP15	J11-15	95
J10-69	J10-TP69	55	J11-TP15	XAG-L	343
J10-70	J10-TP70	56	J11-TP16	J11-16	96

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

		Ma.	Passo	**************************************	alle.
111-1917	J11-17	97	J11-1761	CBS-B1	600
11-7717	XA6-K	345	J11-TP61	J11-61	691
111-1718	J11-18	576	J11-1768	CBS-C1	0.00
11-1718	₹81-8	652	111-1768	J11-62	282
11-7719	NC NC	i	J11-1743	NC.	
11-7720	J11-21	888	J11-7754 J11-7754	311-64 191-22	4.55
11 -772 1 11 -77 21	116-TP6	401	J11-7765	J11-65	505 117
11-1722	J11-52	884	J11-1755	NC NC	4.84
11-17-22	XAG-E	102	J11-1766	NC NC	
11-17-23	E3	748	J11-7767	CB4-A1	610
11-7725	J11-23	100	J11-TP67	J11-67	6-93
11-1724	J11-34	434	J11-4428	C84-81	611
11-7724	743 SHLD	169	Ji1-17758	J11-68	594
11-1745	I NC	į i	J11-1769	CB4-CI	61.2
11-7796	NC		J1:-7766	J11-69	595
11-1727	J11-27	459 447	311-1769	NC .	
11-7727 11-7725	TB:-5 J11-88	104	Jul-1901 Jul-1901	E23 J:1-61	273
11-1720	J16-1712	346	J11-4702	NC NC	500
11-7729	J11-20	105	J11-1763	I NC	
11-77-20	X46-17	847	J11-1764	J11-64	1.23
11-7930	J11-60	106	Ju-Mee	Ke-Xi	764
11-77930	NC NC		J11-1	Ju-TPi	81
11-7791	NC		J11-2	J11-TP2	68
11-7793	J11-32	108	J11-9	J11-TP8	420
11-17932	XAG-P	848	J11-4	JII-TP4	89
11 -77 25	J11-88	100	J11-6	J11-TP6	90
11-1783	MC .		J11-6	NC	
11-1734	NC .		J11-7	J11-TP7	91
11-7735	J11-86	1111	111-9	J11-TP8	92
11-1735	XA6-13	849 854	J11-9	J11-779	422
11—1796 11—1796	J1:-95 NC	624	J11-10 J11-11	J11-TP10 J11-7P11	69
11-1727	J11-87	112	J11-12	NC NC	1
11-1737	TD1-9	742	J11-13	J11-7-13	677
22-7738	J11-88	425	J11-16	J11-TP14	485
11-7738	742 SHLD	770	J11-16	J11-TP12	95
11-7739	J11-89	484	J11-10	J11-7716	93
11-7739	TB1-11	501	J11-17	J11-7717	97
11-1740	J11-40	485	J14-18	J12-TP18	576
11-TP40	781-12	502	J11-19	MC	
11-1741	J11-7742	771	J11-20	NC	
11-1741	J11-41	469 771	J11-21	J11-TP21 J11-TP22	363
11-TP42 11-TP42	J11-774: J11-42	670	J11-22 J11-23	J11-TP28	384 100
11-7743	J11-43	113	J11-24	J11-7724	424
11-7743	# XA4-M	741	111-26	NC	
11-1744	J11-44	466	Ji 1 26	NC	I
11-TP44	TB1-14	503	Jul - 27	J11-TP27	489
11-77-6	J11-45	114	J11-28	J11-TP28	104
11-1746	J15-TP16	695	J11-20	J11-/1729	105
11-1746	J11-46	676	J11-80	J11-TP30	106
11-T946	J15-TP17	583	J11-31	NC	
11-1747	J11-47	487	J11-82	J11-TP32	108
111-1747	TB1-26	504	J11-33	J11-TP33	109
11-7748	NC		J11-34	NC J11-TP85	111
11-T749	J11-49	544 556	J11-85	J11-TP36	854
/11TP49 /11TP50	TB1-16 J11-60	900	J11-36 J11-37	J11-1736 J11-TP37	113
1 1 - X F 3333	1 611 04	3	971_91	J11-TP38	425

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

1:-40	224-220	T			
1:-40		434	J.5-771	191-1	8.54
T N MANUE	JOB-2240	435	J15-1193	33.6-8	449
1 4 (A)	311-7241	469	J15-777	131-3	81.7
The second second	J:1-47943	470	J16-493	J16-C	439
b-43	332-7943	113	J115TP3	J14-175	443
1-44	Jul 19744	435	J15-774	NC.	
Same A. Same	Jul-1945	114	J15-175	MC	
H-mad ()	J11-17946	573	J15-776	311-17931	433
1-47	J11-1947	487	J15-1796	J15-8	3.15
1-43	NC.		JUS-1821	NC	
1-49	J11-7749	544	J15T70	MC	
1-40	J1.1-TF50		J15-779	NC	
1. b6.k	43.4- 479 5.1	55.	J:5-TP:0	NC:	
15-43	111-7752	592	J15-7711	115-L	4.27
1-43	NC.		JIG-VPLI	781-6	449
15-54	111-7964	436	J:5-7713	J11-TP26	346
11-66	111-7756	117	J15- 4713	114-M	1,30
h-48	NC		J15-7713	J15W	.96
11-67	J1.1-17567	590	115-7713	TB121	6.06
1 I - 68	Jn 1-7793	594	J15-7714	125-P	433
11-50	J11-47700	696	J15-77714	791-12	\$627
1-40	NC		J16-7715	J11-1745	495
11-41	· 321-7751	860	J15-T915	J15-R	131
11-62	NC		J15-7716	J14-6	433
11-63	NC		J15-7716	T01-20	5-118
11-64	J11-7794	123	J15-7717	J1:-774a	583
17-A	FL1-1	348	J15-7717	J15-T	6.00
5	CB1-A1	490	115-7716	J15-U	88.5
12-C	NC		J15-7718	T31-15	509
1.5-A	CD2-A1	652	EIA	436 SHILD	40.1
1.5-8	C32-51	653	5:3:1711	J16-V	688
1.3-C	CB2-C1	664	Jib-Trib	T51-16	347
13-0	NC		J15-TP20	87	43/2A
3-4	9LA-1	673	J15-TP20	J15-W	1.1.2
14-171	NC		J15-TP21		44:28
14-172	NC		J15-TP21	JIA-X	1.11
14-773	J14-C	386	J15-TP22	84	30.20
14-173	815-1		J15-TP22	Jos-Y	1.24
4-4774	J14-D	429	J15-7723	L Sa	633A
14-4794	N15-2		J15-TP23	J15-2	411
14-775	NC:	f	J15-TP24	8 1	600
14-776	J14-9	156	J15-7724	714	114
14	1.3-1	229	J15-Tr-25	N.C.	-
4-177	NC		J15-TP26	63	trac
4-179	J14-81	158	J15-T726	J15	191
14-477	LA-1	230	J15-7727	NC TO THE RESERVE TO	
4-7779	114-4	150	J15 7720	NC NC	
4-179	L4-2	221	J15-TP29	NC	
14-7710	J14-K	160	27%-TP30	NC	
14-1710	1.3-2	232	J16- T731	nc .	
A and A	NC		J15-T732	NC	
M - 0	NC	į.	J16TP33	NC	
M-40	J.4-TP3	386	J15-77734	NC	
14O	J14-TP4	429	J15-TP38	NC:	Ĩ.
14-6	NC:	74.49.49	J15-TP36	NC NC	
A complete	114-477	1.56	J15-1737	NC NC	
14-0	NC.		J15-1738	NC .	
14-41	374-479	158	J15-1739 J15-7 7 39	NC	
14-1	J14-T79	159	J15-7740	l NC	
49-748	J14-1710	160	J15-TP40 J15-TP41	NC	I
14-8					

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

		W2.6 \$45.		-	94 8
Des	21.5-7773	4.33	216-G	NC NC	
NS-C	J15-TY5	4.25	J16-H	NC NC	
45-0	NC .		216-2	NC NC	
106-8	342		316-K	216-7710	207
J15-7	J15-796	2:95	117-A	210-774	TILL
As-G	SEC.	į.	417 -8	110-175	71.15
21.6 -H 21.6-2	NC NC		41-6	J10-776	7130
216-K	2.00 ± 6	ă i	117-6	712 SMLD 210-7215	749
	75-77-1	427	117-7	310-TF14	703A
J16-M	J15-7712	150	/17-G	703 SHLD	1005
115-N	A16-77:18	440	217-4	110-721	627
315-P		752	31.7 - 3	J10-TP2	648
/12-B	215-77-16	1.91	J1 7 - K	/10-17/12	585
J16-6	215-3716	492	J17-L	NC NC	
115-17	313-TT17	5.50	317-M		I .
M4-U	J15-TP18	84.5	317-N	J10-TP18	704A
J15-V	216-7919	6.1.8	J17-P	J10-1711	1348
115-W	J15-7720	182	J17-8	104 SHLD	76.0
J14-X	\$15-TP23	133	J17-6	J10-179	713A
119-A	J16-7922	186	327-T	J10-278	7119
115-2	\$1.6~TP28	4.53	J17U	J10-TY10	718C
116-0	\$1.5-TYE4	146	317-V	713 SMLD	751
115-6	NC		J16-TP1	J16-A	663
116-4	J1.67726	1.27	J18-TP1	K6-81	205
115-d			116-772	J16-6	861
#15-0	NC.		J18-5P2	K6-A1	266
115-4 115-4			116-778 116-773	81-63 716-C	277
714-4	MC.	M	J16-774	J18-D	851
J15-4		Į.	J16-TP6	116-6	865
J15-4			218-776	K5-A1	267
J15-k	N.C.		J18-TP6	J18-F	666
J15-m	NC		J16-776	K5-81	266
120-0	NC		318-TP7	J18-G	867
115-p	NC:	i	J18-778	J16-H	631
J15-q	NC		J19-TP8	T1-6	626
115-1	NC		J15- -179	J18-J	430
J16-1	MC	8	J18-TP9	T1-6	451
J15-4	NC		J16-7710	₹18-K	178
J16-771	116-4	598	J18-TP10	KI-DI	405
J16-771	K2-A1	613	J18-T711	NC NC	
116-1773	J16-8	697	J16-TF12	NC	
716-77°2		614 698	J16-7713	418-N	170
J16-773 J16-773	716-C	615	J16-TP18	K5-B5 J18-P	177
116-173 116-774	K2-C1 NC	49.130	J18-TP14 J18-TP14	K5-AS	270
J16-775	J15-773	448	218-1716	J16-R	431
J16-775	116-6	648	116-TP15	709 BHL	825
J16-176	NC		418-TP16	J16-6	178
J16-177			416-TP16	K6-Å3	271
J16-778	NC		#19-TP17	118-7	179
J16-779	NC		J.8-TP17	K6-03	272
J16-TP10	J16-K	387	J18-TP18	B1-63	718C
J16-TP10	TB9-14	403	116-TP16	J18-U	180
J16-A	J16-TF1	596	J18-7711	J18-V	452
J16-8	J16-TP2	597	318-7719	718 SHLD	838
J18-C	J16-773	598	J18-A	J18-TP1	861
J10-D	NC		J18-8	J18-TP2	803
J16-B	J16-TP6	545	J18-C	J18-TP3 J18-TP4	863 864
J16-F	i NC	M	J18-D	41 37. St. St. second 37 (407) 49.	2 2000

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

Parameter and the second secon	***	Wiya No.	7 190-	70-	Wes No.
· Anna A	J13-175	805	J20-J	NC	
i i	113-779	366	J20-K	NC	
120	J19-TP7	867	J20-L	J20-TF11	269
A-A	119-1798	631	J20-M	J20-TY12	433
3-1 3-1	J13-779	430	J20-N	J20-TP13	192
3	113-7210	173	J20-P	J20-T714	193
13—14 13—14	NC	1	J20-A	J20-TP15	194
13-L 13-M	NC	1	120-8	J20-TP16	196
Jeros Million	118-77713	176	J20-7	J20-T917	156
3	118-7714	177	J20-U	J20-TP18	197
	J13-TP15	431	J20-V	J20-TP19	198
3 8. 3 4	J18-TP18	178	J21-A	NC	
18-0 18-1	J15-1715	179	J21-A	TB2-3	549
-	J15-TF13	180	121-C	TB2-11	539
	J13-TP19	432	J21-0	182-6	8.040
V	NC	1 *** /	J21-B	TB2-10	601
19-A		230	J21-E J21-F	TB212	550
19-8	J10-TP70			TB2-12	437
10-C	NC	201	J21-G		602
19-D	110-1775	1 201	J21-H	T92-1	B
19-8	NC	1	J21-J	J10-1771	301
19-7	J10-TP74	292	/21-K	NC	
19-G	NC	l y	J21-L	NC	400
19-H	NC	l y	J21-M	J10-7762	302
19-J	NC	i P	J21-N	J10-7763	303
19-K	NC .	1	J21-P	J10-7790	304
19-L	J23-V	293	J21-R	J10-TP64	306
19-M	133-3	442	J21-8	J10-T766	306
19-N	J10-T777	294	J21-T	J10-7785	301
19-7	J10-7778	295	J21-U	J10-TF67	308
19-R	J10-1779	296	J21-V	J10-TP20	498
19-8	J10-TP80	297	J21-W	J10-TP21	561
19—T	J10-1781	298	J21-X	NC	
19-U	J10-TP82	299	J21-Y	TB2-6	309
19-V	210-TP83	300	J31-Z	TB2-4	443
20-TP1	J20-A	868	J21-a	NC	
20-172	J20—B	182	J21-6	NC	
20-173	J20-C	183	.21−c	J10-TP61	310
20-174	J20-D	184	/22-TP1	NC	
20-175	J20-B	185	J22-TP2	PL1-2	556
20-176	J20-F	186	J22-TP2	J22-B	434
20-177	NC	l y	J22-TP3	J22-C	633
20-776	NC	l y	J22-TP3	K1-C1	614
20-179	NC	l y	J22-TP4	J22-D	633
20-TP10	NC	t y	J22-TP4	Ki-Bi	617
26-TP11	J20-1.	269	J22-TP5	J22-E	634
20-1712	J20-M	433	J22-YP6	KI-AI	618
20-TP13	J20-N	192	J22-TP6	J22-F	433
120-1713 120-1714	J20-P	193	J22-TP6	722-F	556
120-1714 120-17915	J20-R	194	J22-176 J22-177	J22-G	386
720—1715 120—7716	J20-8	195	J22-TP7	372-0 K1-D1	8
720-1716 120-7717	J20-T	196	J22-1P7 J22- 1P 8		511
120-1717 120-1718	J20-U	197	100	J22-H	639
/30-1718 20-7719	J20-U J20-V	128	J22-TP8	S1-2	619
		8 - 10	J22-TP9	J22-J	870
120—A	J20-TP1	863	J22-TP10	NC	
739- 5	J20-TP2	182	J22-TP11	NC	
J30-C	J20-TP3	183	J22-TP12	J22-M	200
J30-D	J20-TP4	184	J22-TP12	TB3-E1	473
730-E	J20-TP5	185	J22-TP13	J22-N	204
J30-P	J20-TP6	186	J22-TP13	TB3-E2	470
J20-G	NC	i y	J22-TP14	J22-P	200
J20—H	NC	l v	J22-TP14	T93-E3	477

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

**************************************	70-	Wite No.	Pros -	7-	West No.
J22-7915	J22-R	871	123-W	NC	
J22-TP16	J22-8	872	J23-X	NC	
J22-TP17	J23-T	873	323-Y	NC	
J22-TP16	J22-U	209	J23-Z	NC	
122-TF18	T93-84	474	123-	NC	
J22-1719	322-V	369	J23-6	NC NC	
J22-TP10	K1-X1	512	J23-c	NC	
122-1720	322-W	210	J23-d	NC NC	
J22—TP20 J22—TP21	J35-179	475	J23-e J23-f	NC	Ì
122-1722 123-1721	J22-X J22-Y	874 975	J23−1 J23−2	NC NC	
722-1723	122-Z	436	123-6	NC NC	J
/22-1723 22-1723	725-6 131-6	446 560	723-6 723-i		
/22-1723 /22-7 2 24	181-0 J22-a	876	√23~1 √23~i	J10-TP96 J10-TP99	318
132-1724 192-1725	122-b	877	J23-j J23-k	NC TP99	314
1-9-1P95	122-6	878	J23−£ J23−m	J10-1749	690
129-A	NC	575	J25−m J25−n	690 SKLD	752
122-A 122-B	122-172	484	J23-6 J23-6	NC 88LD	101
/2.7_6 12.7_€	122-178	632	723-7 723-0	NC NC	
122-C 122-D	J22-TP4	683	J23-4 J23-4	J10-TP13	816
122-0 122-8	122-TP5	634	723−4 J23−a	NC NC	310
	122-176	435	1 223-1	TB1-4	552
122-G	122-777	388	J24-TP1	J24-A	880
122-H	122-TP8	635	J24-TP2	J24-B	881
122-5 122-J	122-TP9	870	J24-TP3	J24-C	882
122-K	NC	2/0	J24-TP4	J24-D	883
122-L	NC		J24-TP:	J24-B	884
122-M	J22-TP: 2	203	J24-TP(J24-P	495
122-N	722-TP18	204	J24-TP:	R1-1	
122-P	J22-TP14	205	J24-177	J24-G	546
122-R	J22-TP15	871	J24-TP7	R1-2	
122-3	J22-1716	872	J24-TP8	J24-H	885
122-T	J22-7717	673	J24-TP9	J24-J	222
122-U	J22-TP18	209	J24-TP9	83-8	879
122-V	J22-TP19	389	J24-TP10	J24-K	886
122-W	J22-TP20	210	J24-TP11	J24-L	887
122-X	J22-TP21	874	J24-TP12	J24-M	888
122-Y	122-7922	875	J24-TP13	J24-N	869
122Z	J22-TP23	436	J24-TP14	J24-P	890
122-1	J22-TP24	876	J24-TP15	J24-R	228
122-6	J22-TF25	877	J24-TP18	TB3-E	351
122-e	J22-TP26	878	J24-TP16	J2 4 3	891
123-A	NC		J24-TP17	J24 -T	892
123-B	NC		J24-TP18	J24-U	893
23-C	NC	j l	J24-TP19	J24-V	894
123-D	NC		J24-TP20	J26-W	895
13-E	NC		J24-TP21	NC	
23-P	NC		J24-TP22	NC	l
123-G	NC		J24-TP23	NC	
123-H	NC		J24-TP24	J24-0	896
123-J	JIO-TPIOI	311	J24-7P25	J24-b	897
123-K	NC		J24-TP26	J24-c	898
123-L	NC		J24-TP27	NC	i
123-M	NC		J24-TP28	J24−e	899
123-N	NC		J24-TP29	J24-f	900
123-7	NC		J24-TP30	J24-E	242
128-R	J10-TP69	312	J24-TP30	NC	ı
123-6	NC		J24-TP31	J24-h	801
123-1	NC		J24-TP32	J24-i	244
123-U	NC	Y I	J24-TP32	TB3-E10	353
J23-V	J19-L	293	J24-TP33	J24-j	902

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

*********	1	Wwa No.	The same	70-	Ve No
04-1793	793-810	2774	135-3	J10-1768	411
71 - 12 14 11 - 12 14	N.C		J25-K	NC	*
	J24-m	909	J25-L	J10-TP73	81
7.7.1. 71.7.1.1	NC	333	126-M	TB2-2	3.1
	124-0	904	J25-N	SIC .	
Market and Market	J24-0	906	J25-P	NC	
134—11207 134—1123	J24-0	900	145-8	J10-7746	61
	194-4	265	J256	691 SHLD	71
	84-9	364	J26-T	N.C	
04-0240		1 7 3 3	J24-U	NC	
	J24-4	547	J25-V	NC NC	
24-1241	731-7	602	124-49	NC NC	<u> </u>
24-V	J24-TP1	230	J25-X	J10-TP33	77
24-A 24-A	124-172	881	J25Y	J10-TP28	71
	124-124	882	125-2	J19-TP37	7
94-C	124-174	843	125-a	J10-7739	1
134-D	J24-176	884	J25-6	J10-77940	3
24-8	124-176	496	J25-e	J10-TP41	1 3
34-P	124-127	546	J25-d	J19-7742	2
24-G	1	845	J25	J10-TP43	1
24-11	J24-T78 J24-T79	222	125-4	J10-TP44	
34-J	8	828	J25e	J19-TP45	
24	J24-T710	837	J25-k	J10-1738	3
24-L	J34-TP11	833	J25-i	J10-7937	1 3
24-M	J24-TP12	330	J25-1	J10-TP38	3
34-N	J24-1713	4	123-1 123-2	J10-TP31	
24-7	J24-TP14	890		J10-TP97	3
24-8	J24-1715	228	J25-m J25-n	NC	
24-9	J24-TP16	891		J10-T798	3
124-1	J24-TP17	893	J25-p	J10-7924	1 1
24-U	J24-TP18	893	J25-q	J10-1770	3
124-V	J24-TP19	894	J25-r		3
124-17	J24-T?20	895	J25-s	J10-TP36	4
24-X	MC		J25-4	, ,,,,,,	
124-Y	NC	l l	J26-171	J26-A	
124-Z	NC		J26-172	136-8	#i
124-3	J24-TP24	896	J26-TP3	J26-TP5	
124-b	J24-TP25	397	J26-TP3	J28-C	9
124-e	J24-TP26	399	J26-TP4	J26-D	9
124-d	NC		J26-TP5	J26-T73	
124-9	J24-TP28	899	J26-TP5	J26-8	1 3
124-1	J24-TP29	900	J26-TP6	TB3-85	3
124-8	J24-TP30	242	J26-TP6	126-7	4
124-h	J24-T731	901	J26-779	K1-D2	
134-1	J24-TP32	244	J26-TP1	J20-G	1
124-1	J24-TP33	902	J26-TP7	XA2-19	1
124-h	NC	1	J26-TP8	J25-H	1
134-m	J24-TP35	908	J26-TP9	J22-TP20	4
124-10	J24-TP30	904	J20-779	J26-J	4
124-p	J24-TP37	906	J26-TP10	J26−K	9
J24-q	J24-TP38	908	J26-TP11	J28-L	9
J24-1	J24-TP39	250	J26-TP12	J26-M	9
J24-s	NC		J26-TP13	J26-N	9
J24-t	J24-TP41	547	J28-TP14	J26-P	\$
J25-A	J10-TP32	714A	J26-TP15	J26-R	1
J25—B	714 SHLD	753	J26-T:15	XA1-Y	(
J25-C	J10-TP29	316	J20-T710	J26-S	4
J35-D	705 SHLD	755	J28-TP16	699 SHLD	[6
J35-K	J10-1725	317	J26-TP17	NC	
J25P	J10-7757	471	J26-T718	NC	Į.
JSS-O	J10-TP24	319	J26-TP19	J26-V	1
J25-H	J10-TP72	320	TE	NC	RE.

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

	***	No.	From -	₩	Wax Me.
J98-7921	J26-X	918	128-1	J26-TP82	22.0
196-TP22	J26-Y	919	J26-i	J26-TP83	251
126-1723	126-2 126-a	920	J25-t J26-m	J26-T754	925
196-TP24 126-TP25	325-6 326-6	921 922	/25-m	J26-TP36 J26-TP36	243 929
126-1726 126-1726	125-6	929	J25-0	J26-TP37	286
26-7727	J25-d	934	128-6	J26-TP38	226
126-7728	J26-e	925	J26	J26-TP39	287
156-TP29	J26-f	926	J25-a	J26-TP40	284
36-TP30	126-6	927	J26-€	J20-TP41	663
25-1731	J26-5	279	K1-V1	J22-TP6	618
25-7731	XA1-3 J26i	358 280	K1-A1	T1-2	625
) 16-1752 28-1752	XA1-D	350	KI-AI KI-A2	T2-2 XA6-Y	650 622
/25-17-34 /26-17-33	J26-i	231	KI-BI	J22-TP4	617
96-TP38	XA1-E	860	K1-B1	T2-8	351
135-1784	J25-4	928	K1-82	XA5-T	621
78-7885	J25-m	283	K1-C1	J22-TP3	616
26-1735	XA2-17	361	K1-C1	T2-1	649
26-TP36	100-0	929	K1-C2	XA5-P	620
26-1731 26-1731	J26-p XA2-18	2.35 \$5.7	K1-D1 K1-D1	J18-TP10 J22-TP7	405
	245-0	256	K1-D1	XDS1-1	639
24-1728	XA2-21	362	Ki-D2	FL2-2	526
25-7750	J26-7	267	K1-D2	J26-TP6	514
25-1729	TB3-64	363	K1-X1	J22-TP19	512
26-7740	125-4	288	K1-X2	PL1-2	455
26-7740	XA2-Y	364	K1-X2	XDS1-2	454
26-1741 26-1741	182-13	441 452	K2-A1 K2-A2	J16-TP1 CB4-A2	613 624
126-A	J26-TP1	907	K2-81	JIG-TP2	614
14-8	J26-172	908	K2-82	CB4-B2	625
26-C	J26-TP3	909	K2-C1	J16-TP3	615
26-D	J25-T74	910	K2-C2	CB4-C2	626
25-8	J36-1775	254	K2-D1	K2-X2	537
25-F 25-G	J25-TP6	479 256	K2-D1	K3-7	536
35-U 25-H	126-TP7 126-TP8	911	K2-D. K2-D3	K3-5 K3-3	533 570
124-J	126-179	465	K2-X1	K3-2	671
196-K	J36-TP10	912	K2-X2	K2-D1	537
16-L	J26-TP.1	913	K3-2	K2-X1	571
26-M	J26-TY: 2	914	K3-2	TB1-16	575
25-N	J26-TP13	915	K3-8	K2-D3	570
25-P	J36-77 14	916	K3-6	K2-D2	588
25-R 25-S	J26-TP:5 J26-TP:6	264 440	K3-5 K3-7	85-1 K2-D1	534 536
23	NC	1 ***	K4-A1	17 J7	730
26-U	NC	#	K4-A1	K4-B1	825
26-V	J25-TP19	917	K4-A3	15	729
25,-17	NC		K4-B1	K4-A1	825
26-X	139-1631	918	K4-B2	XA6-18	727
35-Y	J26-TP22	919	K4-B3	J3	728
%-Z	J26-TF23	920	K4-X1	J11-TP64	744 457
%—₃ %—ь	J26-TP24 J26-TP25	921	K4-X2 K5-A1	E18 J18-TP5	256
126−0 126−c	J26-TP26	923	K5-A2	B1-R2	7098
24-d	J25-TP27	924	K5-A3	J18-TP14	270
25-e	J28-TP28	925	K5-B1	J18-TPK6	267
26-1	J26-TP29	926	K5-B2	BI-RI	709A
126-1	J26-TP30	927	K5-B3	J18-TP13	269
25-h	J26-7P31	279	K5-X1	K6-X1	836

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

F-12-	7	Wire No.	Press-	7-	Ng Na
(4 – 122	186-X2	837	R181	213	22
6-A1	J18-TP2	225	R19—CW	815	31
8-A2	B1-63	718B	R19-CCW	×41-5	91
3-A3	J18-TP17	272	B20-1	F1.5-3	1 21
2-21	hs-m	265	B202	XA5-20	6 1
953	81-61	718A	R21-1	FL4-2	21
3-03	J18-T916	271	R21-2	XA5- 5	64
3-X1	K5-X1	836	R23-1	PL3-2	22
18-X1	TB3-17	278	K23-3	XA5-6	
L9-X2	K5-X2	837	81-1	71-3	64
.1	J11-4794	2:23	81-3	J93-7798	6
J.	J11-775	324	82 1	XD89-1	2
2	J11-TP10	225	82-2	235	*
L3	J11-TP11	228	83-1	TB3-14	3
L3	J14-778	229	93-3	J24-TY9	8
L3	J14-1710	233	84-1	T91-29	5.
4	J14-1798	230	84-3	J24-T73t	3
La	J14-TF9	231	95-1	K3-6	5.
NC	J10-TP63		86-3	TB1-15	5.
NC .	J10-TP63		86-2	1703-68	5.
NC	J:0-TP04		89-3	101-30	3
NC	J16-TP89		87-1	XA4-4	3
VC	J10-7790		87-2	132-7	4
NC	J10-7791		TB1-1	J11-7713	
NC	J10-TP92		TD1-1	J15-171	5
NC	J10-TP94		TB1-1	XA3J1-9 J11-T914	5
NC	J10-TP95		TB1-2	1	5
NC	J10-17100	1	TB1-2	J15-TP2	5
NC	J10-52		101-2	XA4-5	4
NC	J10-68		TB1-2	XAGJ1-J	
NC	J10-84		101-3	JII-TPIS XASJI-R	5
NC	J10-89	r r	TB1-3	781-6	•
NC	J10-90	4	TD1-4		4
NC	J10-91		TB1-4 TB1-4	T2-13 XA4-A	1 5
NC NC	J10-92 J10-94		TB1-5	J11-TP27	4
NC			TB1-5	J15-TP11	4
NC NC	J10-56 J10-100		TB1-5	TB1-4	1
NC	J11-TP6	E L	131-5 1781-5	TB1-6	
NC	J11-17912		TB1-5	XA3-6	
NC	J11-77219		751-5 TB1-6	122-7723	9
NC	J11-TP30		TD1-6	TB1-5	•
NC	J11-TP25		T01-6	TB1-7	
NC	J11-TP26		TB1-6	XA6J1-11	6
NC	J11-77930		TB1-7	J34-T741	
NC	J11-TP31	ř.	TB1-7	TB1-6	•
NC	J11-7733		701-7	181-8	
NC	J11-TP34		T01-7	TB1-27	
NC	J11-TP36		T71-8	825	5
NC	J11-TP48		181-8	TB1-7	
NC	J11-TP53		TB1-9	Jo	7
NG	J11TP56		TB1-9	J11-TP37	i
RS-CCW	B15	930	TB1-9	TB1-10	
R9-CCW	R10-CCW	931	TB1-10	TB1-0	
R10-CCW	B15	932	TBi-10	XA6-8	1 7
R10-CCW	R9-CCW	931	78111	J11-TP39	5
R11-CCW	R14-CCW	933	TB1-11	XA6-P	Š
R14-CCW	87	934	TB1-12	J11-TP40	
R14-CCW	R11-CCW	933	181-12	J15-TP14	5
R18-1	XA4-T	227	TB1-12	XA6-S	5
R18-2	XA4-W	371	m -	,	

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

France -	***	Wase No.	Perguita -	WW war	Ware No.
XAI-A	198-18	663	XA2R	NC	
XAI-A	XAI-1	843	XA2-8	XA1-L	5.6.6
xai—8	NC .	i i	XAS-T	NC	
XA1—C	NC		XA2-U	NC	l l
XA1-D	156-TP\$2	359	XA2-V	XA2-A	546
XA1-8	J26-T783	260	XA2-W	NC	
XA1-P	NC	1	XA2-X	NC	
Kai—H	NC		XA2-Y	J26-TP40	364
xai-j	XA1-W	841	XA2-2	TB2-16	517
XA1-K	NC .	366	XA2-Z XA2-1	XA9-22 XA2-A	848 847
XAI-L XAI-M	XAS-S NC	200	XA2-2	NC NC	24 (
AAI-M XAI-N	No.		XA2-3	NC	i i
AAI-N XAI-P	NC.		XA2-4	NC NC	
XAI-R		719	XA2-6	NC	T .
XAI-S	NC:	111	AA2-6	NC	Ĭ
XAI-T	XA4-16	721	XA2-7	NC NC	1
XAI-U	XA1-20	867	XA2-8	NC	•
XAI-V	NC		XA2-0	NG	
XA1W	XAI-J	841	XA2-10	NC	(
XAI-X	NC .		XA2-11	NC	1
XAI-Y	J26-TP15	699	XA2-12	NC	ĺ.
XA1-Z	782-16	515	XA2-13	NC	
XA1-Z	XA1-22	516	XA2-14	NC	
XAI-I	XAI-A	643	XA2-15	NC	¥
XA1-2	T82-16	685	XA2-16	NC	
XA1-8	255-TP31	358	XA2-17	J26-TP36	361
XA1-4	34	722	XA2-18	J26-TP37	857
XA1-6	R19-CW	318	XA2-19	J26-TP7	866
XA1-6	NC		XA2-20	TB2-16	590
XA1-7	NC		XA2-21	J26-TP3F	362
XAI-8	NC		XA2-22	XA2-Z	848
XAI-9	NC		XA3-A	T2-4	639
XA1-10	NC		XA3-B	T2-6	640
XAI-II	NC	i e	XA3C	T2-6	641
XA1-12	NC	# #	XA3-D	NC	
XA1-13	NC		XA3-E	TB1-29	516
XA1-14	NC		XA3-F	NC	1
XA1-15	NC		XA3-H	TB2-17	519
XA1-16	NC		XA3-H	XA3-J	851
XA1-17	NC		XA3-J	XA3 -H	851
XA1-18	NC	l l	XA3-X	12-7	642
XA1-19	NC	262	XA3-L	T2-6	644
XA1-20	XAI-U NC	167	XA3-M	NC 13-9	1 200
XAI-2!	M	516	XA2-N XA3-P	NC NC	
XA1-22 XA2-A	XA1Z TB2: 3	564	XA3-R	NC	1
XA3-A	XA2-V	846	XA3-8	NC NC	
XAS-A	XA2-1	847	XA3-T	NC	
XA2-B	NC	1 ***	XA3-U	NC NC	1
XA2-C	NC		XA3-V	TB2-15	520
XA2-D	NC		XA3-V	XA3-W	852
XA2-8	NC		W-EAX	XA3-V	852
XA2-F	NC		XA3-X	NC	1
XA2-H	NC NC		XA3-Y	NC	İ
XA2-J	NC		XA3-Z	NC	i i
XA2-K	NC NC		XA3-1	XA3-6	772
XA2-L	NC		XA3-1	XA3-16	773
XA2-M	NC		XA3-2	NC	
XA2-N	I NC		XA3 3	NC	l l
XA2-P	NC.	1	XA3-4	TB2-16	586

 $Table\ 3-42.\ Test\ Set\ Subassembly\ MX-8638A/APS-94D,\ Unit\ 1A2\ Wire\ List\ -\ Continued$

*****	**-	Wys No.	711111	Passer	Wigo Mis
191-14	J11-17944	500	TB2-14	XD83-3	46
TD1-14	TB1-16		T82-15	XAI-Z	61
TD1-14	XAG-N	524	TB2-15	XA2-Z	51
101-15	J15-T718	500	T83-15	XA3-V	5.3
191-15	86-3	535	1783-15	XA4-Z	53
TD1-15	T81-14		TB2-16	XA1-3	5.0
TD1-16	J11-TP49	556	TB2-16	XA2-20	59
701-10	J15-17919	557	TB2-16	XA3-4	5.5
791-16	K2-X1	575	792-16	XA4-D	5.8 4.9
TD1-16	TB1-17		783-17	J10-17759 K6-X1	27
181-17	TB1-16		182 -17	, and and	5.3
791-17	XA9-12	869	TB3-17	TB2-14 XA3-H	51
TB1-20	J11-1747	504	103- 17	XA4-Y	5.3
T91-20	J15-TP14	500	792-17 792-15	NC	-
TB1-21	116-7713	505	M	J11-TP2	63
TB1-23	J11-11964 XAG-T	523	TB2-19 TB2-19	XA4-V	37
TB1-22	T01-7	929	182-19	XAG+ A	70
T01-27	84-1	531	TB2-20	J11-1798	6.0
1151-29 1151-29	783-£12	5.3.2	T82-20	XA4-N	3.0
	XA3-8	515	T32-20	XA6-2	1
TB1-30	83-3	278	782-21	J1-796	20
T32-1	J10-773	863	102-31	жа4-с	1
702-1	J21-H	602	102-21	XAGP1-E	74
TT2-2	J10-7793	342	TB2-30	J1-TP2	11
732-2	125-M	323	Th2-30	XA4-B	12
732-3	J10-TP23	681	TB2-30	XAGP2-B	17
702-3	J19-M	442	TB3-E1	J22-TP12	47
TB2-3	J21-6	549	TB3-E2	J22-TP13	47
732-4	J10-TP48	554	TB3-82	J11-TP23	
T32-4	J21-Z	443	TB3-E3	J22-TP14	47
TB2-4	J23-4	552	TB3-E4	J22-TP18	47
T32-4	J26-1	444	TB3-E5	J28-TP6	2.5
TD2-4	TB2-7	573	TB3-26	J23-TP39	36
733- 5	J10-7951	340	TB3-E7	J24-TP15	34
TD2-6	J21-Y	309	TB3-E8	86-2	5.3
TB2-6	J10-TP22	680	TB3B10	J24-TP32	36
TB2-6	J21-G	497	TB3-E10	J24-TP33	27
T92-7	E15	235	TB3-E12	TB1-29	5.3
TB2-7	J10-TP87	446	TB3-#16	XDS1-1	24
TB2-7	37-2	460	TP-E2	J10-TP86	61
753-7	TD2-4	573	T1-1	J22-TP6	5.5
TD2-7	T83-13	574	T1-1	Meax	SA
TD3-7	777 SHLD	826	T1-2	KI-Al	6.1
TB9-6	NC		T1-3	S1-1	64
T32-9	J10-1754	606	T1-4	XDS1-2	44
T32-9	J21-D	600	T1-5	J18-TP8	63
782-10	J10-TP66	606	T1-6	JIS-TP9	41
TB3-10	J21-8	601	T2-1	K1-C1	64
TB2-11 TB2-11	J10-TP63 J21-C	604 599	T2-2	K1-A1	6
TB2-12	J10-T756	555	T3-3	KI-B!	6
TB1-12	J21-P	550	T2-4	XA3-A	65
TD2-13	825	378	T2-6 T2-6	XA3-B XA3-C	6
TD2-13	J26-TP41	452	T2-6 T2-7	XA3-C XA3-K	6
T02-13	735-1741 732-7	574	T2-8	XA3-K XA3-L	6-
TB3-13	XAI-A	543	T2-9	XA3-L XA3-M	6
152-13	XA2-A	564	T2-10	XA3-20	6
TB2-14	Ji6-TP10	403	T2-11	XA3-21	6
TB9-14	S3-1	375	T2-12	XA3-21	64
133-14	TB3-17	538	T2-13	TB1-4	45
9 10 10 10 10 10 10 10 10 10 10 10 10 10	E 5 50 65 5 5	E (3)-31-638	10 A ACT E-35	1 1 10 1 TG	s 49 7

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

	1	Wille No.	Process-	70-	
XA3-5	l MC		XA6-17	NC	
XA3-6	XA3-1	772	XA4-18	NC	
XAS-7	NC		XA4-19	NC	
XA3-8	NC		XA4-20	NC	
XA3-0	NC		XA6-21	NC	
XA3-10	NC .		XA4-82	XA4-Z	
XA3-11	NC		XA6-A	NC	
XA3-12	NC		XA5-8	XA5-C	176
XA3-13	NC		XAS-C	XAS-B	116
XA3-14	NC NC	i l	XAS-C	XAS-D	779
XAS-15			XA6-D	XAS-C	779
XA3-18	TB1-6	565 773	XA6-D	XAS-E	780
XA3-16 XA3-17	XA3-1 NC	775	XAS-E	XAS-D	780
XA3-15			XA6-E	XA6-2	781
XA3-19	NC		XA5-P	K1-C2	620
XA3-90	T2-10	645	XA6-F	XA6-6	797
XA3-21	72-11	646	XA5-1 XA5-J	XAS-J	782
XA3-22	T2-12	647	XA5-J	XAS-H XAS-K	782 785
XA4-A	TR1-4	566	XA5-1	XA5-K XA5-J	765 768
XA4-A	XA4-1	774	XA6-R	XAS-J XAS-L	768 464
XA4-8	782-50	723	XA5-L	XA6-K	784
XA4-C	782-21	268	XAS-L	XA5-7	785
XA4-D	1782-16	687	XAS-M	T1-1	567
XA4-E	N.C		XA5-M	XA5-11	801
XA4-P	NC .		XA6-N	XA6-P	786
XA4-H	E:26	5.29	XAS-P	XA5-N	786
XA4-J	NC		XA5-P	XAS-R	787
XA4-K	NC	1	XAS-R	XAS-P	787
XA4-L	NC:		XAS-R	XAS-6	786
XA4-M	J11-TP43	741	XA5-6	XA5-R	788
XA4-N	792-20	369	XA5-6	XA5-12	789
XA4-P	NC	1	XAS-T	K1-B2	621
XA4-R	NC		XA5-T	XA5-16	605
XA4-8	NC		XA5-U	XA5V	790
XA4T	J10-TP85	841	XA5-V	XA5-U	790
XA4-T	R18-1	227	XA6-V	XAS-W	791
XA4-U	NC		XA5-W	XA5-V	791
XA4-V	T83-19	370	XA5-W	XA5-X	792
XA4-W	R18-2	371	XA5-X	XA5-W	792
XA4-X	XD82-1	321	XA6-X	XA5-17	798
XA4-Y	T52-17	621	XA5-Y	K1-A2	622
XA4-2	T92-15	622	XAS-Y	XA5-21	in and a second
XA4-2	XA4-22		XAS-Z	NC NC	
XA4-1	XA4-A	774	XA6-1	NC	
XA4-3	721 SHLD	776	XA5-2	XA6-E	761
XA4-3	754 SHLD	775	XA6-2	XA5-3	794
*A4-3	67-1	724 872	XA5-8	XA6-2	794
XA4-4 XA4-6	79:-2	404	XA5-3	XA5-4	796
XA4-6	NC	404	XA5-4	XA6-9	796 796
XA4-7	NC		XA5-4	XA5-5	666
XA4-8	NC	i i	XA5-6	R22-2	796
XA4-9	l NC		XA5-5	XA5-4	797
XA4-10	NC NC		XA5-6	XA5-P XA5-L	785
XA:-11	NC NC		XA5-7	XA5-6	798
XA4-12	NC NC	į	XA5-7 XA5-8	XA5-7	798
XA4-13	NC		XA5-8 XA5-8	XA5-9	799
XA4-14	XAS-H	745	XA5-9	XA5-8	799
XA4-15	NC H	170	XA5-9 XA5-9	XA5-10	800
XA4~16	XAI-T	721	XA5-10	PL6-2	672

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

	7 -	Wine No.	Fram-	7	Wigne Mar.	
XA3-10	XA5-9	800	XASF1-8	TB2-30	7177	
XA6-11	XA5-M	801	XA6P1-C	J1-1793	493	
4A5-13	XAS-8	789	XA6P1-D	J1-1794	637	
JA5-12	XA5-13	802	XA6P1-E	TB2-21	745	
XA5-13	XA5-12	802	XA6P1-F	J1 —TP6	876	
XA5-13	XA5-14	803	XA6P1-H	J1-TP8	617	
Ka5-14	XA5-13	803	XAGP1-J	J1-TP9	618	
Kas-14	XA5-15	804	XAGP1K	J1-TP10	619	
KA5-15	R21-3	666	XD51-1	K1-D1	539	
Kab-15	XA8-14	804	XD81-1	TB3-316 K1-X2	239	
KAS-16	XA5-T	805	XD\$1-2 XD\$1-2	T1-4	454 453	
XAS-17	XA5-X	793	XD62-1	82-1	234	
XA5-17	XA53	306	XD62-1	XA4-X	321	
XA5-18	XAS-1?	807	XD92-1	TB2-14	408	
XA5-13 XA5-12	XA5-19 XA5-18	307	682 SHLD	£18	834	
XA5-19	XA5-20	808	682 SHLD	683 SHLD	850	
XA5-20	8.26-2	670	683 SHLD	682 SHLD	8.50	
XA5-20	XA5-19	808	690 SHLD	J10-TP50	763	
XA5-21	XAS-Y	1	600 SHLD	J23-a	752	
XA5-22	NC		691 SHLD	J10-TP47	183	
XAG-A	T62-19	760	40° 9HLD	J25-8	154	
XAG-A	XA6J1-10	373	692 SHLD	J10-TP98	164	
XAJ-B	J11-TP7	695	693 SHLD	XASJ1-3	814	
X AG-C	NC	Á	693 SHLD	694 SHLD	765	
y_ag-d	Blo	725	663 SHLD	701 SHLD	812	
XAG-B	J11-TP22	402	694 SHLI)	J12-T93	766	
XAG-P	TB1-11	523	694 3HLD	693 SHLD	765	
XA6-H	XA4-14	748	696 SHLD	696 SHLD	707	
XAG-J	T91-2	540	696 SHLD	700 SHLD	811	
ХА6—К ХА6—L	J11-1717	345	696 SHLD	J11-TP9	768	
XAS-M	J11-TP15	343 344	696 SHLD	695 SHLD	767 833	
XAS-N	TB1-14	524	698 SHLD 699 SHLD	J16-TP18 J26-TP16	840	
XAG-P	J11-TP32	348	700 SHLD	XA6J1-3	813	
XAG-R	TB1-3	588	700 SHLD	695 SHLD	811	
XA6-8	781-12	525	701 SHLD	693 SHLD	812	
XAG-T	TB1-22	526	702 SHLD	725 SHLD	815	
XA6-U	2 11	726	702 SHLC	726 SHLD	816	
XA8-V	NC		703 SHLE	J10-TP16	758	
XAG-1	Jul-TP1	693	703 SHLE	J17-G	748	
XA6-2	TB3-20	701	704 SHLE	J10-TP19	739	
XA6-3	693 SHLD	814	704 SHLD	J17-R	750	
XA0-3	700 SHILD	813	705 SHLD	J10-TP26	760	
XA0-4	726 SHILD	817	706 SHLD	J25-D	755	
XA6-5	NC	Š	109 SHLD	J18-TP15	8.15	
XA6-6	NC	•	712 SHLD	J10-TP7	756	
XA9-7	NC		712 SHLD	J17-0	749	
XA6-8	TE1-10	702	71.3 SHLD	JIO-TPIL	757	
XA6-9	TB1-1	589	713 SiiLD	J17-V	751	
XA8-10	XA6J1-A	373	714 SHLD	J10-TP30	761	
XAG-11 XAG-11	TB1-6	568	714 SHLD	J25-9	753	
XA6-12	XA6J1-16 TB1-17	809	718 SHLD	J18-TP19	838	
XA6-13	J11-1735	569	719 SHLD	E16	\$18	
XAG-14	NC	349	721 SHLD	XA4-2	176	
XA6-15	727 SHLD	810	722 SHLD 722 SHLD	E17	529 830	
XA6-16	XA6J1-11	809	722 SHLD	E17	845	
XA9-17	J11-TP20	347	724 SHLD	XA4-2	775	
XA6-18	K4-B2	777	725 SHLD	702 SHLD	825	
XAGP1-A	JI-TPI	400	726 SHLD	XA6J1-4	817	
	*		NE PROPERTY AND A SECOND PROPERTY AND A SECO	1 4 2 4 2 4 B	F 40 40 40	

Table 3-42. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2 Wire List - Continued

Prose-	*	Was No.	Pennis -	**	Was No.
726 SHLD 727 SHLD 729 SHLD 730 SHLD	702 SHLD XAGJ: -16 E17 E17	816 810 831 832	731 SHLD 742 SHLD 743 SHLD 777 SHLD	E18 J11_TP38 J11_TP24 TB2_?	170 160 836

3-53. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List.

The wire list for unit 2 is presented in table 3-43. The wire list will be an aid to the repairman when testing or troubleshooting unit 2.

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List

	**	Wee Mo.	* 2000-	70-	Wass Mar.
33-83	XA5-6	684.A	25	XA6-A	5.30
20-23	XA13	694B	08	XA7-A	531
31-61	J4-199	6998	5 7	4-1733	3.8.5
311-53	4-176	399A	87	J4-179101	4.25
20-1	87-96	372	87	87-9	765
33-3	87-W3	376	83	Ca POS	512
33-3	87-93	375	2	200	760
33-4	87 94	374	1 23	XA1-8	524 565
23- -6	82-6	791		XA2-M	160
Barre &	815-3	377	1	25	T-CAS
20-0	102 -6	791	D	810-3	487
31-93	4 TP16	699C	1	J1-1714	5.64
CI NEG	C2 NBG	765	89	XA3-M	543
C1 NRG		433	89	XA4-13	612
CI NEG	J3-17943	522	810	CS NEO	761
C1 POS	J317948	500	B10	811	601
C1 POS	C3 POS	770	310	XAI-0	404
CI POS	J5-125	563	E 10	XA2-N	761
C3 N3O	C1 NBO	765	811	819	120
C3 NEG	C3 NBC	746	E11	h-1913	505
C2 POS	C1 PO8	770 771	B 11	J3-1747 XA3-N	60.5
C2 POS	C3 POS	766	211	XAA-L	606
C3 NEO	C2 NEO C4 POS	767	E11 E12	n-1750	6383
C3 NBG	C2 708	771	1 E12	Ja-191	230
C3 POS C3 POS		572	1 213 213	J2-1751	634
C4 NEG	CS NRO	772	E13	J6-TP2	640
CA NEG	J5-176	500	814	J1-1762	635
CA POS	C2 NRG	767	B14	16-TP3	641
C4 POS	CS POS	763	E15	12-1756	520
CS NEG	CA NEG	772	I E16	E17	762
CS NRG	Ca NEG	773	E16	1-1927	418
CB POS	CA POS	700	B16	J2-1748	515
C3 POS	Ce POS	769	E16	35-7714	523
CB NEG	CS NEG	773	l E16	XA4-6	627
CS NEG	810	612	B17	B16	162
CS POS	CS POS	769	E17	Ria	763
En .	C1 NEG	432	I E17	J3-TP:01	421
81	80A-8	633	817	XAI-A	5.34
81	80C-11	634	817	XAS-T	5.25
	R8-D	792	217	XA3-T	5.26
23	. R6-B	428	818	P.17	763
24	811-7	430	818	1:33	793
5 4	TB3-6	426	E18	452 SHLD	71.
23	XA5-1	528	£18	568 SHLD	719
SS	584 SHLD	749	E19	J1-TP44	554
25	701 SHLD	751	E19	J2-TP22	5.67

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Page -	1	Wiles No.	Free -		***
819	15-78-23	648	J1-18:1	<i>1 1</i> 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	
850	J1-1931	661	11-TP11	SS-6	6788
220	XA4-A	660	A1-1712	11-12	595
521 521	J1-TP47 -35-TP26	555 569	J1-1712 J1-1718	673 SHLD	706
E31	XA1-6	576	J1-7918	J1-13	6.9.
E2:	XA4-2	567	J1-1914		457
522	J1-TP45	667	J1-1914	J1-14	450
532	J2-1746	652	J1-TP16	J1-16	
222	XA1-6	669	J1-7915	J3-TP96	210
532 E22	XA4-M J2-TP49	661 668	J1-1916 J1-1916	J1-16 J3-77-26	10
	A-1746	592	31-1716 31-1717	J1-17	211
R24	13-17-00	594	Ji-1917	J3-TP97	912
E24	XA1-9	615	J1-1718	E26	691
224	XA4-3	607	J1-TP18	J1-18	681
825	J1-1718	591	J1-TP10	NC	
825	23-1713	593	J1-17-20	NC	ř.
E25	45-TP10	600	J1-TP21	J1-21	661
226	21-1749	517	J1-1721	J5-1718	456
236	12-17-23 13-19-23	618	Jn-17922	J1-22	452
836 828	XD41-2	521 260	J1 - TP21 J1 - TP23	35-7718 51-29	459
H23	XD62-2	360	21-17-23 21-17-23	XA4-C	650
E31		463	31-1924	11-24	394
832	X 288-2	861	J1-1924	660 SHLD	100
833	Ere,	793	J1-17924	674 SHLD	707
233	660 SHLD	744	J1-TP25	NC	
E33	661 SKLD	712	J1-7P26	NC	
E33 E32	667 SHLD	700 832	J: -1927	E16 J1-27	416
633 837	34-TP46	466	J1-1721 J1-1728	J1-28	17
E31	510-8	573	J1-1728	J3-TP60	213
E37	XAI-C	385	J1-TP29	J1-29	19
E38	87-1	389	J1-7728	J3-TP54	674A
£39	J1-TP64	556	JI-17930	JI -80	2.0
239	J2-TP50	545	J1-7930	J3-TP55	6748
87 87	J1-1742 J2-1768	501 507	J1-17J1 J1-1732	NC J1-32	22
57 J1—T91	31-1	1	J1-7932	J2-1796	214
J1-171	83-1	670A	J1-1753	J1-88	25
J1-172	J1-776	710	J1-7938	J2-1797	216
J1-TP2	J1-2	2	J1-TP34	NC	(Head
J1-TP2	S1-3	670B	J1-TP35	J1-35	25
J1-173	J1-8	390	J1-1735	J2-T 798	216
J1-173	610 SHILD	702	J1-TP36	J1-36 J2-7P99	217
J1-TP4 J1-TP4	/1-4 65-4	671A	J1-TP36 J1-T737	E20	661
J1-174 J1-775	J1-7P2	710	J1-1737	J1-37	27
J1-176	11-5	4	11-1728	J1-36	395
J1-TP6	83-2	6718	J1-7738	661 SHLD	708
JI-TP6	11-6	391	J1-TV39	11-30	\$40
JI-TPS	671 SHLD	703	J1-TP39	J5-7711	55%
JI-1777	21-7	5	J1-T740	J1-40	541
J1-TP7	83-5	572A	J1—TP40 J1—TP41	J5-TP12	553 490
J1—TP8 J1—T P 8	31-8 53-7	572B	J1-1741 J1-TP41	J2-TP57	500
J1—179	J1-9	392	J1-TP42	E7	501
J1—179	672 SHLD	704	J:-TP42	J1-42	491
J1-TP10	J1-10	7	J1 -TP43	J1-43	2.8
J1-TP10	53-8	673A	J1-TP43	J2-7P49	218

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Prome-	**	Wipe No.	FP4666		Wigon Mos.
G-7844	819	5.54	J1-26	NC	**************************************
13	11-44	542	JI-37	J1-1127	17
	822	667	J1-28	J1:-12:23	1.8
1-1945	J1-48	269	J1:20	J1-TP29	16
12-79-40	834	592	J1-30	J1-77930	30
1-1940	J1-46	582	J1-31	NC	I
n	521	555	J1-32	J1-7733	23
/±-1947	1247	543	J1-33	J1-7733	23
V); -TP48	NC.		J11-34		
h-17943	220	517	J1-35	J17736	215
12-17749	J1-49	510	J1 36	11-7736	34
11-7750	812	633	11-37	1117937	27
n-1750	J1-60	620	Ja- 38	11-17734	201
11-77-11	313	634	11-20	J1-7730	540
*1-7961	11-61	631	J1 -40	J1 - 1740	641
11-7952	\$14	635	J1 -41	J1-174)	4.30
12-7952	J1-02	912	11-42	31-7743 31-7742	451
11-11763	NC .	444	J1:-43 J1:-44	J1-7744	642
31 - 1964	839	544		11-4948	23
11-1764	A Committee of the Comm	30	Ji-45 Ji-46	11-4744	843
11-1756	11-55 14-790	225	11-47	112747	54.3
/\- 1755 il-1756	anc:	440	J1-43	MC.	940
11-17-17	J1-67	623	11-40	11-77949	610
2 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 -	12-17-13	636	J1-60	11-1790	6.23
	J1-48	624	J1 - 4.1	J1 TPS1	621
1-1968	12-174	837	11-42	J1-77952	622
n-1140	11-50	025	11-43		4:4:4
/1-PP50	12-17-56	63.9	11-64	11-47914	644
11 - T2 840	NG:	-	J1-66	J11756	100
/1- 176 1	11-41	12	31-54	NC:	
1-7761	97-91	388	I 11 - 47	11-7797	423
11 - 1993	NC.		Jt-60	J1-7758	624
11 - 7943	NC		11-50	J1-1760	6.34
11-1764	J1-64	31	J:-60	MC	
11-7784	J2-TP:01	321	J1-61	J1-7791	12
11-1	J1-YP1	1 1	J:-42	NC	
1:-2	J1-TP3	2	J1:-63	NC	
1-3	J:-TP3	390	J1-64	J1-7794	24
Ft-4	J1-TP4	3	J2-1791	J2-1	4.4.1
11-6	J1-TP5	4.	J22-TP1	J3-TP1	434.
, ***	J1-1798	391	J2-772	J2-9	374
Jt - 7	J1-TP1	6	J2-172	J3-773	419
st - a	11-7779	6	J2-1773	J2-3	6.24
11 - 9	J1-179	392	J2773	J3-T73	4.3.1
it = 10	J1TP10	7	J2-TP4	13-4	52
A T T T T T T T T T T T T T T T T T T T	J1-/1711		12-T94	J3-T74	694.
1-12	J1-7713	393	J2-T79	J3-5	34
11-13	J1-1713	580	J2-175	J3-TP5	693
\$114	31-1714	450	° 12-170	13-6	34
31 ··· 15	J1-1715	9	J3-776	J3-T76	6954
71-15	J1-7716	10	12-177	J2-7	327
<i>i</i> 1 - 1 7	J1-TP17	11	J2-TP7	695 SHLD	
2118 	J1-77718	381	J2-T78	J2-8	35
J1=19	NC	i.	J3-TP9	J5-TP8	636.
11 20	NC .	**************************************	J2-T79	J3-9	35
11-21 11-21	J1-1721	451	12-175	J3-T79	6361
Σ1 == 12 Ε1 == 42	J1-1723	452	13-TF10	J2-10	37
/1-23	11-1723	14	J2-TP10	J3-TP10	6.56
/1-24 /1-26	J1-7724	394	J2-TP11 J2-TP11	J2-11	398

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

	****	Wigns Man-	*****	***	
In-1718	86-18	8.8	J9-7743	23-7942	23.2
45-1712	18-7712	223	19-1745	12-43	6.3
J2-5713	38-13	39	J2-7748	25-77-cs	5.3.9
39-7718 43-7714	XA4-N 22-14	223 40	32-1744 32-7744	12-44 12-17-4	6.6
43-1714 43-1714	10-7914	675A	12-7745	12-45	\$4.0 6.5
J3-7916	26-15	41	32-17745	18-TP46	241
J3-7716	35-7716	CTLB	22-1746	222	8.53
22-4706	J2-16	290	J2-1746	32-46	6.6
32-2714	ers sald	712	42-1747	28-47	404
31-4911 33-7911	33-17 33-17-17	62 678A	22-1741 22-1748	662 SHLD	716
	32-18	42	19-79-6	12-68	619
12-TP16	45-17:18	6768	12-4949		66.5
79-7719	22-19	400	23-T748	32-43	67
15-7919	ete sello	718	48-4760	J2-60	405
/s-73%	12-30	64	12-17-50	668 SHLD	716
	43-47780 25-81	402 45	J9-7761 -22-7761	12-6: 42-776:	85
	39-7921	5.03	19-19-6	NC.	363
79-21		667	12-17-11	J1-7767	636
Ja-7741	25-52	453	29-1768	J2-63	627
Ja-7713	2:25	51.6	23-TP64	11-11P48	627
15-17-25	J2-25	401	12-7764	12-64	623
23-7734	22-24	46 224	J2-1756	J1-TP69	62.6
33-1754 35-2728	20-20	47	J2-TP65 J2-TP66	Ens.	629
Ja-79:11		225	10-7956	12-46	512
16-77726	12-15	402	J2-1751	J1-7741	500
10-7750	677 SHLD	714	J9-7757	J2-67	492
Ja-17927	39-32	4.8	J2-1748	E7	507
Ja-77771	25-77-27	677A	J2-TP18	J2-68	493
73-7723 73-7724	22-93 25-7728	49 477B	J2-TP60 J2-TP60	E39 J2-40	565
J2-77:19	12-13	60	32-3360	J8-T760	54.6
J2-77756	25-17:20	2:25	J2-11%1	J2-61	70
J2-7770	22-30	403	J2-1761	J3-TP61	24.5
J3-T710	COT SHILD	716	12-11-62	J2-62	71
22-TP21	72-51 75-7751	51 697A	J2-TP62	JS-TP62	246
Jo-7701 Jo-7702	12-12	62	/2-7765 /2-7765	J2-63 J3-TP65	71 247
22-7732	15-77-2	697B	12-7764	12-64	78
J2-1733	22-53	6.3	J2-TP64	J3-TP64	248
J2-7723	J3-7733	697C	J2-TP65	J2-65	74
13-1754	12-34	54	12-1766	J3-T765	249
12-1734		230 65	J2-1766	22-66	75
J2-7735 J2-7735	32-35	221	J2-1766 L J2-1767	J3-TP66 J2-67	250
12-7734	22-16	56	J2-1747	JS-1767	251
12-77'36	13-7736	232	/2-TP68	NC	
29-1717	22-87	67	12-1760	J9-60	77
J2-7737	J3-77777	233	J2-T700	J3-TP00	252
12-1715	22-58 22-58	58	J2-7770	J2-70	78
23-7738	J3-T738 J2-39	234 59	J2-TP70 J2-TP71	J3-TP70 J2-71	253 79
J2-7739 J2-7739	33-TP39	235	J2-TP71	J2-TP71	254
12-1740	32-40	60	J2-TP72	J2-72	80
J2-1740	J3-TP40	236	J2TP72	J3-TP72	255
12-1741	12-41	61	J2-TP73	J2-78	61
J3-TP41	13-7P41	237	J2-TP73	J3-TP78	256
J3-T742	J9-42	62	12-TP74	32-74	62

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Para	15	War. No.	Frem -	70-	Wine Me.
JO-1714	J3-1974	257	J2-14	J2-T714	40
10-1715	J2-75	63	J2-15	J3-7715	41
J2-T715 J2-T716	J3-7775 J2-76	158 54	J2-16 J2-17	J2-TP16 J2-TP17	399 42
12-17/6 12-17/6	13-1774	259	J2-18	J2-TP18	43
Ja-1777	J2-77	85	J2-19	J2-TP19	460
13-17-17	J3-1777	260	J2-20	J2-TP20	44 45
J2-T773 J2-T778	J2-18 J3-1718	262	J3-31 J2-22	J2-1721 J2-1722	453
J2-1719	12-79	87	J2-23	J2-T723	491
13-1779	J3-1919	262	J2-24	12-1724	46
J9-1760	J3-50	88 263	J2-25 J2-26	J2-1725 J2-1726	47 492
J21780 J21781	J3-TP80 J3-81	39	12-27	J2-TP27	48
J2-TP31	J3-7761	254	J2-28	J2-T726	49
J3-T792	J2-82	90	J2-29	J2-1739	50
J2-1792	J3-TP63	265 91	J2-30 J2-31	J2-TP30 J2-TF31	463 51
Ja-TP43 J2-1P43	J2-63 J3-7762	266	J252	J2-TP32	52
J2-1784	NC		J2-33	J2-17933	53
J3-1795	J2-65	92	J2-34	J2-7734	64
J2-1795	J3-7746 J2-86	698A	J3-35 J2-36	J2-T736 J2-T736	55 56
J2-1704 J2-1706	J3~TP86	4963	12-37	J2-7727	57
J2-1797	12-87	94	J2-38	J2-1738	540
12-1761	J3-TP87	699C	J2-59	J2-1738	4.9
J2-7798	J2-66 696 SHLD	407 720	12-40	J2-TP40	60
J2-1788 J2-1789	NC SILLO	720	J2-41 J2-42	J2-TF41 J2-TF42	
J2-7790	NC		J2-43	J2-TP43	63
J2-1791	NC		33-44	J2-7744	64
J2-1792 J2-1798	NC J2-93	96	12-46 12-46	J2-7745 J2-7746	65
J2-1793	J3-T794	267	22-47	J2-1747	494
J2-T794	J2-90	96	J2-48	J2-TP48	611
J2-TP94	J3-TP94	268	J2-40	J2-T740	67
J21798 J21796	NC J1-TP32	214	J2-50 J2-51	J2-T750 J2-T751	405
J2-T796	J2-96	97	J2-62	NC	
J2-1797	J1-7793	215	J2-63	J2-TP63	627
J2-TP97	J2-97	98	J2-64	J2-TP54	623
J2-1798 J2-1798	J1-T735 J2-96	216 99	J2-66 J2-56	J2-T755 J2-T756	629 512
J2-TP99	J1-TP86	217	J2-67	J2-1757	492
J2-1799	J2-99	100	J2-58	J3-T758	493
J2-17100	NC		J2-60	J2-T760	69
J2-17101 J2-17101	J1-TP64 J2-101	221 101	J2-61 J2-62	J2-TP61 J2-TP62	70 71
J2-1	J2-17:	480	J2-63	J2-T763	72
J2-2	J3-T72	396	J2-64	33-T?24	73
J2-8 J2-4	J2-T73 J2-T74	626 32	J2-65	J2-TP65	74
J2-5	J2-176	33	J2-66 J2-67	J2-TP66 J2-TP67	75 76
J 2-6	J3-176	34	13-68	NC .	
32-7	32-777	397	13-69	J2-TP69	77
J 2- 8 J 2-9	J2-178 J2-179	35 36	J2-70 J2-71	J2-TP70	78
J2 -10	J2-TP10	37	J2-72	J2-TP71 J2-TP72	79 80
J2-11	J2-TP11	398	J2-73	J2-T773	81
J3-12	J2-7712	38	J2-74	J2-TP74	82
J3-13	J2-TP13	1 19	J2-76	JO-1776	53

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Prom-		Was No.	Fram-	70-	2.
J2-16	J2-7776	£4	J3-TF18	J3-18	111
13-11	12-1711	#5	J3-7719	JS-19	412
32-78 32-76	J2-1718 J2-1719	86 87	23-7719 23-7720	676 SHLD #2—TP20	831
31-00	J2-7790		43-17:20	13-20	502 495
J2-61	J2-1701	89	J3-1721	J2-7721	508
12-62	J2-1763	90	JS-TP21	J3-21	496
J2-03	12-1783	91	J3-22	E19	556
J2-84 J2-85	NC J2-T765	92	J3-7P22 J3-7P23	J3-22 E26	546
J2- 8 6	J2-7766	93	J3-1723	J3-23	521 513
J2-67	J2-1787	94	JS-TP24	J2-TP24	224
J2-65	J2-TP66	407	J3-TP24	J3-24	112
J2-40	NC .		J3-1725	J2-T726	225
J2-0 0 J2-0 1	NC NC		J3-7725 J3-7726	J3-26 R21	113 550
J2-92	NC NC		23-1726	13-26	EAT
J2-93	J2-T790	96	J3-TP27	J2-TP27	STYA
33-94	J2-7791	**	J3-TP27	J3-27	114
/2-0 5	NC J2-7786	97	J3-T726	J3-7728	617B
12-06 12-07	22-17-97	94	33-7728 33-7729	13-28 12-77-20	116
J2-66	J2-1798		J3-TP29	J2-20	iie
3-00	J2-T760	100	J3-7730	E24	.594
J2-100	NC		JS-7730	J3-30	614
J2-101	13-22101	101	J3-7731	J2-1731	697A
J3-771 J3-771	J9-TP1 J3-1	484 481	J3TP31 J3TP32	39-81 32-7732	117 697E
J3-172	32-TP2	419	J3-1732	13-32	118
43-TF2	39-2	408	43-TP33	J2-T733	697C
13-173	J2-1173	486	33-TP38	12-33	119
13-173 23-174	23-3 23-774	483 696A	#3-TP34 #3-TP34	J2-TP34 J3-84	230 120
13-174	3-4	102	33-1726	12-1725	281
J3-175	J2-175	6958	43-TP35	J3-35	121
J3-175	J3-6	103	J3-TP36	J2-TP36	232
J3-176	J2-176	695C	J3-T736	J3-36	122
33-176 33-777	23-6 23-7	104 409	J3-7737	J2-TP87 J3-87	233 123
33-177	696 SHLD	825	J3TP37 J3TP38	J2-TP38	234
J3-178	J2-178	696A	J3TP38	J3-88	124
J3-777	23-0	106	J3-1739	J2-TP36	235
J3 ² -779	32-7779	696B	J3-TP39	J3-39	125
43-1779 43-17710	33~9 32~7₹10	196 696C	J3-TP40 J3-TP 40	J2-7740 J3-40	236 126
J3-7710	33-10	107	J3-TP41	J2-1741	237
J3-17:11	43-11	410	J3TP41	J3-41	127
J9-1711	696 SHLD	829	J3-T742	J2-1742	236
J3-7712	J2-T712	222	J3-TP42 J3-TP43	J3-42 J2-TP43	125 230
13-1712 13-1713	43-12 E25	494 593	JS-1743 JS-7743	23-1743 23-43	129
J3-17 13	J3-13	583	J3-TP44	J2-TP44	240
J3-TP14	J2-TF14	675A	J3-T744	J3-44	130
J3-17:14	J3-14	108	J3-TP45	J2-TP45	241
13-17: 15 13-17: 15	J2-7715 J3-15	675B	J3-TP45 J3-TP46	J3-45 C1 POS	131 560
33-1715 33-1716	33-16	411	J3-TP46	J3-46	548
J3-1716	675 SHLD	830	J8-TP47	B11	595
J3-7717	J2-TP17	675A	J3-TP47	J3-47	584
J9-1717	33-17	110	J3-TP48	CI NEG	522
39-1718	J2-7718	6768	J3-TP48	33-48	614

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Proces-	*	Wina No.	Process -	70-	94
73-474	J1-1743	218	J3TP19	J3-79	16
J3-1740	J349	132	J3-TP80	J2-1780	261
10-1750	J1-TP23	213	J3-1780	J3-80	160
J3-T750	J3-50	133	J3-T781	J2-TP81	254
J3-TP51	J2-17951	243	J3-TP81	J3-81	16
J3-17951	J3-51	134	J3-TP63	J2-TP82	100
13-17932	J3-53	135	J3-TP83	J3-82	16
J3-1753	XA4-R	6789	J3-/1783	J2-77963	25
13-77753	J3-53	136	J3-TF63	J3-83	160
J3-1P53	XA4-P	678A	J3-TP84	J3-84	16
J3-179-54	J1-TP29	674A	J3-TP84	XA4-13	6.5
13-1794	J3-54	137	J3-1785	J2-1785	00
J3-17955	J1-TP30	6748	J3-TP95	J3-85	16
J3—TP65	J3- 55	138	J3-1796	J2-1788	6.0
J3TP50	J3-58	139	J3T986	J3-86	16
13-1758	XA4-15	679A	J3-1787	J2-TP87	69
J3-TP57	J3-57	140	J3-1787	J3-87	17
J3-TP57	XA4-14	6798	J3-TP88	J3-88	41
13-TP58	J3-53	141	J3/1788	898 SHLD	
13—1758	XA4-8	653	J3-TP80	NC	
J3-7759	J3-59	142	J3- TP90	NC	
13-77750	XA4-D	654	J3-TP91	NC	
J3-1700	J2-TP60	244	13-TF92	NC	
J3-TP60	J360	143	J31793	J2-T793	26
JO-TP01	J2-T761	245	J3-TP93	J3-93	1.7
13— TP6 1	J3-61	144	J3TP94	J2-TP94	24
13-1763	J2-TP62	240	J3-/TP94	J3-94	11
J3-TP63	J3-62	145	J3TP96	J1-TP15	21
J3-TP63	J2-TP63	247	J3-TP96	J3-95	17
J3-TP63	J363	146	J3-TP96	J1-TP16	21
J3-TP64	J2-TP64	248	J3-TP96	J3-96	17
13-1764	J3-64	147	J3- TP97	J1-TP17	21
J3-TP65	J2-TP65	249	J3TP97	J3-97	17
J3-1765	J3-65	148	J3-TP98	NC	
J3-1766	J2-TP66	260	J3-1799	NC	ŭ.
10 -1760	J3-66	149	J3-7P100	NC	
J3-1767	J2-T#67	251	J3-TP101	E17	42
J3 -1767	J3-67 J1-TP55	150	J3-TP101	J3-101	17
J3-T768	J3-68	220	J3-1	J3-TP1	48
J31768 J31769	1 -0 -0	151	J3-2	J3-TP2	40
13-75500 13-75500	J2-TP69	25.2	J3-3	J3-TP3	43
	1 -0 -0	152	J3-4	J3-TP4	10
13-7970	J2-TP70	253	J3-6	J3-TP5	10
13-TP70	J3-70	153	J3-6	J3-TP6	10
13—1797) 13—1797)	J2-7771	25.4	J3-7	J3-TP7	40
13-1771 13-1772	J3-71	154	J38	J3-TP8	10
13-1772 13-1772	J2-TP72	255	J3-9	J3-TP9	10
13-1773	J2-TP73	1 55 256	J3-10	J3-TP10	10
13-1773	J3-73	156	J3-11	J3-TP11	41
13-1713 13-1774	J2-TP74	257	J3-12	J3-TP12	49
13-1774 13-17974	J3-74	L	J3-13	J3-TP13	58
13—1774 13— 77 75	J2-7775	157 258	J3-14	J3- TP14	10
13-1775 13-1775	J3-75	I 18	J3-15	J3- TP15	10
J3-1778	J2-TP78	158 259	J3-16	J3-TP16	41
13-1776	J3-76	159	J3-17	J3- TP17	11
J3-1777	J2-TP77	260	J3-18	J3-TP18	11
J3-1777	J377	160	J3 -19	J3-TP19	41
J31?78	J2-TP78	261	J3-20	J3 TP20	49
10-1718	J3-78	161	J3-21	J3-TP21	49
J3-T979	J2-TP79	1 101	J3-22	J3-TP22	54

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

*****	-	Wign.	Programme von	70-	We.
3-94	32-77%	118	J3-66	JS-1786	160
J3-25	13-1725	113	JS-86	J3-TP86	169
J3- 25	15-17:36	547	15-61	JS-1761	170
19 9 7 19 98	JS-17:57 JS-17:28	114	13-68	JS-1766	418
4-8	J3-1729	115 116	J3-89 J3-90	NC NC	
14-80	23-1729 23-77:50	614	13-01	l RC	
J3 81	J8-7731	117	J3-92	l NC	
19-32	JS-11932	1116	25-05	JS-TP08	121
23-23	15-17:55	119	33-04	JS-TP94	172
JS-84	18-17934	1.20	JS-95	JS-1795	178
13-35	J3-TP25	121	JS06	J9-T790	174
13-56	45-17:56	122	JS-91	JS-TP97	176
J9-87	JS-TPST	123	JS-48	NC	
13-63	49-17738	124	39-00	NC NC	I
19-59	25-79:39	125	JS-100	NC	
13-40	75-1740	126	JS-101	JS-TP101	176
JS-41	JS-1741	1.27	J4-171	34-1	469
JS-42	JS-1743	129	J4-TP1	XA6-6	486
/3-43	J3-1743	120	J4-TP3	4-1	414
13-44 13-46	3-174 3-174	180	Je-178	XA6-18	622
13-45 18-46	35-7946	131 648	J4-193 J4-194	34-S 34-TP6	687 721
13-40 13-47	25-17941	5.84	Je-TPe	2-14.8	8.9.8
J3-48	J2-T248	514	34-176	14-1P0	722
13-49	JS-TP49	122	J4-1795	14-6	839
J3-50	JS-1750	188	J6-176	J4-TP10	728
J9-61	J9-17951	184	J4-TP6	J4-6	840
J3-62	JS-T7962	135	J4-797	J4-TP11	724
13-63	JS-1753	1.26	14-777	34-7	861
18-64	JS-TP54	137	J4-TP8	B!-62	A669
J\$-65	15-TP65	188	74-45-8	J4-174	721
15-66	25-17966	130	J4-1798	14-6	177
J3-57	J3-1767	140	J4-178	P -61	609B
1368 1369	J3-TP68 J3-TP69	141 142	J4-TP9 J4-TP9	.4-TP6 B2-62	722
18-02	J5-TP80	142	J4-1P0	14-0	178
13-61	J3-1761	166	J4-TP10	82-63	699C
13-62	JS-1762	145	J4-TP10	J4-1796	723
13-63	JS-7763	146	Ja-TP10	J4-10	179
19-64	J3-TP64	167	J4-TP11	J6-TP7	724
13-65	43-TP65	148	J4-TP11	J4-11	415
13 -6 8	J3-TF66	149	14-TP11	699 SHLD	725
J367	JS-TF67	150	J4-1712	J4-12	497
19-48	J31768	151	J4-1712	XA5-9	504
15-69	39-1749	162	34-TP19	J4-18	585
J3-70	JS-7770	163	J4-1718	XA1-21	603
13-71	33-TP: 1	154	34-TP18	XA6-W	593
18—12 13—13	J3-TP72 J3-TP72	156 166	J4-7914 J4-7914	34-14 XA6-18	642 382
13-74	J2-1774	167	34-1716	J4-16	643
13-76	JO-7775	158	J4-TP15	XA6-3	882
13-76 13-76	J3-7P76	159	34-TP16	J4-16	844
10-17	J3-1977	160	34-1717	34-17	180
18-78	J3-T716	161	J4-TP17	XA5-14	269
13-79	J3-TP79	162	J4-TP18	J4-18	181
18-80	JS-TP80	163	J4-TP18	XA5-11	335
I8-81	J3-TP81	164	J4-TP19	J4-19	845
18-82	J3-TP82	165	J4—TP20	J4-20	498
10-03	J3-TP83	166	J4-TP20	85-3	505
J 3-8 4	J3-TP84	167	J4-TP21	J4-21	490

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

har	*-	Was No.	Press-	*-	*
14-178II	85-3	504	4-1758	24-68	197
J4-1722	4-2	846	4-7766	XA6-R 34-59	256 186
44-1918 44-1918	14-49 XA4-K	416 425	J4-1769 J4-1769	XAS-H	247
4-174	J4-24	182	J4-T760	4-46	199
Ju-1774	XA1-10	271	J4-1760	XA7-8	636
H-1725	4-25 XA7-6	1.53 272	и—Т761 и—Т762	4-61 4-62	# # # # # # # # # # # # # # # # # # #
4-1725 4-1726	14-25	549	J4-T763	4-63	443
A-1738	XAG-V	561	4-1764	14-64	863
A-1717	J4-37	847	J4— 776 5 J4— 7766	4-65 4-66	664 845
4-1729 4-1729	J4-25 J4-29	848 13	4-1747	24-67	200
34-7930	J4-30	586	4-1767	XA7-4	259
J4-1730	XAG-X	597	14-1700	J4:-48	801
14-1701 14-1702	J4-31 B7	385	.14- ??6 8 .14- ??6 9	89A-W2 J4-49	250 263
A-1713	1 14-32	850	J4-1749	XA7-9	291
A-1713	14-33	851	14-1770	J4-70	204
4-194	14-34	184	4-1770	XA7-3	293
14-1714 14-1716	890-1 J4-85	273 185	4-1711 4-1712	34-71 34-72	
4-1946	89C-3	274	J4-1772	14-13	443
J4-1736	34-36	186	14-7774	34-74	869
34-1794	880-1	275 187	14-7776	14-75 14-76	810
14-1737 14-1737	J4-87 88C-2	276	4-7976 4-7777	34-77	871 872
14-1798	J4-33	188	J4-1778	3418	873
J4-1708	890-3	277	4-1779	34-79	874
14-1719 34-1740	! 34-89 34-40	852 853	4-1780 4-1781	J4-86 J4-81	875 876
34-1741	1 24-41	854	4-1763	34-62	877
J4-1742	14-42	855	J4-7763	J4-63	878
J4-1743 J4-1744	34-43 34-44	856 857	4-1764 4-1764	J4-64 89C-W3	200
J4-1748	4-45	858	14-1795	4-85	879
J4-1746	E37	446	J4-1796	J4-86	840
J4-1746	34-46	560	4-1787	4-67	861
34-1746 34-1747	XAS-7	543 587	J4-7768 J4-7769	J4-68 NC	863
34-1247	VR3 AD	478	H-1790	NC	ľ
24-1747	X.NS-C	596	4-1791	NC	
J4-1748 J4-1748	34-48 XA3-16	515 424	J4-7793	MC	
J4-1749	14-19	189	14-1793 14-1793	34-93 39C-2	203 334
34-1749	XA7-7	278	J4-1794	HC	
14-7750 14-7750	J4-80 XA7-8	190 279	4-7796	4-95	267
J4-1751	14-61	369	J4-TP96 J4-TP98	89A-W3 J496	255 258
J4-T763	44-62	191	J41796	59A-W4	196
J4-1763	R31-8	300	4-1797	34-97	200
4-1763 4-1766	34-83 89C-W4	192	J4-7797 J4-7798	XA1-6	207
34-1764	34-64	193	J4-TP99	NC NC	
J4-1754	XA1-X	878	34-TP100	NC	
J4-1765 J4-1766	34-65 XA1-2	194 312	4-17101	B7	435
J4-1796	H-64	196	J4-TP101 J4-1	4-101 4-171	443
14-T706	89D-W3	354	J4-2	14-172	414
Jr1797	34-67	196	14-8	34-773	847
14-1757	1 890-1	255	J4-4	1 34-174	838

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

France -	₹•-	Wire He.	Fram-	70-	1
34-6	4-775	689	J4-66	J4-77966	865
4-6	14-776	840	J4-67	Je-7767	200
4-1	34-1171	841	J4 -6 8	J4-77968	201
4-6	14-179	177	J4-69	14-1760	203
₩- •	36-179	178	J4 -70	J4-7770	204
14- 10	34-1710	179	34-71	36-7771	EBB
4-11	34-TP11	415	34-72	J4-TP72	867
J4-12	34-7712	497	34-73	J4-1773	868
34—13 34—14	34—1713 34—1714	865 842	34-74	J4-7P74	869
##-15	4-TP15	643	J4-75 J4-76	34-TP75 34-TP76	870
J4-16	4-1716	840	J4-77	4-1777	871
J4-17	44-TF17	180	34-78	J4-TP78	i 872 873
J4-18	Ja-TP18	181	14-70	J4-TP79	874
J4-19	4-TP19	845	14-80	J4-1760	675
14-20	J4-77:20	498	J4-81	J4-TP81	876
14-21	34-77:21	499	14-62	14-TP82	877
14-22	34-7722	846	34-63	14-1783	878
J4-23	J4-1723	416	34-84	14-1784	205
J4-24	34-TF34	182	34-65	J4-TP66	679
34-25	34-TF25	183	J4-86	J4-TP86	088
J4-96	J4TF36	549	J4-87	J4-7787	881
J4-27	J4-7727	547	J468	14-TP68	881
J4-20°	M-T738	848	J4-89	NC	l
14-29	34-7729	13	J4 9 0	NC	
14-30	34-TP30	586	J4-91	NC	
J4-31	34-1731	849	J4-9 2	NC	
44-3 <u>1</u>	34-1782	850	34−9 3	J4-7793	206
J4-83	J4-TF33	851	34-94	NC	
14-34	Je-7734	184	J4-95	34-1 P9 5	207
J4-85 J4-86	J4-T785	185	J4-96	J4-TP96	208
44-35 14-37	34-TP36 34-TP37	186 187	J4 -9 7 J4 -9 8	J4-TP97 NC	209
14-38	24-TP38	186	34 -8 9	NC NC	1
	J4-TP20	852	J4-100	NC NC	1
J4-40	34-TP40	853	H-101	J4-TP101	617
J4-41	J4-1741	854	J5-TP1	E12	639
J4-41	Je-1742	855	J5-TP1	J6-1	630
14-43	34-1743	856	J5-TP2	E13	640
34-44	J4-TF44	857	J5-TP2	J5-2	631
J4-45	J4-TP45	858	J5-TP3	E14	641
J4 -4 6	34-TF46	550	J5-TP3	J5-8	582
J4-47	34-7747	587	J6-TP4	NC	ı
H-48	J4-1748	515	J5-TP5	NC	
¥ ~ 49	34-1749	189	35-TP6	C4 NEG	599
H-50	J4-TF50	190	J5TP6	J5-6	588
34-51	34-7751	859	J5-TP7	NC	
14-62	34-7752	191	J6-178	C1 POS	563
J4-63	34-7753	192	J5-TP8	J6-8	575
34-54	34-TF54	193	J5-TP0	NC	
14-45 14-46	J4-T755	194	J5-TP10	E25	600 569
34 -66 14-43	34-1756 34-1757	195 196	J5-TP10 J6-TP11	J5-10 J1-7939	562
J4-67 J4-68	34-1758	197	35-7711	J5-11	551
24-59 14-59	J4-TP59	196	J5-TP12	J1-TP40	553
34-6 0	34-1P60	199	J6-7712	J5-12	454
J4-61	24-TP61	860	J5-TP13	J1-TP21	458
34-62	J4-TP62	861	J6-TP13	J5-13	455
4-6 3	4-TP63	862	J5-TP14	E16	523
14-64	J4-TP64	863	J5-TP14	J5-14	516
	1	, ,		J5-15	15

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Page 1		Wwo No.	# 888188-W	7	Wign Mo.
J-870	15-16	1.8	W-8	84-4	324
JS-1917	NC NC		85-C	R5- D	175
J6-T913	J1-77933	459	R5-A	XA6-W	610
JS-47913	JS-18	456	46-B	E3	429
JS-T919	siC .		R4-C	S3-W5	168
JS-17920	NC		R3-a	XA1-2	3179
J5-TP31	NC	1	R3-B	52	792
J8-1733	MC	l	fis-B	XAI-T	309
15-7723	NC		R9-1	TB3-3	351
J5-1724	NC	į.	R9-2	89C-10	370
J3-77925	NC		R9-3	TB3-4	352
J9-17733	NC		R10-1	783-1	353
35-1	J6-171	630	R10-3	R21-1	350
35-3	33-173	631	B10-3	TB3-13	354
15-3	J6-TP3	632	R11-1	TB3-14	356
46-4	NC		R11-2	XAI-L	302
16-6	NC		R11-3	TB3-13	955
J5-6	J5-4P6	588	R13-1	793-16	358
137	NC		R.13-3	99C-12	271
35-8	J5-7778	575	R12-3	T93-15	357
15-9	NC	5.89	R31-1	R10-3	350 764
J5-10	J5-7710		R31-1	R21-2	764
J5-11	J5-4711	551 454	R21-2	R21-1	230
J5-13	JS-TP12 JS-TP13	455	R31-3	J4TP\$3 R2C	
J5-13 J5-14	J5-T714	516	82-3 62-2	XA2-A	325
J5-15	J6-T215	18	1 82-3 1 82-1	242-8	0.53
J5-18	J5-TP16	18	82-4	R3-8	243
J5-17	NC	1 .0	82-4	TP1	354
J3-18	J5-TP18	456	82-6	XA2-P	127
J519	NC	400	1 32-4	XA2-C	331
J@-20	NC NC	1	43-W1	XA2-U	630A
J6-21	NC	ĺ	83-W2	XA2-V	6309
J8-23	NC		83-W3	XA3-U	691A
J5-23	NC		83-W4	XAS-V	651B
J5-24	NC		83-775	Re-C	1 262
J3-25	NC		1 83-W6	NC	
J5-25	NC		83-1	J1-791	610A
Q1-B	XA6-20	570	83-2	J1-775	671B
Q1-C	TB311	462	83-3	J1TP2	8709
Q1-C	XA6-V	461	83-4	J1-TP4	671A
Q1- B	SSC-W1	319	S3-5	J1-777	672A
Q1—E	XAS-D	4 30	S3-6	J1-TP11	613B
Q1-E	XA7-12	467	S3-7	J1-1798	6723
93- 9	XA6-21	611	83-8	J1-TP10	673A
63-C	TB3-10	477	83-0	XAI-X	262
93-C	XA6-X	476	83-10	XAI-Z	283
63-8	XAG-B	475	83-11	NC	
R2-A	XA1-8	307	S3-12	NC	
R2-B	XA1-16	320	84-1	R4-C	305
R3-C	52-3	362	84-2	XA3-A	328
133-B	R3-C	774	84-3	XA3-E	339
R3-A	T93-26	387	84-4	R5-B	366
R3-A	XA2-B	558	84-4	TP2	36?
R3-3	83-4 Ba B	363	84-6	XA3-P	330
R3-C	R3-B	774	S4-6	XA3-C	380
R4-A	XAI-R	308	85-2	J4-TP21	506
R4-B M-C	XA!-13	317	85-1	NC	
R3-B	\$4-1 P5-C	385	95-3	J4-TP20	505
R5-A	R5-C	775	S5-3	XD84-1	369
my h	XA3-B	688	86- 1	NC	1

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

	**	Wwo No.	Frank	T	Vur
86-3	85-8	217	Sub-6	Sep-4	
86-1	XA7-19	671	SSD-7	\$6B-5	822
Si-3	XA5-6	323	SSD-7	XAI-7	81.5
85-4 85-5	93 -6	776	\$2 5 -8	SSB-6	821
S6-6	86-2	777	856-8	SEB-0	826
82-4	36-4 XA5-10	778 254	SSB-9 SSB-9	SSB-6 XAI-F	825
87-41	J1-TP61	234 288	85B-10	8: 3-W2	229 781
87-W2	B2-2	276	88A-11	898-W1	760
67-W3	5/2-2	373	68B-12	S9A-W1	779
S7-W4	B2-4	374	66C-W1	Q1-E	319
S7-95	B2-3	875	68C-W1	89C-W1	794
57-W6	89-1	919	88C-1	J4-TV56	276
87-1	E38	380	88C-2	J4-TPS?	276
87-3	E7	795	S8C-8	A-TPS8	277
87-3	XA5-N	101B	SOA-WI	SSB-19	779
87-4 87-6	XA5-D XA5-M	700B	89A-W2 89A-W3	J4-TP68 J4-TP96	260
87-6	XAG-E	701A 700C	89A-W4	36-1795 36-1795	295 296
81-1	4-0-0 9-0AX	101C	S9A-1	80A-8	1 766
87-0	XA5-C	AOOT	89A-2	XA7-18	889
87-9	XA5-8	CESA	69A-8	69A-1	796
87-10	XA5-8	6828	59A-3	898-2	799
87-11	XAS-S	683B	89A-4	888-472	769
87-12	XA5-A	682A	80A-4	59A-6	613
88A-W1	89A-6	766	89A-5	868-W8	790
58A-W2	89A-10	786	59A-6	69A-4	81.5
53A-W3 S2A-W4	89A-11 89A-0	787 785	89A-7 89A-6	89A-0 88A-W1	811 786
55A-1	65A=6	824	0-A98	88A-W4	785
S3A-1	88A-11	825	0-A08	80A-7	611
55A-2	88A-8	814	89A-10	S8AW2	766
88A-2	88A-10	815	69A-10	89A-12	812
93A8	65A-2	814	89A-11	SEA-W3	787
88A-3	58A-4	817	80A-12	S9A-10	812
88A~4	68A-3	817	808-W1	S6B-11	780
88A-4 88A-6	SBA-6 SBA-4	818	698-W2 598-W3	\$88-10 \$68-2	781 783
88A-5	88 A-7	818	89B-W4	88B-8	782
S8A-6	S8A-1	824	S9B-1	S0B-3	800
SSA-6	88A-8	623	S9B-2	S0A-3	709
98A-7	58A5	819	S9B-2	XA7-22	346
SSA-7	XAI-8	314	S9B-3	S9B-1	800
88A-6	81	533	S9B-3	S9B-6	801
98A-8	89A-6	825	69B-4	S9B-6	802
S8A-8	88A-9	820	698-4 898-5	XA6-M S9B-3	337 801
83A-0	88A-8	820	898-6	XA7-16	340
88A-10 88A-10	88A-2 88A-12	815 816	50B-6	S9B-4	802
88A-11	88A-1	425	S98-6	XA7-21	345
58A-12	88A-10	816	59B-7	S0B-0	605
85A-12	XA6-V	883	50B-6	S9B-12	804
899-71	XAG-P	664	S9B8	XA7-20	344
839-W2	S9A-4	769	50B- 0	S9B-7	805
83D-W3	89A-5	790	896-9	89C-5	806
93D-174	XAG-P	662	S9B-10	S9B-12	803 341
89B-1	990-W2	784	89B-11 89B-12	XA7-16 S98-6	804
88B-3	898-W3 898-W4	783 752	59B-12	89B-10	803
889-4	XAI-H	290	89C-W1	88C-W1	794
81B-5	- 88B-7	822	Mac-W3	SAB-1	784
		1 200 \$	4		

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

***************************************	*-	Wille No.	Para -	To-	Wan No.
XAI-14	XAT-P	318	XAC-D	45-7759	634
XA1-15	NC		XA4-E	45-TP68	9 68
XA1-16	RS-8	320	XA4-P	650 SHLD	738
XA1-17	811—0	321	XA4-H	664 SHLD	740
XA1-18	XAG-U	324	XAC-H	678 SHLD	741
XA1-19	S11-3	523	XA4-J	XAS-B	659
XA1-30	NC		XA4-K	XAI-B	658
XAI-SI	J4-1713	603	XA4-K	XAS-B	657
XA1-22	NC .	1	XA4-L	Ell	606
XA2-A XA2-B	82-2 R3-A	325	XA4-M	E22 J2-1715	661
AA2-8 XA2-8	XA4-K	668 657	XA4-N XA4-P	48-1715 48-1768	223
XAS-C	\$2-6	\$81	XA4-R	J3-1762	6784 6781
XA2-D	657 SNLD	728	XA4-S	NC	6 102
XA2-D	658 SHLD	729	XA4-1	E24	607
XA2-8	\$2-1	\$26 I	XA4-2	Esi	567
XA2-F	82-6	327	XA4-3	NC	1 207
XAS-H	NC		XA4-4	NC	ı
XA9-J	NC		XA4-5	NC	#
XA2	NC.		XA4-6	E16	527
KA9-L	NC		XA4 -7	656 SHLD	145
XA2-M		565	XA4-7	679 SHLD	46
KAS-M	XA2-P	730	XA4-8	NC	
XA2-M	810	604	XA4-9	NC	
KA2-N	XAS-R	731	XA4-10	NC	Į.
SAR-P	XA2-M	730	XA4-11	NC	3
XA1-R	XA2-N	731	XA4-12	89	5.68
XA2-8	680 SHLD	732	XA4-18	J3-TP84	655
XA2T	817	525	XA4-14	J3-TP67	6791
XA2U	\$3-W1	680A	XA4-15	43-TP56	6797
XA2-V	S3-W2	680B	XA5-A	87-12	6824
KA2-W	NC		XA5-8	87-10	6821
Ka2-31	NC	1	XA6-C	57-6	700/
KA3-A	84-2	328	ひーさん父	S7-4	7001
Kas-B	Ro-A	666	XAS-E	S7-6	7000
KA3-B	XA4-J	659	XA6-F	NC	
Ka3-C	S4-6	380	XAS—H	XA5-7	752
CA3-D	658 SHLD	734	XAS—H	XAG-E	569
Cas-D	659 SHLD	733	XA5-J	XA7-6	331
KA3-D	666 SHILD	742	XA5-K	J4-TP23	423
Kas-e	\$4-3	329	XA5—K	XD84-2	429
Ka3-P	84-5	330	XA5-L	S9D-8	608
KA3-H	NC	1	XA5-L	XAG-C	609
KAS-J	NC	i i	XA5-M	\$7-6	701
Ka3-K	NC		XA5-N	S7-3	7011
Ka3-L	NC	1	XA5-P	S7-7	7010
CA3-M	29	566	XA5-R	87-0	6831 6831
M-CAZ	XA3-P	735	XA5-8	S7-11	628
Kas—N Kas—N	211 XA3-R	605 736	XA5-1	E5 NC	920
\A3~?! \A3~P	XA3-M	736 736	XA6-2	J4-TP16	332
kaj-r Kaj-r	XA3-M XA3-N	736	XA5-3	NC NC	3.2
VA3-R VA3-8	681 SKLD	737	XA5-4 XA5-5	BI-RI	6647
LA3-9 (A3-T	E17	526	XA5-5 XA5-5	J4-7791	486
CA3-1 CA3-U	S3-W3	681A	XA5-6	NC NC	700
UNS-U KAS-V	83-W4	681B	XA5-7	J4-TP46	562
(A3-W	NC	9010	XA5-7	XA5-H	752
laj-w Kaj-x	NC NC		XA5-8	S6-3	333
M-A	E20	660	XA5-9	J4-TP12	504
XA4-B	NC	-	XA5-10	S6-6	334
KA4-C	J1-TP23	650	XA5-11	J4-TP18	335

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

	10-	Wigo No.	F1220 -	7-	W
DC-99	M-1794		T23-12	816-3	1 35
	14-1703	281	193-13	R11-3	36
55-1	14-75984	272	153-14	R11-1	3.6
100-4	JA-7990	204	TB3-15	R12-3	35
10C-8	14-1996	274	133-16	812-:	55
10C-4	85C-6	808	1703-26	R3-A	29
	XAG-J	663	TP1	89-4	3.8
19C-6	893-9	808	TP2	84-4	3/3
ISC-5	89C-0	807	VB1 AD	VR2 AD	79
10C-0	89C-4	808	VR 1C	XDS1-1	43
30C-0	93C-9	840	VB3 AD	VRIAD	13
ISC-1	89C-0	610	VR3 AD	VR3 AD	79
10C-3	39C-5	807	VR2 C	XD\$3-1	43
10C-8	XA7-17	343	VR3 AD	J4-7747	47
10C-0	890-6	809	VR3 AD	VR3 AD] ")
10C-0	89C-7	810	VR3 C	XD63-1	40
10C-0	XA7-10	343	XA1-A	B17	5.0
10C-16	80-3	270	XAI-A	XAI-1	73
10C-11	81	884	XAI-A	656 SHLO	73
DC-13	R13-3	371	XAI-B	KA4-K	6.5
9D-W1	NC		XAI-C	B37	3.0
DD-93	NC		XA1-D	2 10	640
DD83	34-17750	284	XA1-B	E3	E48
MD-M4	NC		XAI-F	839-9	23
10D-1	NC		KAI-H	383-4	15
DD-1	NC		XA1-J	183-3	34
10D-0	NC		KA1-K	XAS-T	30
100-1	MC		Ka1—L	R11-2	36
10D-6	NC .		XA1-M	XD91-9	34
10D-6	NC		N-1AX	XD83-3	34
10D-7	J4-17987	236	XA1-P	XD83-2	30
10D-7	89D-9		XAI-R	BA-A	300
19D-8	XAS-L	608	XA1-6	R2-A	1 34
30-9	SOD-7		XAI-T	R8-8	30
100-10	NC		XAI-U	811-6	30
9D-11	NC		XA1-V	S11-1	33
DD-13	NC TO		XAI-V	XA6-6	31
ho-3	231	463	XA1-W	811-3	31
110—8 11.1—171	B37 XAS-N	673 338	XAI-X	4-1764	37
111-W1 111-W2	NC NC	230	XAI-X	83-9 NC	24
111-W3	XAG-K	336	XAI-A	J4-TPSS	l
11-1 111-1	XA1-V	243	XA1-2 XA1-2	S3-10	1 31
111-2	XAI-W	311	XA1-1	XA1-A	4
11-0	XA1-19	323	XAI-I	689 SHLD	71
11-4	NC NC	1	XA1-3	RS-A	37
11-6	NC NC		XA1-8	NC NC	1
11-6	NC	1	XA1-4	NC NC	ŀ
ni-7	Bá	430	XA1-6	NC NC	ł
11-0	XAI-U	309	XA1-6	B22	1 66
11-0	XA1-17	321	XA1-7	98B-7	31
13-4	87-173	373	XA1-0	B21	57
no-0	B3-6	377	XA1-0	34-1797	29
70-1	R19-1	363	XA1-6	98A-7	31
	XAI-J	300	XA1-9	B24	61
755-6	R9-1	351	XA1-9	XAG-X	60
133-4	30-0	352	XA1-10	J4-TP24	27
750-0	1 34	428	XA1-11	XA7-H	31
733-10	63-c	477	XA1-12	XA7-J	31

Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

F100-500	74-	Whyter Mess,	Prougg.		W A
XA5-12	JA-17914	382	XA7-A	86	<u> </u>
XA5-13	8182	684 8	XA7 A	XA7-1	7
ZA5-13	JA-1793	422	XAT-B	NC	
XA5-14	M-7717	269	XAT-C	NC	
XA5-15	J4-17948	424	XAT-D	NC	į.
XAG-A	23	530	XA7—E	NC	Į.
X.AG-A	XA6-1	753	XA7-F	XA1-14	3
XAS-A	664 SHLD	758	XA7—H	XA1-11	3
Kag-b	KA5-H	549	XA7-J	XA1-12	3
XAG-3	XA6-D	754	XA7-K	NC	
Хл6-С	J4-TP47	599	XA/-L	NC	
Kag-C	XAS-L	609	3A7-M	NC	
NAG-C	XAS-E	755	XA7-N	NC	
XAS-D	Q1-8	460	3A7-P	NC	
KAG-D	XAG-B	754	XA7-R	NC	¥.
XA6-2	Q2-E	475	XA7-8	NC	N.
XAG-B	XAS-C	756	XA7-T	NC	
XAG-F	86 B-W4	662	XA7-U	MC	1
XA6-H	14-1759	287	XA7-V	NC	
XAG-J	99C-4	663	XA7-W	NC	
ХАВ—К ХАВ—L	911-W3	336	XA7-X	NC NC	
XAG-M	NC 308-4	254	XA?-Y	NC	
AAD-N		337	XA7-2	NC	
XAS-P	\$11-W1 \$8B-W1	338	XA7-1	XA7-A	1
XA8-2	30.5-W1 J4—17958	664	XA7-2	J4-TP70	2
XA6-9	XAI-V	286	XA7-3	J4-1760	
лав-5 Хаб-Т	XAI-K	310 301	XA7-4	J4-TP67	3
XAG-U	XA1-18	1	XA7-5	J4-1P25	2
XAS-V	14-1P26	324 561	XA76	XA5-J	3
XAS-V	Q1-C	461	XA7-7	J4-TP49	2
XAG-V	S0A-12	883	XA7-8	M-7750	2
XAS-W	4-TP13	596	XA7-9	J1-77'99	2:
XAG-W	RA-A	810	XA7-10	NC	
XAG-X	J4-TP30	597	XA7-11	NC .	
XAG-X	G2-C	478	XA7-12	Q1-E	4
XA8-X	XA1-9	802	XA7-12	36-2	5
XAS-Y	NC NC	30.4	XA7-13	39 A?	3
Y. A.6-Z	NC		XA7-14	S9 B5	3
XA6-1	XA6-A	753	KA7-15	NC .	
XA6-2	NC	1	XA7-16 XA7-17	S98-11	3
XA6-3	NC		XA7-17 XA7-18	S9C-8 NC	3
KA8-4	NC		XA7-19	SOC-9	
CAS-5	NC		XA7-20		3
KA6-6	NC		XA7-21	55.3-6 50.5-6	3
LAG-7	NC		XA7-22	S9 8 ··· 2	3
XA6-6	NC		XD81-2	E28	3
KA8-9	NC	1	XD81-1	VRI-C	4
KA6-10	NC		XD61-2	XAI-M	3
KA6-11	NC		XD82-2	629	3
XA6-13	l NC		XD62-1	VR2-C	4.
KA6-13	NC		XD82-2	XAI-N	3
XA6-14	NC		XD83-2	E32	R -
KA6-15	NC		XD83-1	VR3-C	34
KA8-16	NC		XD83-2	XAI-P	30
KA6-17	NC		XD84 - A	S5 -3	34
XA6-18	NC		XD\$4 · B	XA5-K	4:
KA6-19	NC		650 SHLD	J1- TP24	70
KA6-20	Q1-B	570	650 SHLD	XA4-F	7:
XA6-21	Q2-B	811	651 SHLD	J1-TP38	70
KA9-22	NC NC		652 SHLD	212 1736 218	71
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Table 3-43. Test Set Subassembly MX-8639A/APS-94D, Unit 2 Wire List - Continued

Pensa-	****	Mare Dis-	第 章(4) (4) (4)	7	O see
CJK8 \$HLD	29-17941	716	67 i ShilD	21-17%	101
ist shld	654 SHLD	739	672 SMLD	J:-799	7 to e
isa shild	XA4-H	740	673 St!LD	J1 -TP12	705
ise shild	653 SMLD	739	674 SALD	J1-TP24	107
ISS SHLD	XA4-7	745	675 SHLD	J2-TP16	7:2
M SHLD	XA1-A	127	675 SHLD	23-7716	8.10
IST SHLD	XA2-D	726	676 SHLD	J2-TP19	713
48 SHLD	XA2-D	729	676 SHLD	23-TP19	831
18 SHLD	XAX-D	734	677 SHLD	J2-TP26	714
59 SHLD	XA3-D	TRE	67# SHLD	XA4-H	741
60 SHLD	E33	744	679 SHLD	XA4-7	746
61 SHLD	E33	742	680 SHLD	XA2-S	732
62 SHLD	663 SHLD	756	681 SHLD	XA3S	727
43 SHLD	662 SHLD	756	684 SHLD	E5	749
63 SIILD	664 SHLD	757	695 SHLD	J2-TP7	
64 SHLD	XA6-A	758	695 SHLD	J3-TP7	626
64 SHLD	663 SHLO	757	696 SHLD	J2-TP11	711
46 SHLD	XA3-D	743	696 SHLD	23-TP11	629
61 SHLD	E:3.5	209	697 SHLD	J2-TP30	1 715
es shld	£18	719	698 SHLD	J2-1988	720
88 SHLD	42-7850	718	698 SHLD	Ja-TPee	
49 SHLD	E:3:3	m32	699 SHLD	J4-TP11	725
69 SHLD	XAI-I	#27	TO I SHILD	8 55	751
70 SHLD	JI-TPS	102			3
					er Electron
				•	k
		i i			

APPENDIX A

REFERENCES

The following applicable publications should be available to direct support personnel for use with Test Set Group, indicator, Sadar OQ-65A/APS-94D.

Group, indicator, Radat Uy-	68A/A73-34D.
DA Pam 310-4	Index of Technical Publications: Technical Manuals, Technical Bulletins, Supply
	Manuals, (Types 7, 8, and 9), Supply Bulletins, and Lubrication Orders.
DA Pam 310-7	US Army Equipment Index of Modification Work Orders.
TB 11-1833-35-1	Calibration Procedure for Radar Indicator Test Set Group OQ-63A/APS-94D (NSN 6625-01-058-7874).
TB 43-0119	Field Instructions for Painting and Preserving Electronics Command Equipment Including Camouflage Pattern Fainting of Electrical Equipment Shelters.
TM 11-5895-967-12	Operator's and Organizational Maintenance Manual Radar Surveillance Set AN/APS-94E.
TM 11-6625-444-14-1	Operator's, Organizational, Direct Support and General Support Maintenance Manual Including Repair Parts and Special Tools List: Voltmeter, Digital AN/GSM-64B (NSN 6625-00-022-7894) Including Plug-la, Electronic Test Equipment PL-1370/GSM-64B (NSN 6625-00-137-8366).
TM 11-6625-654-14	Operator's, Organizational, Direct Support, and General Support Maintenance Manual Repair Farts and Special Tools Lists (Including Depot Maintenance Repair Part and Special Tools) for Multimeter AN/USM-223.
TM 11-6625-1833-12	Operator and Organizational Maintenance Manual, Test Set Group, Indicator, Radar OQ-63A/APS-94D.
TM 11-6625-2658-14	Operator's, Organizational, Direct Support and General Support Maintenance Manual for Oscilloscope AN/USM-281C (NSN 6625-00-106-9622).
TM 38-750	The Army Maintenance Management System (TAMMS).

APPENDIX B

EXPENDABLE SUPPLIES AND MATERIALS LIST

Section I. INTRODUCTION

B-1. Scope

This appendix lists expendable supplies and materials you will need to operate and maintain the OQ-63A/APS-94D. These items are authorized to you by CTA 50-970, Expendable Items (Except Medical, Class V. Repair Parts, and Horaldic Items).

B-2. Explanation of Columns

- a. Column 1—Item Number. This number is assigned to the entry in the listing and is referenced in the narrative instructions to identify the material (e.g., "Use cleaning compound, item 5, App. D").
- b. Column 2—Level. This column identifies the lowest level of maintenance that requires the listed item.
 - C-Operator/Crew
 - 3-Organizational Maintenance

F-Direct Support Maintenance H-General Support Maintenance

- c. Column 8—National Stock Number. This is the National stock number assigned to the item; use it to request or requisition the item.
- d. Column 4—Description. Indicates the Federal item name and, if required, a description to identify the item. The last line for each item indicates the part number followed by the Federal Supply Code for Manufacturer (PSCM) in parentheses, if applicable.
- e. Column 5—Unit of Measure (U/M). Indicates the measure used in performing the actual maintenance function. This measure is expressed by a two-character alphabetical abbreviation (e.g., es, in, pr). If the unit of measure differs from the unit of issue, requisition the lowest unit of issue that will satisfy your requirements.

(Next printed page B-3)

SECTION II EXPENDABLE SUPPLIES AND MATERIALS LIST

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on the same of		NUMBER		MEAS	
			PART NO AND FSCM		
B	0	5350-00-264-3485	PAPER, AGRASIVE, FLINT (SANGPAPER, FIME) MEL-PP-105	PKG.	
2	0	7570-00-933-7372	tape, sleetrical (black plastic) 1/2 inch	RGL L	
¥	c,a	8020-00-178-8305	BRUSH, PAINT MIL-H-8-420 (81343)	EA	- And State of the
4	0	5350-00-145-0747	PRIMER, COLOR Y PER MIL-P-8585 (81348)	QTT	
5	0	8010-00-575-0808	ENAMEL, LIGHT GRAV (CLASS-2 - METAL)	W L	
6	c,o	6810-00-551-1487	TRICHLORGETHANE, TECHNICAL, CLEANING COMPOUND G-T-620, TYPE ! (81348)	q a	A CONTRACTOR OF THE CONTRACTOR
7	6.0	8305-00-285-3436	CLOTH, COTTON, (LINT-FREE) CCC-C-440 (81348)	19	
8	0,3	7920-00-205-2404	Brush. Cleaning Wil-8-298 (81348)	EA	Official

INDEX

	Paragraph, Figure Table, Number
	Table, Number
ADAS Simulator	3-30c, T3-30
Beach Test	F2-2, 2-14
Block diagram analysis	2-93, FO-10
Circuit analysis Functional description	F2-10, 2-47
Troubleshooting	3-30b, T3-31
ADAS Simulator Circuit Analysis:	,
BCD/ALT/NUM selection	2-93j
But counter	2-931
Bit enable	2-93h
Clock generator	2-93b
Deflection clock	2-93k
Input buffer and clock enable	2-93a
Programable read only memory (PROM)	2-93g
Ramp generator	2-931 2-93c
Reset circuit	2-93d
Three decade counter and decode	2-93i
Unblank level shifter	2 - 9 3 f
Word counter	_ , 5 1
Amplifiers: Antilogarithmic	2-70, FO-24
Cubing	2-63, FO-24
Direct current	2-41, 2-65, 2-72
April 1944 Broke B	F2-7 FO-23
Logarithmie	2-69, FO-24
Servo	2-80, FO-25
Squaring	2-78, F2-16
Threshold summing	2-70, 2-15, FO-24
Video	2-8, 2-31, FO-2 2-89, FO-9
Anode and Focus Loads	2-58, F2-12, FO-16
Antenna Counter	2-70, FO-24
Antilogarithmic Amplifier A Sine #/A Cosine # Signal Generation	2-18, FO-2
	2-93i
BCD/ALT/NUM Selection	2-96. FO-13
Binary Counter	2-93e
Bit Counter	
BITE and Power Supply Circuits Analysis:	2-93, FO-10
ADAS simulator	2-89, FO-9
BITE Circuitry	2-83, FO-18
Film speed sources	2-90
Indicating system series regulated supplies	2-84, FO-12
Indicating system shunt regulated supplies	2-85, FO-12
Low voltage power supplies (module 1 A2A3)	F-88, FO-17 2-92
+26 Volt DC power supply	2-92 2-91. F2-9
+28 Volt regulated DC supply and high voltage loads	Δ-91, 1·Δ-9
BITE Circuit: Block Diagram Analysis:	2-14
ADAS	2-14
BITE	2-9
Ground speed/drift angle servo loop	2 - 6
Horizontal sweep Low voltage supply	2 - 1 2
TOM AOITSTA STIDITA	

	Paragraph, Figure Table, Number
Monitor adaptor input simulator Overvoltage protection Sweep (CRT and range display) Vertical sweep Video amplifier Video simulator and synchronizing BITE Circuity Bit Enable Circuit	2 - 1 1 2 - 5 2 - 7 2 - 8 2 - 4
BITE, Sweep, Indicator and Servo Fault: Bench test Block diagram analysis Circuit analysis Troubleshooting BITE Troubleshooting Cable Repair	2-10, F2-2 2-83, FO-18 3-29b, T3-29 3 - 6
Calibration: GS/DFT dial Servo synchro coarse Servo synchro fine Cathode Ray Tube Circuits:	3 - 4 1
Ragulator and focus, functional description Unblanking, circuit analysis Unblanking, functional description Cathode Ray Tube Pocus, Circuit Analysis:	2-75, FO-20 2-33, FO-2
Drift angle serve loop Ft and Mt dynamic focus Serve amplifier Serve loop stepper motor Squaring amplifier Cathode Ray Tube Regulator and Focus Circuit Cathode Ray Tube Unblanking	2-81, F2-17 2-78, F2-16
Circuit, Description: ADAS simulator A Sine # A Cosine # signal generation BITE Cathode ray tube regulator and focus Cathode ray tube unblanking Direct current amplifiers Dynamic focus Fault isolation Groundspeed/drift L angle serve loop Horizontal offset Horizontal pin cushion correction Horizontal range selection Horizontal sweep Horizontal sweep generator Horizontal unipolarizer Horizontal yoke loads Indicating system low voltage power supplies	2-18, FO-2 2-42, F2-8 2-34 2-33, FO-2 2-41, F2-7 2-36, FO-2 2-44, F2-8 2-37, FO-3 2-22, FO-2 2-24, FO-2 2-19, FO-2 2-21, FO-2 2-23, FO-2
(modules 1A1A3, 4) Low voltage power supplies (module 1A2A3) Monitor adaptor input simulator	

	Paragraph, Figure Table, Number
Over voltage protection Plus 26 volt power supply Plus 28 volt regulated power supply and high voltage loads Primary fault detection Regulated plus and minus 9-volt source Static focusing Sweep control Vertical offset Vertical pin cushion correction Vertical range selection Vertical sweep Vertical sweep generator Video amplifier Video simulator and synchronizing Cleaning Clock Generator	2-40, F2-6 2-45, F2-9 2-4, F2-8 2-27, FO-2 2-35, FO-24 2-17, FO-2 2-29, FO-2 2-31, FO-2 2-20, FO-2 2-28, FO-2 2-30, FO-2 2-30, FO-2 2-13, T2-1 F-16, F2-3 3-38 2-95, FO-13
Clock Waveform: Bench test Troubleshooting Compressor Networks, Selectable Connector Continuity Test Counter, Antenna Counter, Binary Counters:	3-21a, T3-13 3-21b, T3-13 T2-1 3-11 2-58, FO-16 2-96
Binary Bit 750-Hz prf clock Word CRT Sweep Requirements Cubing Amplifier Deflection Clock	2-96, FO-13 2-93e 2-52 2-93f 2-3, F2-1 2-63, FO-24 2-105
Deflection Decoder Detector, Negative Sweep Direct Current Amplifier	2-99, F2-20 2-64, FO-24 2-41, 2-72 F2-7, 0-23
Direct Support Maintenance: Scope Organization Tools and equipment required Discrepancy in Shipment Report Drift Angle Servo Loop	3-1 3-2 3-3 1-3c 2-79, FO-3
Dynamic Focus: Bench test Functional description Troubleshooting Electrical Tests	3-32a, T3-34 2-36, FO-2 3-32b, T3-35 3 - 4 9 3 - 7
FAILURE Light Indications Fault Isolation Circuit Film Speed: Bench test Functional Description Troubleshooting Film Speed Sources	2-44, F2-8 3-22a, T3-14 2-90 3-22b, T3-15 2-90, F2-18 2-51, F2-12, FO-15
Five-MHz Oscillator	Index 3

	Paragraph, Figure Table, Number
Fixed Target Video Amplifier	2-74, FO-20
Focusing: Dynamic focus Ft and Mt dynamic focus Static focusing Focus Loads Focus and Records Ft and Mt Dynamic Focus Circuit Ft Enable	2-36, FO-2 2-77, FO-24 2-35, FO-24 2-89, F0-9 1-3 2-77, FO-24 2-59, F2-12, FO-16
Generator: Clock Horizontal sweep Ramp Generator, Clock Generator Simulator, Unit 2, Connector Continuity	2 - 9 7 2 - 38, FO - 13
Procedure Generator Simulator, Unit 2, Physical Test and Inspection	3 - 1 4 3-48, T3-40 2-9, 2-37, F2-2, F0-3 3-43
GS/DFT Diai Calibration	3-43 2-45. F2-9
Horizontal Circuits: Offset Pincushion correction Range selection	2-22, FO-2 2-24, FO-2 2-19, FO-2
Sweep Unipolarizer Yokaloads Horizontal Offset Horizontal Pincushion Correction Horizontal Range Selection	2-26, FO-2 2 - 25, FO - 22 2-22, FO-2 2-24, FO-2 2-19, FO-2
Horizontal Sweep: Bench test Block diagram analysis Functional description Troubleshooting Horizontal Sweep Circuit Horizontal Sweep Generator Horizontal Unipolarizer Horizontal Yoke Loads	3-25a, T3-20 2 - 6 2-21, FO-2 3-25b, T3-21 2-6, 2-21, F2-2 2-23, FO-2 2-26, FO-2 2 - 25, FO-2 2
Indexes of Publications Indicating System Low Voltage Power Supplies Indicating System Overcurrent Protection Indicating System Power Supplies:	1 - 2 2-38, F2-24 2-86, FO-12
Overcurrent protection Secondary Power Sources Series Regulated Shunt Regulated Indicating System Series Regulated Symplics	2-38, 2-39 F2-4, F2-5 2-86, F0-12 2-87, F0-8, F0-26 2-84, F0-12 2-85, F0-12
Indicating System Shunt Regulated Supplies INDICATOR FAULT Light Indications	2-85, FO-12 3 - 9

	Paragraph, Figure Table, Number
Indicator Simulator (Unit 1A1) Connector Continuity Procedure Indicator Simulator, Unit 1A1, Physical Test and Inspections Indicator Simulator (Unit 1A2) Connector Continuity Procedure Indicator Simulator, Unit 1A2, Physical Test and Inspection	3 - 1 2 3-46, T3-38 3 - 1 3 3-47, T3-39 2 - 9 3 a
Input Buffer and Clock Enable Intensity Control Voltage: Be ch test Troubleshooting	3-23a, T3-16 3-23b, T3-17
Level Shifter Circuit	2 - 9 3 a
Light Indications: Failure Indicator fault	3 - 7 3 - 9
Servo vault	3 - 1 0 3 - 8
Logarithmic Amplifiers Low Voltage Power Supplies:	2-69, FO-24
Bench test Block diagram analysis Circuit analysis Troubleshooting Low Voltage Power Supplies (Module 1A2A3)	3-17a, T3-5 2-12, F2-2 2-39, F2-5 3-17b, T3-6 2-88, FO-17
Low Voltage Power Supply Circuits	2-12, 2-39 F2-2, F2-5
Modules: Indicating system low voltage power supplies (1A1A3, A4)	2-38, F2-4 2-39, F2-5
Monitor Adapter Input Simulator: Bench test Block diagram analysis Circuit description Troubleshooting	3-31a, T3-32 2-13, F2-2 2-48, F2-11 3-31b, T3-33
Monitor Adaptor Simulator Circuit Analysis: Binary counter	2 - 9 6 2 - 9 5
Clock generator Deflection decoder Ramp generator Summer	2 - 9 9 2 - 9 7 2 - 1 0 0
Video decoder	2 - 9 8 2-60, F2-12, FO-16
MX-8636A/APS-94D, Unit 1A2: Electrical test Physical test and inspection	3 - 4 9 3-47, T3-39 3 - 3 6 b
Removal and replacement procedures Wire list MX-8638A/APS-94D, Unit 1A1:	3-52, T3-42 3-49
Electrical test Physical test and inspection	3-46, T3-38 3-36a 3-51, T3-41
MX-8639A/APS-94D, Unit 2: Electrical test	3 - 4 9 3-48, T3-40
Physical test and inspection	3-36c 3-53, T3-43

Reset pulse

Paragraph, Figure Table, Number Unblanking Cathode Ray Tube: 2 - 7 5 Circuit analysis 2-33. FO-2 Functional description 2 - 93iUnblank Level Shifter Unipolarizers: 2-64, FO-34 Alar7 2-68, FO-24 2-26. FO-2 Horizontal 2-29, FO-2 Vertical Offset 2-74, FO-24 Vertical Output Switching 2-31, FO-2 Vertical Pineushion Correction 2-20, FO-2 Vertical Sweep Circuit 2-7, 2-29 F2-2, FO-2 2-30. FO-2 Vertical Sweep Generator Vertical Sweep Waveform: 3-24a, T3-18 Bench test 2-7. F2-2 Block diagram analysis..... 3-24b, T3-18 Troubleshooting 2-8, 2-32, Video Amplifier Circuit F2-2, FO-20 Video Compression 3-28a, T3-25 Bench test 3-25b, T3-26 Troubleshooting 2-98. FO-13 Video Simulator and Synchronizing Circuit Analysis: 2-58, FO-16 Antenna counter 2-51, FO-15 2-59, FO-16 Pt enable 2 - 60, FO - 16 2-54, FO-15 Reset pulse generation 2-52, FO-15 750-Hz prf clocked counter 2-53, FO-15 750-Hz prf generation 2 - 5 6, FO - 1 5 2 - 5 5, FO - 1 5 Sweep gate generation Test video generation 2 - 50Video simulator and synchronizing 2-57, F2-12, FO-15 Yoke clamp gate generation 2-4, 2-16, F2-2 Video Simulator and Synchronizing Circuit Description Voltage Sources: 2-89. F2-9 2 - 90Film speed sources 2-38, F2-4 Indicating system low voltage power supplies (Modules 1A1A3, A4) 2-84, FO-12 Indicating system series regulated power supplies 2-85, FO-12 Indicating system shunt regulated power supplies 2-39, F2-5, Low voltage power supplies (Module 1A2A3) 2-88, FO-7 2-46, 2-96 +26 volt dc power supply 2-45, 2-91, F2-9 2-27. FO-2 Regulated plus and minus 9 volts 2-97, FO-8 Secondary power sources 2-46, 2-96 +26 Volt DC Power Supply 2-45, F2-9 + 28 Volt Regulated Power Supply and High Voltage Loads 3-51, T3-41 Wire List, MX-8638A/APS-94D, Unit 1A1

	Paragraph, Figure Table, Number
750 Hz ovf	2 - 5 3
Sweep rate	
Test video	2 5 5
Yoke clamp gate	2 5 7
Squaring Amplifier	
Static Pocusing	,
Summer Circuits	,
Sweep Circuit, Description	
Sweep Chronits, Vertical:	- 0, 1
	2-29, FO-2
Pincushion correction	
Range selection sweep	
Sweep analysis	
Sweep generator	2-30, FO-2
Sweep Control Circuit	
SWEEP PAULT Light Indications	3 - 8
Sweep Gate Generation	2-56 F2-12 FO-15
Sweep Generation	
System Punction	2-02, 2-07, 10-24
Terminal Board IAZTB3, Parts Location	F 3 - 9
Terminal Board 2TB3, Parts Location	F 3 - 1 3
Test Point-Connector Pin Cross-Reference	T 3 - 2
Test, Continuity	3-11 3-15
Test Set Group Functional Tests	2 7 7
Peat Video Generation	2 0 2 1
Three Decade Counter and Decode	
Threshold Summing Amplifler	2-70, F2-15, FO-24
Tools and Test Equipment Required for Direct Support Maintenance	3-3, T3-1
Troubleshooting:	3 - 3 0
ADAS Simulator	
BITE, sweep, indicator, and servo faults circuits	3-29
Clock waveform	3 - 2 1 3 - 3 2
Dynamie foeus	3 - 3 2 3 - 2 2
Film speed	3 - 3 3
High voltage load	3 - 3 3 3 - 2 5
Horizontal sweep waveform	3-23 3-23
Intensity control voltage	3-23
Low voltage power supplies	3 - 3 1
Monitor adaptor input	3-27
Offset circuit	3-18
Panel lights	3-16
Primary power distribution	3-10
Servo loop	3-19
Servo loop supplementary tests	3 - 2 0 3 - 2 6
Unblank circuits	3 - 2 6
Vertical sweep waveform	_
Video compression	3 - 2 8
Froubleshooting with BITE	3 - 6
Unblank Circuit:	
Bench test	3-36a, T3-22
Circuit analysis	2 - 7 5
Functional description	2-33, FO-2
Troubleshooting	3-26b, T3-23

	Paragraph, Figure Table, Number
Wire List, MX-8638A/APS-94D, Unit 1A2 Wire List, MX-8639A/APS-94D, Unit 2 Word Counter	3-53, T3-43
Yoke Clamp Gate Generation Yoke Loads, Horizontal	2-57, F2-12, FO-15



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2-25	2-28	GREENING COURTER-CATABOOK CONTRACTOR CONTRAC	in-designation which Academic and Commission	Recommend that the installation antenna alignment procedure be changed through the specify a 2° IFF antenna lag rather than 1°. RNASON: Experience has shown that with only a 1° lag, the antenna serve system is too sensitive to wind
	WANTA THE SECOND TO THE SECOND			gusting in excess of knots, and has a tendency to rapidly accelerate and occlerate as it nunts, carring strain to the drive train. Hunting is minimized by adjusting the lag to 2° without degradation of operation
3-10	3-3	SPRESSESSION CONTRACTOR CONTRACTO	3-1	REASON: The sustment procedure for the TRANS POWER FAULT indicator calls for a 3 db (500 watts) adjust-
				ment to light the TRANS POWER FAULT indicator.
5-6	5-8	A CONTRACTOR AND AND AND AND AND AND AND AND AND AND		Add agg step f.1 to read, "Replace cover plate removed in the state of
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		F03	G	Zone C 3. On J1-2, change "+24 VDC to "+5 VDC."
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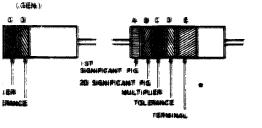
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FIGURE OF THE RESISTANCE VALUE

HPLIER IS THE FACTOR BY WHICH THE ME MULTIPLIED TO YIELD THE

1

b resistors, band e indicates failure — rate level ! Percent failure isistors, this band shall be approximately en bands, and noicates type of terminal

M MUMBERS AND LETTERS

HARE OR FOUR DIGIT ALPHA NUMERIC

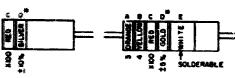
D IN PLACE OF A DECIMAL POINT WHEN EXPRESSED FOR EXAMPLE

1080 + 10 0 0HHS

COLOR CODING IS NOT USED, IDENTI-IACH OF THE APPLICABLE SPECIFICATIONS

ES OF COLOR CODING

(GEN)



SISTANCE 1,400 OHMS TOLERANCE ±10%

NOMERAL RESISTANCE 3400 CHMS RESISTANCE TOLERANCE 15% TERMINAL SOLDERABLE

FORS FILM - TYPE RESISTORS

EMANCE IS \$ 20% AND THE RESISTOR IS NOT MIL-STD.

MLITARY STANDARD RESISTORS

(ER) (SEN) A E ist to the second secon DENIFICANT FIG. 20 SIGNIFICANT FIG. 20 SISNIFICANT FIG 26 SEMERANT RE MULTIPLIER MALTIPLIER MUSITIFICATION THERMEE TOLERANCE TOLERANCE MILLINE-MOTE LEVEL
(ESTABLISHED MELMELITY
TYPES GREY)

COLOR CORE MARKING FOR COMPOSITION TYPE RESISTORS.

COLOR-CODE MARKING FOR FILM-TYPE MESISTEMS

TABLE COLOR CODE FOR COMPOSITION TYPE AND FILM TYPE RESISTORS

96/46	SAND A		9 8	BAN	D C	8	AMD D	BAND E		
COLOR	First Denficiat Figure	COLOR	SECONO SIGNIFICANT FIGURE	COLOR	MALTIPLES	COLOR	RESISTANCE TOLERANCE (PERCENT)	COTOS	PAILURE RATE LEVEL	TERM
MZWTE		BLACK		BLACK				BROWN	M-1.0	
SAGWA:	В	SPONAL		88048	10			RED	P-0.1	
MED)	2	rep.	2	RED	100			GRAAGE	R-0.0	1
SRANGE.	3	GRANGE		CRANCE	1,000			WELLOW	5-0.00	
TELLOW	•	AETTOM	•	TELLOR	HJ,000	SILVER	#10 (COMP. TYPE CALLY)	WANTE		SOLD-
SPEEN	5	GMEEN.		GREEN	200,000	60LD	*5			
SILUE	- 6		•	BLUE	1200,200	RED	#2 (NOT AP-			
(WIGLET)	77	PURME (WOLET)	7				PLICABLE TO			
SRAW		6848		SILVER	9.01		RELIABILITY			
WHITE !		WHITE:		60LD	انها					

AARO A — THE FIRST SIGNIFICANT FIGURE OF THE RESISTANCE VALUE (BARDS A THRU D SHALL BE OF EQUAL WIDTH)

NO 8 -- THE SECOND SIGNIFICANT FIGURE OF THE RESISTANCE VALUE

C - THE MULTIPLIER (THE MULTIPLIER IS THE FACTOR BY WINICH TIME THE SIGNIFICANT FIGURES ARE MULTIPLIED TO YIELD THE ACCORDAL BESISTANCE VALUE)

SARP D - THE RESISTANCE TOLERANCE.

BANG E -- WHEN USED ON COMPOSITION RESISTORS, BAND E INDICATES
ESTABLISHED RELIABILITY FAILURE - RATE LEVEL (PERCENT FAILURE
FER ILDOO HOURS) ON FILM RESISTORS, THIS BAND SHALL BE APPROXIMATELY
II-NZ THES THE WOTH OF OTHER BANDS, AND INDICATES TYPE OF TERMINAL

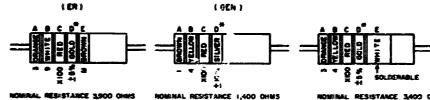
RESISTANCES IDENTIFIED BY NUMBERS AND LETTERS
(THESE ARE NOT COLGR CODED)

SOME RESISTORS ARE IDENTIFIED BY THREE OR FOUR DIGIT ALPHA NUMERIC BESIGNATORS THE LETTER R IS USED IN PLACE OF A DECIMAL POINT WHEN FRACTIONAL VALUES OF AN OHM ARE EXPRESSED FOR EXAMPLE

287 - 2.7 CHMS | IORO = 10 0 CHMS

FOR WIRE-WOURD-TYPE RESISTORS COLOR CODING IS NOT USED, IDENTI-FICATION MARKING IS S'ECIFIED IN EACH OF THE APPLICABLE SPECIFICATIONS

EXAMPLES OF COLOR CODING



RESISTANCE TOLERANCE ±5% FAILURE RATE LEVEL M

MOMINAL RESISTANCE 1,400 OHMS RESISTANCE TOLERANCE \$10%

MOMINAL RESISTANCE 3400 DHAS RESISTANCE TOLERANCE \$5% TERMINAL SOLDERABLE

COMPOSITION-TYPE RESISTORS

FILM - TYPE RESISTORS

IF BAND D IS GMITTED, THE RESISTOR TOLERANCE IS \$ 20% AND THE RESISTOR IS NOT MIL-STD

A. COLOR CODE MARKING FOR MILITARY STANDARD RESISTORS

MIL SPEC IDENT (SILVER) MIL SPEC IDENT IST FIGSGRAY). IST FIS SECHMAL (GOLD) 20 FIG (ORANGE) 20 F(6 (4E). TOLERANCE (SILVER) MULT (BROWN) TOLERANCE (SOLD) (A) 82UH ± 10% (8) 330UH 1 5%

COLOR CODING FOR THBULAR ENCAPSULATED R.F. CHOKES AT A. AN EXAMPLE OF OF THE CODING FOR AN BEUM CHOISE IS GIVEN AT 8, THE COLOR BANDS FOR A 330 UN INDUCTOR ARE ILLUSTRATED

TABLE 2
COLOR CODING FOR TUBULAR ENCAPSULATED R.F. CHOKES

COLOR	SISNI- FICANT FIGURE	MULTIPLIER	INDUCTANCE TOLERANCE (FERCENT)
BLACK	0	1	
SROWN	1	30	1
RED	2	100	5
CRANGE	3	1,000	3
*ELLOW	4		
GREEN	5		
BLUE			
VIOLET	7		
GRAY	9		
WHITE	•		
MONE			20
SILVER			10
60LD	DECIMAL	POINT	5

MULTIPLIER IS THE FACTOR BY WHICH THE TWO COLOR FOURES ARE MULTIPLIED TO OBTAIN THE INDUCTANCE JALUE OF THE CHOKE COIL

B COLOR CODE MARKING FOR MILITARY STANDARD INDUCTORS

F 200 S d - manual 1 CARROLE CHIBACTER · OPERATIO ₹ VIBN

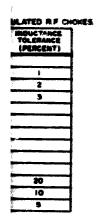
CAPACITORS.

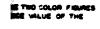
MICA - DE



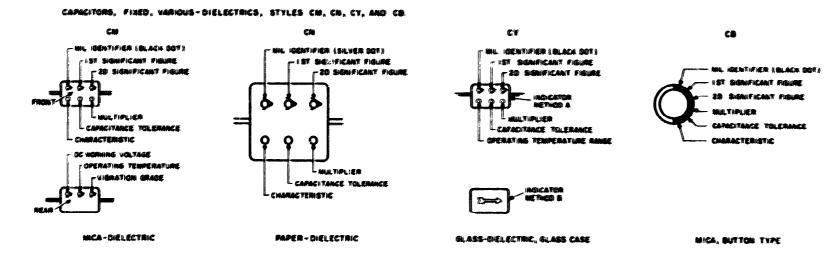
MES. AT A, AN EXAMPLE OF IF 8, THE COLOR BANGS FOR

| 330 UH ± 5%





STANDARD INDUCTORS.



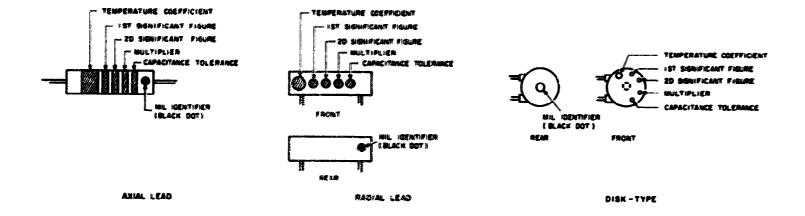


TABLE 3 - FOR USE WITH STYLES CH, CH, CY AND CO.

COTOS	##L	HET BAS FAS	20 1016 146	MILTIPLES	ULTIPLIER CAPACITANCE TOLER							MORKINS VOLTAGE	OFFICE OF	SALE SALE
			инь		C	CN	CN		CH	CN	0	CM	CX. CM	(20)
BLACK		9	0	đ			120%	±20%		A			-88-40+ ₂₀₋ C	⊕-\$6 #2
		А	1	10					•	E	•			
		\$	\$	100	±2%		±2%	42.8	¢				-55°10+60°C	
SHANGE		3	3	1,000		±30%			Ð		•	300		
MELLOW		4	4	40,000					E				-99"10+12:"	Ø 2.000mg
SPEEN		5	5		25%				F			900		
BLEEF		•	6										-9910010	
(NOLET)		7	77						\vdash				- 1	
GRAY		•	•											
MINITE		9	9											
(SECOLLED				01			±5%	25%						
SLYER	CN			0.01	±10%	DO%	210%	±10%			Н			

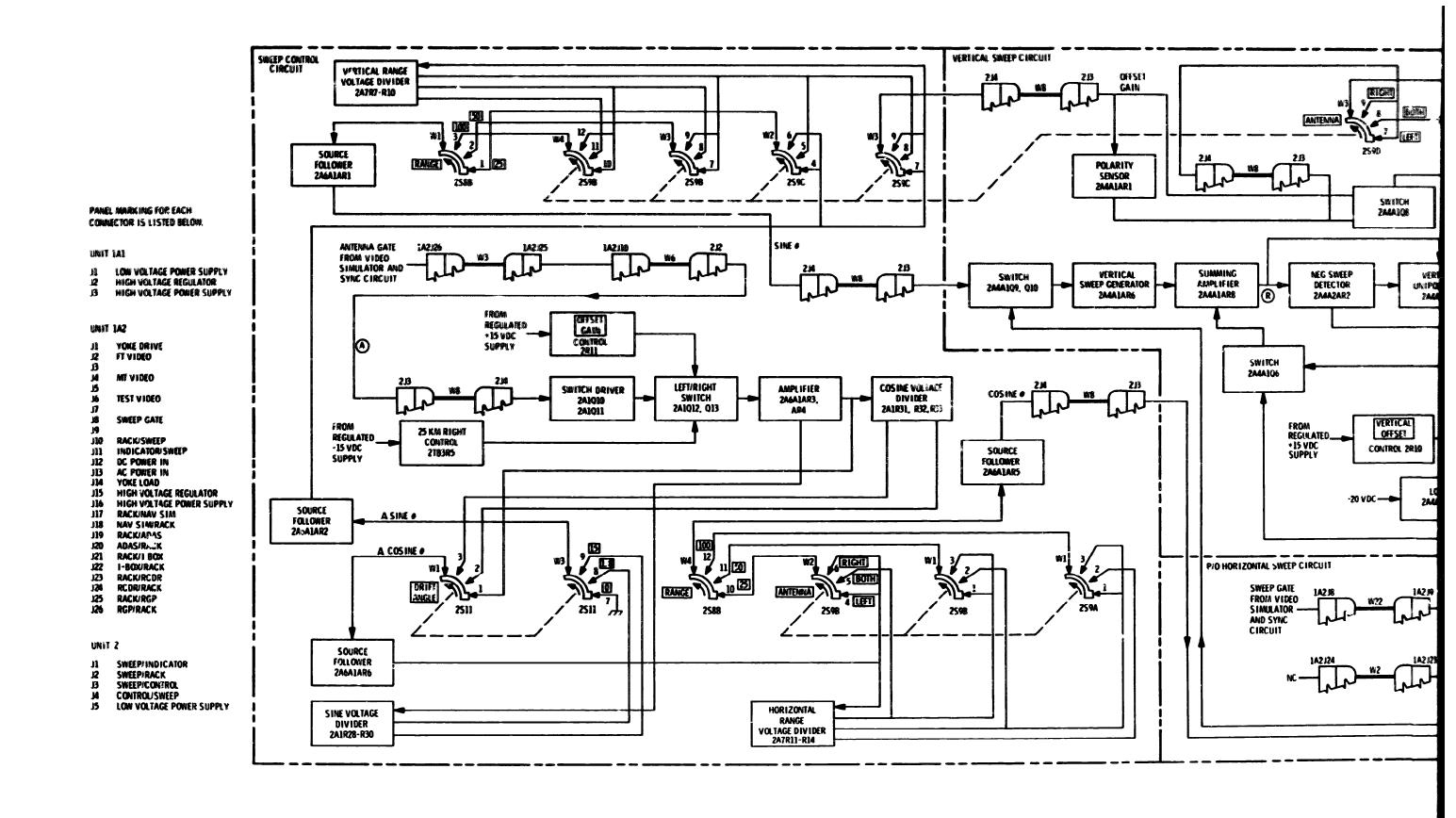
TABLE 4 - TEMPERATURE COMPENSATING, STYLE CC

COLOR	TEMPERATURE	457			CAPACITANCE TOLERANCE				
	COEFFICIENT	SIG FIG	\$16. *16.	MULTIPLIER'	CAPACITANCES OVER 10 UUF	CAPACITANCES 10 UUF OR LESS	10		
BLACK	•	0	ð	1		± 20 UUF	œ		
BRDWN	-30	1	4	10	±1%		Г		
RED	-80	2	2	100	±2%	±0.25 UUF			
CRAMBE	-x 3 0	3	3	1,000			Г		
WELLOW	~220	4	4				Г		
GREEN	-330	5	5		±5%	±05 UUF	Г		
BLUE	-470	6	6				Г		
PURPLE (VIOLET)	-750	7	7						
GRAY		•	•	0.0i ≢			Г		
SE:ME		•	•	01#	±10%				
SOLD	+100			0 1		±10 UUF	Г		
SALVER				© 01			Γ		

- 1 THE MULTIPLIER IS THE MUMBER BY WHICH THE THO SIGNIFICANT (SIG) FIGURES ARE MULTIPLIED TO OBTAIN THE CAPACITANCE IN USF
- 2 LETTERS INDICATE THE CHARACTERISTICS DESIGNATED IN APPLICABLE SPECIFICATIONS MIL-C-5. MIL-C-250, MIL-C-112728, AND MIL-C-10980C RESPECTIVELY
- 3 LETTERS MOICATE THE TEMPERATURE RANGE AND VOLTAGE-TEMPERATURE LIMITS DESIGNATED IN MIL-C-11015D
- 4 TEMPERATURE COEFFICIENT IN PARTS PER MILLION PER DEGREE CENTIGRADO
- # OFTIONAL CODING WHERE METALLIC PIGMENTS ARE UNDESIRABLE

C. COLOR CODE MARKING FOR MILITARY STANDARD CAPACITORS

ESC-FM 913 73



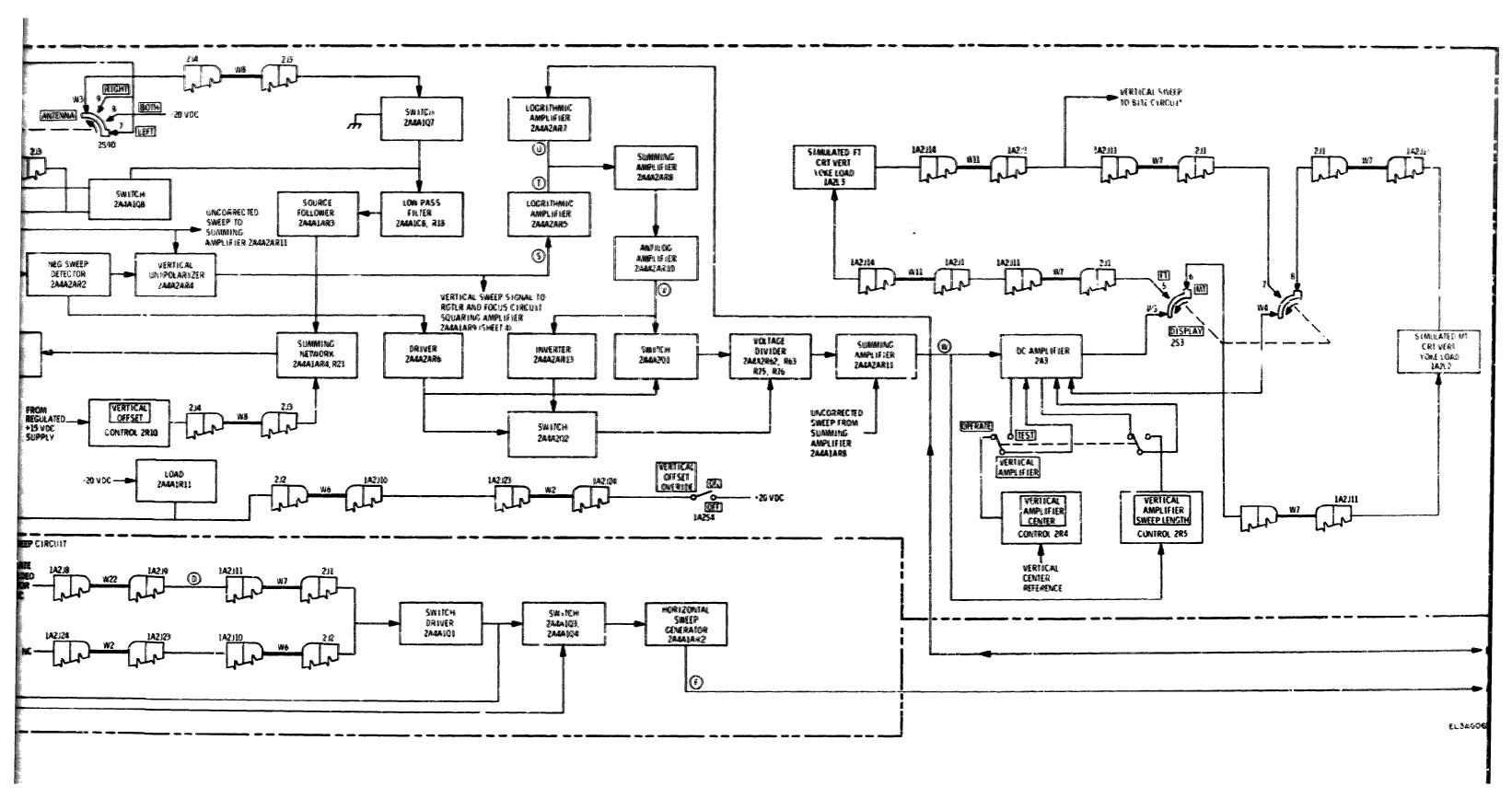
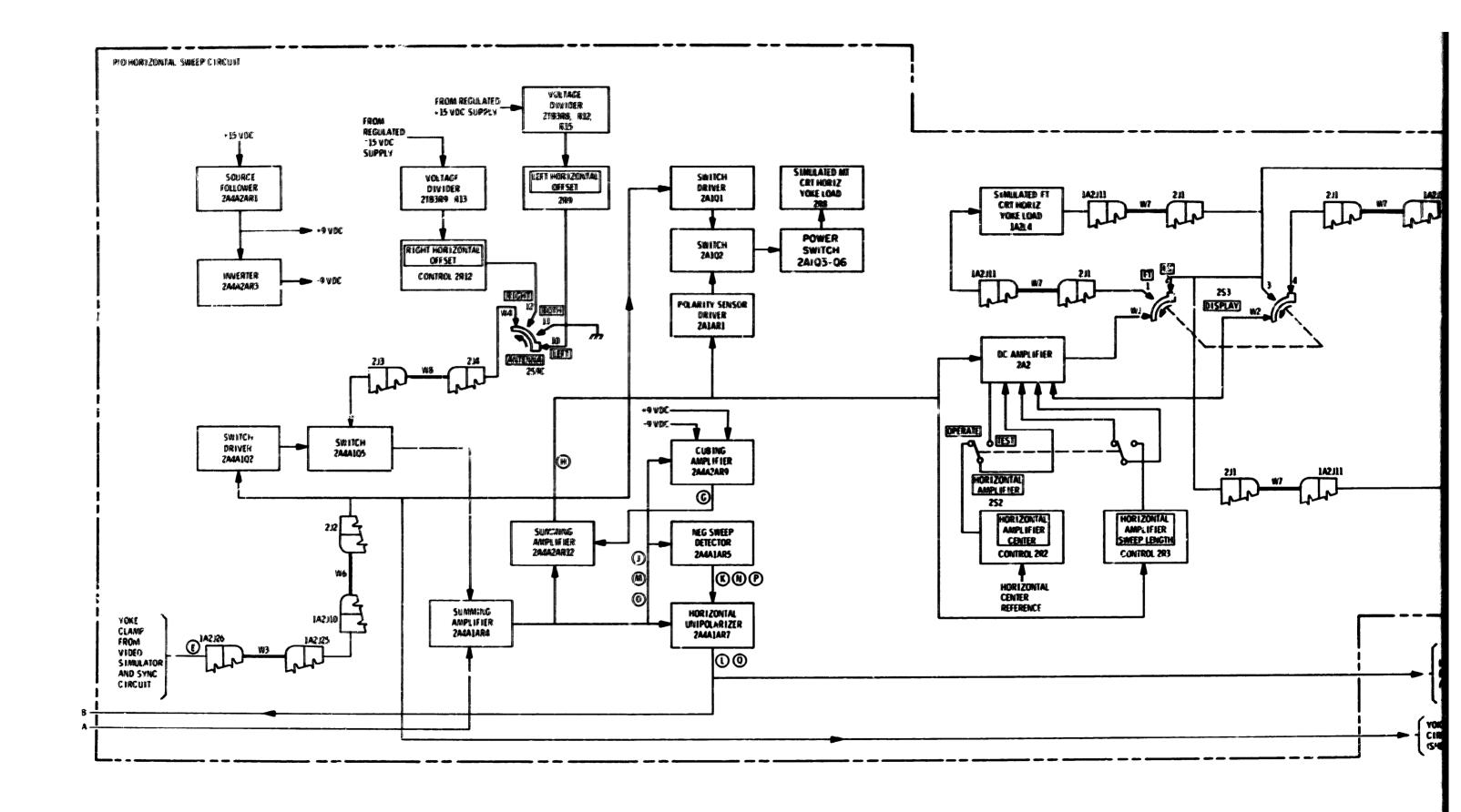


Figure FO-2. Indicating system detailed functions, block diagram (sheet 1 of 4)



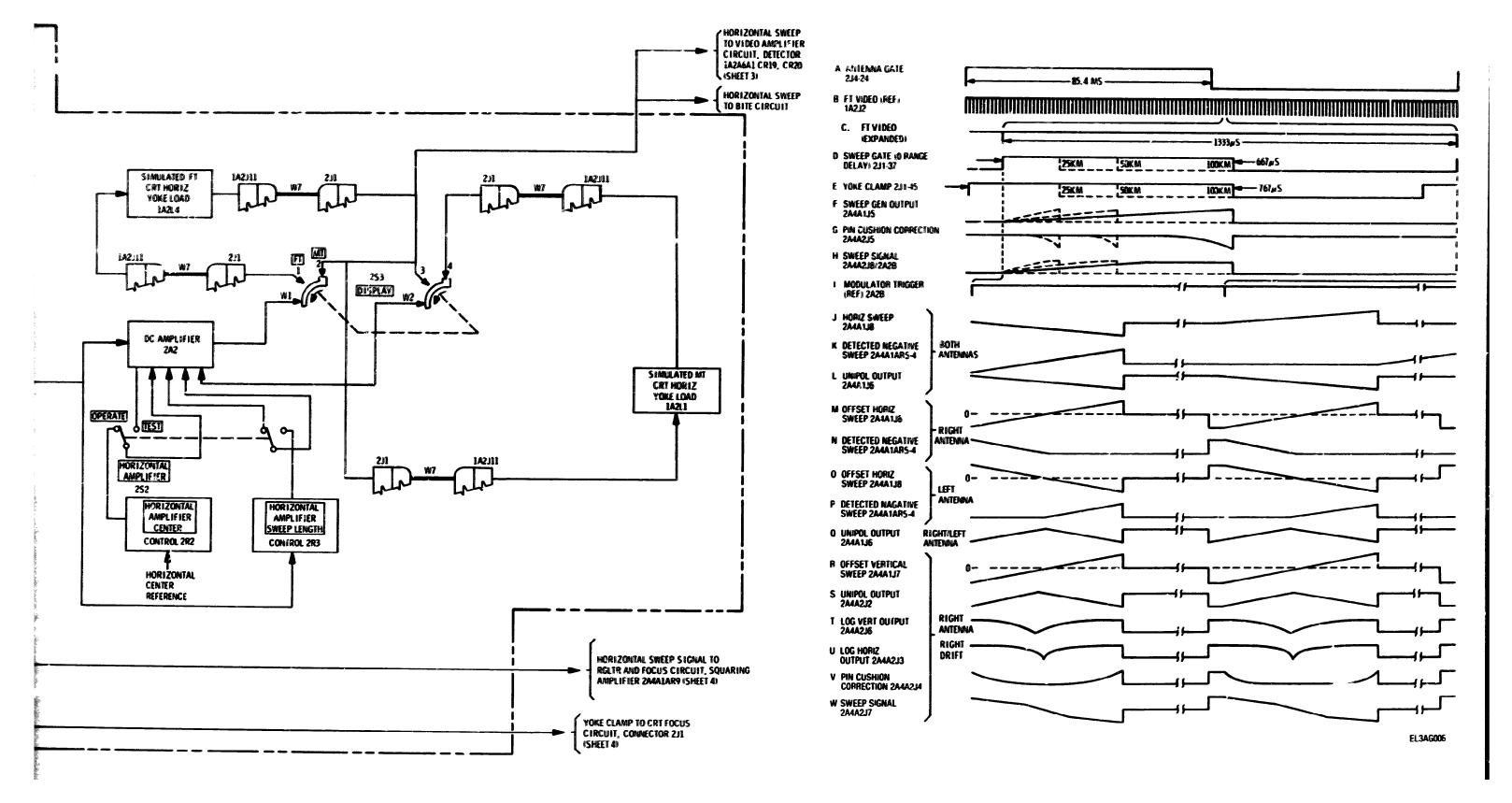
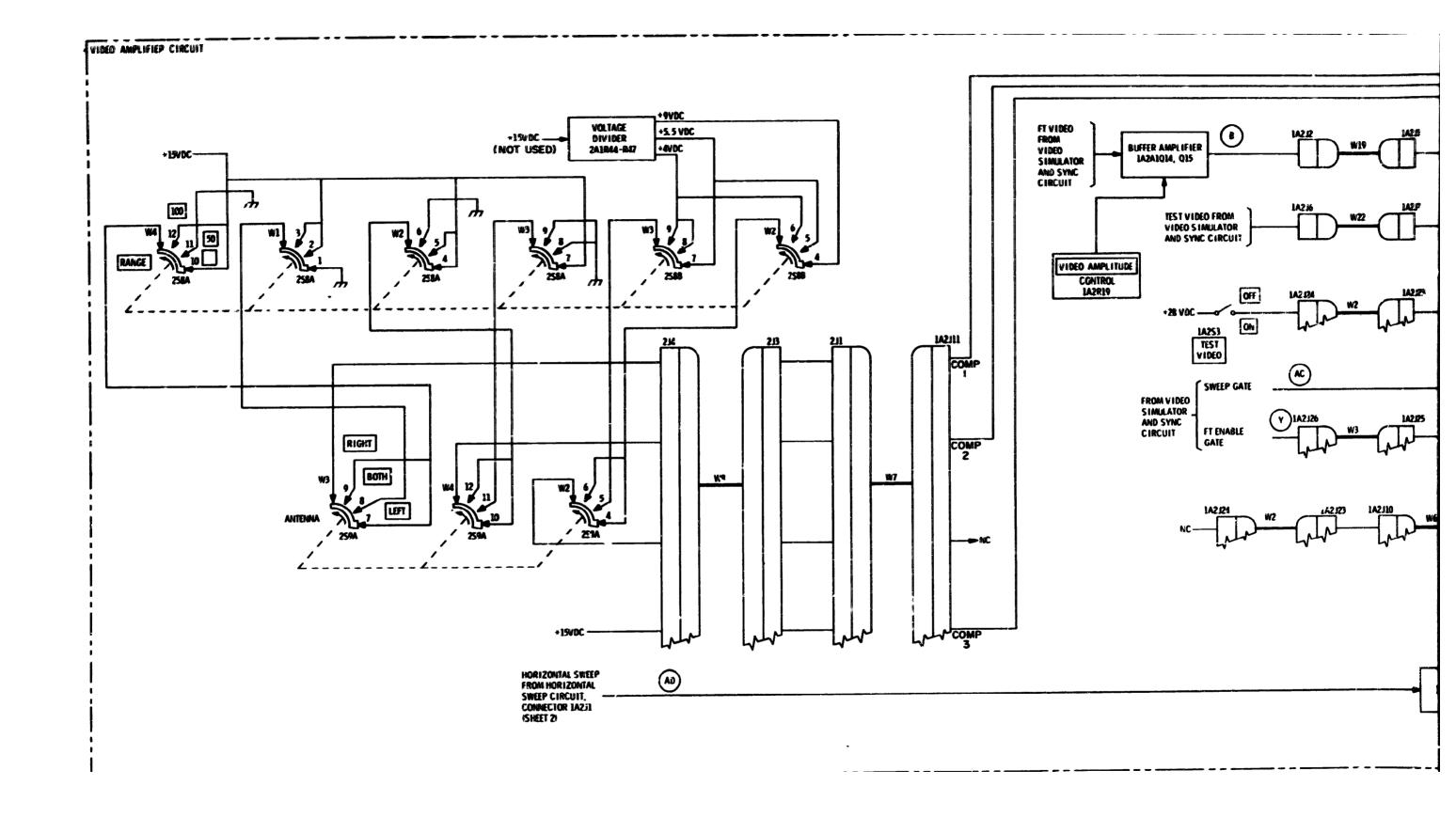


Figure FO-2. Indicating system detailed functions, block diagram (sheet 2 of 4)



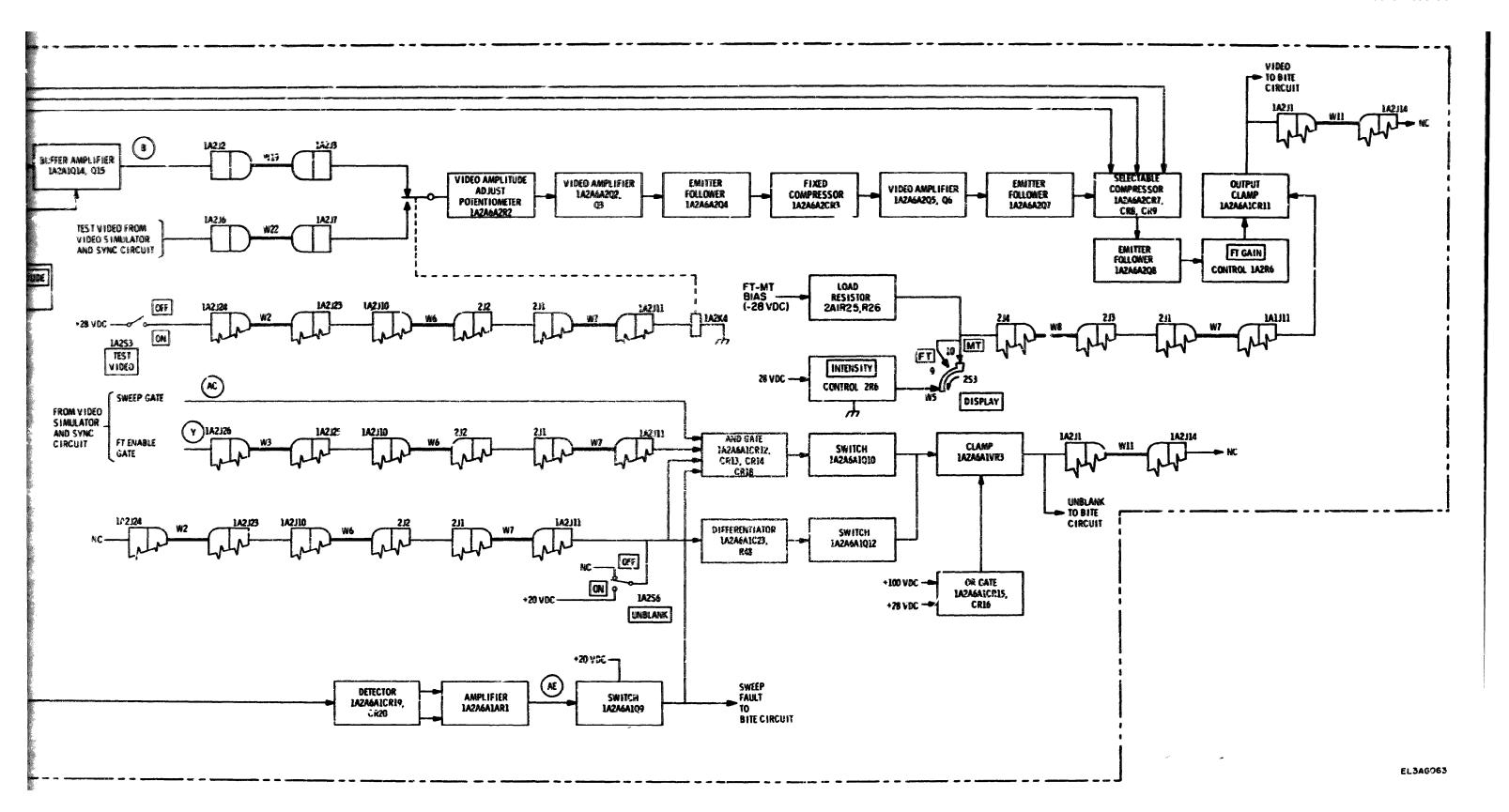


Figure FO-2. Indicating system detailed functions, block diagram (sheet 3 of 4)

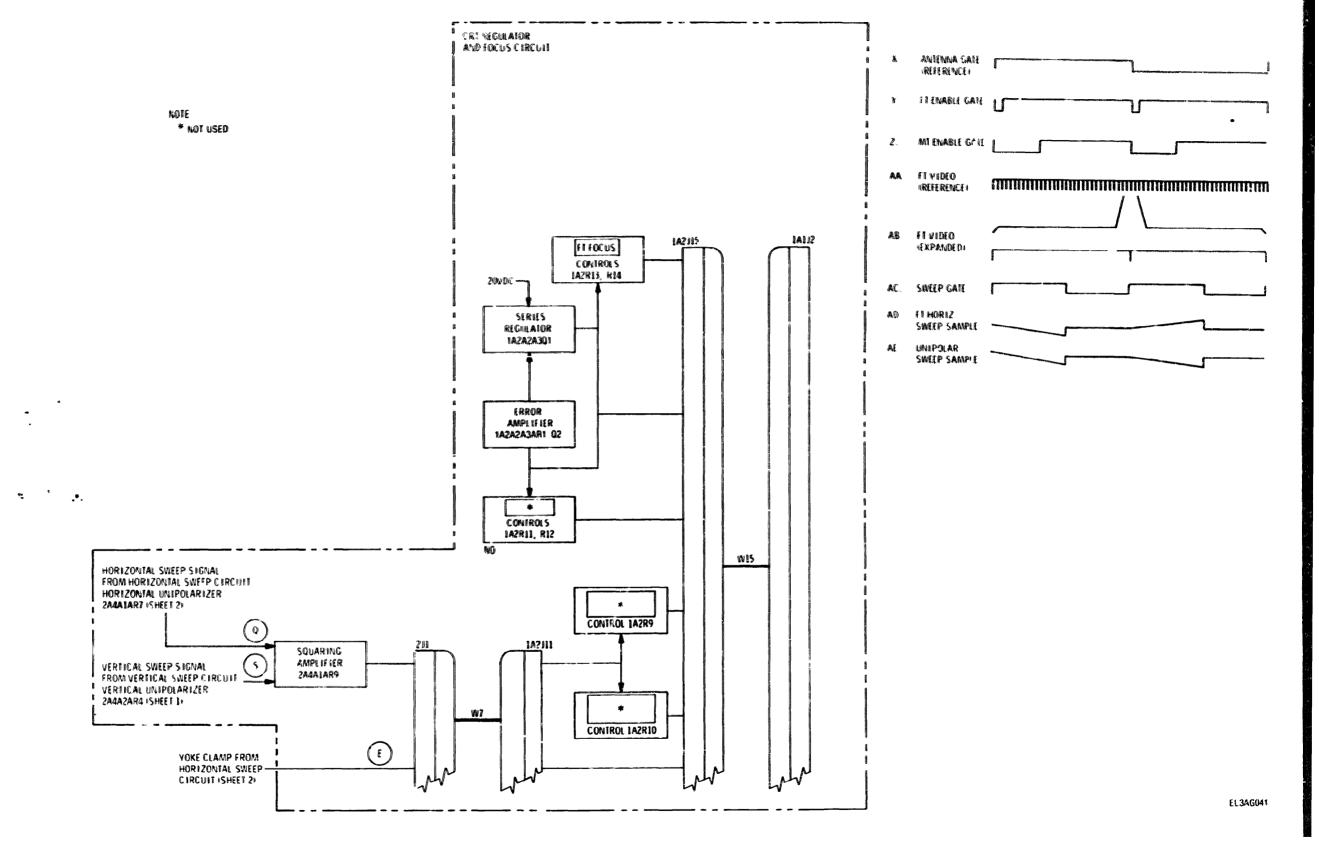
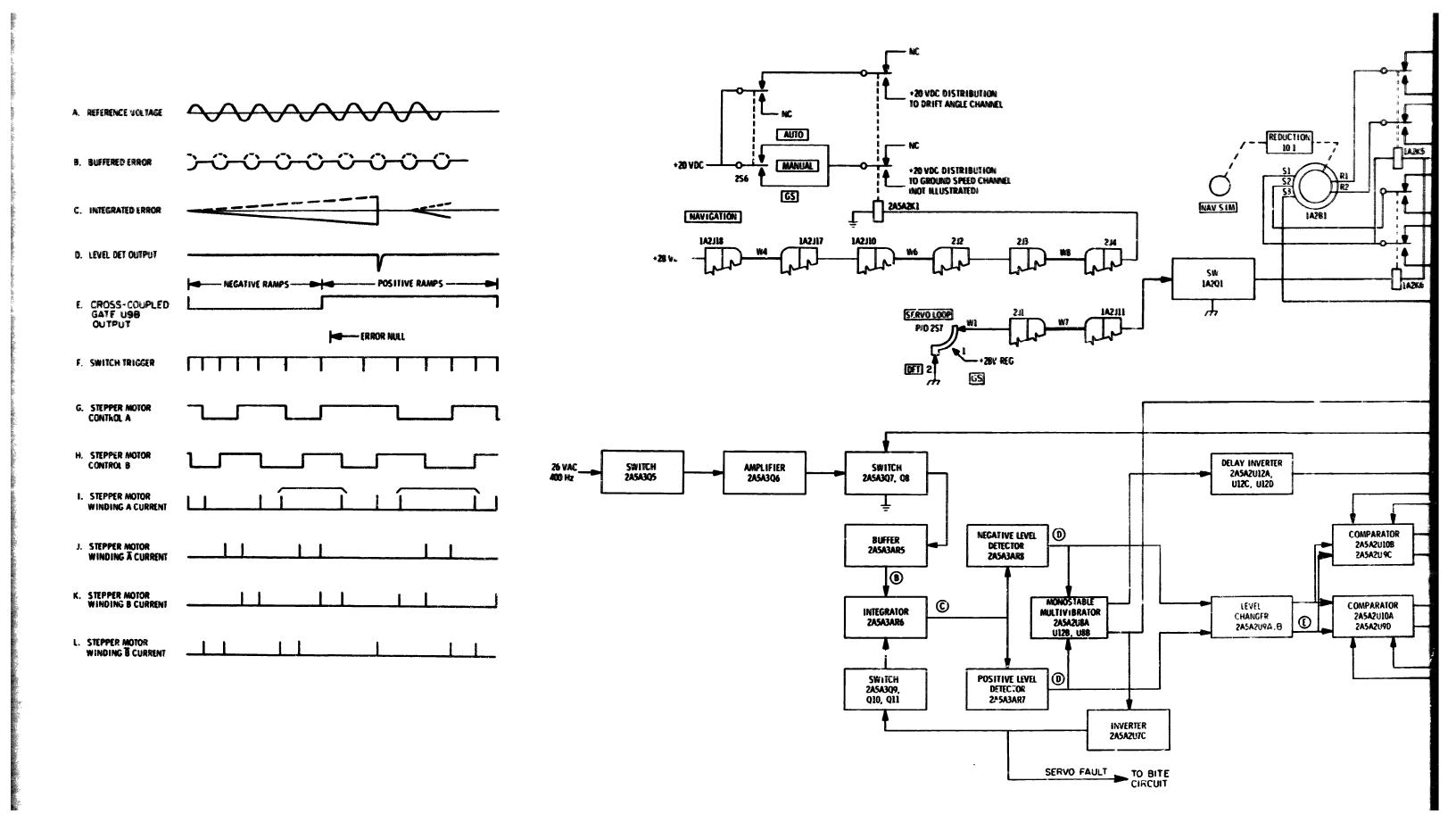


Figure FO-2. Indicating system detailed functions, block diagram (sheet 4 of 4)



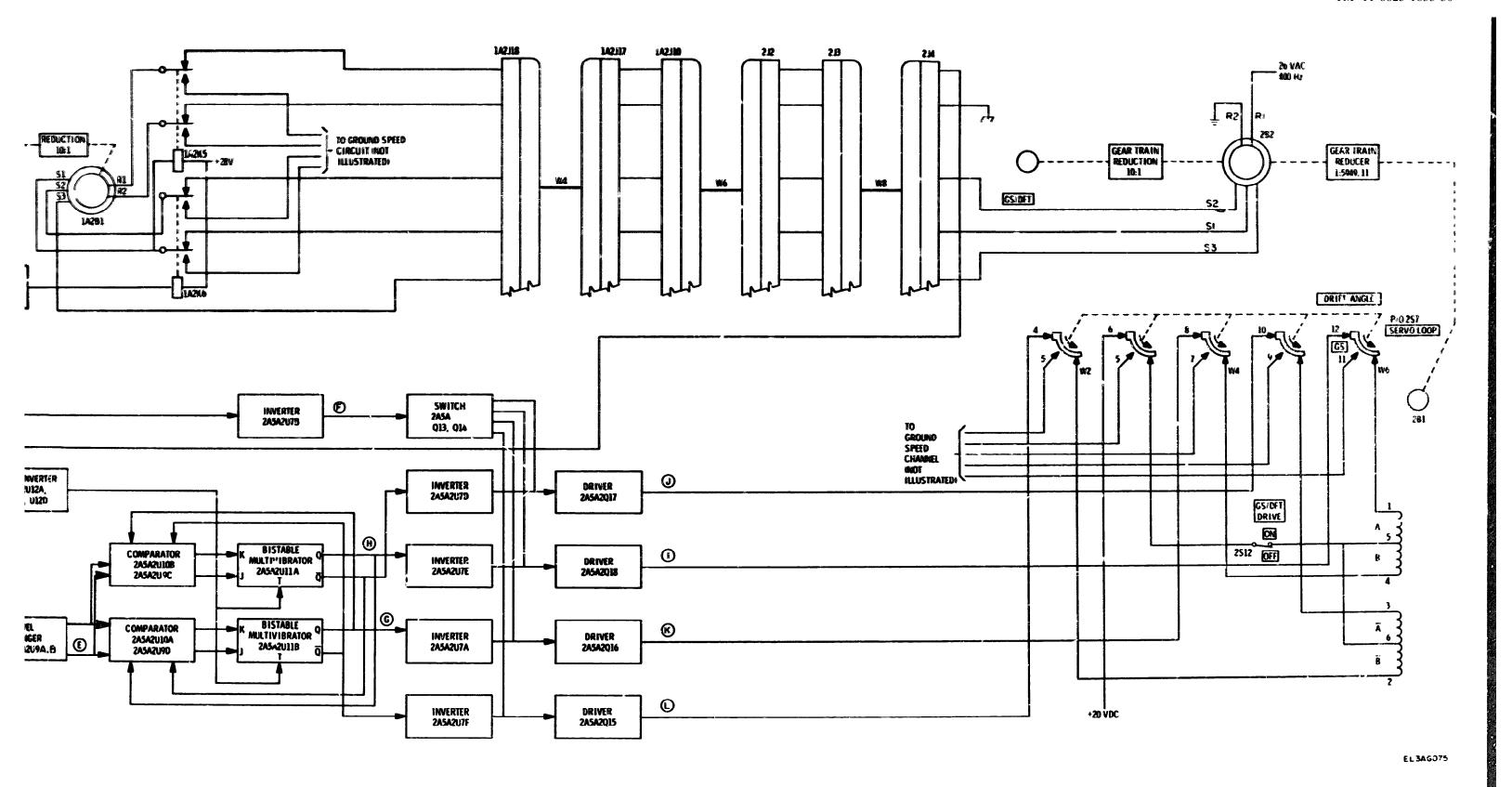
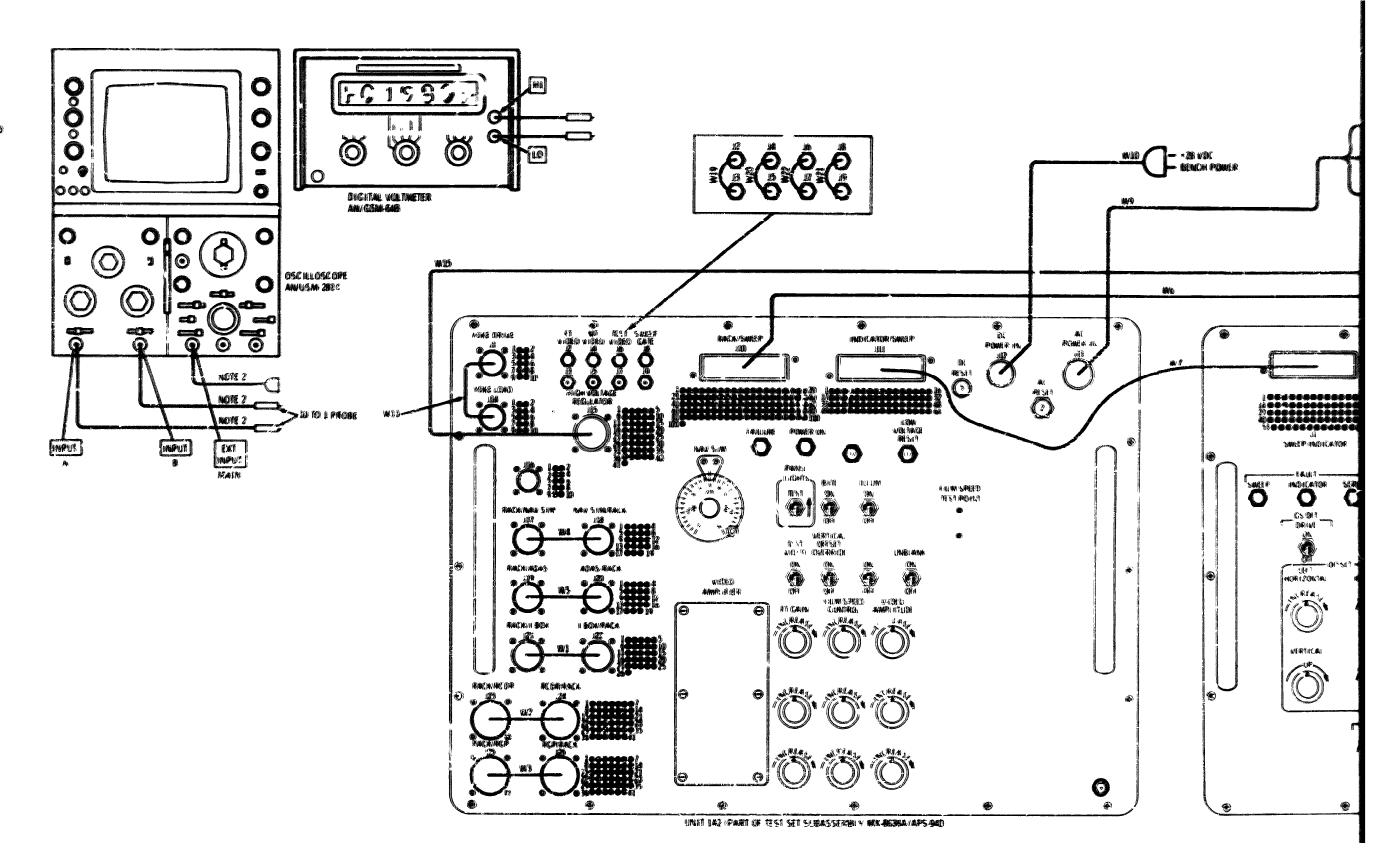


Figure FO-3. Draft angle servo loop, block diagram

NOTES

- E. Cagles we inhough wee, wee, wer wir inhough wee and web and pairt of test set subassembly mu-8630 aps 940
- 2. CABLES ARE PART OF OSCILLO-SCOPE ANNUSM-281A.
- 3. INDICATES EQUIPMENT MARKING.



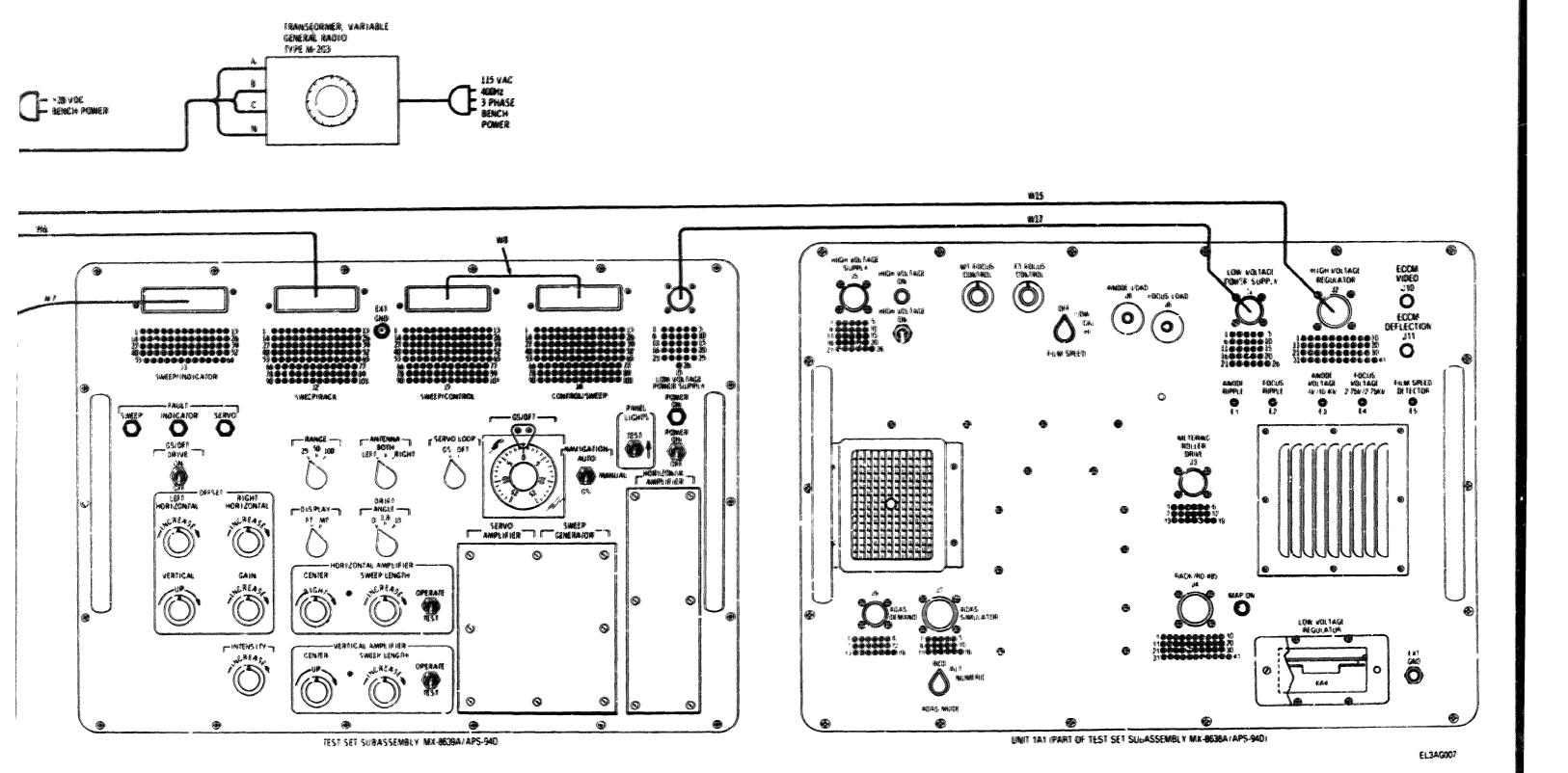


Figure FO-4. Test set group, band test setup

SMEST RANCA INDICATOR! MORCATOR RACK/ RGP 125 P2 1A2125 SMETP SMEP RACK/ SHEEP JID RCP: RACX 126 SMEEP RACK IND (CATOR SWEEP SMEEP MOKATOR SI. 310 411 114 P1 212 P/0 PID P1 211 231 Pi PP LATURE LARISS PR 1A2 126 P1 PIO (III **M**3 国人 NOTE [_____ INDICATES EQUIPMENT PO LAZISE SMELP CONTROL SMELP NAV SIMI RACK 118 RACK RACA OC POWER IN 112 £16 RACK 12 OC RESET NAV SIM SACEP CONTROL SMITP ×29W 43 120 IA2 **◆** 国 P1 230 22 1A2117 213 P2 PIO P2 142112 P1 232 1A2118 P1 union pr 12 12 H 1-90x SWEEP RACK 12 P1 2.12 SWEEP! INDICATOR 海 1-80x 121 P2 1A2121 BACK SWELP 1111 P2 (A2/11) DC "OWER 122 6 POMER ON SPARE 14?782 1A2110 P2 22 22 IA2 - 28V RIN FL-LP PARSUP A PO JAZAD LOW VOLTAGE PINE SUP AND REG AC POWER 100 LAZAS OVERVOLI P/0 [a2%] CONTROL ADASI SMIP AC RESELI CM? ADAS RACK J20 CONTROL SMELP **PROMECT** 922 1 1 5 2 13 P) 750 1A2110 P2 213 P2 P1 142,220 本国 Li 115 VAC) PHASE HIS WAR 人回 400 Hz FL-LP 021 1. 5 E E SPARE Own -142181 BIS WAT I-BOK/ RACK J22 RACK/ 1 BOX 121 P2 1A2121 MIP RACA SWEEP \Diamond 17 110 PI 212 142122 P1 LAZJIO PZ 920 1.5 Out -188 189 200 WW WW IIIS WAC 国 18 图》 回春 001-{ **\$** 142 11 SMIP EXI CHO RACK SWILE RACK/NAV COL RO P1 232 115 VAC RACK U18 SIM H7 1A2E26 EXT GNO OH **S**1 110 219 PZ PZ TAZJIT 1AZJIO PZ LAZILE PI EXT GNO ON

NUA "KING

* NOT USED

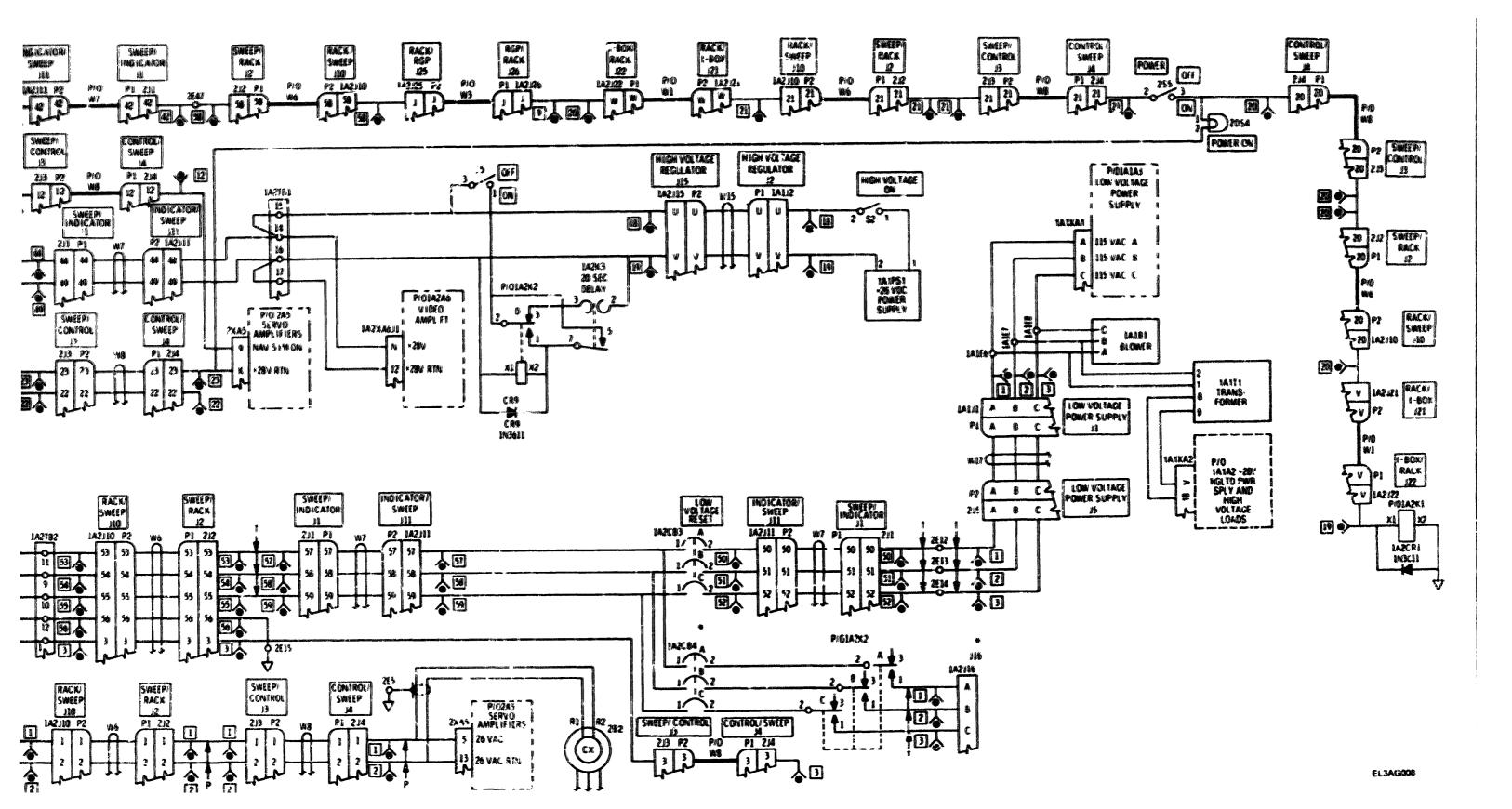


Figure FO-5. Primary power distribution and control diagram

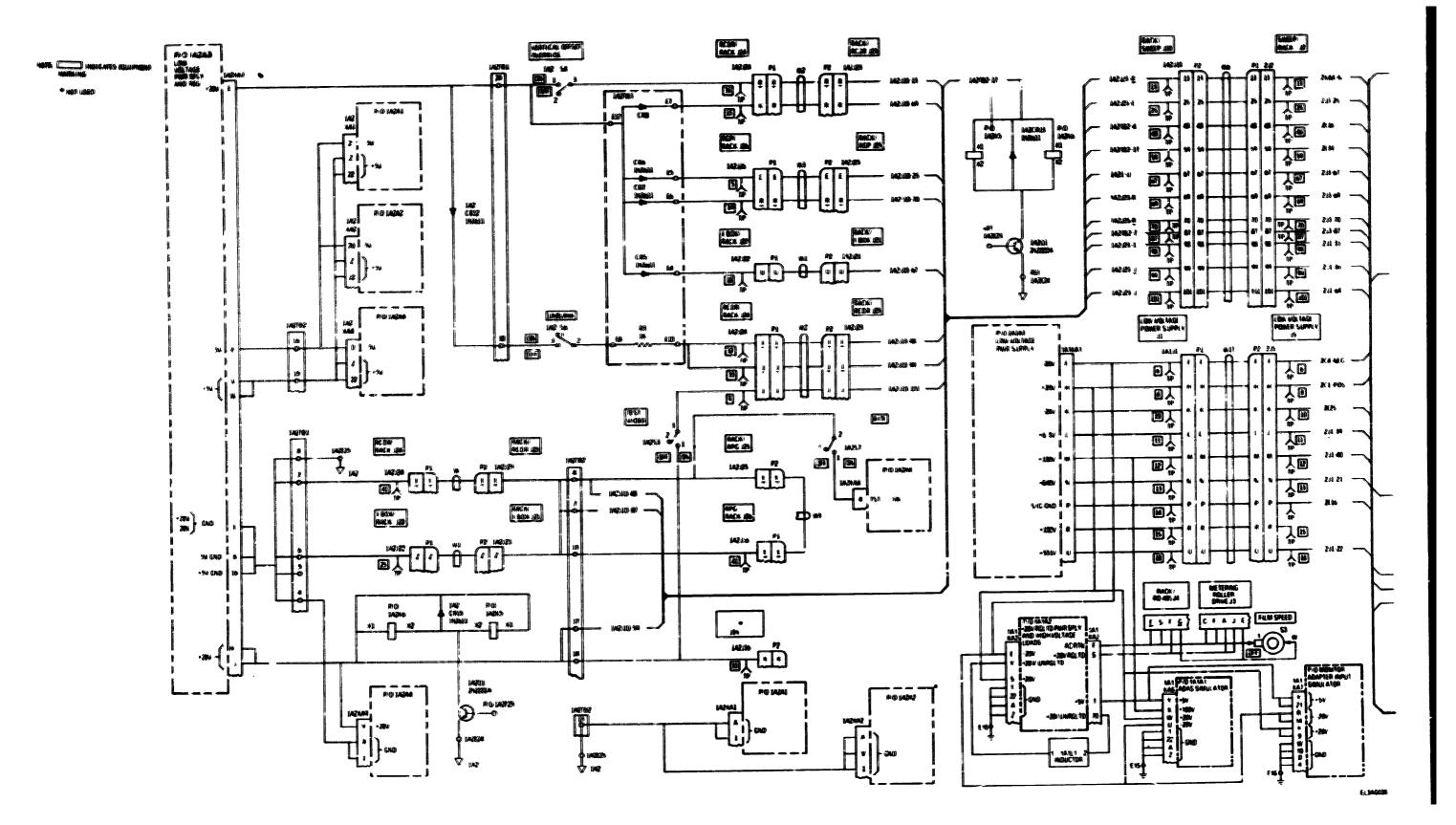
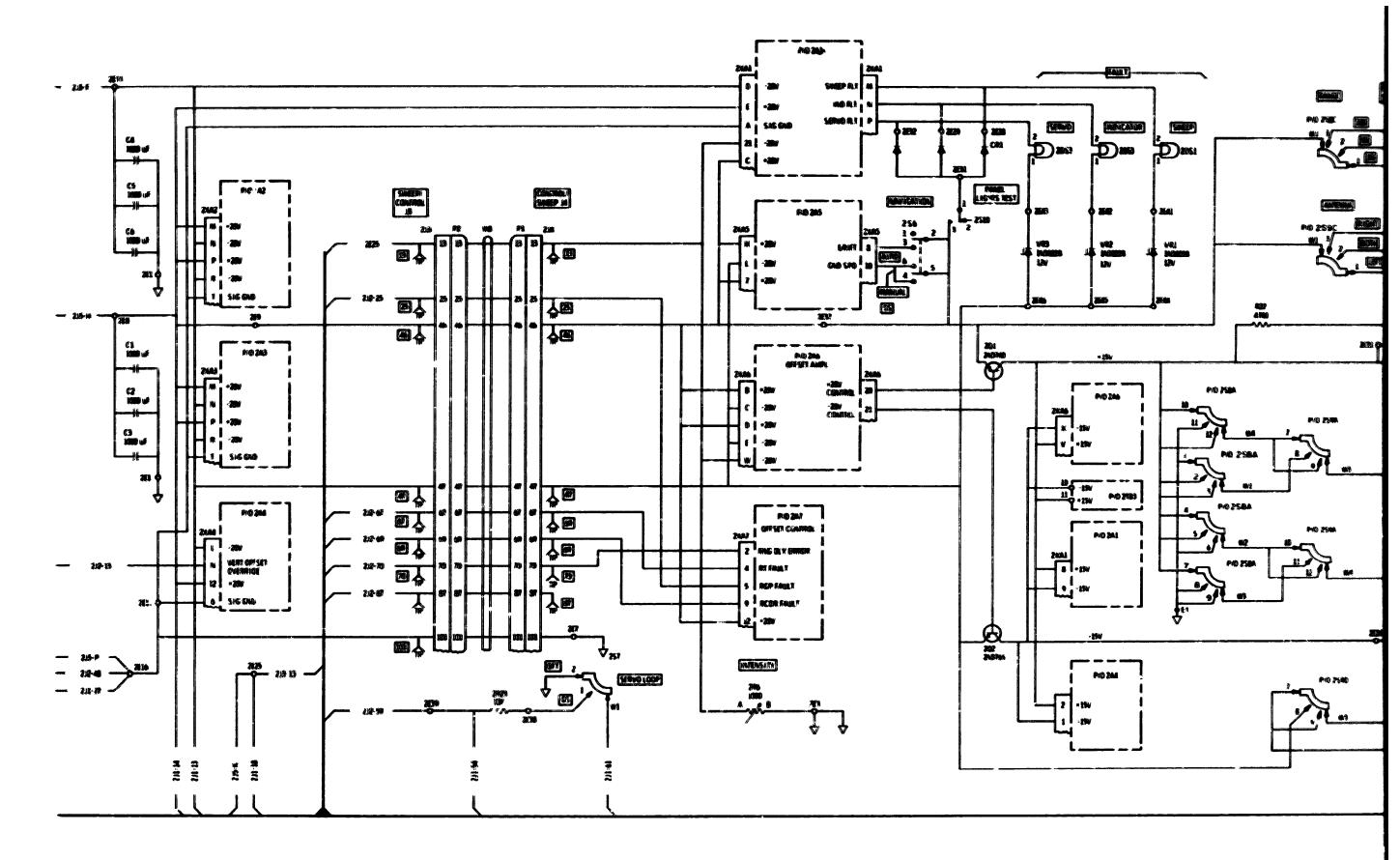


Figure FO-6. Secondary power distribution and control circuit diagram (sheet 1 of 3)



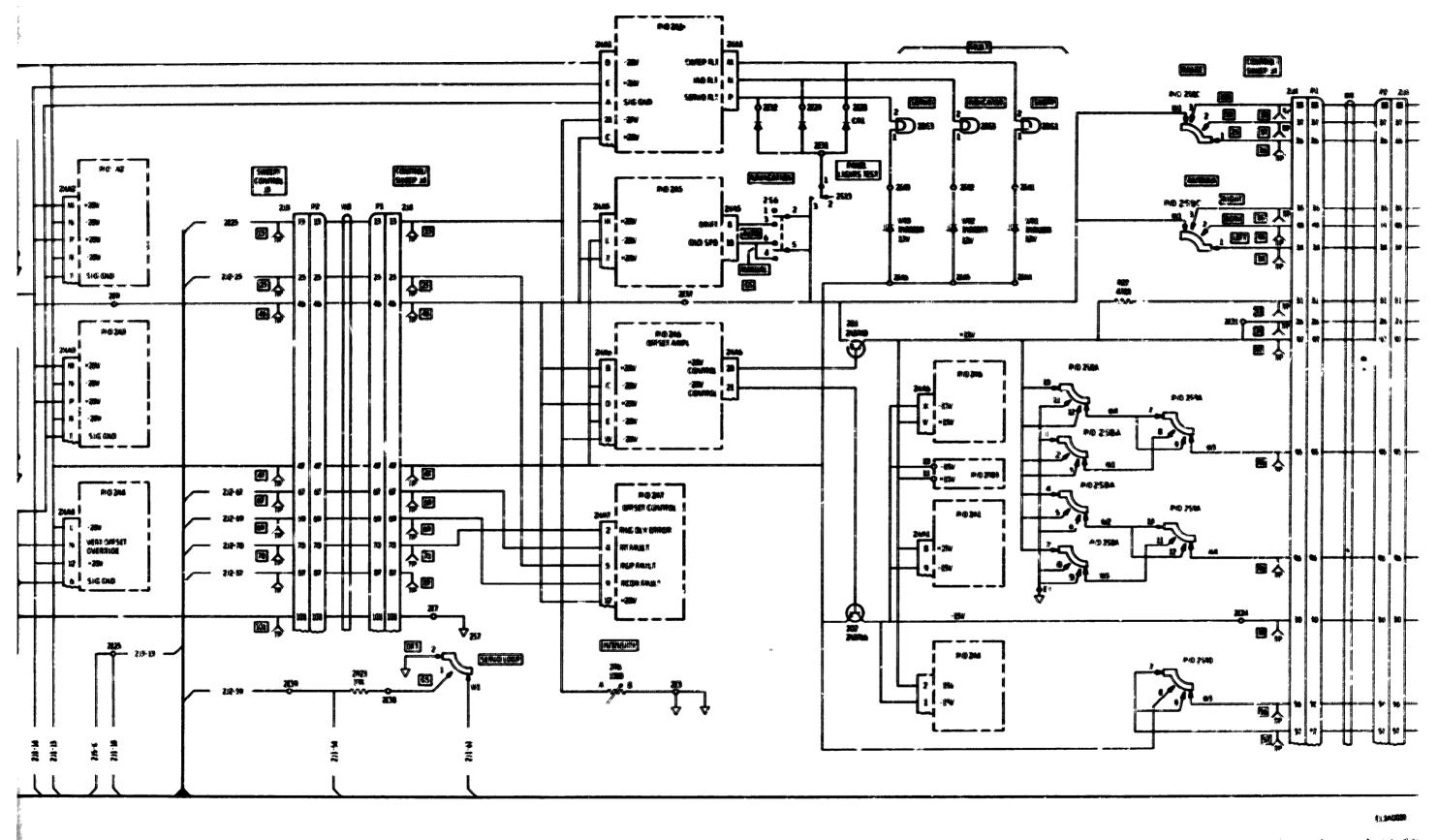


Figure FO-6 Secondary power destribution and control circ . dagram (short 2 of 3)

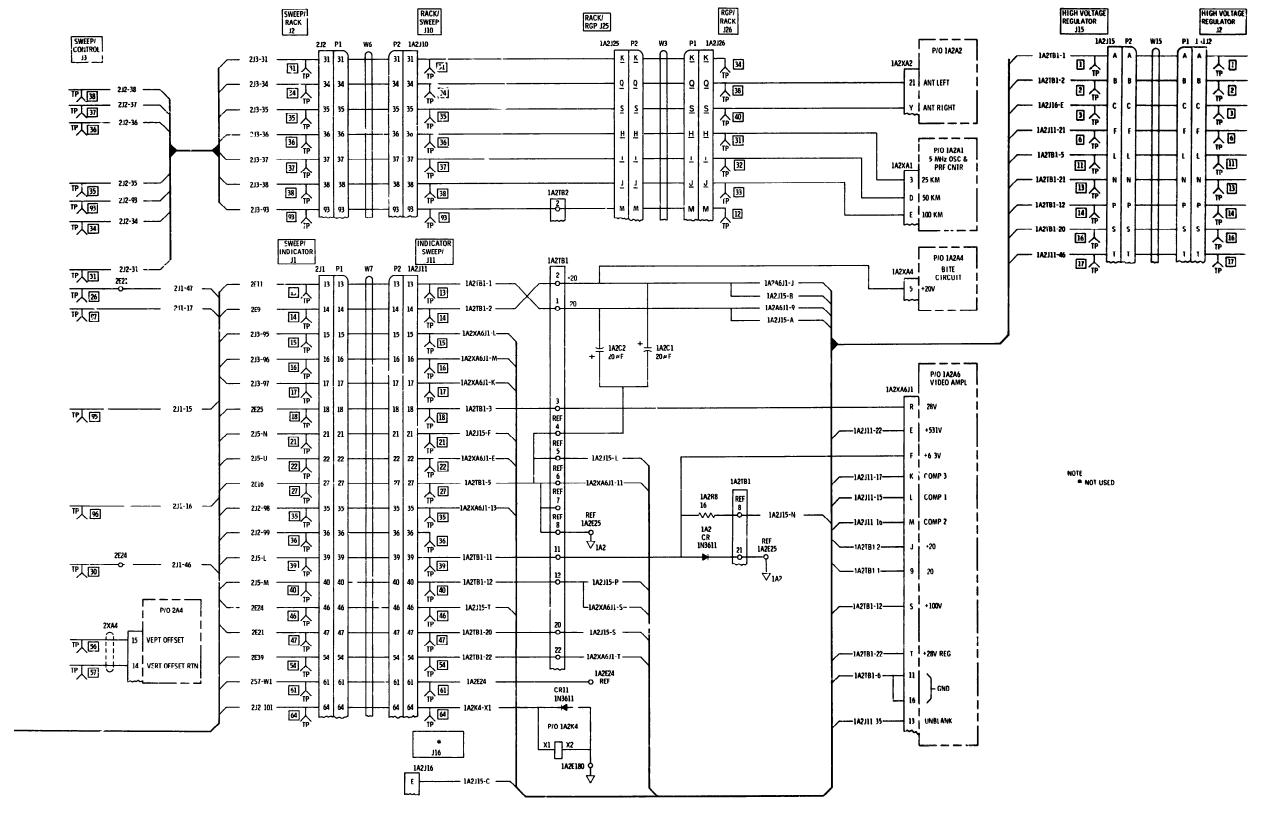


Figure FO-6. Secondary power distribution and control circuit diagram (sheet 3 of 3)

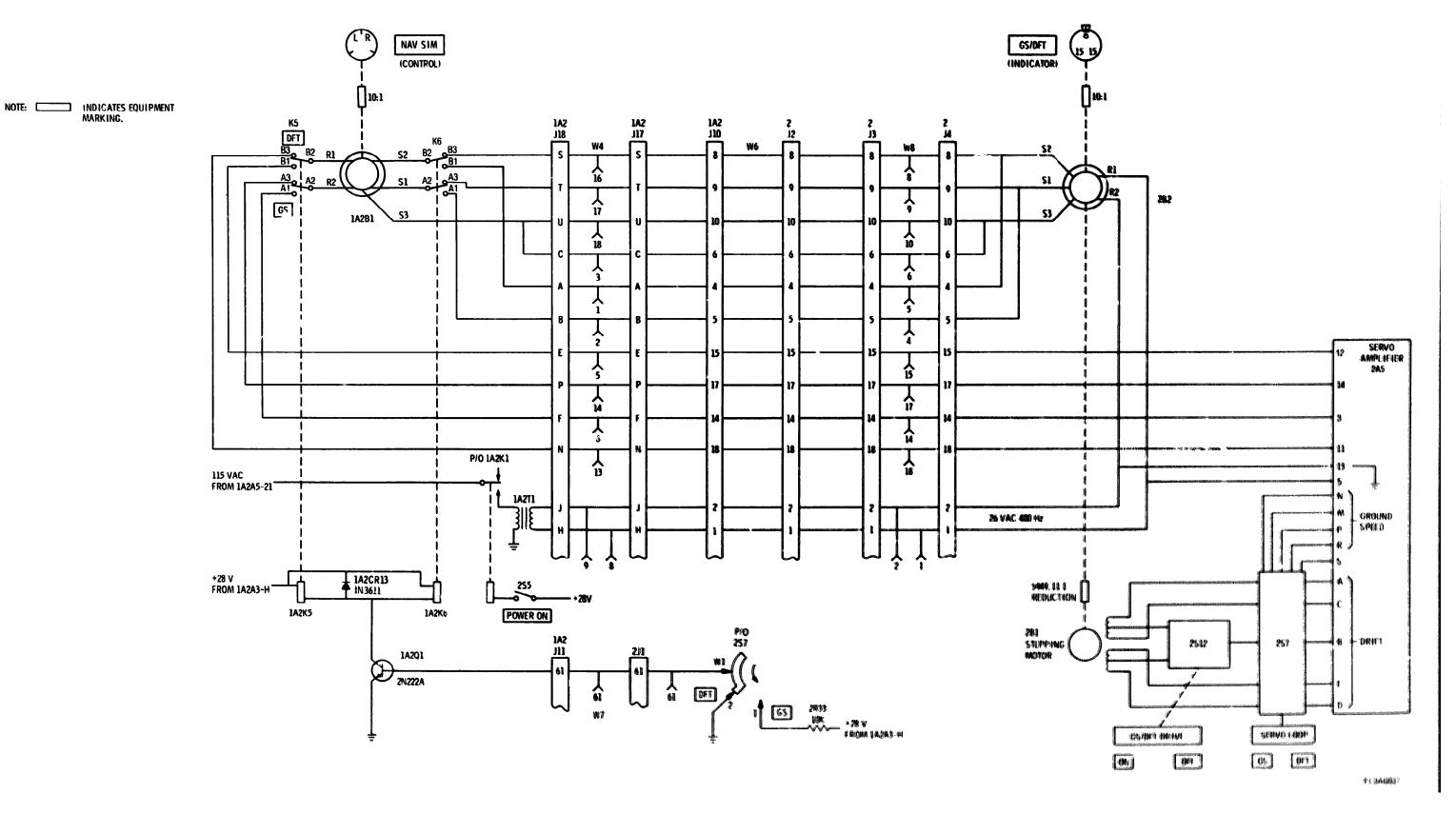


Figure FO-7.

NOTES:

- PARTIAL REFERENCE DESIGNATIONS
 ARE SHOWN FOR COMPLETE DESIGNATIONS
 PREFIX WITH 2.
- UNLESS OTHERWISE SPECIFIED: ALL RESISTORS ARE IN OHMS. ALL CAPACITORS ARE IN µF.
- 3. SEMICONDUCTOR DEVICES A6A1Q4 AND A6A1Q2 PIN ORIENTATION IS AS SHOWN BELOW.



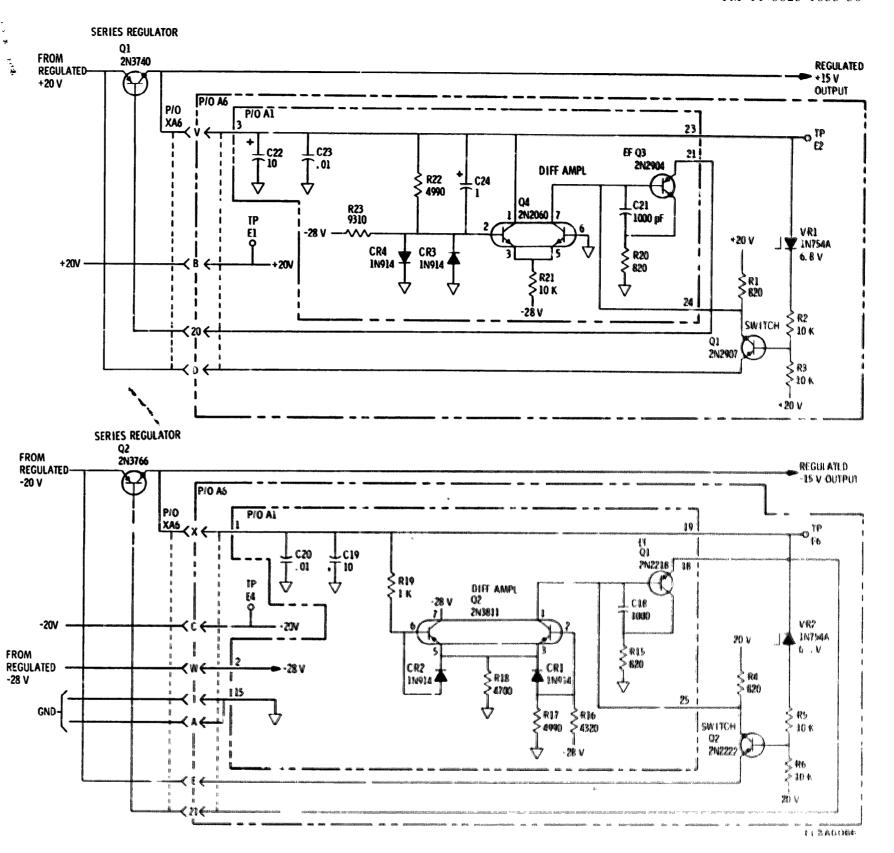
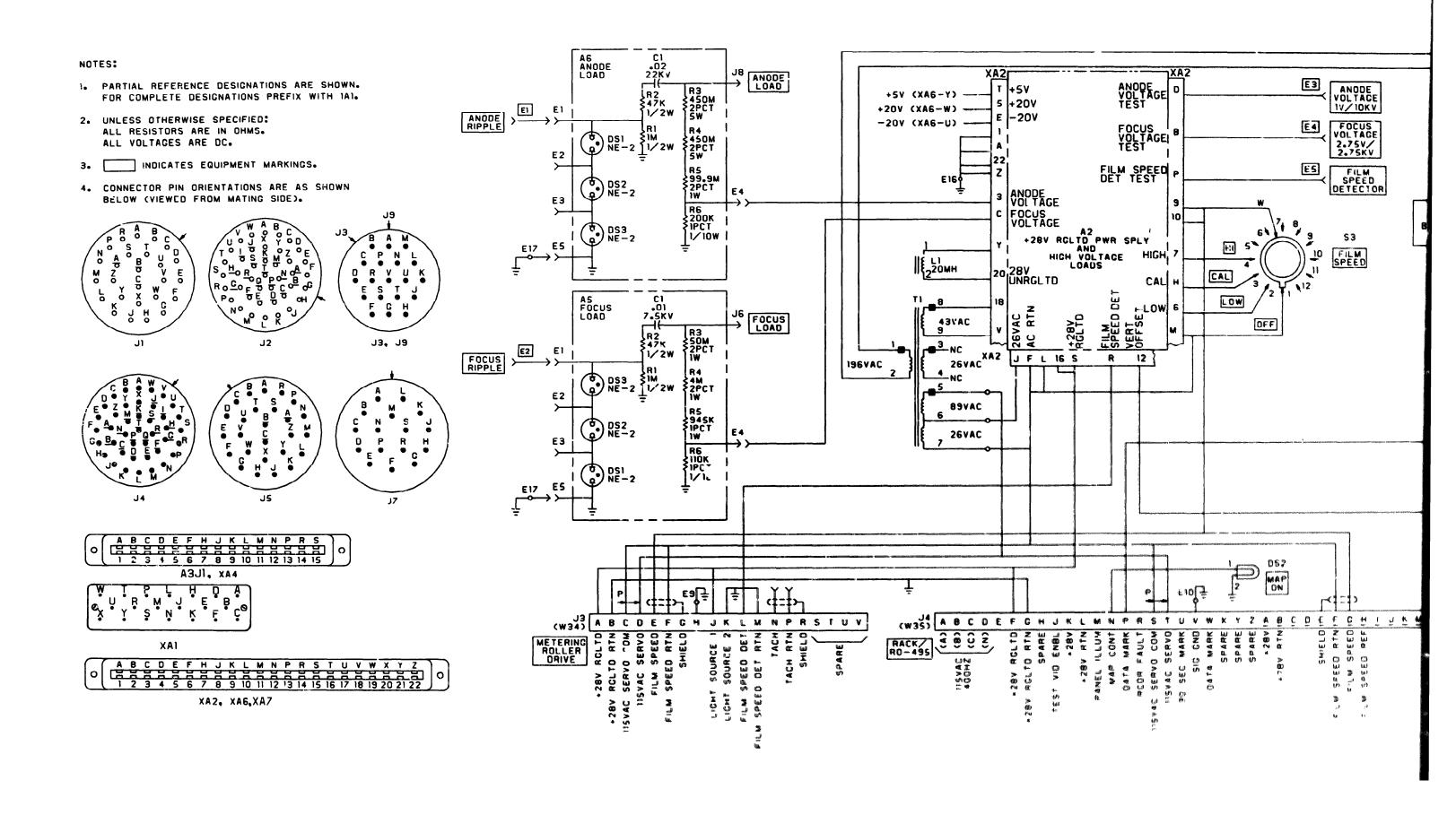


Figure FO-8. pyram will pinner augustus functional achemistic



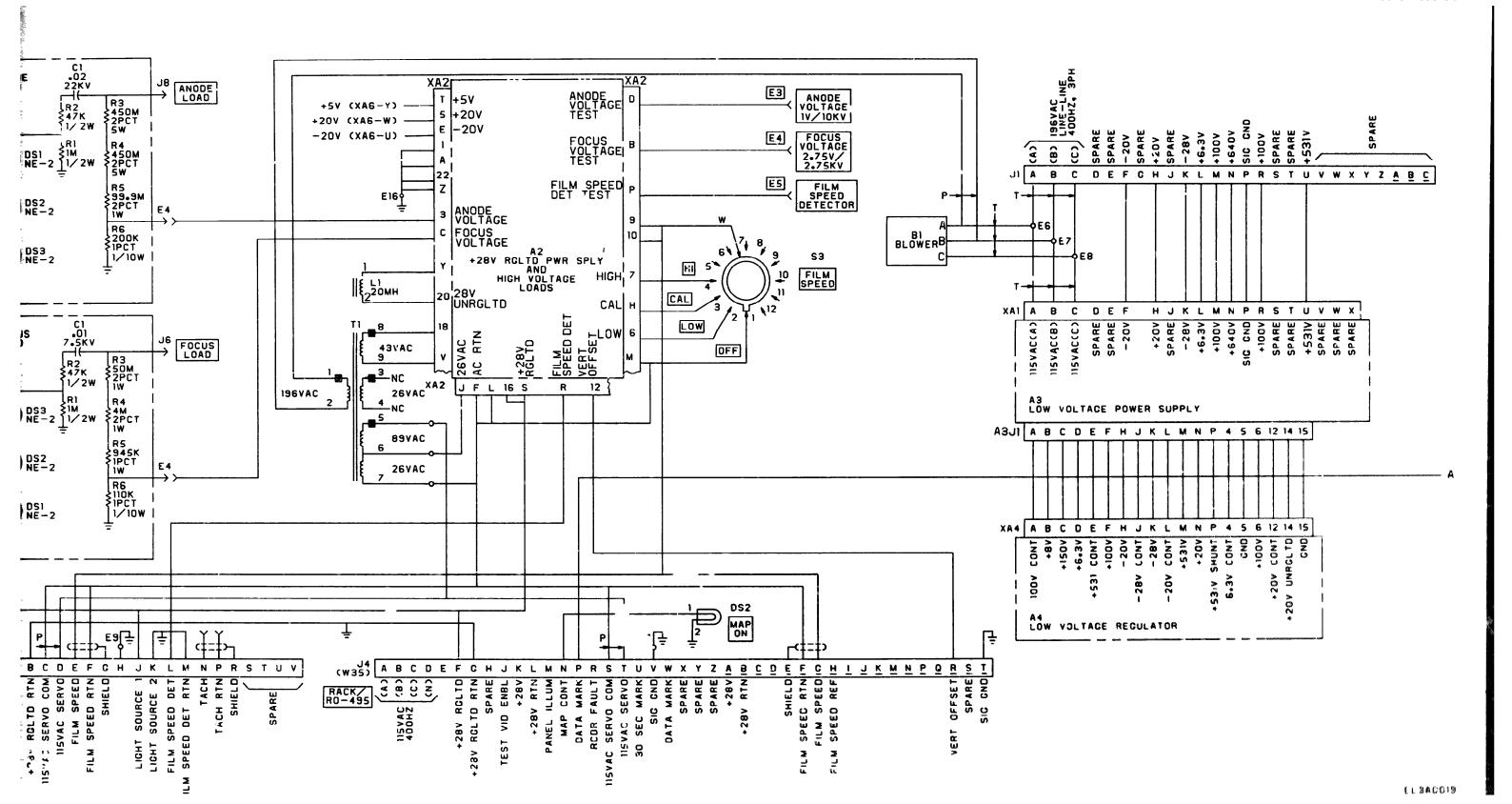


Figure FO-9. Test Set Subassembly MX-8638A/APS-94D Unit 1A1, interconnection diagram (sheet 1 of 2)

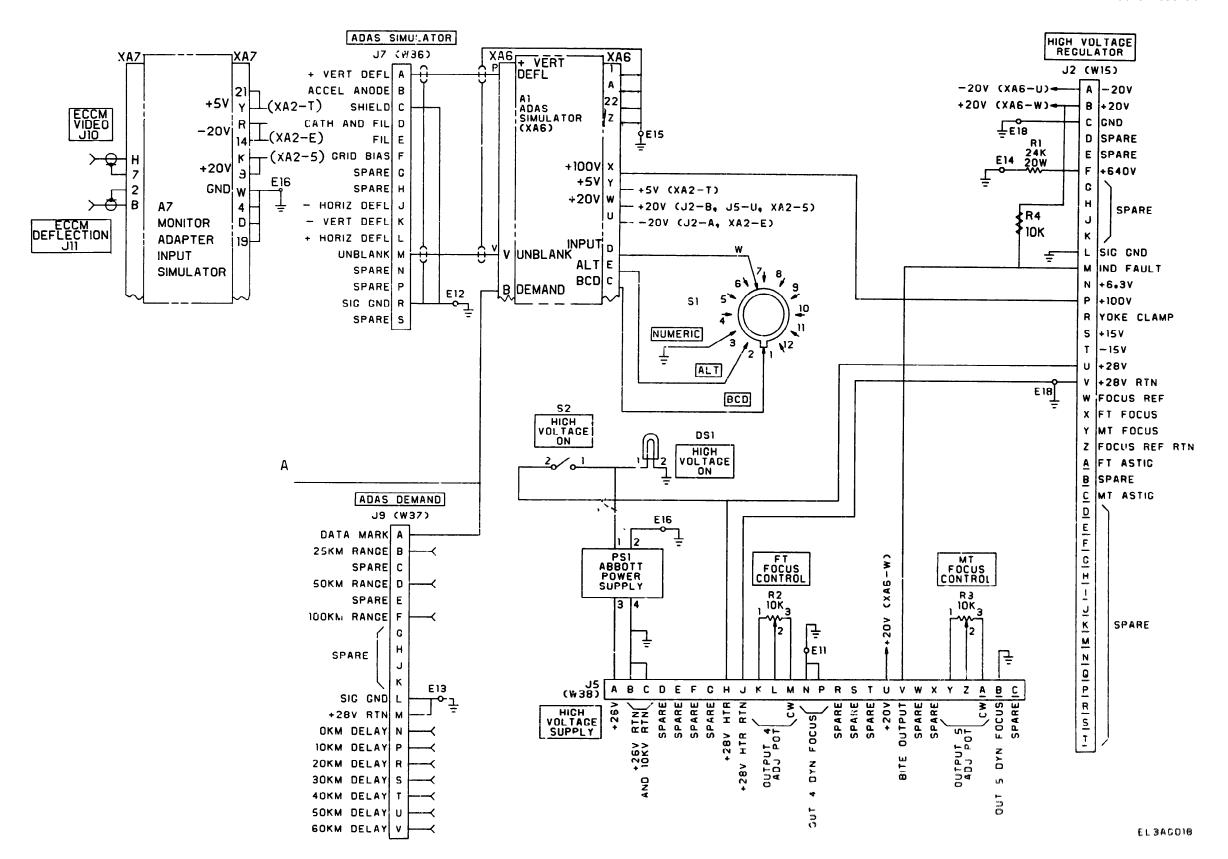


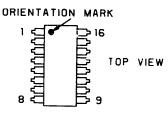
Figure FO-9. Test Set Subassembly MX-8638A/APS-94D, Unit 1A1, interconnection diagram (sheet 2 of 2)

NOTES:

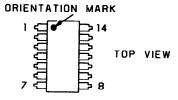
- 1. PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. FOR COMPLETE DESIGNATION PREFIX WITH IAIAI.
- 2. UNLESS OTHERWISE SPECIFIED:
 ALL RESISTORS ARE IN OHMS, ±5 PCT, 1/4 WATT.
 ALL CAPACITORS ARE IN UF.
 ALL VOLTAGES ARE IN DC.
- 3. INTEGRATED CIRCUIT DEVICES ARE IDENTIFIED ON THE DRAWING BY THE UNDERLINED PORTION OF THE TYPE NUMBER LISTED BELOW. VOLTAGE AND GROUND PINS. PINS WITH NO INTERNAL CONNECTION (NC) AND SPARES (IN PARENTHESIS) ARE INDICATED.

REF DES	TYPE NUMBER	+5V PIN	CND PIN	NO INTERNAL CONNECTION AND SPARE PINS
Ul	MC14 <u>528</u> B	16	8	
N.S	MC4324	14	7	(8,10,11,12,13)
N3	MC14 <u>024</u>	14	7	
U4	MC14 <u>011</u>	14	7	
U5	MC14 <u>069</u>	14	7	
U6	MC14 <u>017</u>	16	8	
U7	MC14 <u>017</u>	16	8	
N8	MC14017	16	8	
U9	MC14 <u>023</u>	14	7	
บาอ	MC14 <u>163</u> B	16	8	
บท	MC14 <u>044</u> B	16	8	
U12	MC14 <u>528</u> B	16	8	
บาว	MC14 <u>040</u> B	16	8	
U14	51-P06640F001	16	8	
U15	MC14512	16	8	
U16	MC14 <u>001</u>	14	7	(1,2,3)
U17	MC14 <u>013</u> B	14	7	
U18	MC14 <u>011</u>	14	7	

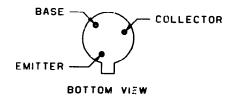
PIN ORIENTATION FOR INTEGRATED CIRCUIT DEVICES UI.
U6. AND U10 THRU U15 IS SHOWN BELOW.



5. PIN ORIENTATION FOR INTEGRATED CIRCUIT DEVICES U3 THRU U5, U9, U16, AND U17 IS SHOWN BELOW.



6. PIN ORIENTATION FOR SEMICONDUCTOR DEVICES
Q1 THRU Q11 IS SHOWN BELOW.



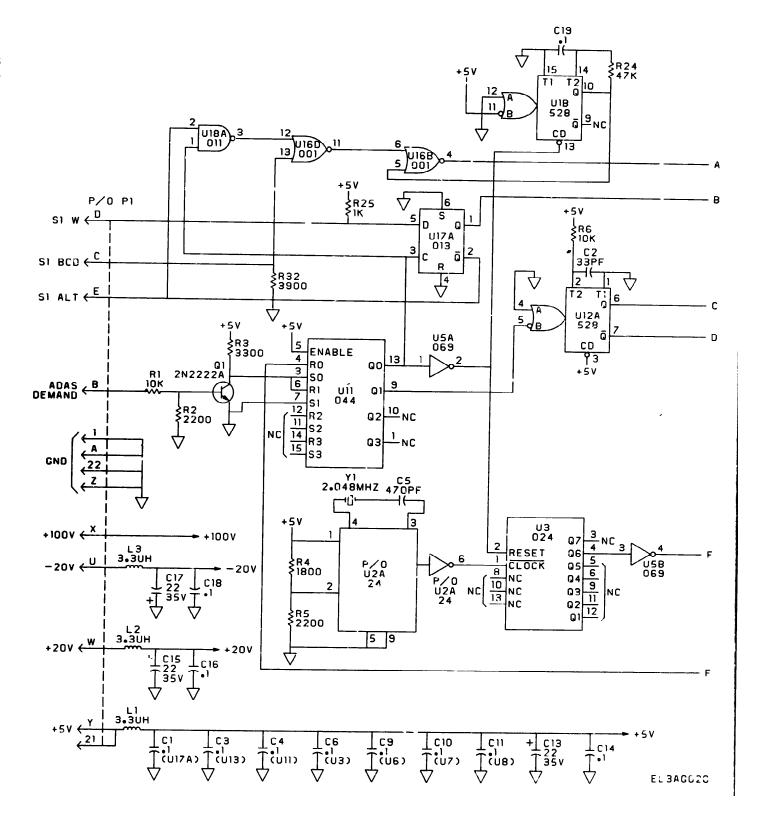
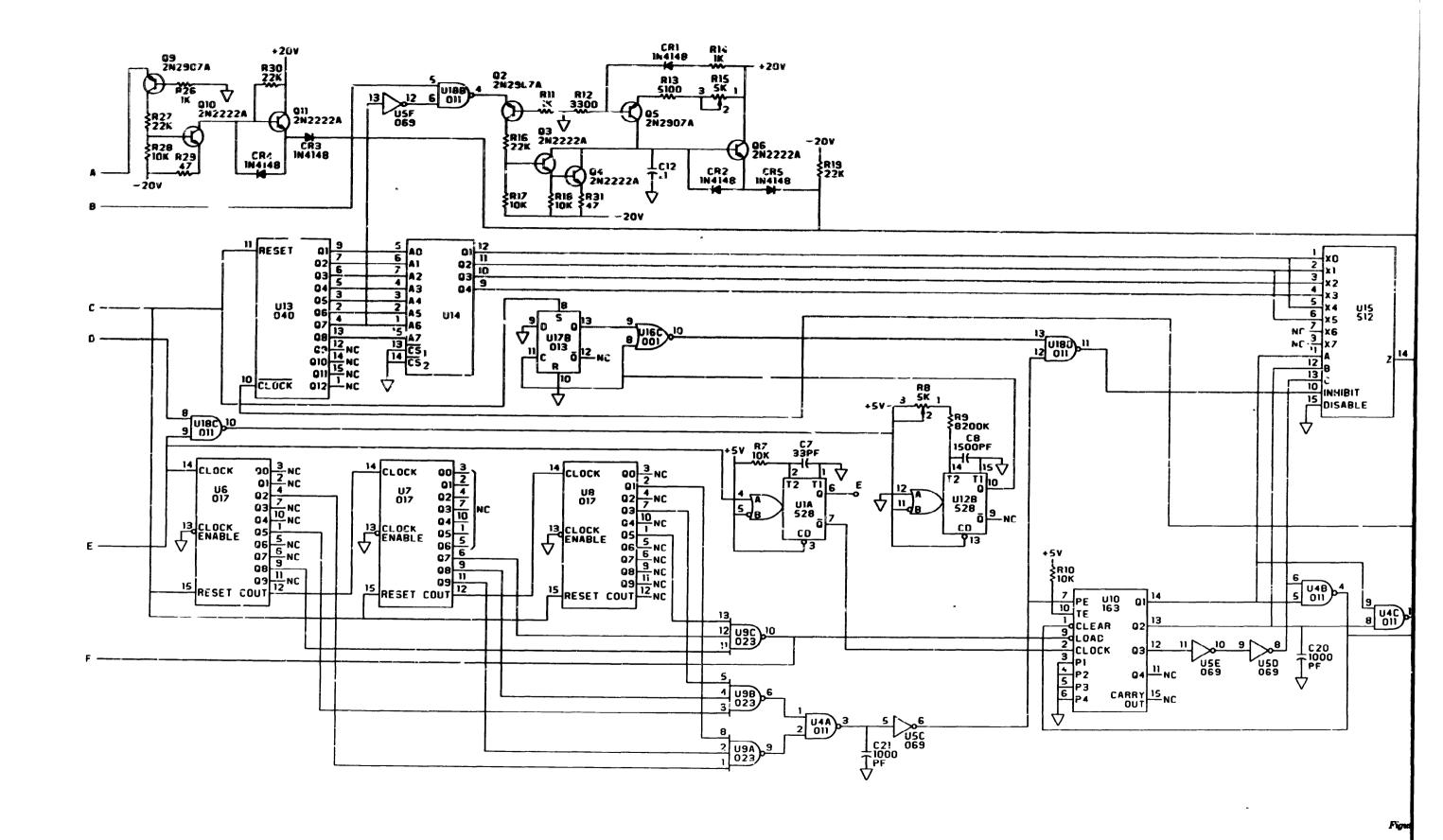


Figure FO-10. ADAS Simulator module 1A1A1, schematic diagram (sheet 1 of 2)



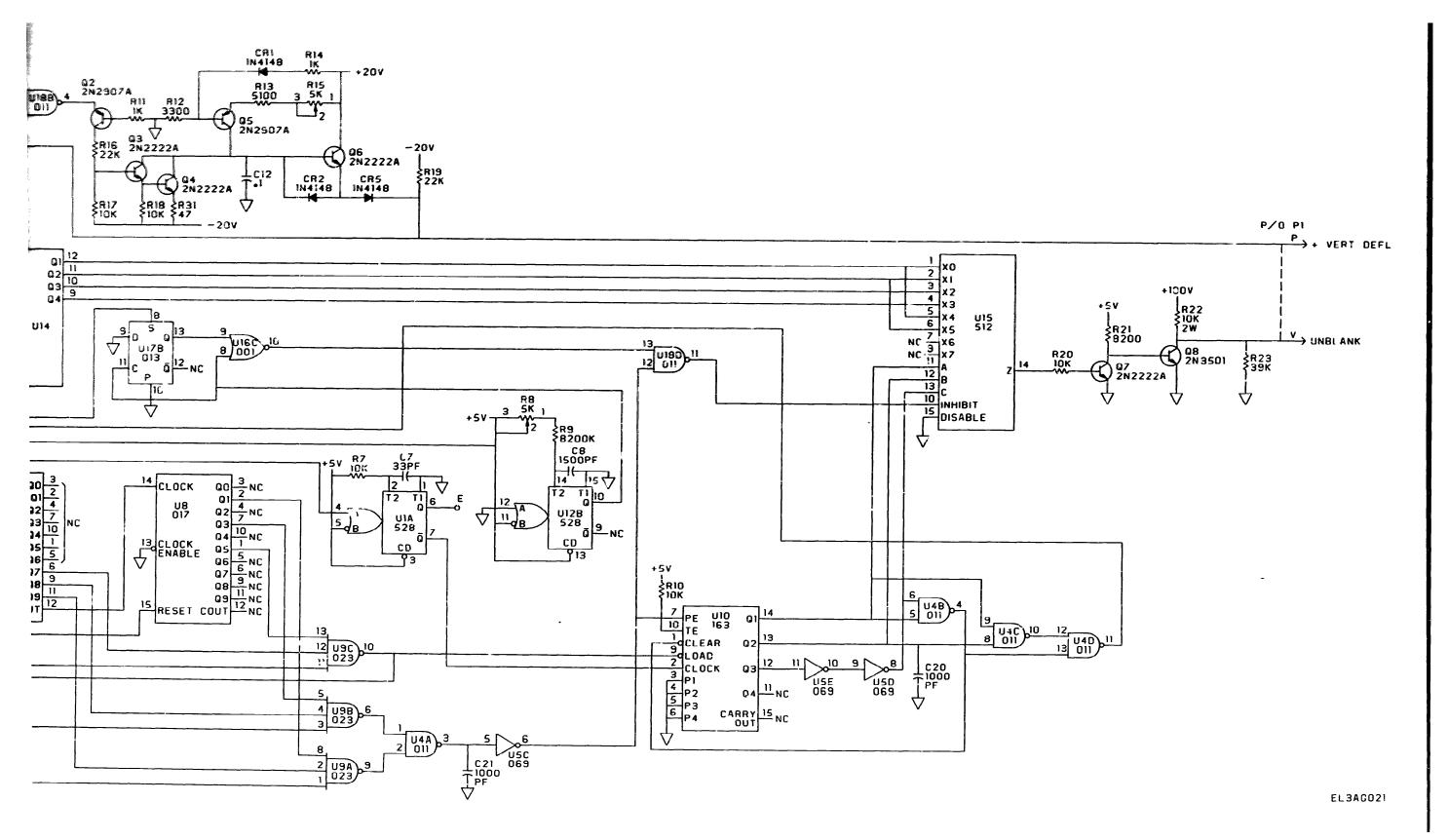
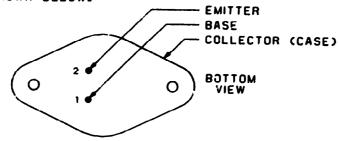
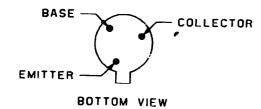


Figure FO-10. ADAS Simulator module 1A1A1, schematic diagram (sheet 2 of 2)

- PARTIAL REFERENCE DESIGNATIONS ARE SHOWN.
 FOR COMPLETE DESIGNATION PREFIX WITH 1A1A2.
- 2. UNLESS OTHERWISE SPECIFIED:
 ALL RESISISTORS ARE IN OHMS, ±5PCT, 1/4 WATT.
 ALL CAPACITORS ARE IN UF.
 ALL INDUCTORS ARE IN UH.
 ALL VOLTAGES ARE DC.
- 3. PIN ORIENTATION FOR TRANSISTOR TYPE 2N3715 IS SHOWN BELOW.



4. PIN ORIENTATION FOR TRANSISTOR TYPE 2N2907 IS SHOWN BELOW.



5. PIN ORIENTATION FOR INTEGRATED CIRCUIT HA2-2600-2 IS SHOWN BELOW.



BOTTOM VIEW

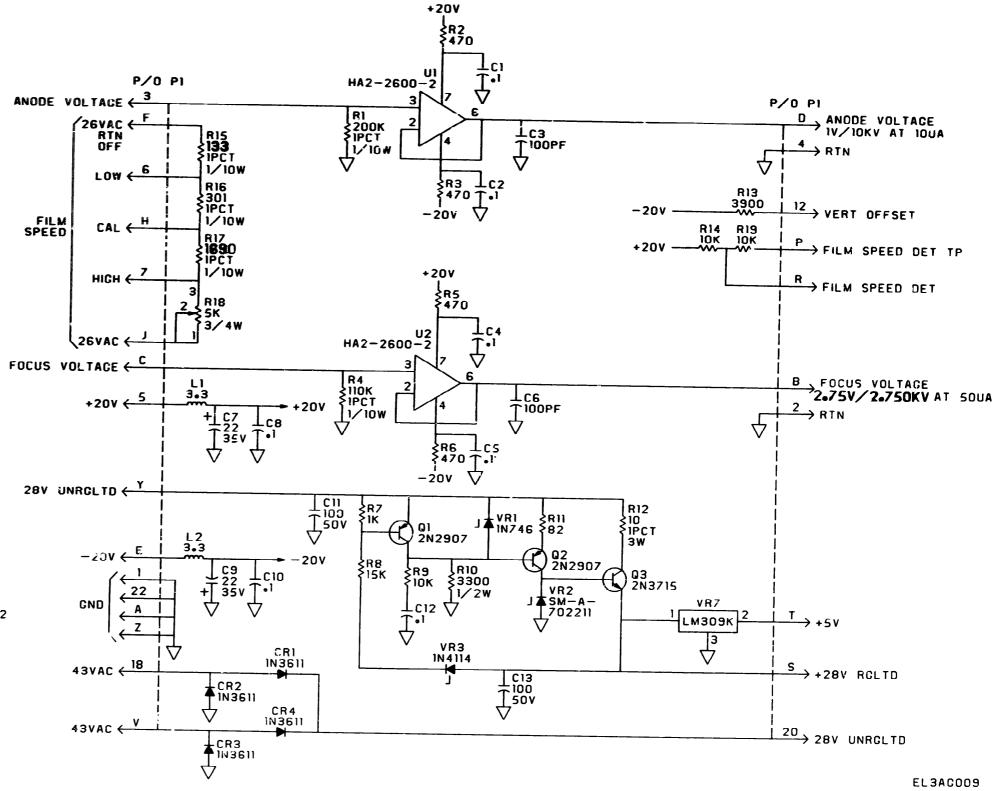


Figure FO-11. Regulated +28-volt power supply and high voltage loads

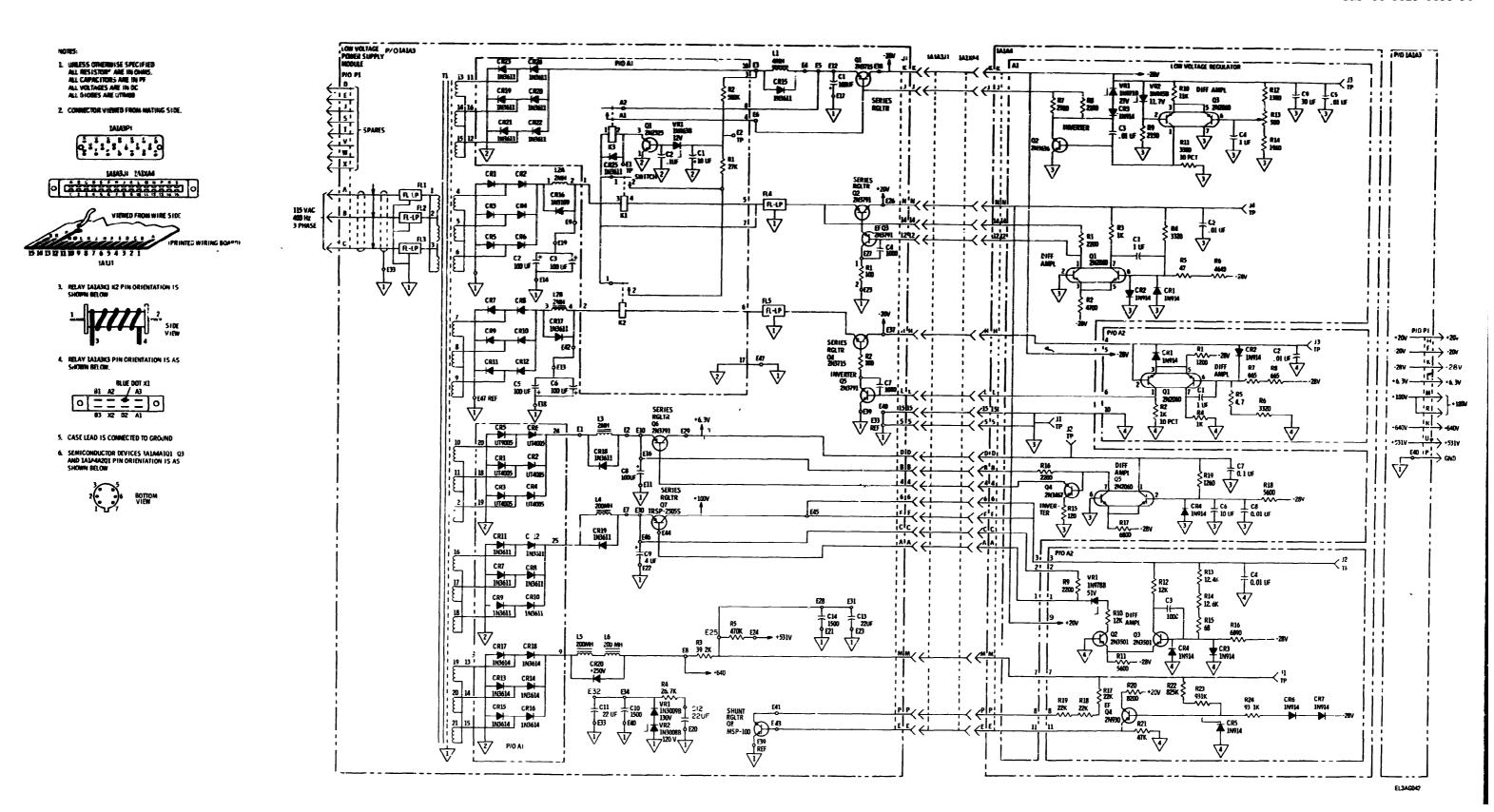
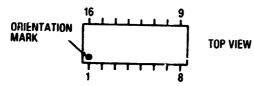


Figure FO-12. Low voltage power supply, 1A1A3, and regulator 1A1A4 schematic diagram

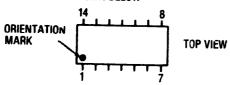
- 1 PARTIAL REFERENCE DESIGNATIONS ARE SHOWN FOR COMPLETE DESIGNATION PREFIX WITH 1A1A7
- 2. UNLESS OTHERWISE SPECIFIED
 ALL RESISTORS ARE IN OHMS, ±5 PCT, 1/4 WATT.
 ALL CAPACITORS ARE IN UF
 ALL VOLTAGES ARE IN DC.
- 3. INTEGRATED CIRCUIT DEVICES U3 AND U4 ARE IDENTIFIED ON THE DRAWING BY THE UNDERLINED PORTION OF THE TYPE NUMBER LISTED BELOW. VOLTAGE AND GROUND PINS ARE INDICATED.

REF DES	TYPE NUMBER	+5V PIN	GND PIN
U3	SN54L <u>S03</u>	14	7
U4	SN54LS05	14	7

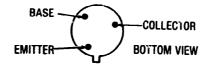
4 PIN ORIENTATION FOR INTEGRATED CIRCUIT DEVICE UZ IS SHOWN BELOW



5 PIN ORIENTATION FOR INTEGRATED CIRCUIT DEVICES U3 AND U4 IS SHOWN BELOW



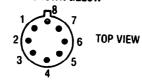
6 PIN ORIENTATION FOR SEMICONDUCTOR DEVICES Q1. Q2. Q4. AND Q5 THRU Q11 IS SHOWN BELOW



7 PIN ORIENTATION FOR SEMICONDUCTOR DEVICE Q3 IS SHOWN BELOW



8 PIN ORIENTATION FOR INTEGRATED CIRCUIT DEVICES U1, U6, U7, AND U8 IS SHOWN BELOW



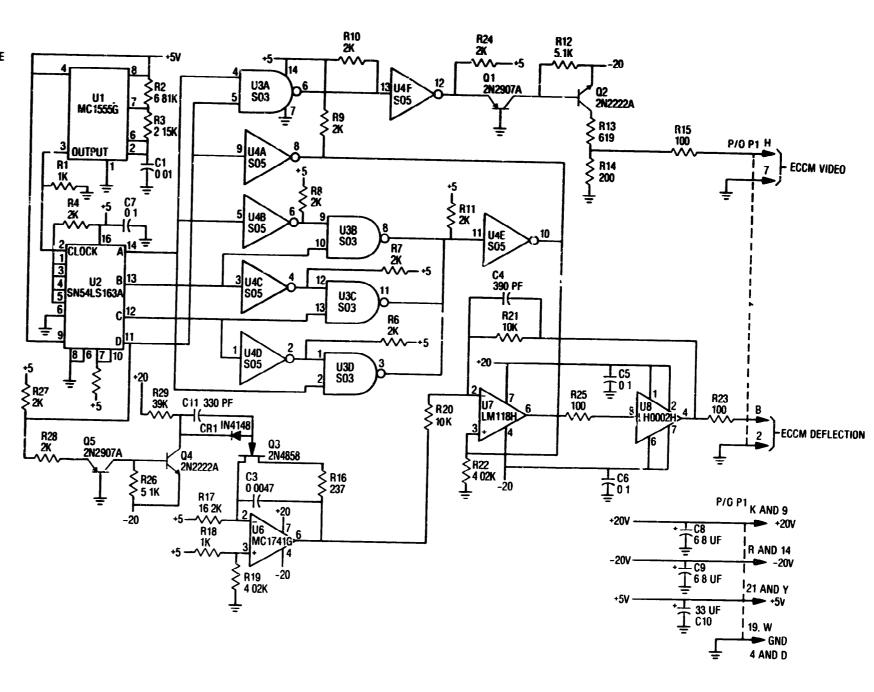


Figure FO-13. Monitor- adapter input simulator, schematic diagram

EL3AG074

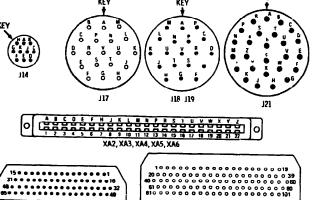


- L. PARTIAL REFERENCE DESIGNATIONS ARE SHOWING FOR CO PREFIX WITH I
- 2. UNLESS OTHER ALL RESISTORS ALL VOLTAGE
- 3. □□□[™ .ć. MARKINGS.

K1, K2

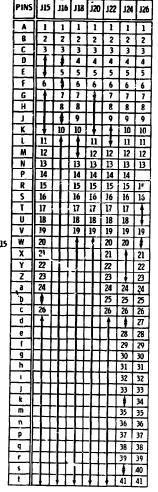
PINS OF CONNECTORS JIO AND JII ARE CONNECTED TO LIKE-HUMBERED TEST JACKS ON THE FRONT PANEL

COMPLETE DESIGNATIONS 1A2.		PACKS ON THE FRONT "ANEL OTH THE EXCEPTIONS NOTED BELOW
RWISE SPECIFIED	CONN	PINS NOT CONNECTED TO TEST JACKS
E Julios Am NOS	110	52, 68, 84, 89, 90, 91, 92, 94, 95, 100
(*) (#*)	'uı	6, 12, 19, 20, 25, 26, 31, 34, 48, 53, 56, 60, 62, 53
Si	KEY A	B1 A2 X1 A3 DOT A3 DOT
	J16 J1	J24 J26 J25 J27 J26 J27 J27 J27 J27 J27 J27 J27 J27 J27 J27
KEY		KĒY "♣'



J10

PINS OF CONNECTORS JI, JI4, JI5, JI6, JI8, J20, J22, J24 AND J26 ARE CONNECTED TO TEST JACKS OF THE FRONT PANEL IN ACCORDANCE WITH THE TABLES BELOW. EXCEPTIONS ARE BLANK.



PINS A B C D E F G H J K
JI 1 2 3 4 5 6 7 8 9 10

JI4 + 3 4 + 6 + 8 9 10

123

ç o

J15, J23, J25

KEY

(fo ™o x o o o o

J22

ó ò

o² o 5

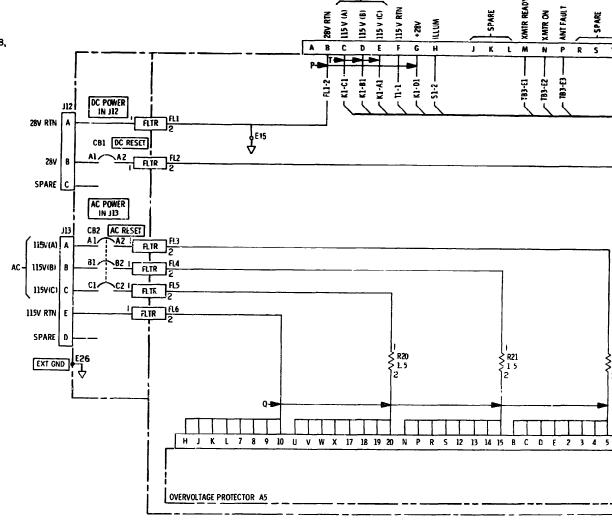
° 0

E0 Y0

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o* •*

04,



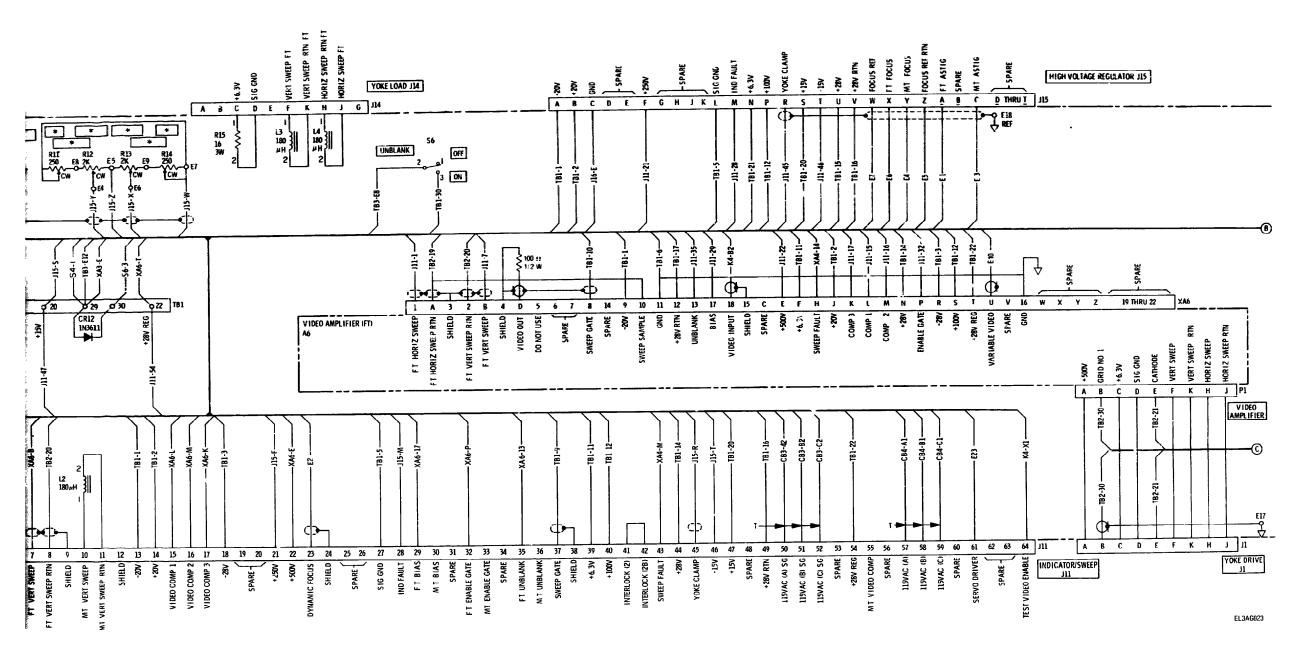


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, interconnection diagram (sheet 2 of 4)

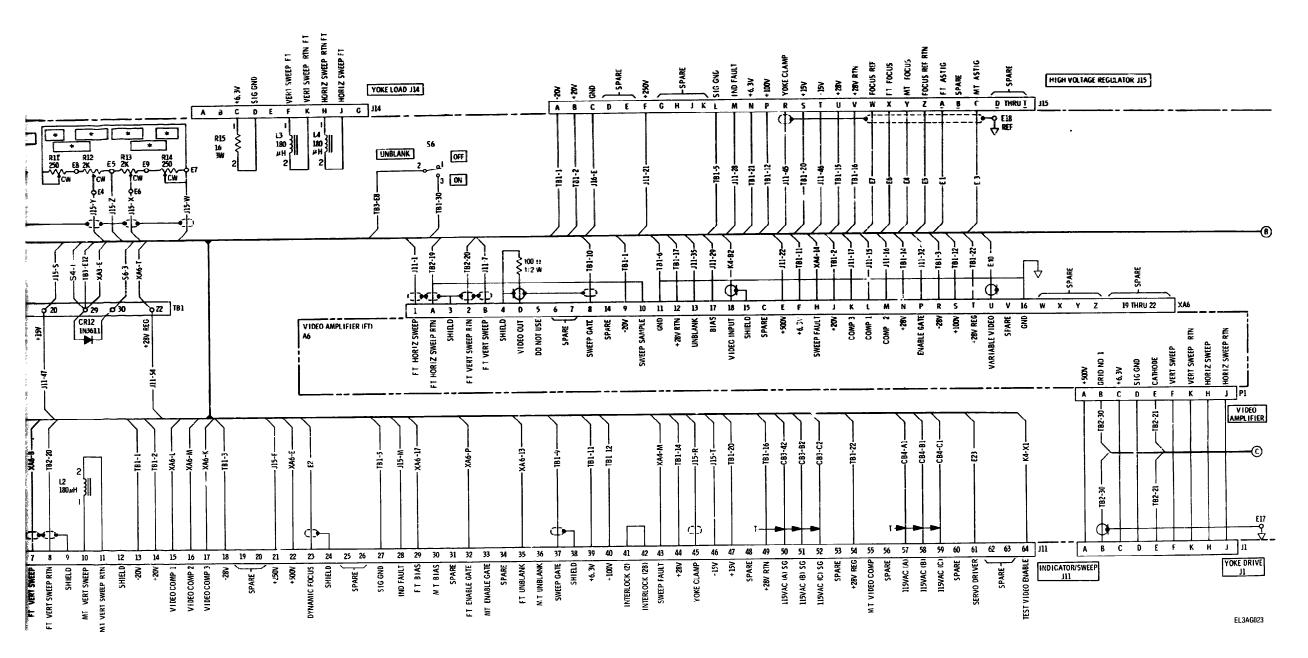


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, interconnection diagram (sheet 2 of 4)

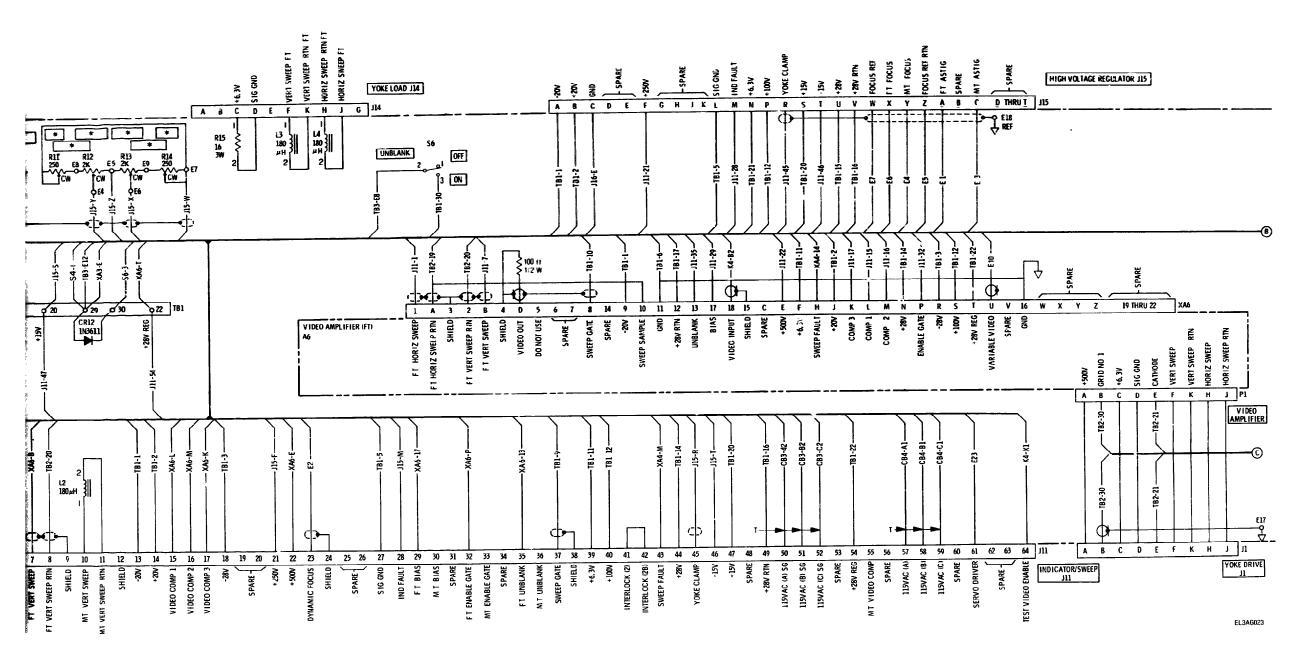


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, Interconnection diagram (sheet 2 of 4)

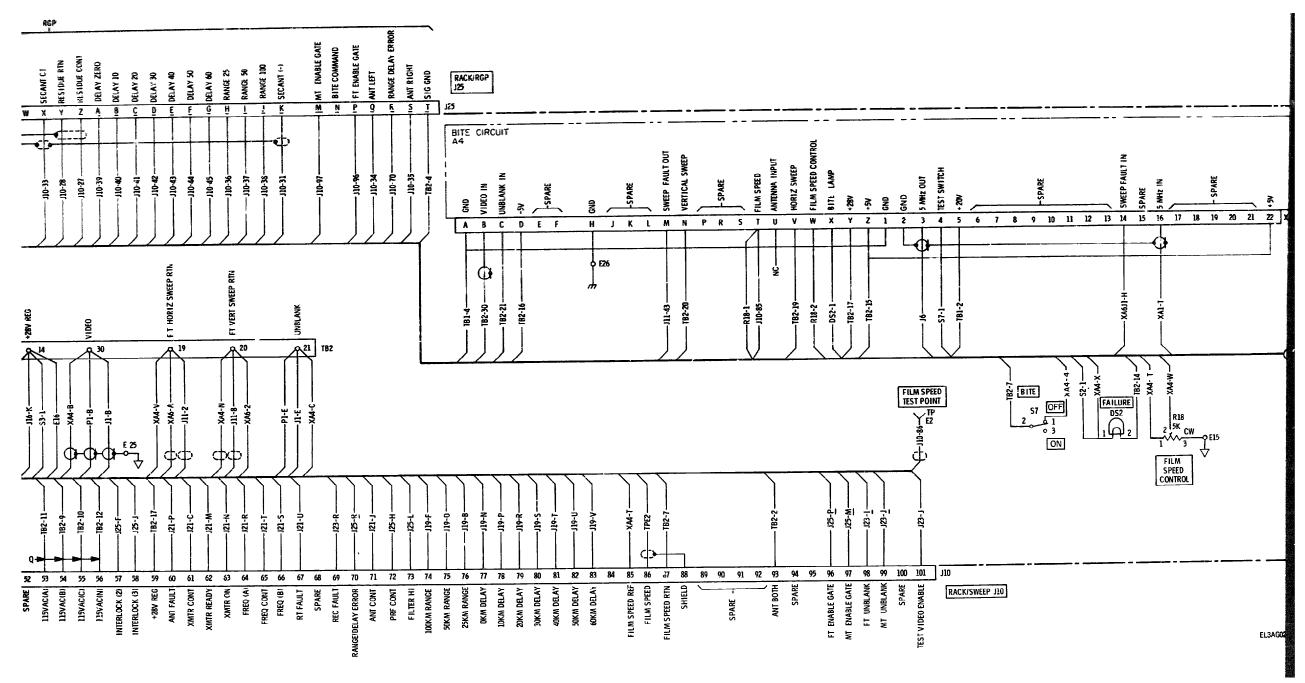


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D, Unit 1A2, interconnection diagram (sheet 3 of 4)

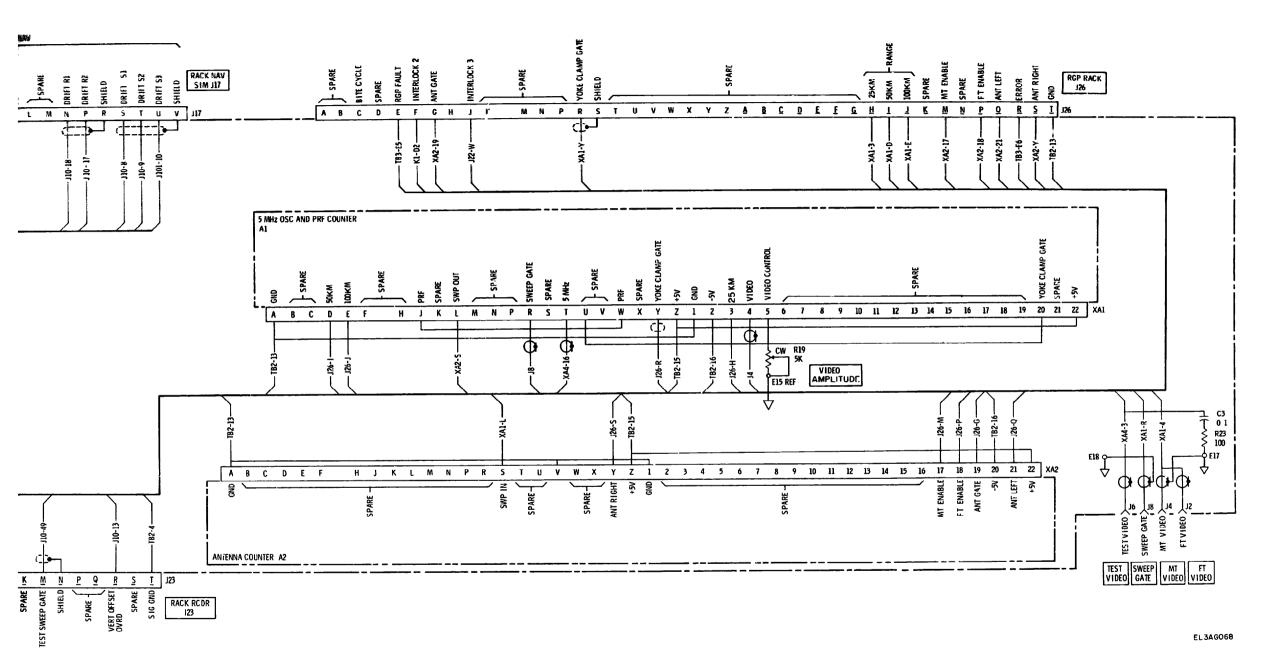


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D. Unit 1A2, interconnection diagram (sheet 4 of 4)

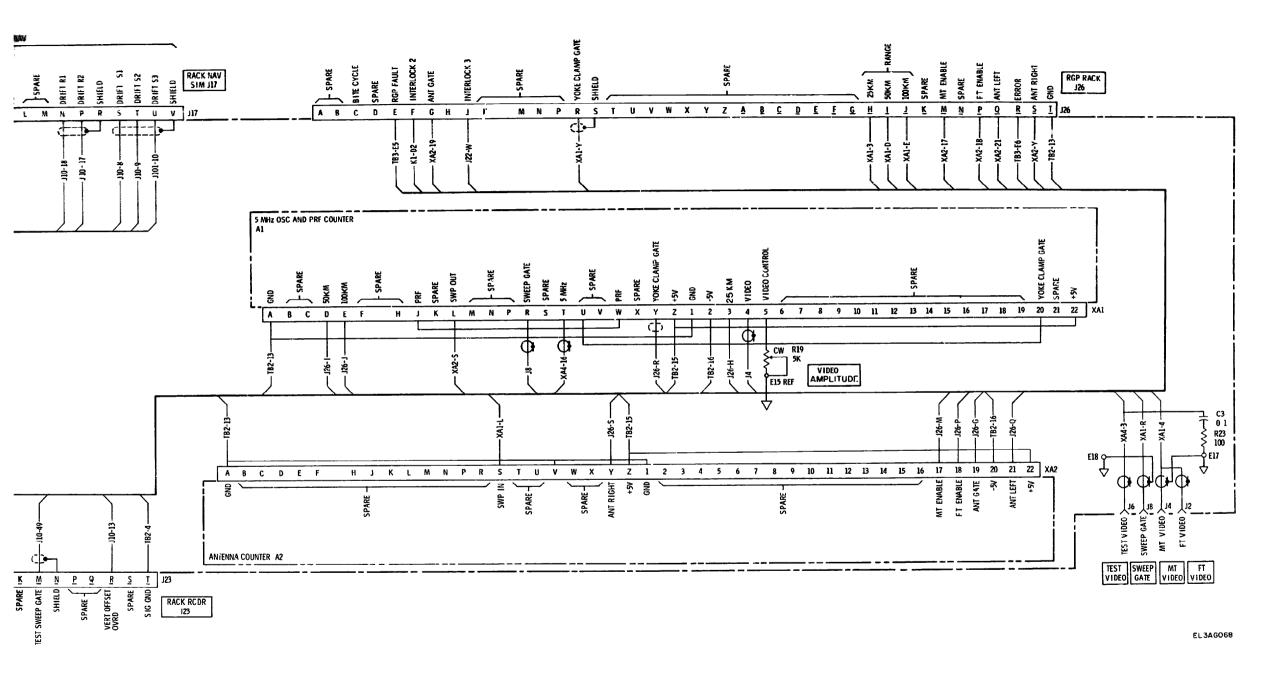
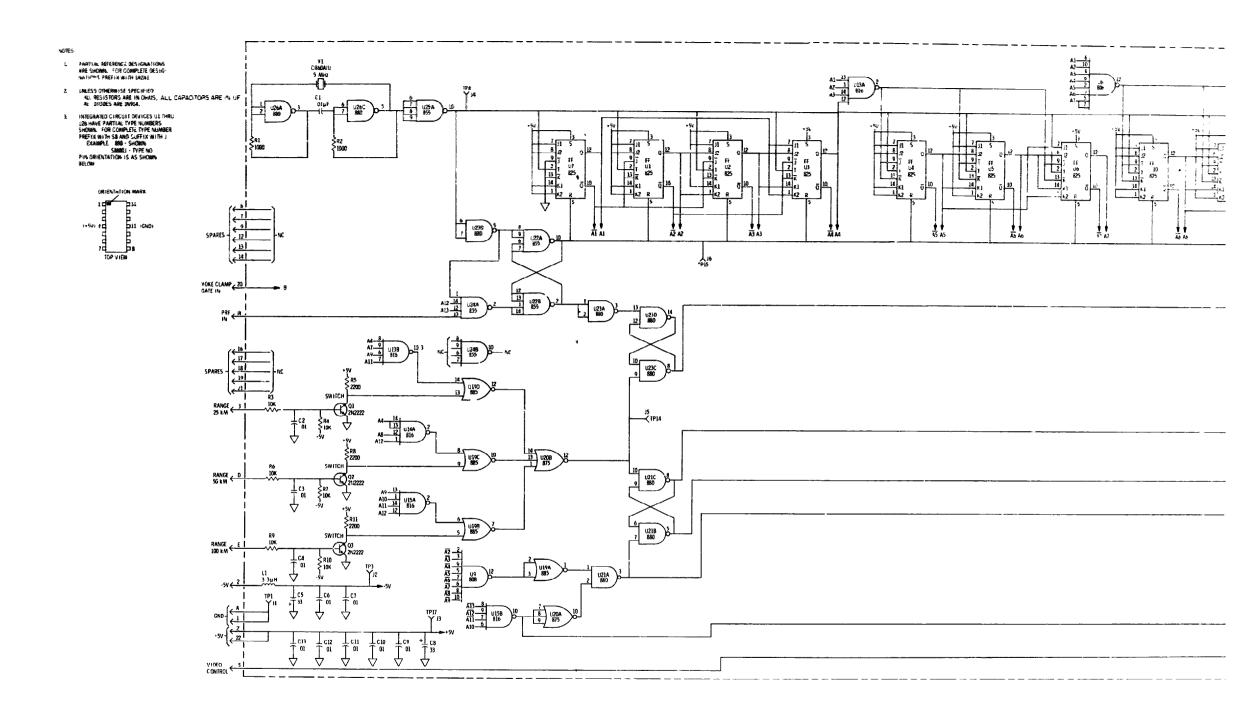


Figure FO-14. Test Set Subassembly MX-8638A/APS-94D. Unit IA2, interconnection diagram (sheet 4 of 4)



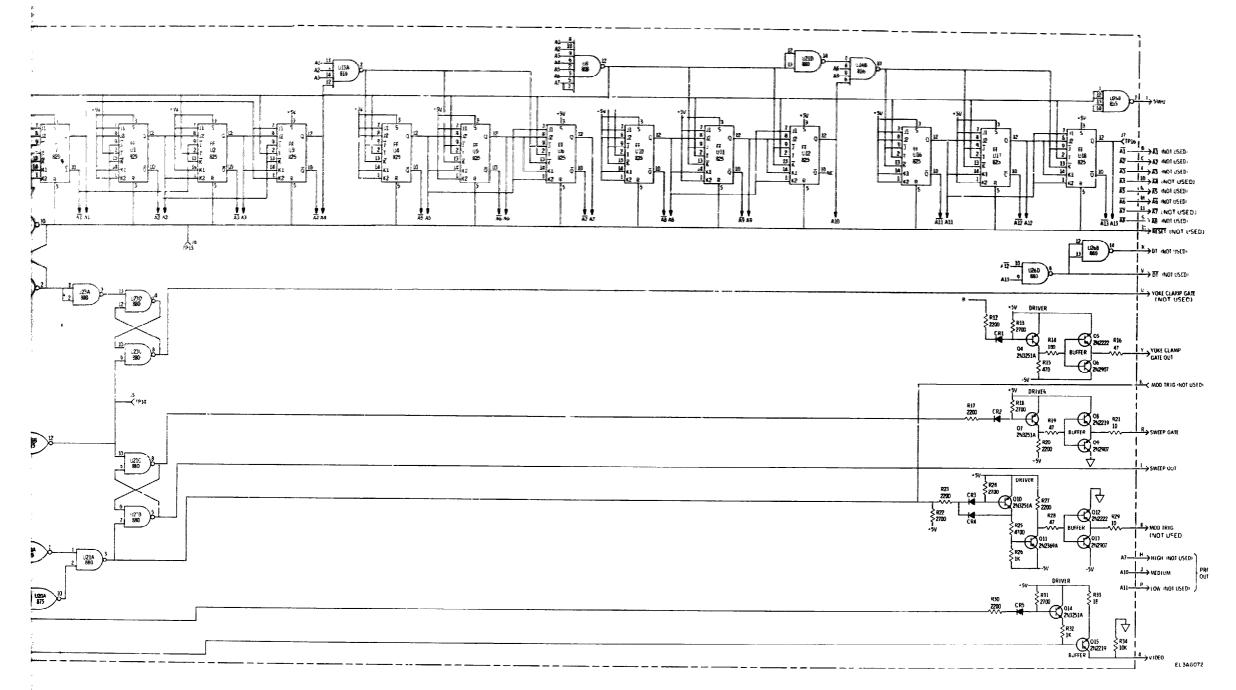
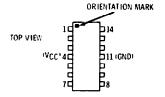


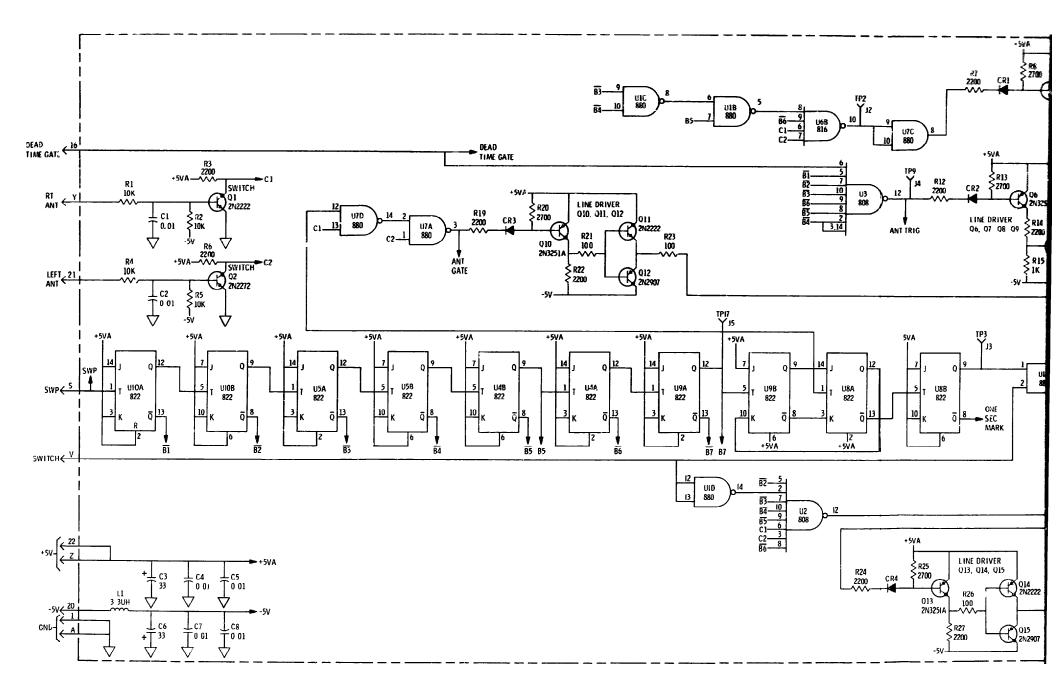
Figure FO-15. Five-MHz oscillator and prf counter, 1A2A1, schematic diagram

- 1. PARTIAL REFERENCE DESIGNATIONS ARE SHOWN FOR COMPLETE DESIG-VATIONS PREFIX WITH 1A2A2.
- 2 UNLESS OTHERWISE SPECIFIED ALL ALL RESISTORS ARE IN OHMS
 ALL CAPACITORS ARE IN UF ALL DIDDES ARE IN914
- 3 INTEGRATED CIRCUIT DEVICES UT THRU UZ3 HAVE PARTIAL TYPE NUMBERS SHOWN FOR COMPLETE TYPE NUMBER PREFIX WITH S8 AND SUFFIX WITH J EXAMPLE 880 SHOWN S8880J - TYPE NO

PIN ORIENTATION IS AS SHOWN BELOW



U1 THRU U10 ARE +5V A AT (VCC) PIN 4. U11 THRU U23 ARE +5V B AT (VCC) PIN 4.



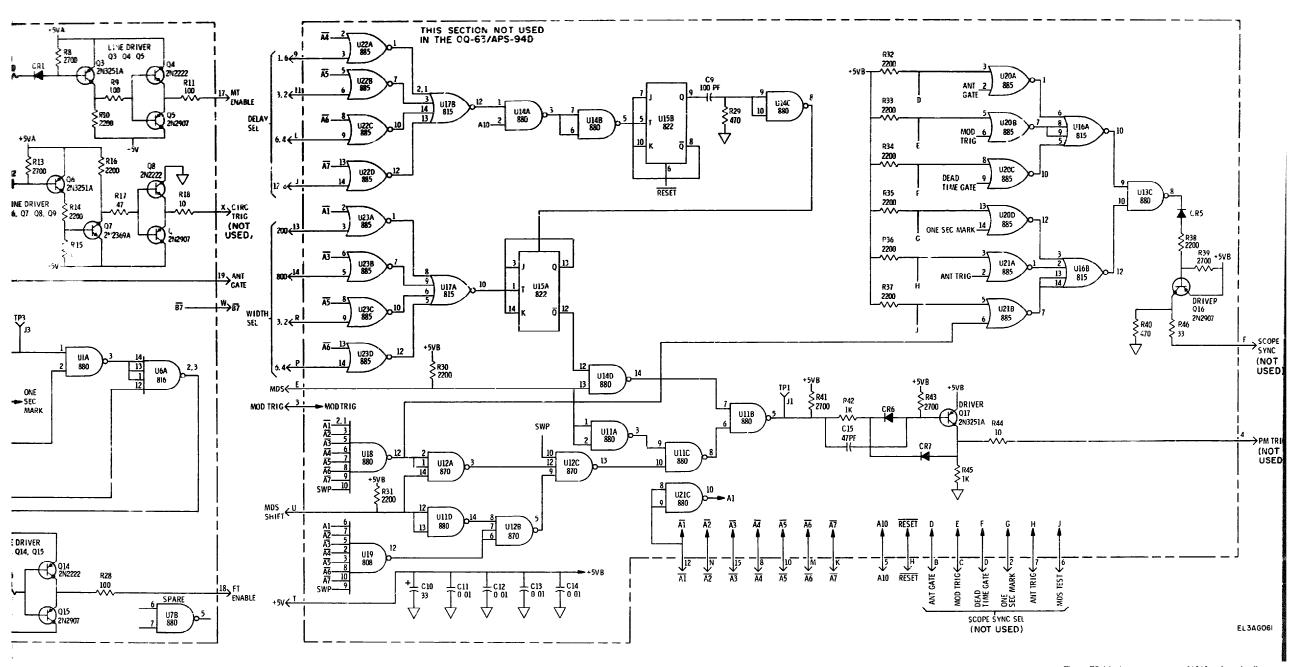


Figure FO-16. Antenna counter, 1A2A2, schematic diagram

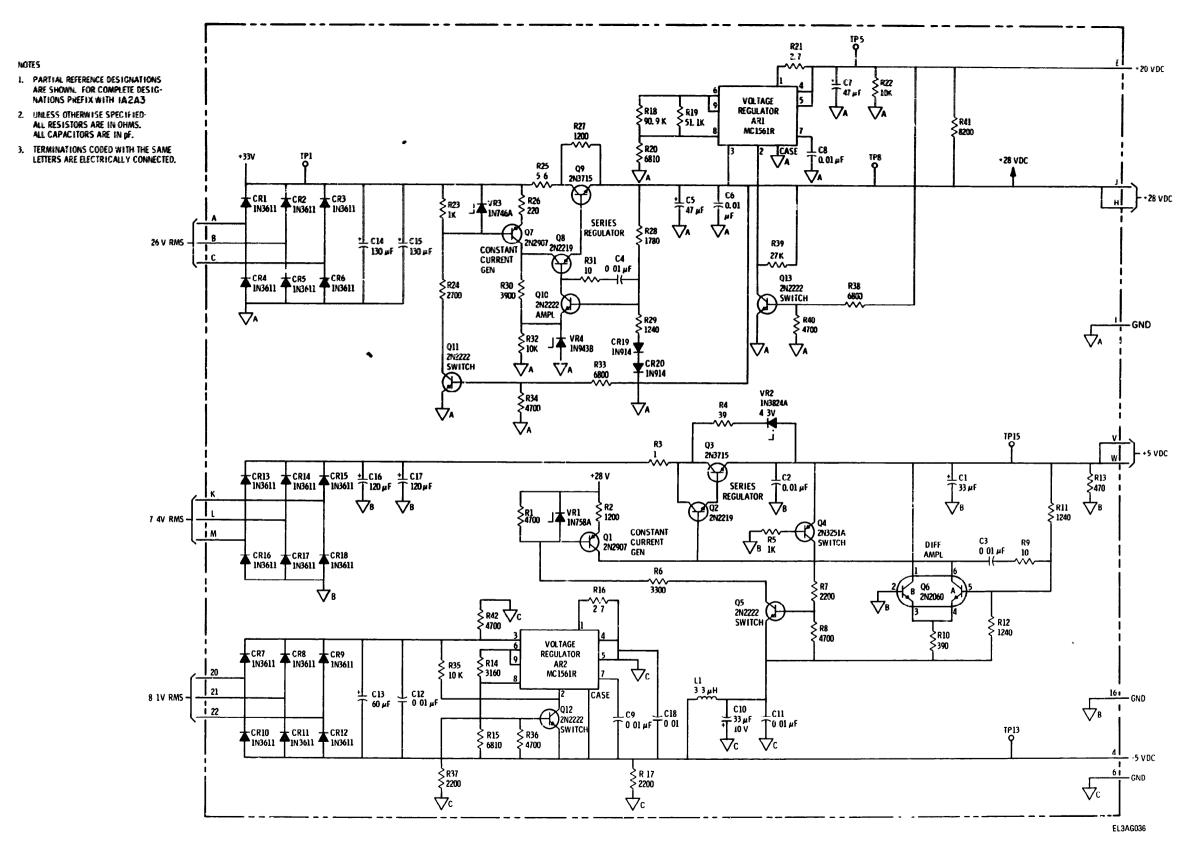


Figure FO-17. Low voltage power supply regulator, 1A2A3, schematic diagram

 PARTIAL REPERENCE DESIGNATIONS ARE SHOWN. FOR COMPLETE DESIGNATIONS PREFIX WITH EAZAL

2. UNLESS OTHERWISE SPECIFIED
ALL RESISTORS ARE IN 10
ALL CAPACITORS AF
ALL DIODES ARE 1N014

3. INTEGRATED CIRCUIT DEVICES AR2, 4, 6, and 8 PIN ORIENTATION IS AS SHOWN BELOW



BOTTOM V IEW

4. INTEGRATED CIRCUIT DEVICES ARI, 3, 5, and 7 PIN ORIENTATION IS AS SHOWN BELOW.



BOTTOM VIEW

5. SEMICONDUCTOR DEVICES Q2 AND Q3 PIN ORIENTATION IS AS



SYMBOL INDICATES
P CHANNEL MOS-16FET
DESIGNED FOR ENHANCEMENT
MODE OPERATION

6. L3 AND L4 ARE FERRITE BEADS, FERROXCUBE PART NO 56-590-

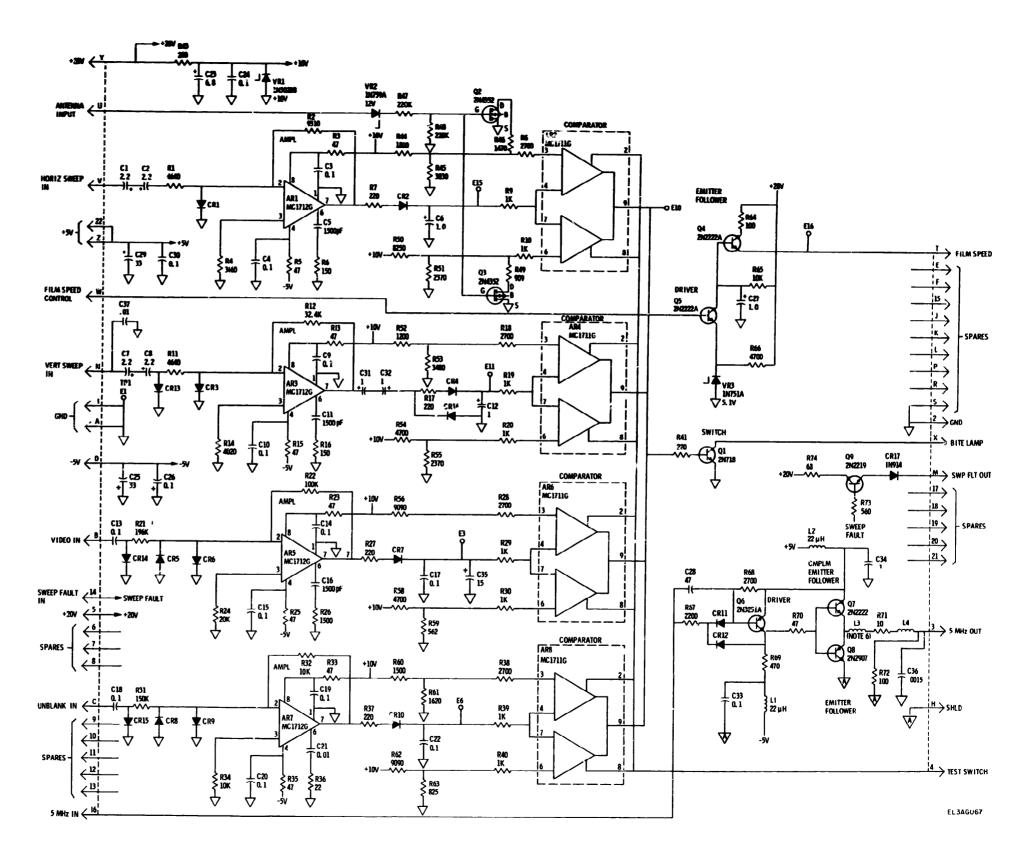
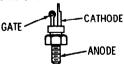


Figure FO-18. BITE circuit, 1A2A4, schematic diagram

- PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. FOR COMPLETE DESIGNATIONS PREFIX WITH 1A2A5.
- 2. UNLESS OTHERWISE SPECIFIED
 ALL RESISTORS ARE IN OHMS.
 ALL CAPACITORS ARE IN µF.
 ALL DIODES ARE IN3612.
- 3. PIN ORIENTATION
 OF SCR Q2, Q5, Q7,
 Q10, Q12, AND Q15
 IS AS SHOWN BELOW.



4. SYMBOL MEANS SCR.

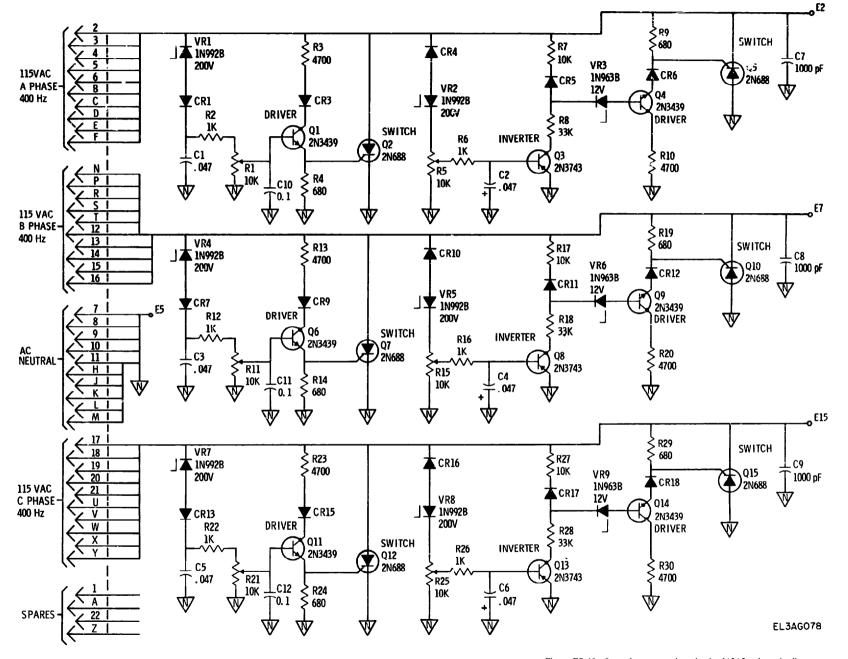


Figure FO-19. Overvoltage protection circuit, 1A2A5, schematic diagram

- PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. FOR COMPLETE DESIGNATIONS PREFIX WITH 1A2A6.
- 2. UNLESS OTHERWISE SPECIFIED ALL RESISTORS ARE IN OHMS. ALL CAPACITORS ARE IN µF. ALL INDUCTORS ARE IN µH. ALL DIODES ARE IN914.
- 3 SEMICONDUCTOR DEVICE A1Q9 PIN ORIENTATION IS AS SHOWN BELOW.



4. HEATER DEVICES A2HR1, AND 3, PIN ORIENTATION IS AS SHOWN BELOW.

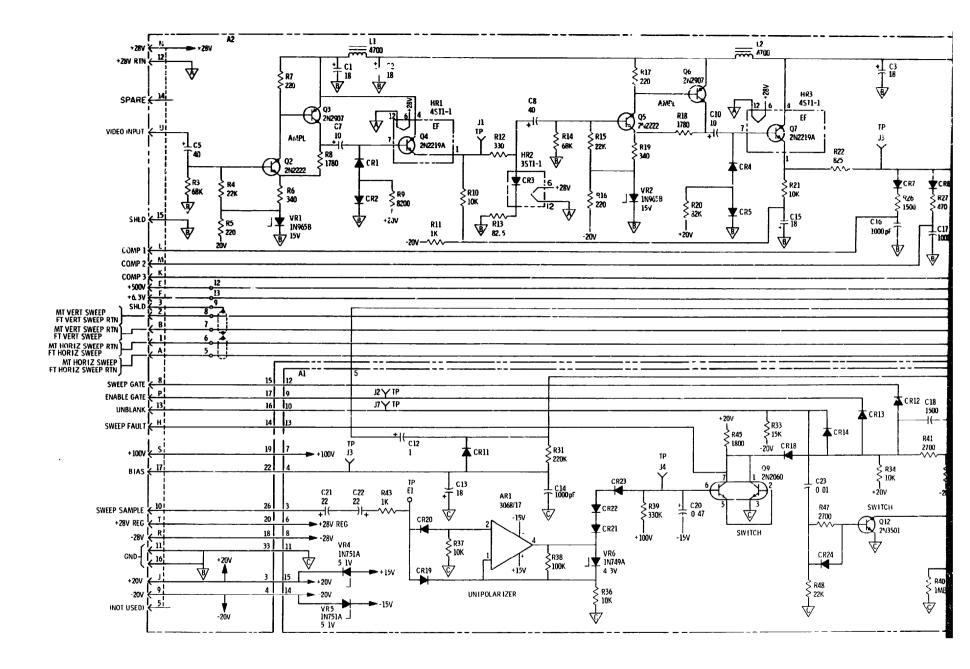


5 INTEGRATED CIRCUIT DEVICE AIARI PIN ORIENTATION IS AS SHOWN REIOW



6 CONNECTOR VIEWED FROM MATING SIDE





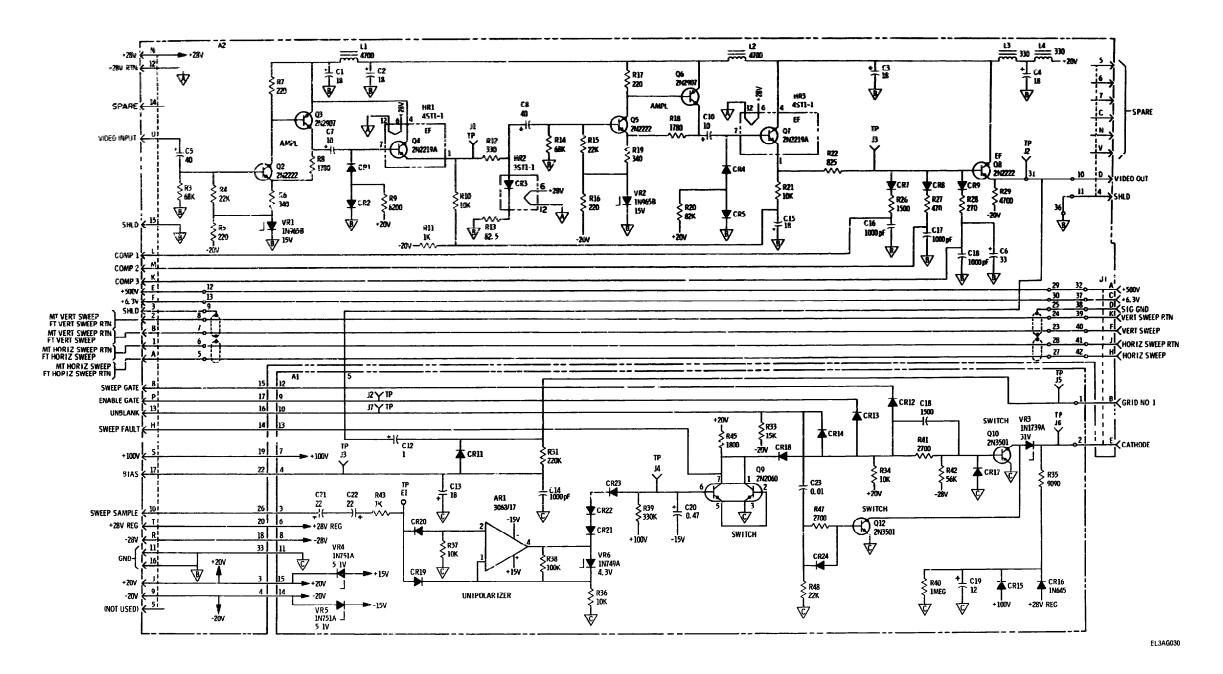


Figure FO-20. Video amplifier, 1A2A6, schematic diagram

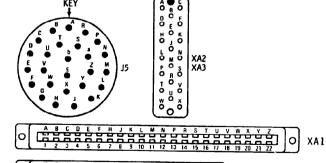
- PARTIAL REFERENCE DESIGNATIONS ARE SHOWN, FOR COMPLETE DESIGNATIONS PREFIX WITH 2.
- 2. UNLESS OTHERWISE SPECIFIED: ALL RESISTORS ARE IN OHMS ALL VOLTAGES ARE IN DC.
- 3. MOTOR BI PIN ORIENTATION IS AS SHOWN BELOW.



BOTTOM VIEWS

4. CONNECTORS VIEWED FROM MATING SIDE.



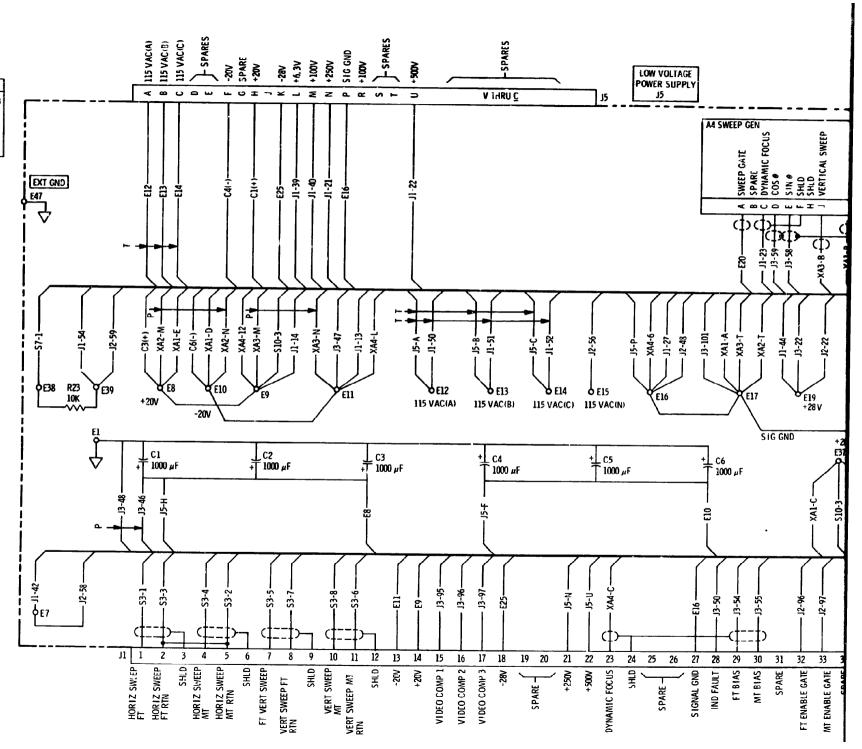


5 EACH PIN OF CONNECTOR J5 IS CONNECTED TO NUMBERED TEST JACKS ON THE FRONT PANEL IN ACCORDANCE WITH THE TABLE BELOW WITH THE EXCEPTIONS BLANKED OUT

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	~	U		טו		P	ı	ιн	IJ	I K	I L	I M	ΙNΙ	ľ	I R	15	ΙT	111	IV.	l W	ľ	ıv	7	1 2	b		16
		_	ľ	_	_			_	_	_	_		-	_		1							-	9	ט ו		,
		7	3			16		8		l 1n	111	12	112	14	11	14		10									
1	- 1	-	-					U		10	11	14	כגו	14	15	10		18.									TP
			_		_	$\overline{}$		_										-									

 EACH PIN OF CONNECTORS J1, J2, J3, AND J4 ARE CONNECTED TO LIKE-NUMBERED TEST JACKS ON THE FRONT PANEL WITH THE EXCEPTIONS LISTED BELOW.

CONN	PINS NOT CONNECTED TO TEST JACKS
IJ	19, 20, 25, 26, 31, 34, 48, 53, 56, 60, 62, 63
J2	52, 68, 84, 89, 90, 91, 92, 95, 100
J3	89, 90, 91, 92, 98, 99, 100
J4	89, 90, 91, 92, 94, 98, 99, 100



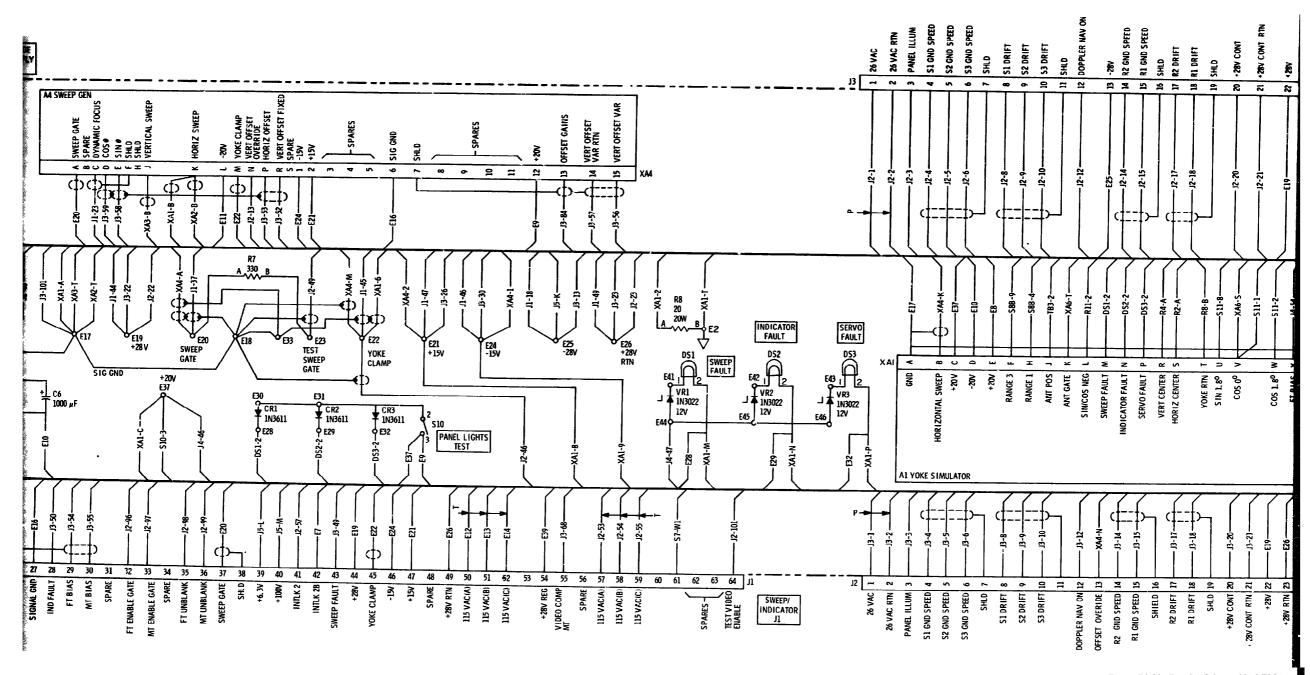


Figure FO-21. Test Set Subassembly MX-869A7

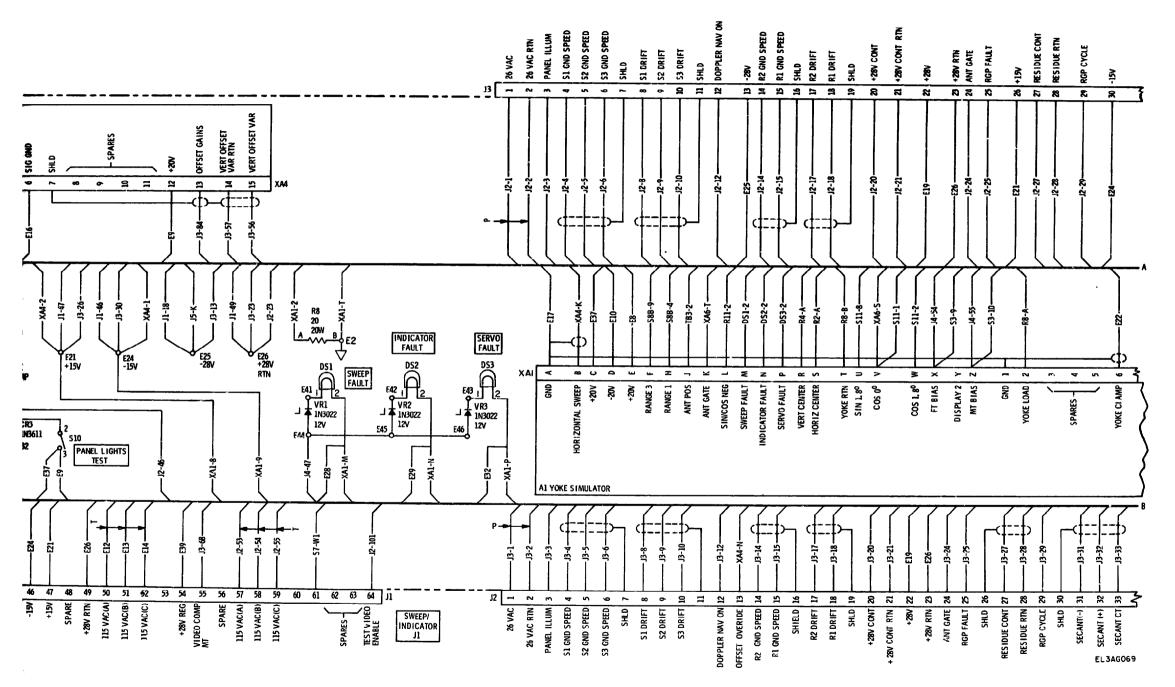


Figure FO-21. Test Set Subassembly MX-8639A/APS-94-D, Unit 2 interconnection diagram (sheet 1 of 4)

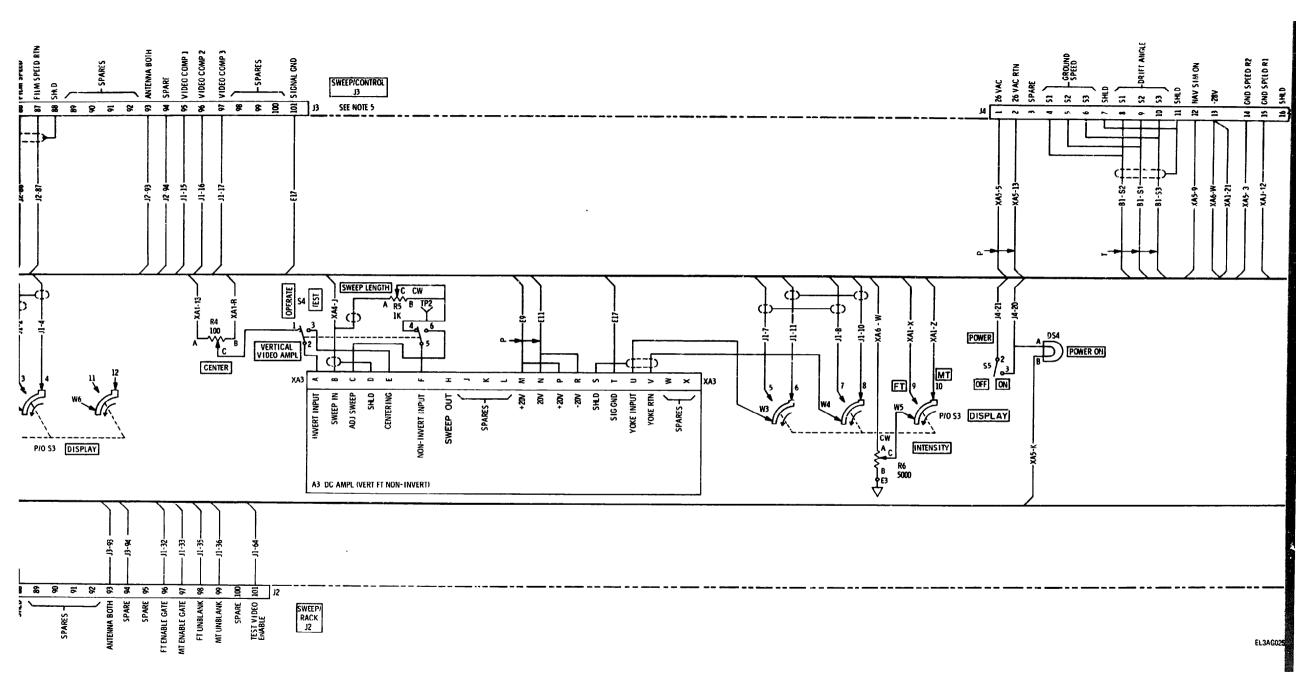


Figure FO-21. Test Set Subassembly MX-8639A/APS-94D, Unit 2 interconnection diagram (sheet 2 of 4)

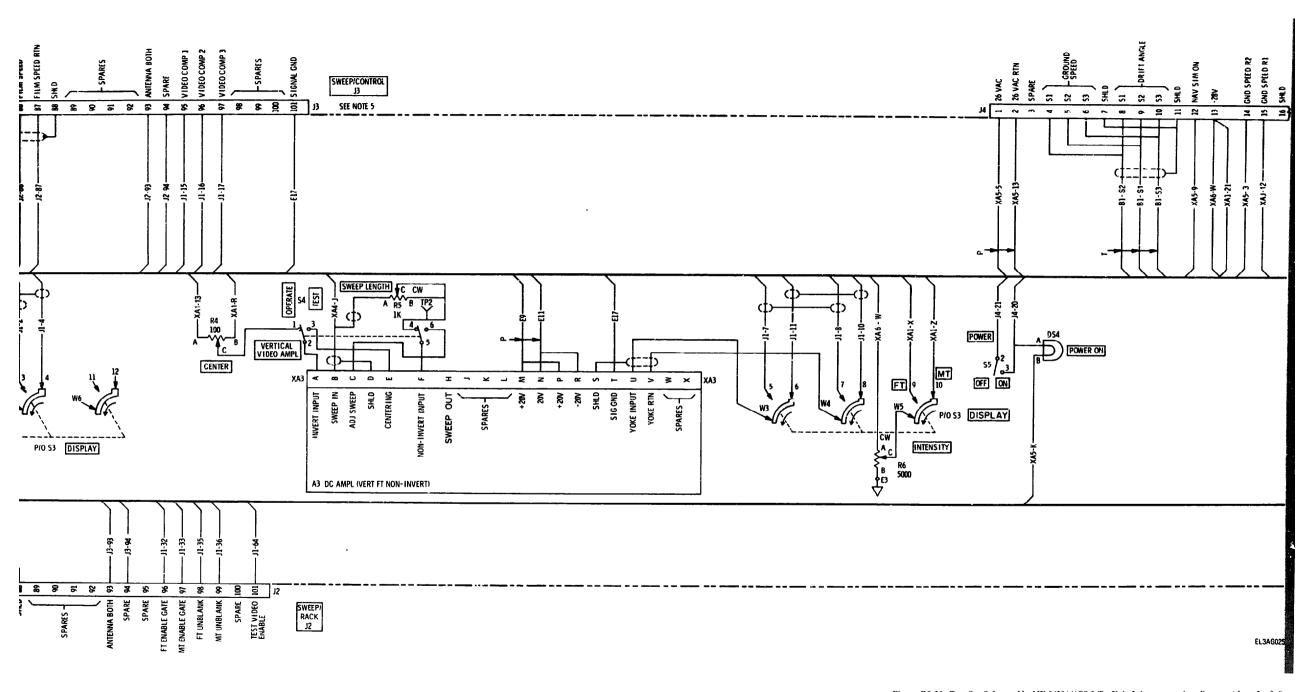
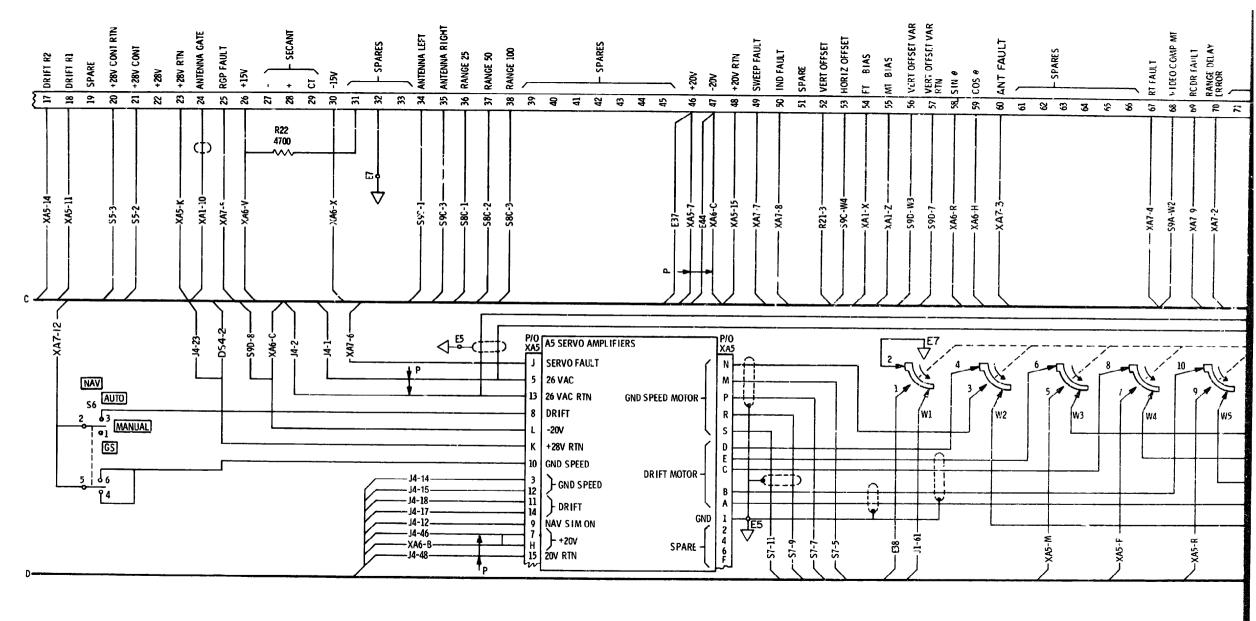
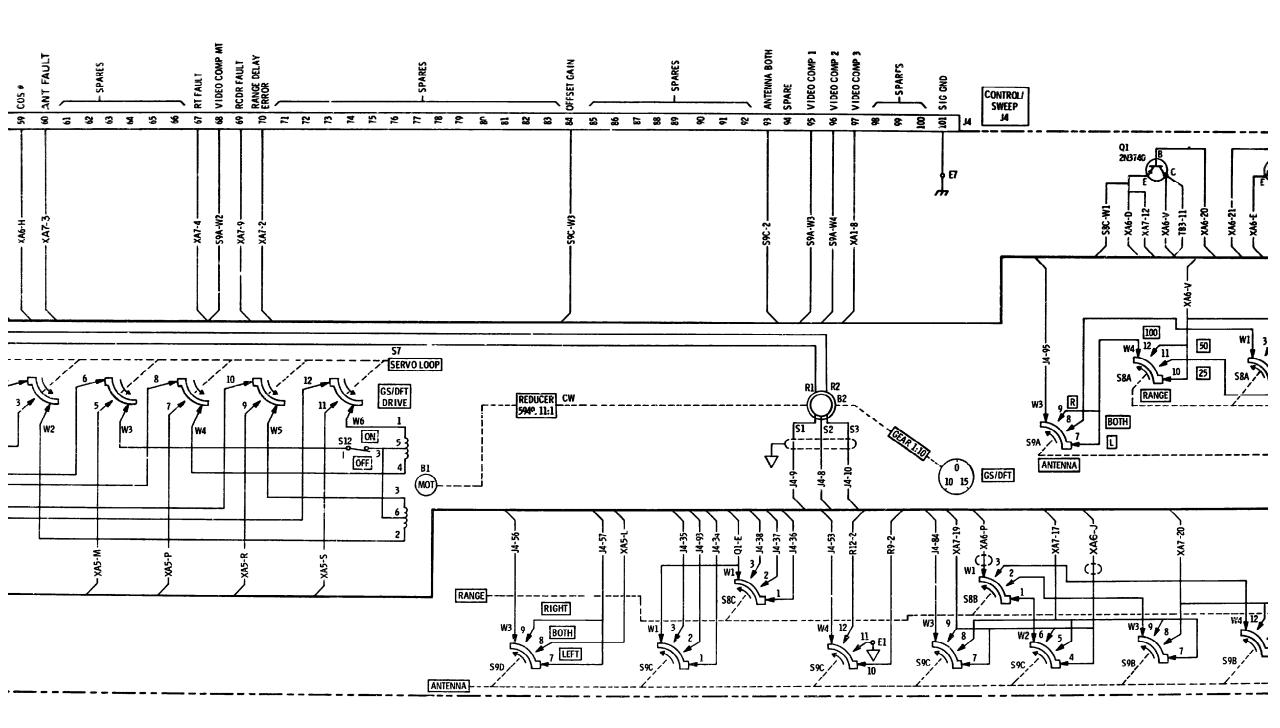
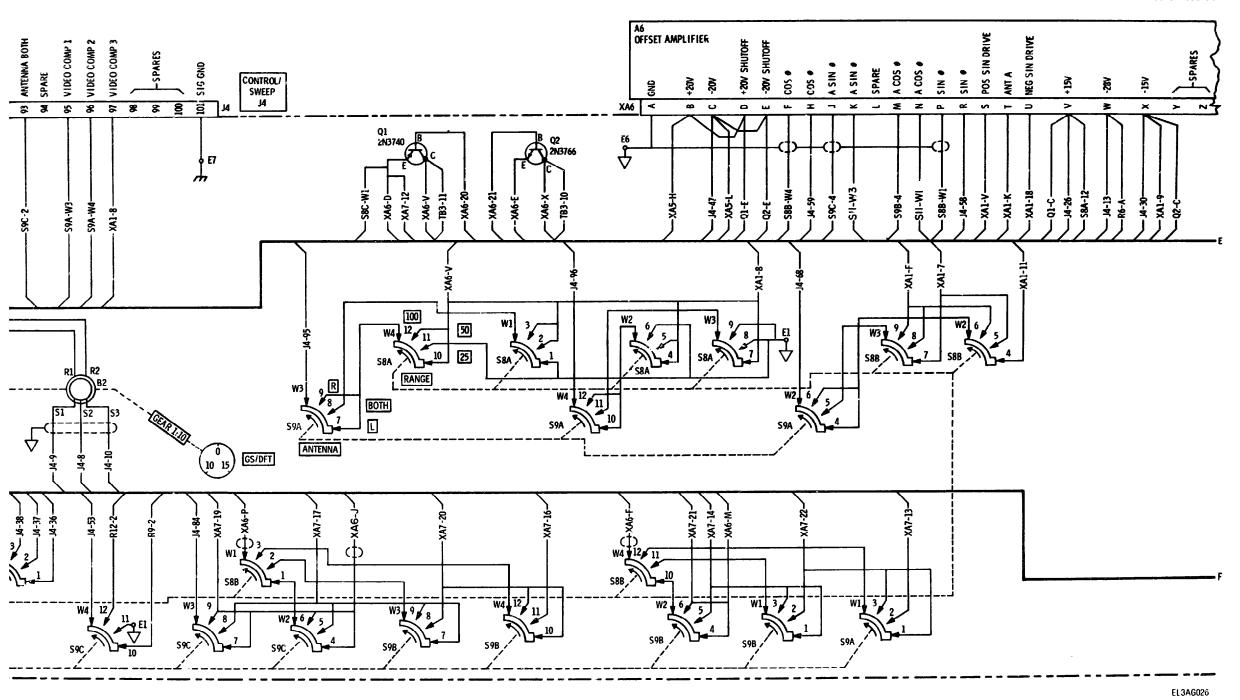
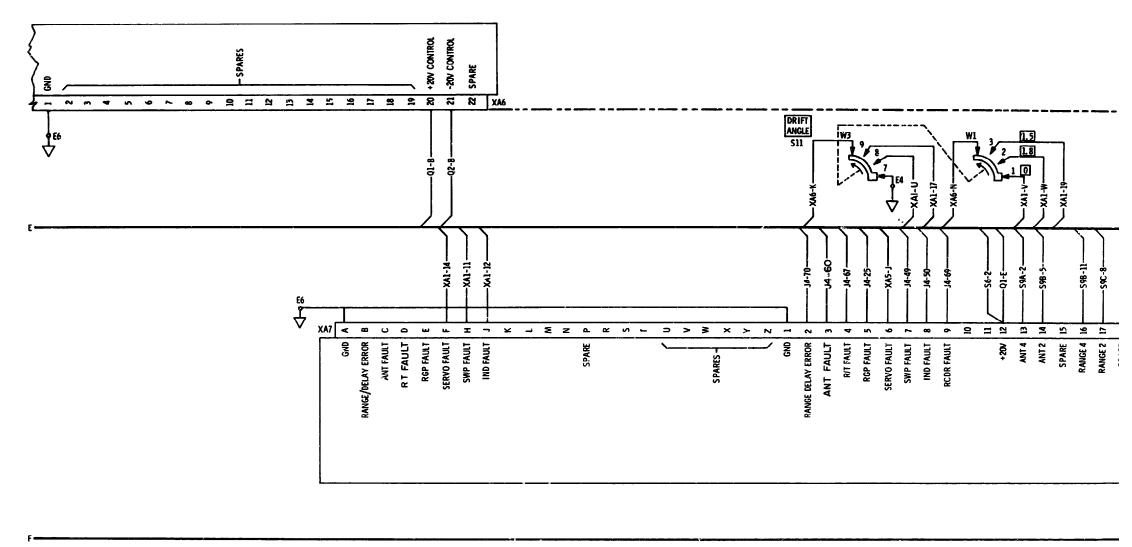


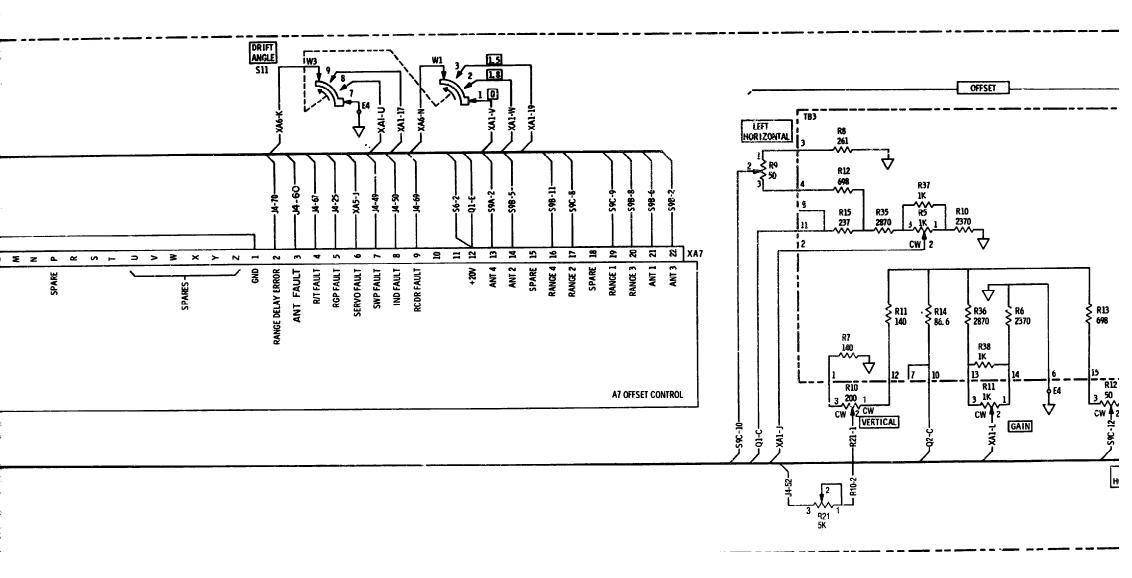
Figure FO-21. Test Set Subassembly MX-8639A/APS-94D, Unit 2 interconnection diagram (sheet 2 of 4)











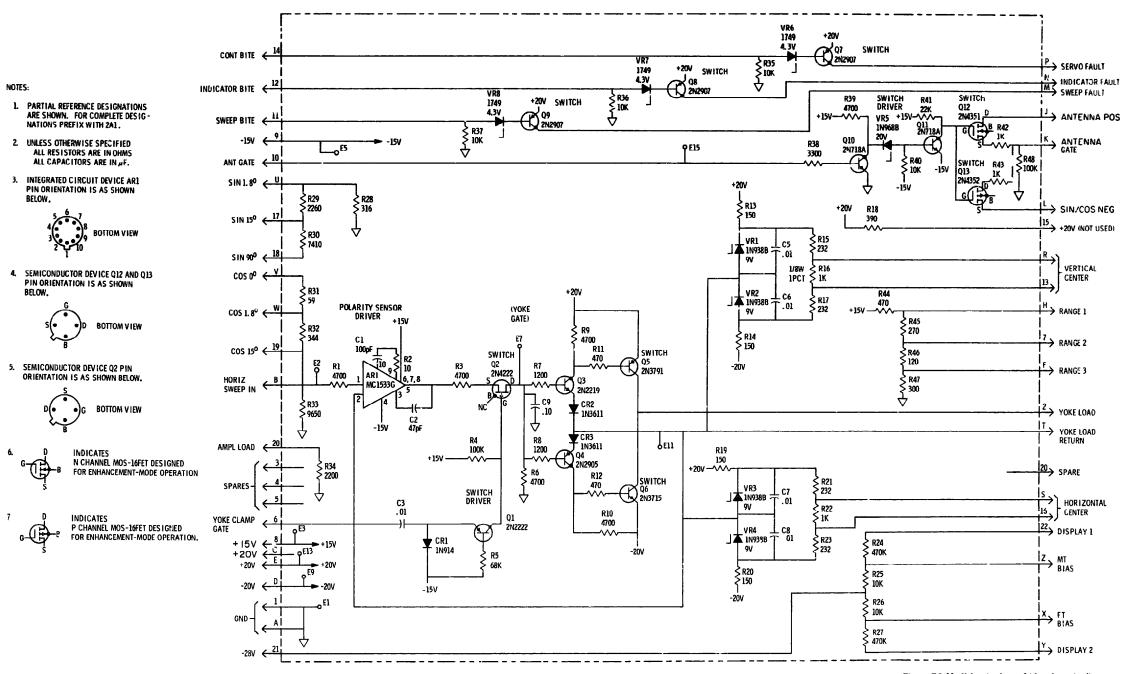
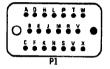
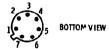


Figure FO-22. Yoke simulator, 2A1, schematic diagram

- 1. PARTIAL REFERENCE DESIGNATIONS ARE SHOWN FOR COMPLETE DESIGNATIONS PREFIX WITH 2A2, 2A3.
- 2. UNLESS OTHERWISE SPECIFICE: ALL RESISTORS ARE IN OHMS VLL CAPACITORS ARE IN µF.
- 3. CONNECTOR VIEWED FROM MATING SIDE.



4. PIN ORIENTATION OF Q1 IS SHOWN BELOW:



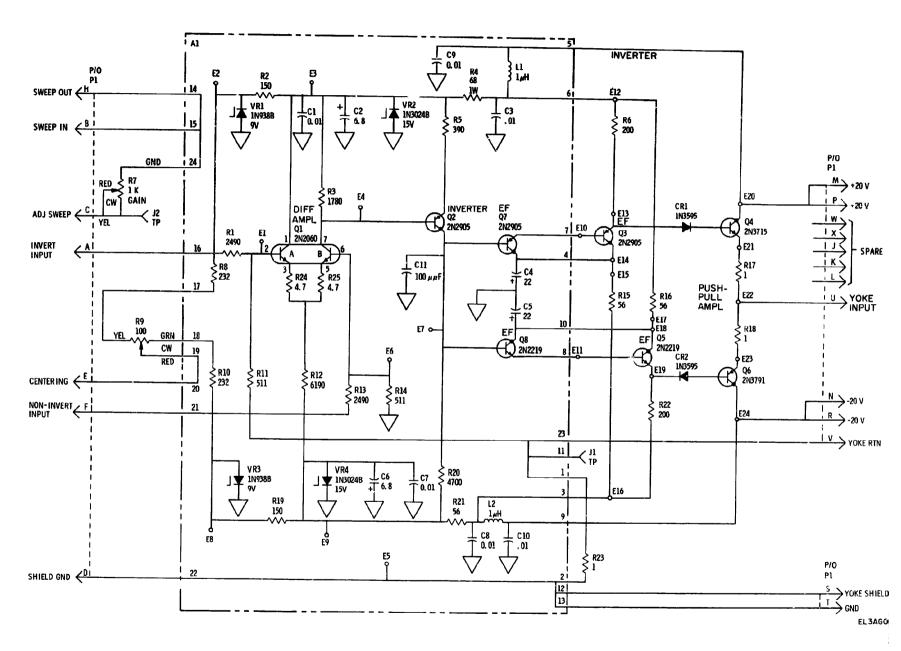
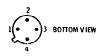


Figure FO-23. Direct current amplifiers, 2A2/2A3, schematic diagram

 PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. FOP COMPLETE DESIGNATIONS PREFIX WITH 2A4. 3 SYMBOL MEANS P-CHANNEL
1 INSULATED GATE ENHANCEMENT
1 TYPE S INCLE GATE MOS-FET.

2. UNLESS OTHERWISE SPECIFIED ALL RESISTORS ARE IN OHMS ALL CAPACITORS ARE IN pF

3. SEMICONDUCTOR DEVICES A1Q3 4, 5, 6, 7, 8, 9, 10, AND A2Q1 & 2 PIN ORIENTATION IS AS SHOWN BELOW



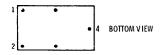
4 INTEGRATED CIRCUIT DEVICES AIARI, 2 5, 6, 7 8, AND AZAIRZ, 4, 5, 6, 7 8, 9, 10 11 12 & 13 PIN ORIENTATION IS AS SHOWN BELOW



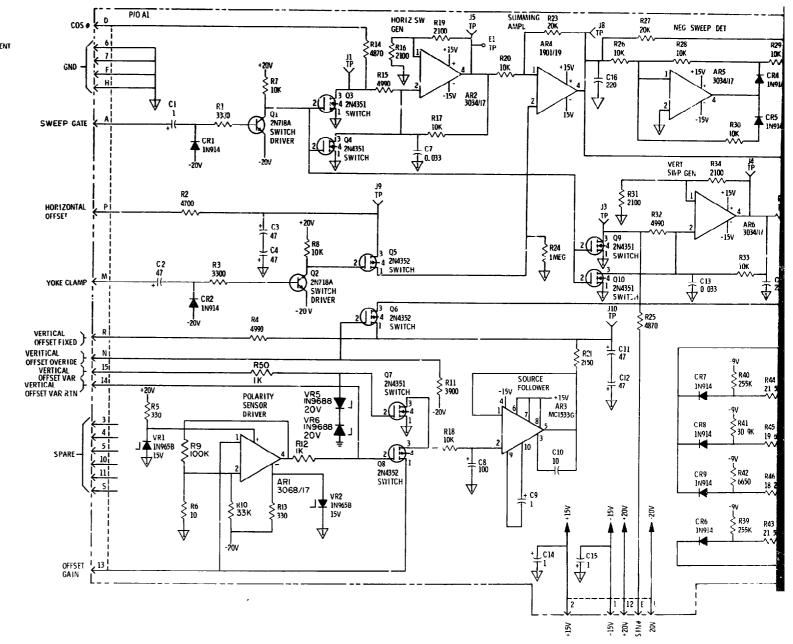
5 INTEGRATED CIRCUIT DEVICES ALAR3 AND AZAR1 & 3 PIN ORIENTATION IS AS SHOWN BELOW



6. INTEGRATED CIRCUIT DEVICE ALAR4 & 9
PIN ORIENTATION IS AS SHOWN BELOW



3 SYMBC MEANS N-CHANNEL
INSULATED GATE ENHANCEMENT
TYPE SINGLE GATE MCS-FET

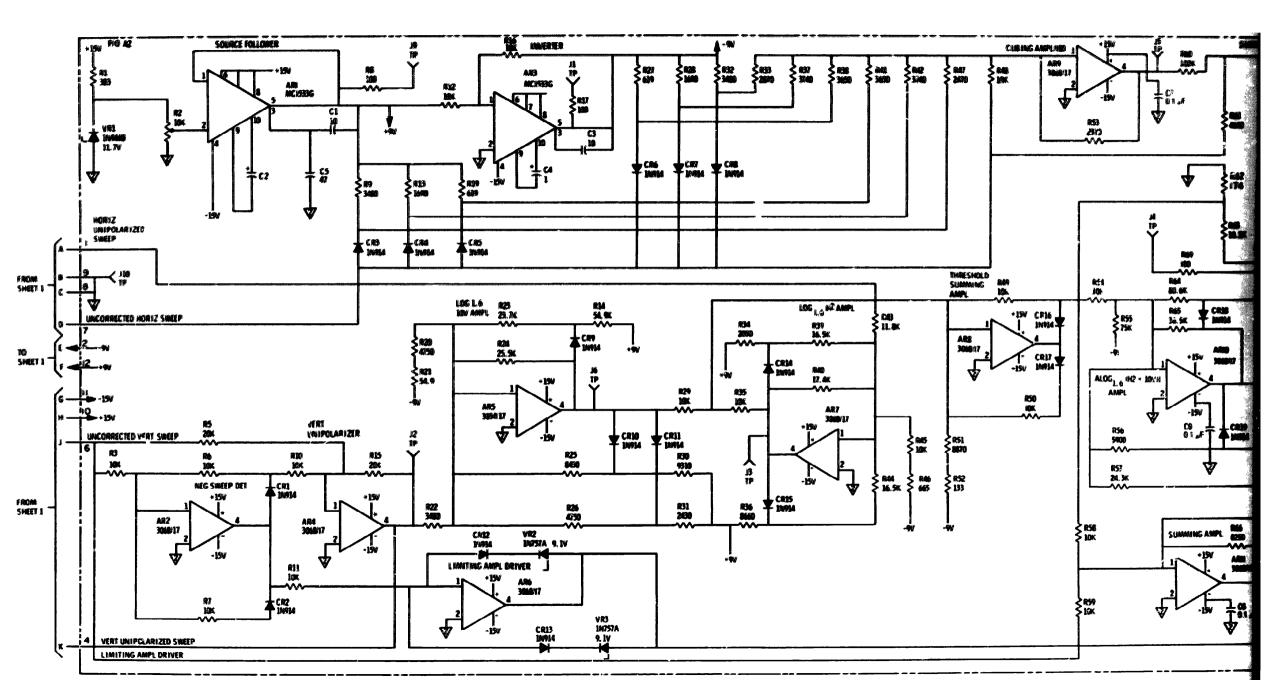


PHO AL HORIZ UNIPOLANIZER INSULATED GATE ENHANCEMENT ZNASA SWATCH SWEEP SAIR TE OF SAME 10 SHEET 2 VERT SAP CEN - FROM SHEET 2 mgrizgintal Gefset 2 421 5 1046 ER GE SMITTEM SMITTCH DRINGR A 0.000 YOME CHAMP 1 200 200302 5441000 VERTICAL OFFSET FIXED OURSEL AND BEST AESLICHE AESLICHE OURSEL ONEURE AENTIFCHE H2. V2 SQUARING SOUPCI FOLLOWER ZIMEISE SAMRCH - 10 SHEET 2 1058 20V POLARITY SENSOR DRIVER TOWNS > \$R9 \$IOOK 2 (15) 4 204892 SHINTICH ARII 3068/17 丰品 -201 GANN 13 EL: AGG26 3 3 3 8 ÷

SYMBOL MEANS H-CHARREL

THE SINGLE GATE MOS-FET

Figure FO-24. Sweep generator, 2A4, schematic diagram (sheet 1 of 2)



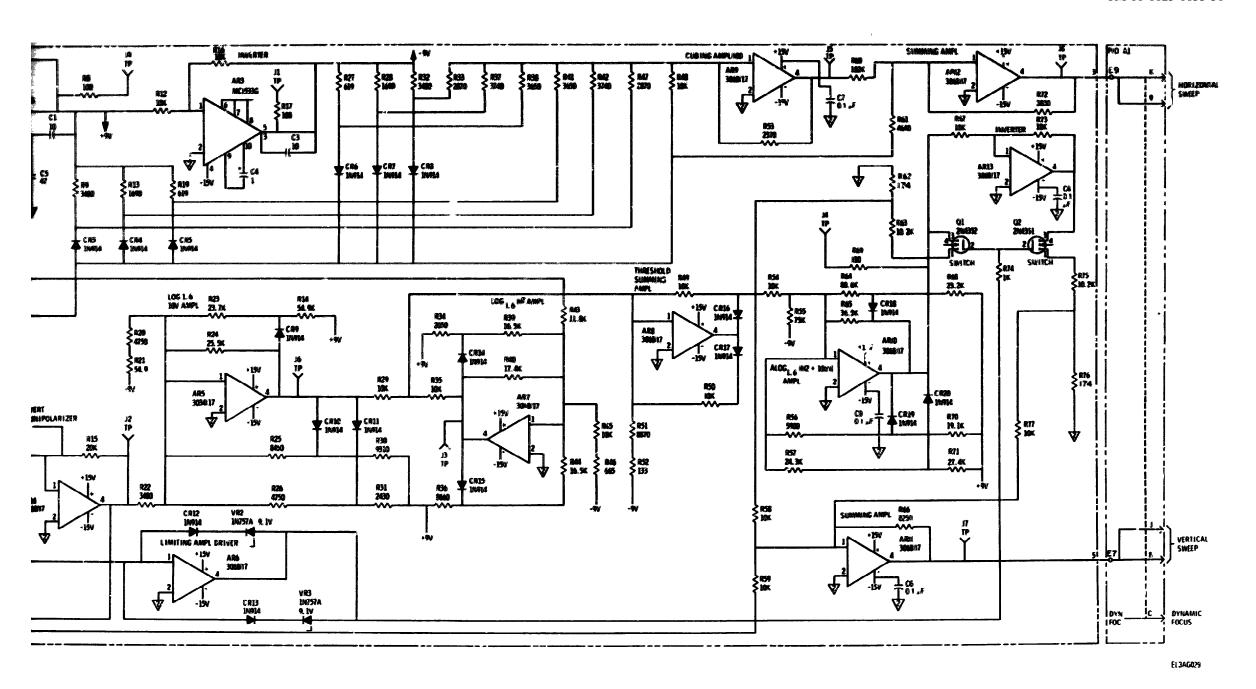
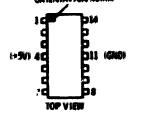


Figure FO-24. Sweep generator, 2A4, schematic diagram (sheet 2 of 2)

NOTES:

- L PARTIAL REFERENCE DESIGNATIONS
 ARE SHOWN. FOR COMPLETE DESIGNATIONS PREFIX WITH 245.
- 2. UNLESS OTHERWISE SPECIFIED ALL RESISTORS ARE IN OHMS ALL CAPACITORS ARE IN UF ALL INDUCTORS ARE IN UF
- 3. INTEGRATED CIRCUIT DEVICES UZ THRU
 US2 HAWE PARTIAL TYPE NUMBERS
 SHOWN, FOR COMPLETE TYPE NUMBER
 PREFIX BITH SE AND SUFFIX WITH J.
 EXAMPLE: 880 SHOWN
 SERSI TYPE NO.
 PIN GRIENTATION IS AS SHOWN BELOW.
 OBJERNATION MARK



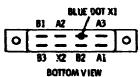
4. INTEGRATED CIRCUIT DEVICES ASARS, 2, 5, AND 6 PIN ORIENTATION IS AS SHOWN BELOW.

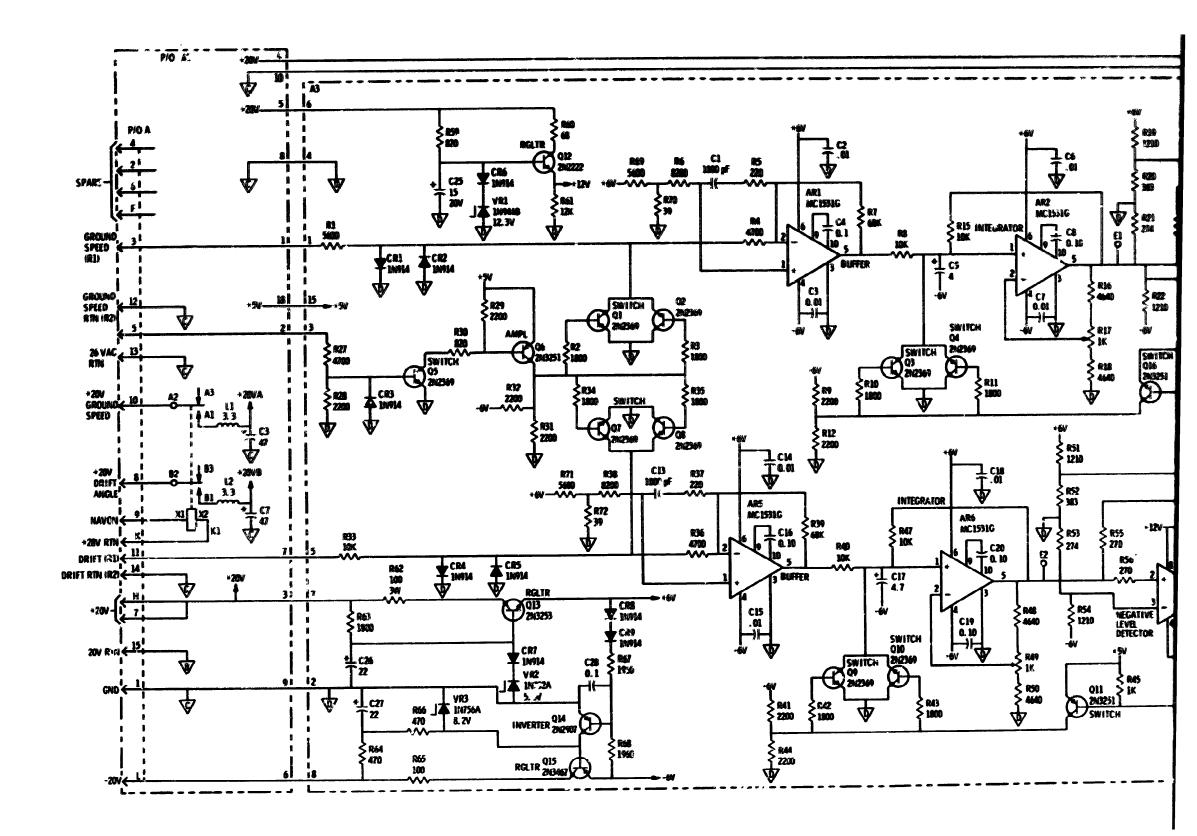


5. INTEGRATED CIRCUIT DEVICES A3AR3, 4, 7, AND 8 PIN ORIENTATION IS AS SHOWN BELOW.



6. RELAY AZKI IS SHOWN IN DE-ENERGIZED STATE. PIN ORIENTATION IS AS SHOWN BELOW.





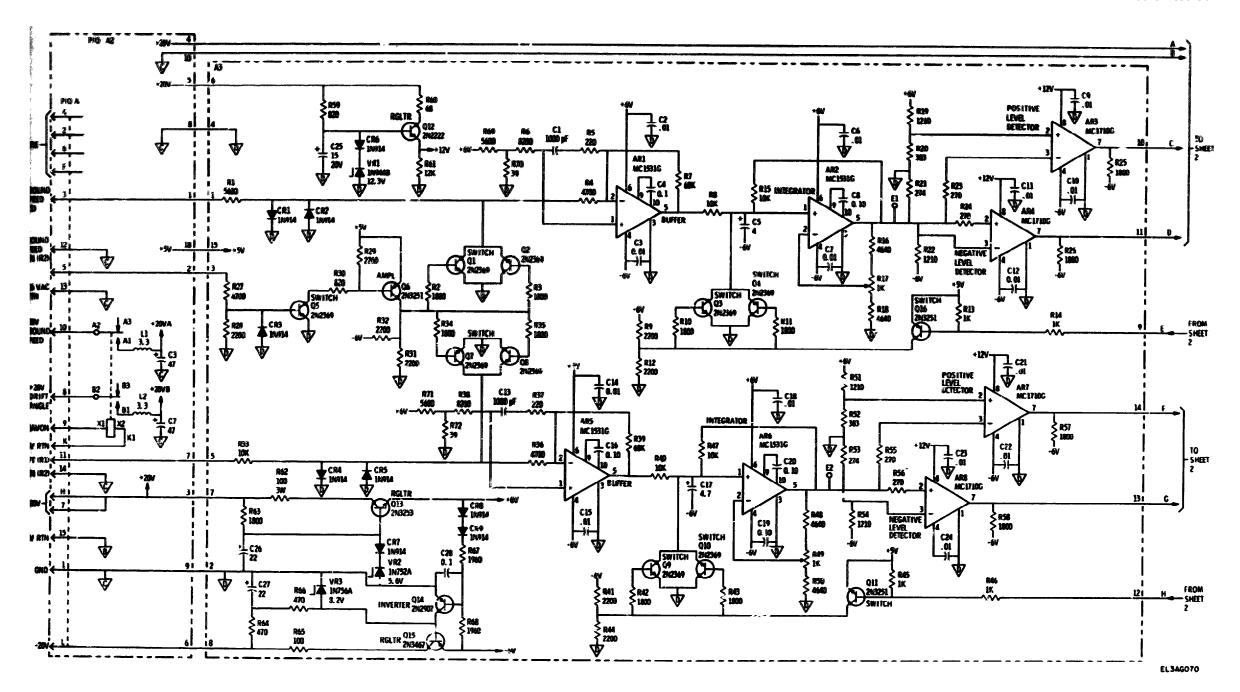
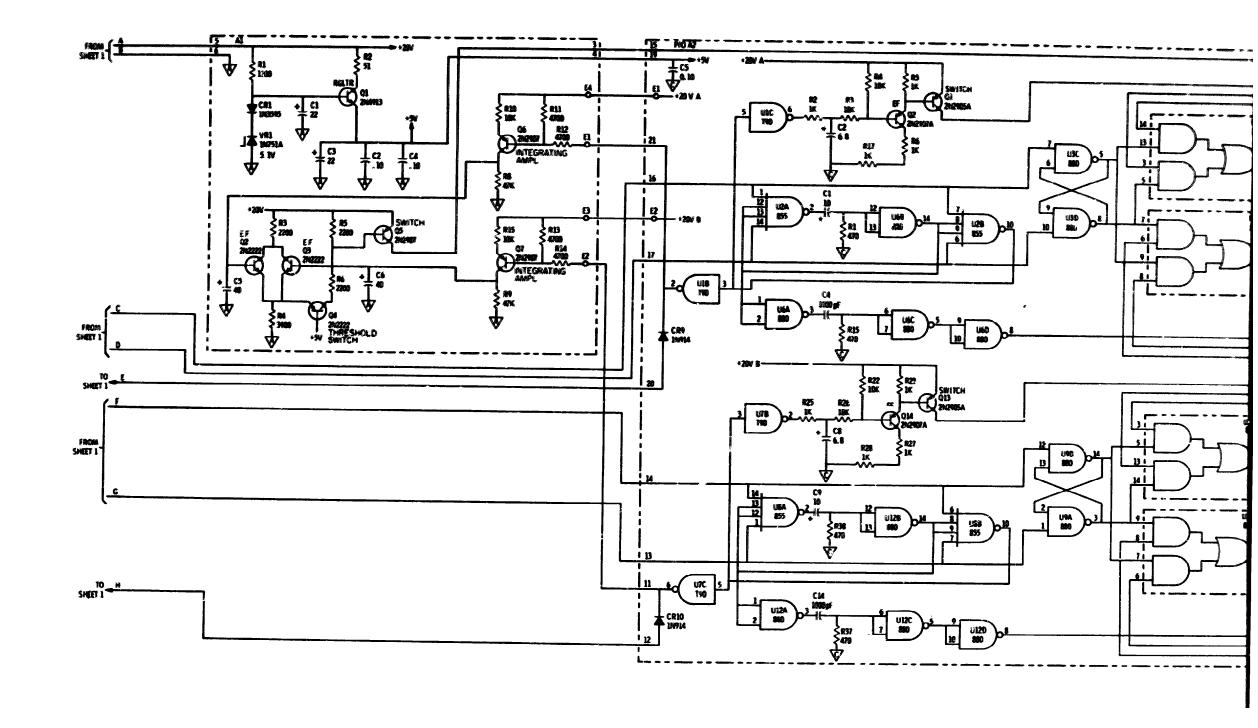


Figure FO-25,. servoamplifer, 2A5, schematic diagram (sheet 1 of 2).



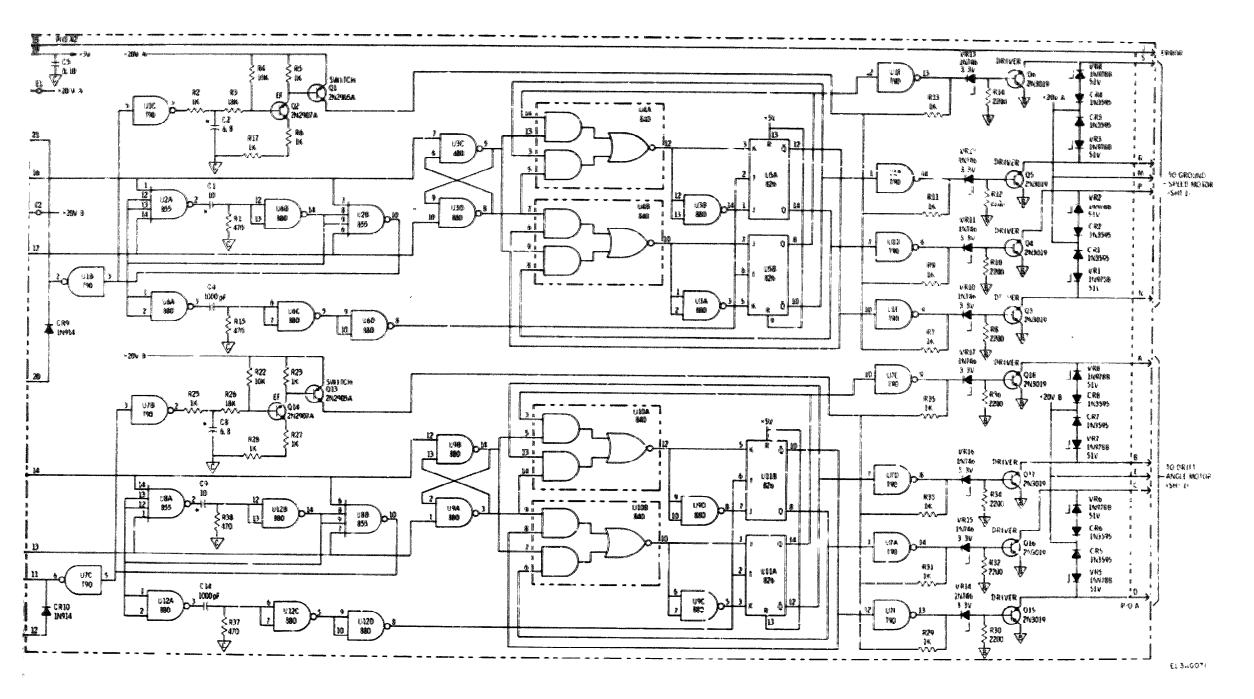


Figure FO-25. Servoamplifer, 2A5 schematic diagram (sheet 2 of 2)

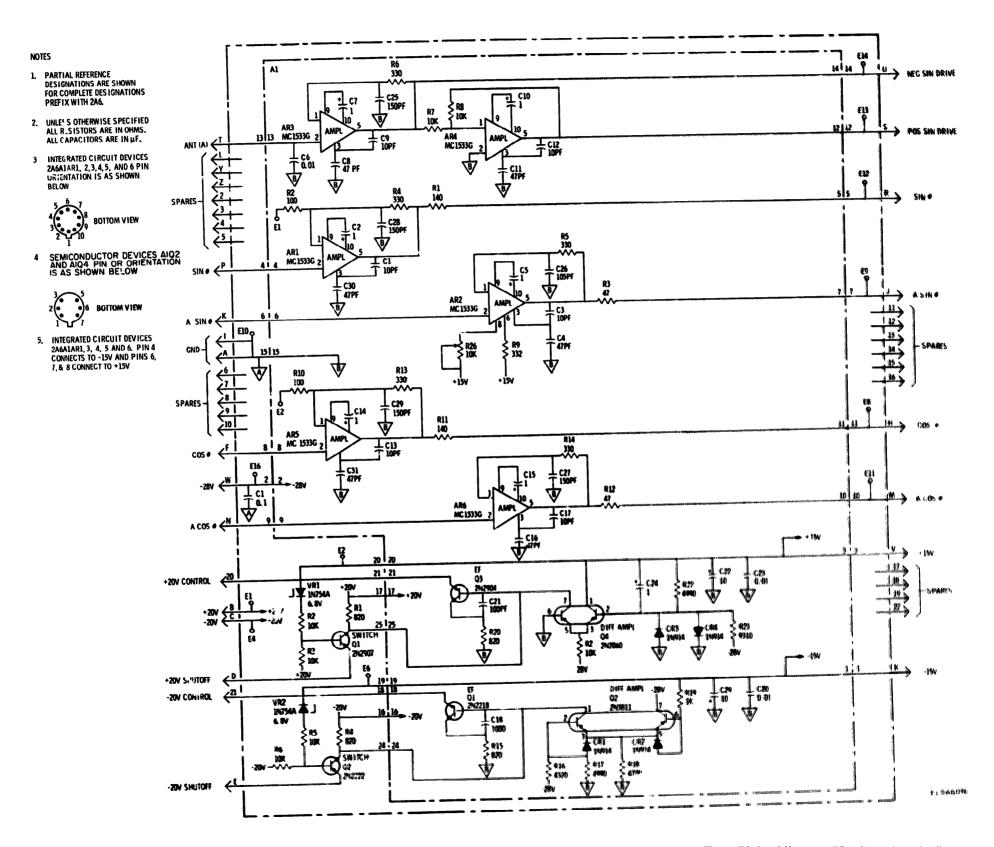
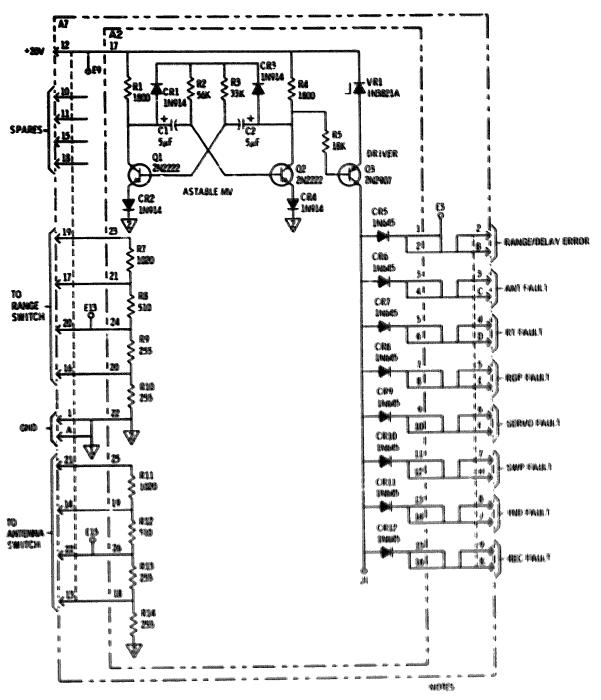


Figure FO-26. Offset amplifier 2A6 schematic diagram



- PARTIAL REFERENCE BESIGNATIONS AND SHOWN FOR COMPLETE BESIGN WITH SAF
- APP DESTRUMENT OF A SAME APP DESTRUMENT OF A SAME

Order of the Secretary of the Army:

BERNARD W. ROGERS General, United States Army Chief of Staff

cial:

J. C. PENNINGTON ior General, United States Army The Adjutant General

TRIBUTION:

To be distributed in accordance with DA Form 12-36, Direct and General Support maintenance requireits for AN/APS-94.

END 03-17-83

DATE





